Radiation Report

TPS7H5007-SEP and TPS7H5003-SP QMLP Neutron Displacement Damage (NDD) Characterization Report

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H5007-SEP and TPS7H5003-SP QMLP PWM controller. Both the TPS7H5007-SEP and TPS7H5003-SP QMLP showed a strong degree of hardness to neutron irradiation up to fluence level 1 × 10^{13} n/cm^2.

The neutron irradiation test is a destructive test. Test procedure follows MIL-STD-883 method 1017 as guidance. The purpose of this test is to determine the device susceptibility to non-ionizing energy loss (NIEL) degradation. Objectives of the test are, to detect and measure the degradation of critical device parameters as a function of neutron fluence and to determine if these parameters are within specified limits after exposure to a specified level of neutron fluence.

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1 Device Information

1.1 Product Description

The TPS7H5007-SEP and TPS7H5003-SP QMLP are a 4-V to 14-V single output PWM controller that contains an integrated synchronous rectification output, optimized for DC-DC converters. The dead time and leading edge blank time are fixed at 50 ns for this device. The controller can be configured for maximum duty cycle of 75% or 100%. As such, the DCL pin can be left floating or connected to VLDO. Connection of the DCL pin to AVSS is not permissible for this device. The 0.613-V ±1% accurate internal reference allows design of high-current buck converters for FPGA core voltages.

The TPS7H5007-SEP and TPS7H5003-SP QMLP can be driven using an external clock through the SYNC pin or run using its internal oscillator at a frequency programmed by the user. Other programmable features include the UVLO threshold, soft start, and slope compensation. These devices are packaged in a very small 24-pin TSSOP (thin-shrink small outline package) package. As the TPS7H5003-SP QMLP uses the same material set, the results are applicable to both devices.

1.2 Device Details

Device and Exposure Details lists the device information and test conditions used in the NDD characterization.

Table 1-1. Device and Exposure Details

NDD Exposure Details	
TI Devices	TPS7H5007-SEP
TI Part Name	TPS7H5007MPWTSEP
Device Function	PWM controller
Package	24-pin TSSOP
Technology	LBC7
Lot Number / Lot Trace Code	2013065 / 1AC9LRK
Sample Quantity	9 + 1 control unit
Exposure Facility	Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor (UMLRR)
Neutron Fluence (1-MeV equivalent) Level	1 × 10^{12}, 5 × 10^{12}, 1 × 10^{13} n/cm^2
Irradiation Temperature	25°C

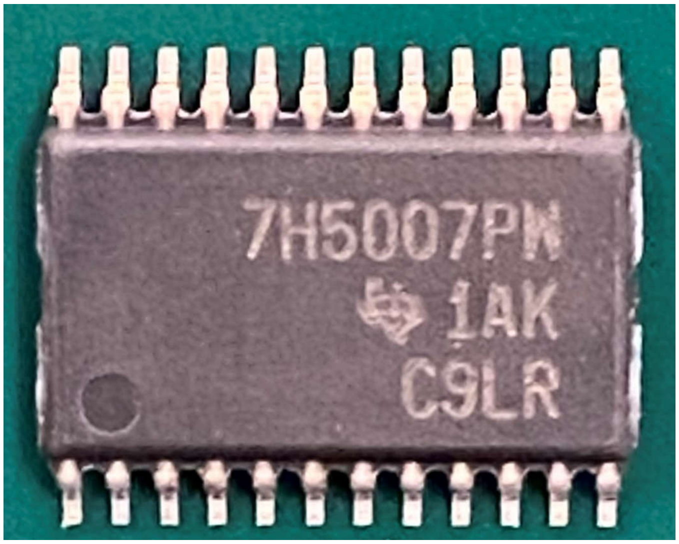


Figure 1-1. TPS7H5007-SEP Device

2 Total Dose Test Setup

2.1 Test Overview

General test procedures adhere to MIL-STD-883, Method 1017 as a guide for neutron irradiation. The TPS7H5007-SEP was electrically tested using the production automated test equipment (ATE) program at an ambient room temperature of 25°C before and after neutron irradiation.

2.2 Test Facility

The utilized test facility is the Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor. The neutron fluence for this irradiation was measured utilizing ASTM E-265 “Measuring Reaction Rates and Fast Neutron Fluence by Radioactivation of Sulfur-32” and correlated to the measured reactor power level. All irradiation conditions required under ASTM 722 were met, this includes: neutron fluence, distribution and uncertainty. The Average Integrated Neutron Fluence, 1-MeV(Si) equivalent, reflects these factors.

Detailed information of the radiation facility is available at the following link:

https://www.uml.edu/docs/FNI%20Brochure_tcm18-90375.pdf

2.3 Test Setup Details

Devices were irradiated at three fluence levels in unbiased conditions: 1.0×10^{12} n/cm^2, 5.0×10^{12} n/cm^2 and 1.0×10^{13} n/cm^2.

Table 2-1. Neutron Irradiation Conditions

GROUP	SAMPLE QTY	NEUTRON FLUENCE (n/cm^2)	BIAS
A	3	1.0×10^{12}	Unbias
B	3	5.0×10^{12}	Unbias
C	3	1.0×10^{13}	Unbias
Control Unit	1	N/A	N/A

3 Test Results

3.1 NDD Characterization Summary

The results show that all devices were fully functional and within specification limits. A sample size of nine units was exposed for neutron irradiation and an additional unirradiated control unit was used as correlation.

Overall, the TPS7H5007-SEP showed a strong degree of hardness to Neutron irradiation up to fluence level 1 × 10^{13} n/cm^2. As the TPS7H5003-SP QMLP uses the same material set, the results are applicable to this orderable as well.The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each fluence level. The parameters that showed a greater degree of change between pre- and post- irradiation were still within the Electrical Performance Characteristics specified in the Data Sheet Electrical Parameters table. See Table 3-1 for the Data Sheet Electrical Parameters and Associated Tests.

Electrical testing is done for pre- and post- neutron irradiation by ATE. ATE electrical test is done at an ambient room temperature of 25°C. Parameters not listed in the Table 3-1 are omitted either because there is no parametric data or because verification was done through bench testing.

See Appendix A for NDD report up to 1.0 × 10^{13} n/cm^2.

3.2 Data Sheet Electrical Parameters and Associated Tests

Table 3-1. TPS7H5007-SEP and TPS7H5003-SP QMLP Electrical Parameters Table

PARAMETER	TEST CONDITION	TPS7H5007-SEP and TPS7H5003-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
SUPPLY VOLTAGES AND CURRENTS						
IDD Operating supply current	f_{SW} = 500 kHz, No load for OUTA, OUTB, SRA, and SRB		6.25	8	mA	5.24 __IDD_ACT_500K_NOLOAD_4V, 5.25 __IDD_ACT_500K_NOLOAD_5V, 5.26 __IDD_ACT_500K_NOLOAD_12V, 5.27 __IDD_ACT_500K_NOLOAD_14V
	f_{SW} = 1 MHz, No load for OUTA, OUTB, SRA, and SRB		6.75	9.5	mA	5.28 __IDD_ACT_1M_NOLOAD_4V, 5.29 __IDD_ACT_1M_NOLOAD_5V, 5.30 __IDD_ACT_1M_NOLOAD_12V, 5.31 __IDD_ACT_1M_NOLOAD_14V
	f_{SW} = 2 MHz, No load for OUTA, OUTB, SRA, and SRB		8.5	13.5	mA	5.36 __IDD_ACT_2M_NOLOAD_4V, 5.37 __IDD_ACT_2M_NOLOAD_5V, 5.38 __IDD_ACT_2M_NOLOAD_12V, 5.39 __IDD_ACT_2M_NOLOAD_14V
	f_{SW} = 500 kHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		7.5	9.5	mA	5.48 __IDD_ACT_500K_4V, 5.49 __IDD_ACT_500K_5V, 5.50 __IDD_ACT_500K_12V, 5.51 __IDD_ACT_500K_14V
	f_{SW} = 1 MHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		9	12	mA	5.52 __IDD_ACT_1M_4V, 5.53 __IDD_ACT_1M_5V, 5.54 __IDD_ACT_1M_12V, 5.55 __IDD_ACT_1M_14V
	f_{SW} = 2 MHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		14	19.5	mA	5.60 __IDD_ACT_2M_4V, 5.61 __IDD_ACT_2M_5V, 5.62 __IDD_ACT_2M_12V, 5.63 __IDD_ACT_2M_14V
$I_{DD(dis)}$ Standby current	EN = 0 V			3	mA	5.1 __IDD_DIS_4V, 5.2 __IDD_DIS_5V, 5.3 __IDD_DIS_12V 5.4 __IDD_DIS_14V
VLDO Internal linear regulator output voltage	5 V ≤VIN ≤ 14 V, fsw ≤ 1 MHz	4.75	5	5.2	V	5.65 __V_LDO_100K_5V, 5.66 __V_LDO_100K_12V, 5.67 __V_LDO_100K_14V, 5.69 __V_LDO_200K_5V, 5.70 __V_LDO_200K_12V, 5.71 __V_LDO_200K_14V, 5.73 __V_LDO_500K_5V, 5.74 __V_LDO_500K_12V, 5.75 __V_LDO_500K_14V, 5.77 __V_LDO_1M_5V, 5.78 __V_LDO_1M_12V, 5.79 __V_LDO_1M_14V
	5 V ≤ VIN ≤ 14 V, fsw = 2 MHz	4.65	5	5.2	V	5.85 __V_LDO_2M_5V, 5.86 __V_LDO_2M_12V, 5.87 __V_LDO_2M_14V
ENABLE AND UNDERVOLTAGE LOCKOUT						
V_{ENR} EN threshold rising		0.57	0.6	0.65	V	6.5 __V_EN_RISE_4V, 6.8 __V_EN_RISE_5V, 6.11 __V_EN_RISE_12V, 6.14 __V_EN_RISE_14V
V_{ENF} EN threshold falling		0.47	0.5	0.55	V	6.6 __V_EN_FALL_4V, 6.9 __V_EN_FALL_5V, 6.12 __V_EN_FALL_12V, 6.15 __V_EN_FALL_14V
V_{ENH} EN hysteresis voltage		85	95	105	mV	6.7 __V_EN_HYS_4V, 6.10 __V_EN_HYS_5V, 6.13 __V_EN_HYS_12V, 6.16 __V_EN_HYS_14V
I_{EN} EN pin input leakage current	VIN = 14 V, EN = 5V		5	50	nA	6.1 __I_EN_LEAK_4V, 6.2 __I_EN_LEAK_5V, 6.3 __I_EN_LEAK_12V, 6.4 __I_EN_LEAK_14V
$VLDO_{UVLOR}$ VLDO UVLO rising		3.44	3.55	3.66	V	6.34 __UVLO_VLDO_RISE_1MHz, 6.37 __UVLO_VLDO_RISE_100kHz, 6.40 __UVLO_VLDO_RISE_200kHz, 6.43 __UVLO_VLDO_RISE_500kHz, 6.46 __UVLO_VLDO_RISE_2MHz
$VLDO_{UVLOF}$ VLDO UVLO falling		3.29	3.4	3.51	V	6.35 __UVLO_VLDO_FALL_1MHz, 6.38 __UVLO_VLDO_FALL_100kHz, 6.41 __UVLO_VLDO_FALL_200kHz, 6.44 __UVLO_VLDO_FALL_500kHz, 6.47 __UVLO_VLDO_FALL_2MHz
$VLDO_{UVLOH}$ VLDO UVLO hysteresis		115	135	160	mV	6.36 __UVLO_VLDO_HYS_1MHz, 6.39 __UVLO_VLDO_HYS_100kHz, 6.42 __UVLO_VLDO_HYS_200kHz, 6.45 __UVLO_VLDO_HYS_500kHz, 6.48 __UVLO_VLDO_HYS_2MHz
SOFT START						
I_{SS} Soft-start current	SS = 0.3 V	1.98	2.7	3.32	µA	7.1 __I_SS_4V, 7.3 __I_SS_5V, 7.5 __I_SS_12V, 7.7 __I_SS_14V
ERROR AMPLIFIER						
EA_{gm} Transconductance	–2 µA < I_{COMP} < 2 µA, $V_{(COMP)}$ = 1 V	1150	1800	2500	µA/V	8.9 __EA_GM_4V, 8.10 __EA_GM_5V, 8.11 __EA_GM_12V, 8.12 __EA_GM_14V

Table 3-1. TPS7H5007-SEP and TPS7H5003-SP QMLP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5007-SEP and TPS7H5003-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
EA$_{ISRC}$ Error amplifier source current	V$_{(COMP)}$ = 1 V, 100-mV input overdrive	100		190	µA	8.13 __EA_I_SOURCE_4V, 8.14 __EA_I_SOURCE_5V, 8.15 __EA_I_SOURCE_12V, 8.16 __EA_I_SOURCE_14V
EA$_{ISNK}$ Error amplifier sink current	V$_{(COMP)}$ = 1 V, 100-mV input overdrive	100		190	µA	8.17 __EA_I_SINK_4V, 8.18 __EA_I_SINK_5V, 8.19 __EA_I_SINK_12V, 8.20 __EA_I_SINK_14V
EA$_{OS}$ Error amplifier offset voltage		–2		2	mV	8.5 __EA_OS_4V, 8.6 __EA_OS_5V, 8.7 __EA_OS_12V, 8.8 __EA_OS_14V
OSCILLATOR						
SYNC$_{RT}$ SYNC out low-to-high rise time (10%/90%)	C$_{LOAD}$ = 25 pF		6	15	ns	9.1 __T_SYNC_RISE_100kHz_4V, 9.5 __T_SYNC_RISE_200kHz_4V, 9.9 __T_SYNC_RISE_500kHz_4V, 9.13 __T_SYNC_RISE_1MHz_4V, 9.17 __T_SYNC_RISE_1p5MHz_4V, 9.21 __T_SYNC_RISE_2MHz_4V, 9.25 __T_SYNC_RISE_100kHz_5V, 9.29 __T_SYNC_RISE_200kHz_5V, 9.33 __T_SYNC_RISE_500kHz_5V, 9.37 __T_SYNC_RISE_1MHz_5V, 9.41 __T_SYNC_RISE_1p5MHz_5V, 9.45 __T_SYNC_RISE_2MHz_5V, 9.49 __T_SYNC_RISE_100kHz_12V, 9.53 __T_SYNC_RISE_200kHz_12V, 9.57 __T_SYNC_RISE_500kHz_12V, 9.61 __T_SYNC_RISE_1MHz_12V, 9.65 __T_SYNC_RISE_1p5MHz_12V, 9.69 __T_SYNC_RISE_2MHz_12V, 9.73 __T_SYNC_RISE_100kHz_14V, 9.77 __T_SYNC_RISE_200kHz_14V, 9.81 __T_SYNC_RISE_500kHz_14V, 9.85 __T_SYNC_RISE_1MHz_14V, 9.89 __T_SYNC_RISE_1p5MHz_14V, 9.93 __T_SYNC_RISE_2MHz_14V
SYNC$_{FT}$ SYNC out high-to-low fall time (10%/90%)	C$_{LOAD}$ = 25 pF		6	17	ns	9.2 __T_SYNC_FALL_100kHz_4V, 9.14 __T_SYNC_FALL_1MHz_4V, 9.22 __T_SYNC_FALL_2MHz_4V, 9.26 __T_SYNC_FALL_100kHz_5V, 9.38 __T_SYNC_FALL_1MHz_5V, 9.46 __T_SYNC_FALL_2MHz_5V, 9.74 __T_SYNC_FALL_100kHz_14V, 9.86 __T_SYNC_FALL_1MHz_14V, 9.94 __T_SYNC_FALL_2MHz_14V
SYNC$_{OL}$ SYNC out low level	I$_{OL}$= 10 mA			500	mV	9.186__SYNC_VOL_4V, 9.187__SYNC_VOL_5V, 9.188__SYNC_VOL_12V, 9.189__SYNC_VOL_14V
EXT$_{DT}$ Externally set frequency detection time	RT = Open, f = 200 kHz			20	µs	9.185__T_SYNC_DETECT
FSW$_{EXT}$ Externally set frequency	RT = 1.07 MΩ	95	105	115	kHz	9.4 __FSW_EXT_RT_100kHz_4V, 9.28 __FSW_EXT_RT_100kHz_5V, 9.52 __FSW_EXT_RT_100kHz_12V, 9.76 __FSW_EXT_RT_100kHz_14V
	RT = 511 kΩ	190	210	230	kHz	9.8 __FSW_EXT_RT_200kHz_4V, 9.32 __FSW_EXT_RT_200kHz_5V, 9.56 __FSW_EXT_RT_200kHz_12V, 9.80 __FSW_EXT_RT_200kHz_14V
	RT =90.9 kΩ	900	1000	1100	kHz	9.16 __FSW_EXT_RT_1MHz_4V, 9.40 __FSW_EXT_RT_1MHz_5V, 9.64 __FSW_EXT_RT_1MHz_12V, 9.88 __FSW_EXT_RT_1MHz_14V
	RT = 34.8 kΩ	1700	2000	2300	kHz	9.24 __FSW_EXT_RT_2MHz_4V, 9.48 __FSW_EXT_RT_2MHz_5V, 9.72 __FSW_EXT_RT_2MHz_12V, 9.96 __FSW_EXT_RT_2MHz_14V
VOLTAGE REFERENCE						
VREF Internal voltage reference initial tolerance	Measured at COMP, 25°C	0.609	0.613	0.615	V	8.1 __VREF_4V, 8.2 __VREF_5V, 8.3 __VREF_12V, 8.4 __VREF_14V

Table 3-1. TPS7H5007-SEP and TPS7H5003-SP QMLP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5007-SEP and TPS7H5003-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
REFCAP REFCAP voltage	REFCAP = 470 nF	1.213	1.225	1.237	V	5.88 __V_REFCAP_100K_4V, 5.89 __V_REFCAP_100K_5V, 5.90 __V_REFCAP_100K_12V, 5.91 __V_REFCAP_100K_14V, 5.92 __V_REFCAP_200K_4V, 5.93 __V_REFCAP_200K_5V, 5.94 __V_REFCAP_200K_12V, 5.95 __V_REFCAP_200K_14V, 5.96 __V_REFCAP_500K_4V, 5.97 __V_REFCAP_500K_5V, 5.98 __V_REFCAP_500K_12V, 5.99 __V_REFCAP_500K_14V, 5.100__V_REFCAP_1M_4V, 5.101__V_REFCAP_1M_5V, 5.102__V_REFCAP_1M_12V, 5.103__V_REFCAP_1M_14V, 5.104__V_REFCAP_1P5M_4V, 5.105__V_REFCAP_1P5M_5V, 5.106__V_REFCAP_1P5M_12V, 5.107__V_REFCAP_1P5M_14V, 5.108__V_REFCAP_2M_4V, 5.109__V_REFCAP_2M_5V, 5.110__V_REFCAP_2M_12V, 5.111__V_REFCAP_2M_14V
CURRENT SENSE, CURRENT LIMIT, AND HICCUP						
CCSR	COMP to CS_ILIM ratio	2.00	2.06	2.12		10.49 __CCSR_Ratio
V_{CS_ILIM} Current limit (over-current) threshold			1.05	1.09	V	10.1 __V_CS_ILIM_OC_Rise_4V, 10.3 __V_CS_ILIM_OC_Rise_5V, 10.5 __V_CS_ILIM_OC_Rise_12V, 10.7 __V_CS_ILIM_OC_Rise_14V
FAULT						
V_{FLTR} FLT threshold rising		0.57	0.6	0.65	V	12.1 __V_FAULT_RISE_4V, 12.4 __V_FAULT_RISE_5V, 12.7 __V_FAULT_RISE_12V, 12.10 __V_FAULT_RISE_14V
V_{FLTF} FLT threshold falling		0.47	0.5	0.55	V	12.2 __V_FAULT_FALL_4V, 12.5 __V_FAULT_FALL_5V, 12.8 __V_FAULT_FALL_12V, 12.11 __V_FAULT_FALL_14V
V_{FLTH} FLT hysteresis voltage		90	100	110	mV	12.3 __V_FAULT_HYS_4V, 12.6 __V_FAULT_HYS_5V, 12.9 __V_FAULT_HYS_12V, 12.12 __V_FAULT_HYS_14V
T_{FLT} FLT minimum pulse width	V_{FLT} = 1 V	0.4		1.4	µs	12.14 __T_FAULT_MIN
t_{DFLT} FLT delay duration	f_{sw} = 100 kHz	140	152	169	µs	12.15 __T_FAULT_DELAY_100kHz
	f_{sw} = 200 kHz	66	78	86	µs	12.17 __T_FAULT_DELAY_200kHz
	f_{sw} = 1 MHz	14	17	21	µs	12.21 __T_FAULT_DELAY_1MHz
	f_{sw} = 2 MHz	7	11	14	µs	12.23 __T_FAULT_DELAY_2MHz
PRIMARY AND SYNCHRONOUS RECTIFIER OUTPUTS						
Rise/fall time	R_{LOAD} = 50 kΩ, C_{LOAD} = 100 pF, 10% to 90%		10	17	ns	13.1 __OUTA_RISE_1MHz_4V, 13.9 __OUTA_RISE_1MHz_5V, 13.17 __OUTA_RISE_1MHz_12V, 13.25 __OUTA_RISE_1MHz_14V, 13.3 __OUTA_FALL_1MHz_4V, 13.11 __OUTA_FALL_1MHz_5V, 13.19 __OUTA_FALL_1MHz_12V, 13.27 __OUTA_FALL_1MHz_14V
t_{MIN} Minimum on-time	5 V ≤ VIN ≤ 14 V			115	ns	13.145__OUT_T_ON_MIN
TD_{PS} Primary off to secondary on dead time	5 V ≤ VIN ≤ 14 V, 90% of OUTx falling to 10% of SRx rising, OUTx and SRx floating	40	50	60	ns	13.53 __PSA_DT_50ns_1M_5V, 13.57 __PSA_DT_50ns_1M_12V, 13.61 __PSA_DT_50ns_1M_14V,
TD_{SP} Secondary off to primary on dead time	5 V ≤ VIN ≤ 14 V, 90% of SRx falling to 10% of OUTx rising edge, OUTx and SRx floating	40	50	60	ns	13.55 __SPA_DT_50ns_1M_5V, 13.59 __SPA_DT_50ns_1M_12V, 13.63 __SPA_DT_50ns_1M_14V
DUTY CYCLE						
D_{MAX} Maximum duty cycle	DCL = floating	70	75	80	%	13.163__MAX_DC_DCL_OPEN
	DCL =VLDO			100	%	13.166__MAX_DC_DCL_VLDO

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H5007-SEP Radiation-Hardness-Assured Si and GaN Dual Output Controller* data sheet
- Texas Instruments, TPS7H500x-SP Radiation-Hardness-Assured 2-MHz Current Mode PWM Controllers
- Texas Instruments, TPS7H500x-SEP Evaluation Module (EVM)
- Texas Instruments, *TPS7H500x-SEP Single-Event Effects (SEE)* radiation report

4.2 Reference Documents

Texas Instruments neutron irradiation test follow the guideline from MIL-STD-883 TM 1017. The document is available in Defense Logistic Agency's website.

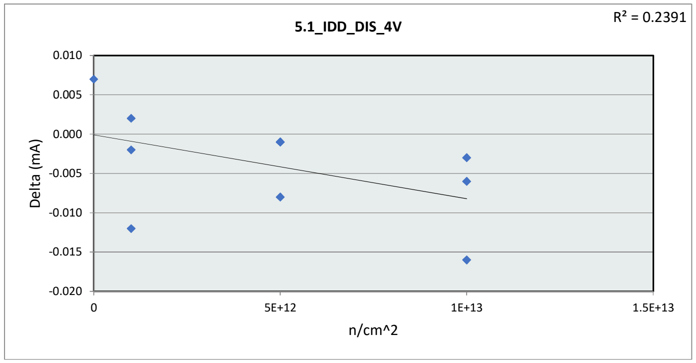
A Appendix: NDD Report Data

This appendix contains the NDD report data.

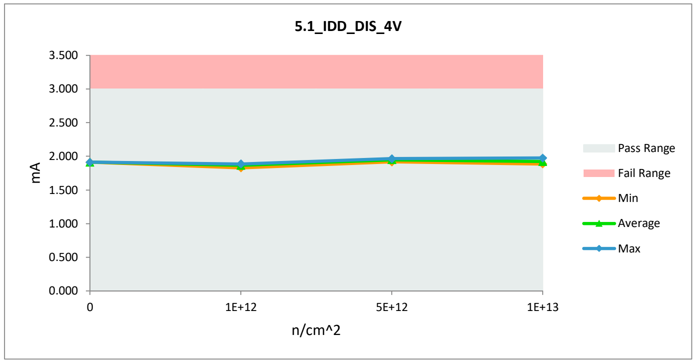
NDD Characterization Report
TPS7H5007-SEP

NDD Characterization Report
TPS7H5007-SEP

		5.1_IDD_DIS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	2.6	3	
	Min Limit	1	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.907	1.914	0.007
1E+12	21	1.885	1.887	0.002
1E+12	22	1.886	1.884	-0.002
1E+12	23	1.841	1.829	-0.012
5E+12	24	1.926	1.918	-0.008
5E+12	25	1.966	1.965	-0.001
5E+12	26	1.966	1.965	-0.001
1E+13	27	1.902	1.886	-0.016
1E+13	28	1.979	1.976	-0.003
1E+13	29	1.919	1.913	-0.006
	Max	1.979	1.976	0.007
	Average	1.918	1.914	-0.004
	Min	1.841	1.829	-0.016
	Std Dev	0.043	0.046	0.007

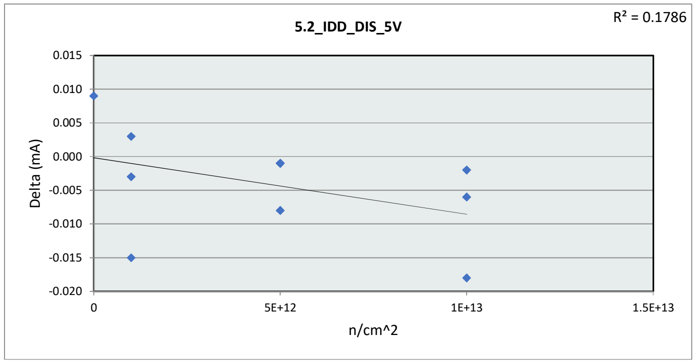


	5.1_IDD_DIS_4V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	1.914	1.829	1.918	1.886
Average	1.914	1.867	1.949	1.925
Max	1.914	1.887	1.965	1.976
UL	3.000	3.000	3.000	3.000

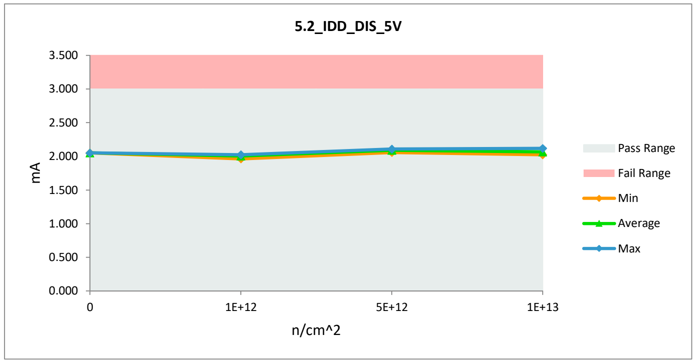


NDD Characterization Report
TPS7H5007-SEP

		5.2_IDD_DIS_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.8	3	
Min Limit		1	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.042	2.051	0.009
1E+12	21	2.021	2.024	0.003
1E+12	22	2.025	2.022	-0.003
1E+12	23	1.979	1.964	-0.015
5E+12	24	2.065	2.057	-0.008
5E+12	25	2.106	2.105	-0.001
5E+12	26	2.108	2.107	-0.001
1E+13	27	2.042	2.024	-0.018
1E+13	28	2.119	2.117	-0.002
1E+13	29	2.059	2.053	-0.006
	Max	2.119	2.117	0.009
	Average	2.057	2.052	-0.004
	Min	1.979	1.964	-0.018
	Std Dev	0.044	0.047	0.008

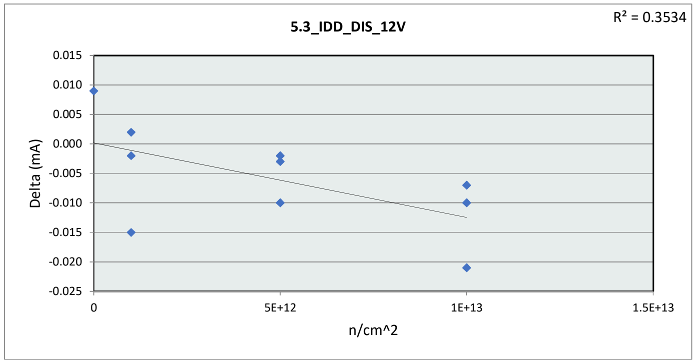


	5.2_IDD_DIS_5V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	2.051	1.964	2.057	2.024
Average	2.051	2.003	2.090	2.065
Max	2.051	2.024	2.107	2.117
UL	3.000	3.000	3.000	3.000

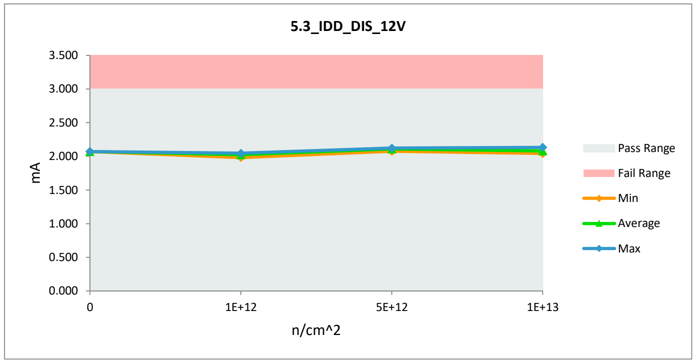


NDD Characterization Report
TPS7H5007-SEP

		5.3_IDD_DIS_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.8	3	
Min Limit		1	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.063	2.072	0.009
1E+12	21	2.043	2.045	0.002
1E+12	22	2.045	2.043	-0.002
1E+12	23	1.998	1.983	-0.015
5E+12	24	2.085	2.075	-0.010
5E+12	25	2.127	2.124	-0.003
5E+12	26	2.127	2.125	-0.002
1E+13	27	2.061	2.040	-0.021
1E+13	28	2.142	2.135	-0.007
1E+13	29	2.079	2.069	-0.010
	Max	2.142	2.135	0.009
	Average	2.077	2.071	-0.006
	Min	1.998	1.983	-0.021
	Std Dev	0.045	0.047	0.009

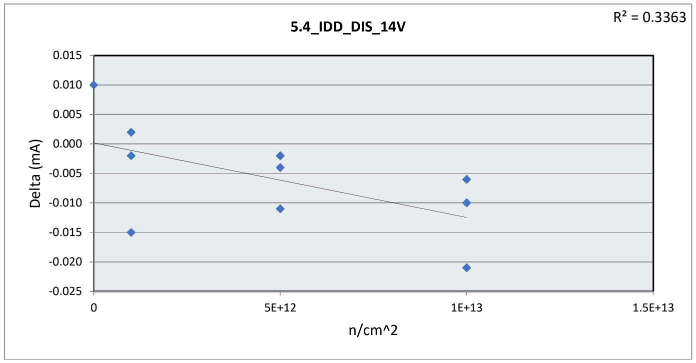


	5.3_IDD_DIS_12V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	2.072	1.983	2.075	2.040
Average	2.072	2.024	2.108	2.081
Max	2.072	2.045	2.125	2.135
UL	3.000	3.000	3.000	3.000

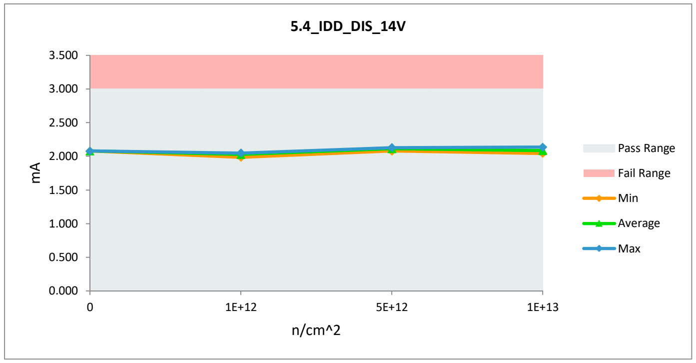


NDD Characterization Report
TPS7H5007-SEP

		5.4_IDD_DIS_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.8	3	
Min Limit		1	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.067	2.077	0.010
1E+12	21	2.047	2.049	0.002
1E+12	22	2.050	2.048	-0.002
1E+12	23	2.002	1.987	-0.015
5E+12	24	2.090	2.079	-0.011
5E+12	25	2.132	2.128	-0.004
5E+12	26	2.131	2.129	-0.002
1E+13	27	2.066	2.045	-0.021
1E+13	28	2.145	2.139	-0.006
1E+13	29	2.084	2.074	-0.010
	Max	2.145	2.139	0.010
	Average	2.081	2.075	-0.006
	Min	2.002	1.987	-0.021
	Std Dev	0.045	0.047	0.009

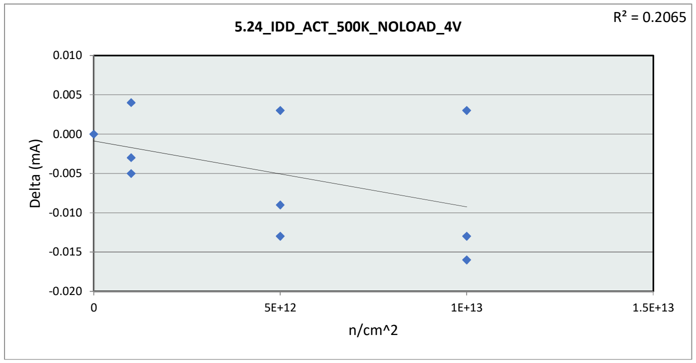


5.4_IDD_DIS_14V				
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	2.077	1.987	2.079	2.045
Average	2.077	2.028	2.112	2.086
Max	2.077	2.049	2.129	2.139
UL	3.000	3.000	3.000	3.000

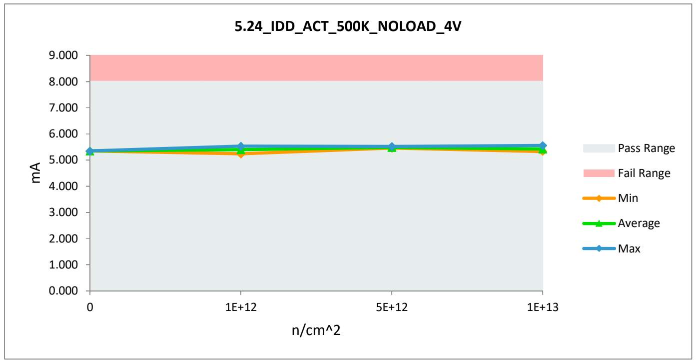


NDD Characterization Report
TPS7H5007-SEP

		5.24_IDD_ACT_500K_NOLOAD_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	7.8	8	
	Min Limit	2	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.345	5.345	0.000
1E+12	21	5.523	5.527	0.004
1E+12	22	5.421	5.416	-0.005
1E+12	23	5.239	5.236	-0.003
5E+12	24	5.468	5.455	-0.013
5E+12	25	5.466	5.469	0.003
5E+12	26	5.528	5.519	-0.009
1E+13	27	5.340	5.327	-0.013
1E+13	28	5.554	5.557	0.003
1E+13	29	5.406	5.390	-0.016
	Max	5.554	5.557	0.004
	Average	5.429	5.424	-0.005
	Min	5.239	5.236	-0.016
	Std Dev	0.099	0.101	0.007

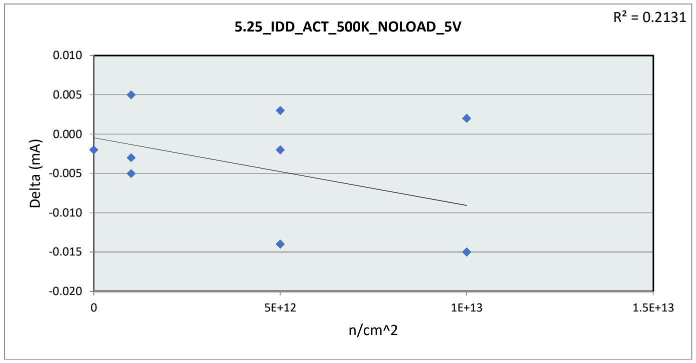


	5.24_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	5.345	5.236	5.455	5.327
Average	5.345	5.393	5.481	5.425
Max	5.345	5.527	5.519	5.557
UL	8.000	8.000	8.000	8.000

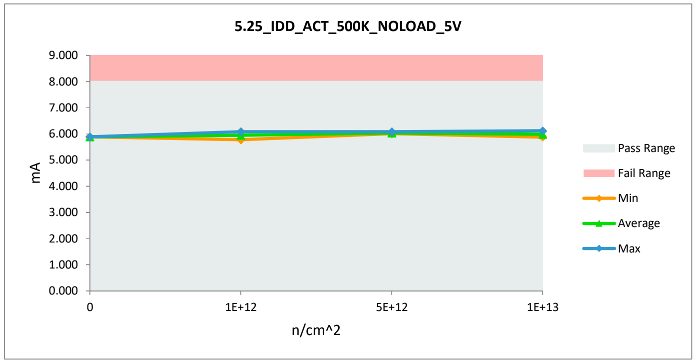


NDD Characterization Report
TPS7H5007-SEP

		5.25_IDD_ACT_500K_NOLOAD_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	7.8	8	
	Min Limit	2	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.892	5.890	-0.002
1E+12	21	6.078	6.083	0.005
1E+12	22	5.975	5.972	-0.003
1E+12	23	5.785	5.780	-0.005
5E+12	24	6.020	6.006	-0.014
5E+12	25	6.023	6.026	0.003
5E+12	26	6.080	6.078	-0.002
1E+13	27	5.892	5.877	-0.015
1E+13	28	6.113	6.115	0.002
1E+13	29	5.961	5.946	-0.015
	Max	6.113	6.115	0.005
	Average	5.982	5.977	-0.005
	Min	5.785	5.780	-0.015
	Std Dev	0.103	0.106	0.008

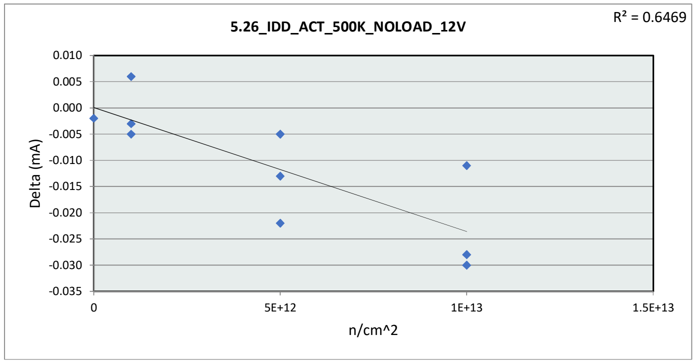


	5.25_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	5.890	5.780	6.006	5.877
Average	5.890	5.945	6.037	5.979
Max	5.890	6.083	6.078	6.115
UL	8.000	8.000	8.000	8.000

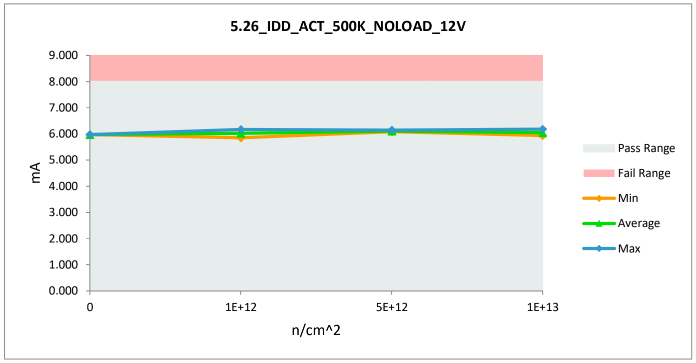


NDD Characterization Report
TPS7H5007-SEP

		5.26_IDD_ACT_500K_NOLOAD_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	7.8	8	
	Min Limit	2	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.974	5.972	-0.002
1E+12	21	6.161	6.167	0.006
1E+12	22	6.058	6.055	-0.003
1E+12	23	5.855	5.850	-0.005
5E+12	24	6.100	6.078	-0.022
5E+12	25	6.105	6.100	-0.005
5E+12	26	6.159	6.146	-0.013
1E+13	27	5.965	5.937	-0.028
1E+13	28	6.194	6.183	-0.011
1E+13	29	6.037	6.007	-0.030
	Max	6.194	6.183	0.006
	Average	6.061	6.049	-0.011
	Min	5.855	5.850	-0.030
	Std Dev	0.106	0.108	0.012

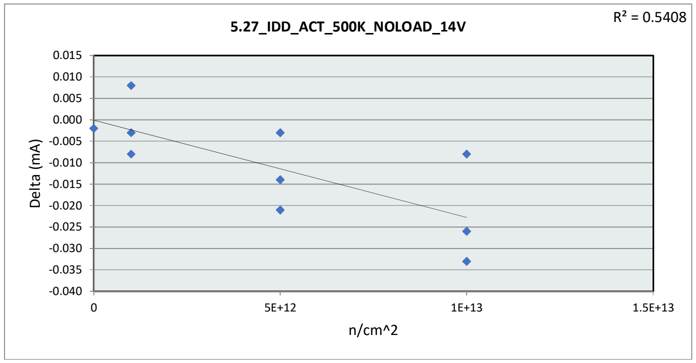


	5.26_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	5.972	5.850	6.078	5.937
Average	5.972	6.024	6.108	6.042
Max	5.972	6.167	6.146	6.183
UL	8.000	8.000	8.000	8.000

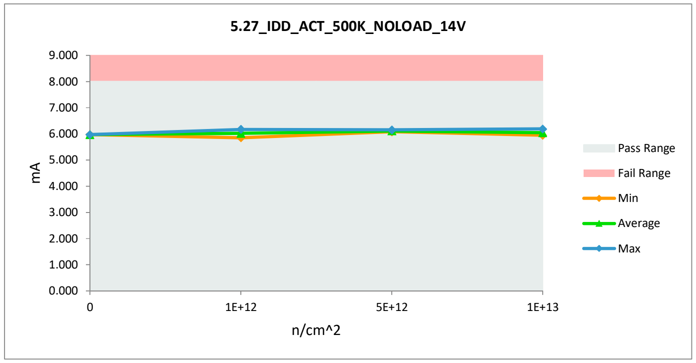


NDD Characterization Report
TPS7H5007-SEP

		5.27_IDD_ACT_500K_NOLOAD_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		7.8	8	
Min Limit		2	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.979	5.977	-0.002
1E+12	21	6.166	6.174	0.008
1E+12	22	6.066	6.058	-0.008
1E+12	23	5.858	5.855	-0.003
5E+12	24	6.104	6.083	-0.021
5E+12	25	6.110	6.107	-0.003
5E+12	26	6.164	6.150	-0.014
1E+13	27	5.971	5.945	-0.026
1E+13	28	6.198	6.190	-0.008
1E+13	29	6.044	6.011	-0.033
	Max	6.198	6.190	0.008
	Average	6.066	6.055	-0.011
	Min	5.858	5.855	-0.033
	Std Dev	0.106	0.108	0.012

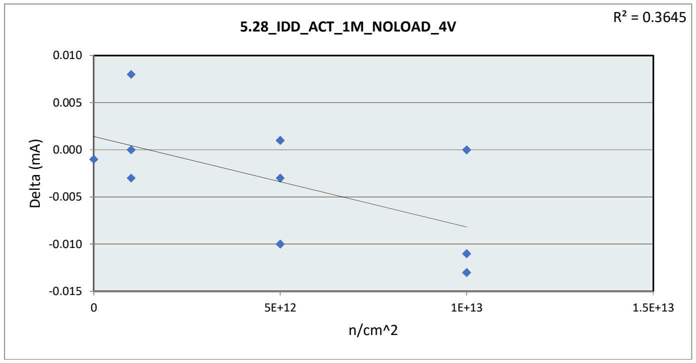


	5.27_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	5.977	5.855	6.083	5.945
Average	5.977	6.029	6.113	6.049
Max	5.977	6.174	6.150	6.190
UL	8.000	8.000	8.000	8.000

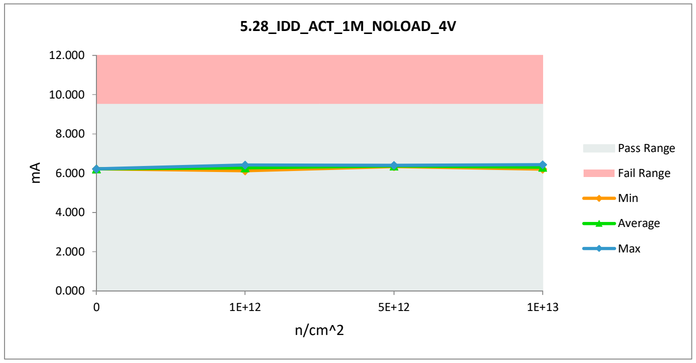


NDD Characterization Report
TPS7H5007-SEP

		5.28_IDD_ACT_1M_NOLOAD_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	6.215	6.214	-0.001
1E+12	21	6.407	6.415	0.008
1E+12	22	6.303	6.300	-0.003
1E+12	23	6.116	6.116	0.000
5E+12	24	6.342	6.332	-0.010
5E+12	25	6.354	6.355	0.001
5E+12	26	6.407	6.404	-0.003
1E+13	27	6.217	6.204	-0.013
1E+13	28	6.436	6.436	0.000
1E+13	29	6.289	6.278	-0.011
	Max	6.436	6.436	0.008
	Average	6.309	6.305	-0.003
	Min	6.116	6.116	-0.013
	Std Dev	0.102	0.104	0.006

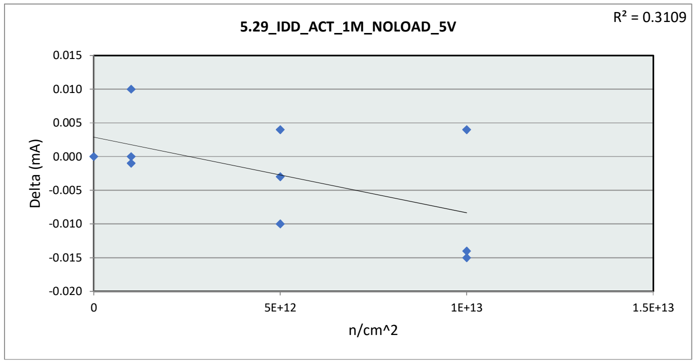


	5.28_IDD_ACT_1M_NOLOAD_4			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.214	6.116	6.332	6.204
Average	6.214	6.277	6.364	6.306
Max	6.214	6.415	6.404	6.436
UL	9.500	9.500	9.500	9.500

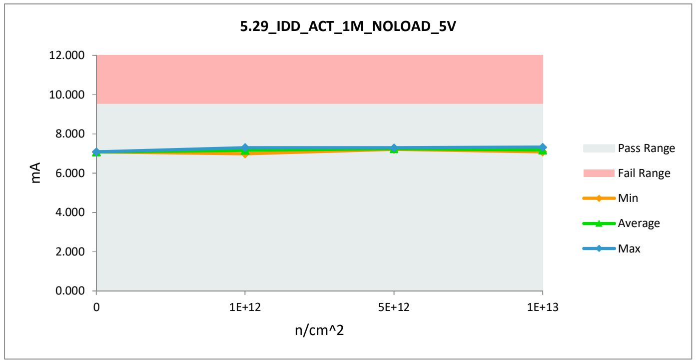


NDD Characterization Report
TPS7H5007-SEP

		5.29_IDD_ACT_1M_NOLOAD_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.1	9.5	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.083	7.083	0.000
1E+12	21	7.295	7.305	0.010
1E+12	22	7.191	7.190	-0.001
1E+12	23	6.991	6.991	0.000
5E+12	24	7.221	7.211	-0.010
5E+12	25	7.240	7.244	0.004
5E+12	26	7.295	7.292	-0.003
1E+13	27	7.097	7.082	-0.015
1E+13	28	7.318	7.322	0.004
1E+13	29	7.171	7.157	-0.014
	Max	7.318	7.322	0.010
	Average	7.190	7.188	-0.003
	Min	6.991	6.991	-0.015
	Std Dev	0.106	0.110	0.008

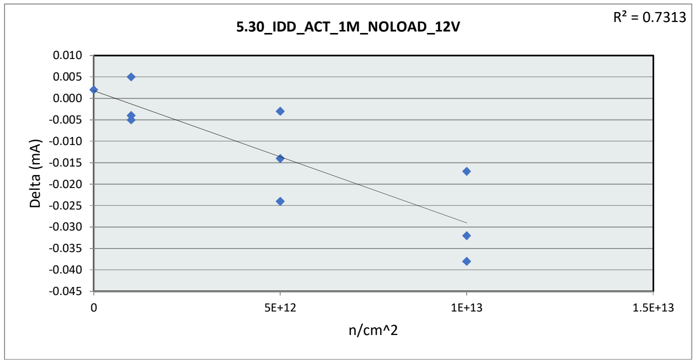


	5.29_IDD_ACT_1M_NOLOAD_5			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.083	6.991	7.211	7.082
Average	7.083	7.162	7.249	7.187
Max	7.083	7.305	7.292	7.322
UL	9.500	9.500	9.500	9.500

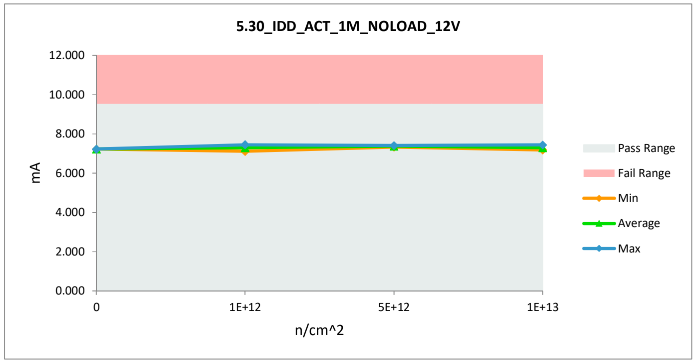


NDD Characterization Report
TPS7H5007-SEP

		5.30_IDD_ACT_1M_NOLOAD_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.1	9.5	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.226	7.228	0.002
1E+12	21	7.443	7.448	0.005
1E+12	22	7.329	7.324	-0.005
1E+12	23	7.114	7.110	-0.004
5E+12	24	7.358	7.334	-0.024
5E+12	25	7.378	7.375	-0.003
5E+12	26	7.423	7.409	-0.014
1E+13	27	7.221	7.189	-0.032
1E+13	28	7.459	7.442	-0.017
1E+13	29	7.301	7.263	-0.038
	Max	7.459	7.448	0.005
	Average	7.325	7.312	-0.013
	Min	7.114	7.110	-0.038
	Std Dev	0.111	0.113	0.015

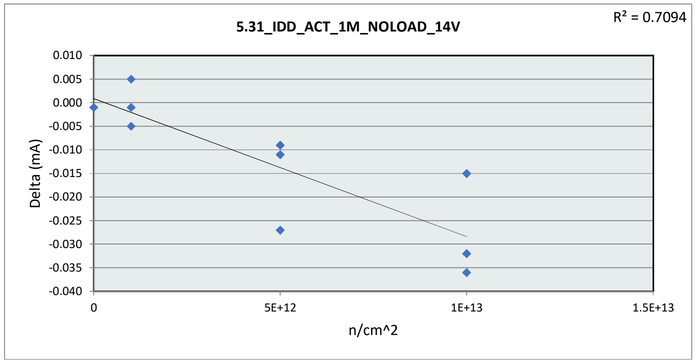


	5.30_IDD_ACT_1M_NOLOAD_1			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.228	7.110	7.334	7.189
Average	7.228	7.294	7.373	7.298
Max	7.228	7.448	7.409	7.442
UL	9.500	9.500	9.500	9.500

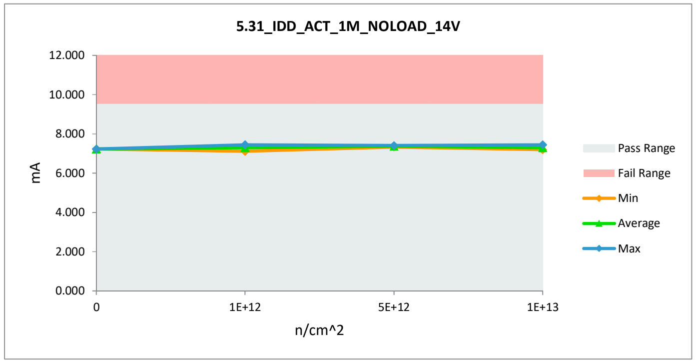


NDD Characterization Report
TPS7H5007-SEP

		5.31_IDD_ACT_1M_NOLOAD_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.1	9.5	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.230	7.229	-0.001
1E+12	21	7.446	7.451	0.005
1E+12	22	7.335	7.330	-0.005
1E+12	23	7.117	7.116	-0.001
5E+12	24	7.363	7.336	-0.027
5E+12	25	7.385	7.376	-0.009
5E+12	26	7.424	7.413	-0.011
1E+13	27	7.224	7.192	-0.032
1E+13	28	7.463	7.448	-0.015
1E+13	29	7.305	7.269	-0.036
	Max	7.463	7.451	0.005
	Average	7.329	7.316	-0.013
	Min	7.117	7.116	-0.036
	Std Dev	0.111	0.113	0.014

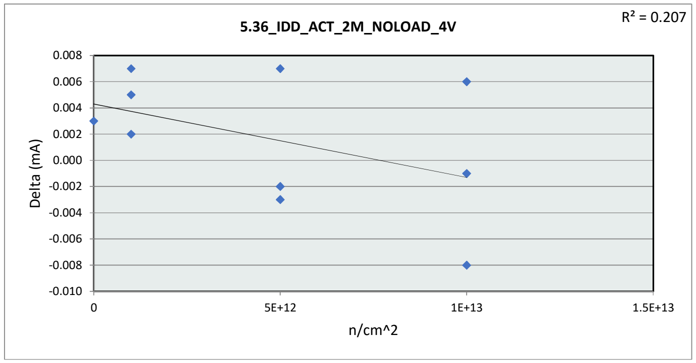


	5.31_IDD_ACT_1M_NOLOAD_1			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.229	7.116	7.336	7.192
Average	7.229	7.299	7.375	7.303
Max	7.229	7.451	7.413	7.448
UL	9.500	9.500	9.500	9.500

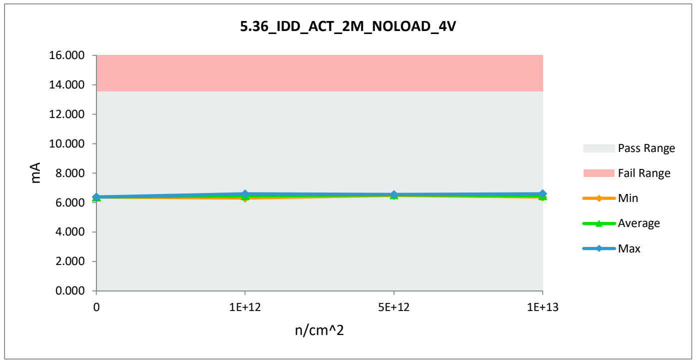


NDD Characterization Report
TPS7H5007-SEP

		5.36_IDD_ACT_2M_NOLOAD_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.5	13.5	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	6.375	6.378	0.003
1E+12	21	6.580	6.587	0.007
1E+12	22	6.504	6.509	0.005
1E+12	23	6.310	6.312	0.002
5E+12	24	6.491	6.488	-0.003
5E+12	25	6.541	6.548	0.007
5E+12	26	6.560	6.558	-0.002
1E+13	27	6.378	6.377	-0.001
1E+13	28	6.594	6.600	0.006
1E+13	29	6.444	6.436	-0.008
	Max	6.594	6.600	0.007
	Average	6.478	6.479	0.002
	Min	6.310	6.312	-0.008
	Std Dev	0.097	0.099	0.005

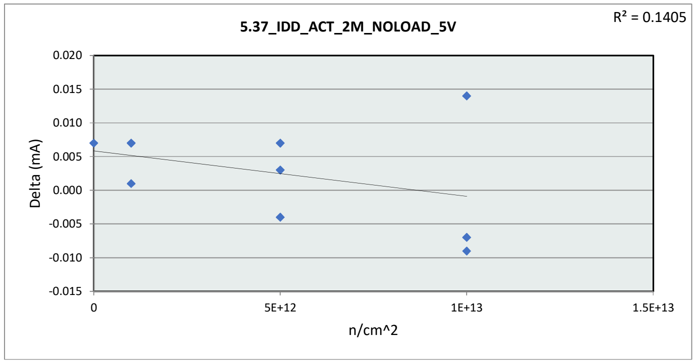


	5.36_IDD_ACT_2M_NOLOAD_4			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.378	6.312	6.488	6.377
Average	6.378	6.469	6.531	6.471
Max	6.378	6.587	6.558	6.600
UL	13.500	13.500	13.500	13.500

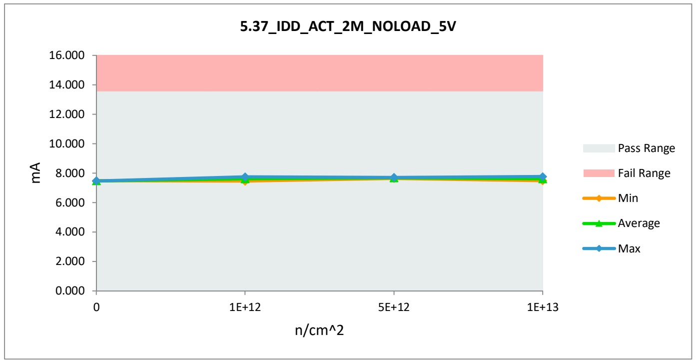


NDD Characterization Report
TPS7H5007-SEP

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
		5.37_IDD_ACT_2M_NOLOAD_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		12	13.5	
Min Limit		5	0	
0	48	7.468	7.475	0.007
1E+12	21	7.751	7.758	0.007
1E+12	22	7.644	7.645	0.001
1E+12	23	7.452	7.459	0.007
5E+12	24	7.644	7.640	-0.004
5E+12	25	7.689	7.696	0.007
5E+12	26	7.709	7.712	0.003
1E+13	27	7.505	7.498	-0.007
1E+13	28	7.755	7.769	0.014
1E+13	29	7.610	7.601	-0.009
	Max	7.755	7.769	0.014
	Average	7.623	7.625	0.003
	Min	7.452	7.459	-0.009
	Std Dev	0.112	0.115	0.007

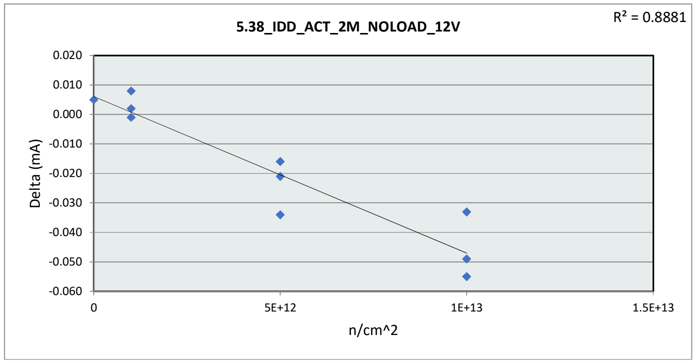


n/cm^2	0	1E+12	5E+12	1E+13
	5.37_IDD_ACT_2M_NOLOAD_5			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit	0	mA		
LL	0.000	0.000	0.000	0.000
Min	7.475	7.459	7.640	7.498
Average	7.475	7.621	7.683	7.623
Max	7.475	7.758	7.712	7.769
UL	13.500	13.500	13.500	13.500

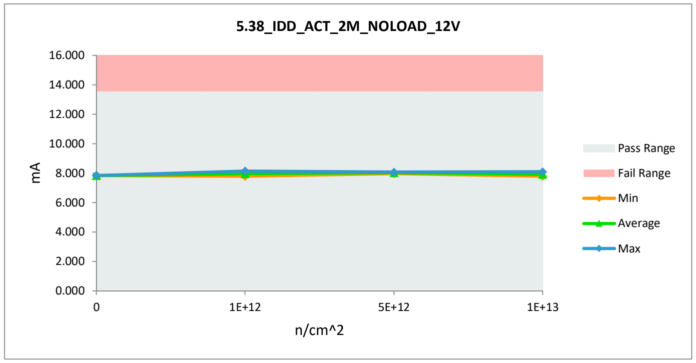


NDD Characterization Report
TPS7H5007-SEP

		5.38_IDD_ACT_2M_NOLOAD_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	12	13.5	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.841	7.846	0.005
1E+12	21	8.131	8.139	0.008
1E+12	22	8.014	8.013	-0.001
1E+12	23	7.787	7.789	0.002
5E+12	24	7.997	7.963	-0.034
5E+12	25	8.059	8.043	-0.016
5E+12	26	8.089	8.068	-0.021
1E+13	27	7.834	7.785	-0.049
1E+13	28	8.123	8.090	-0.033
1E+13	29	7.948	7.893	-0.055
	Max	8.131	8.139	0.008
	Average	7.982	7.963	-0.019
	Min	7.787	7.785	-0.055
	Std Dev	0.125	0.128	0.023

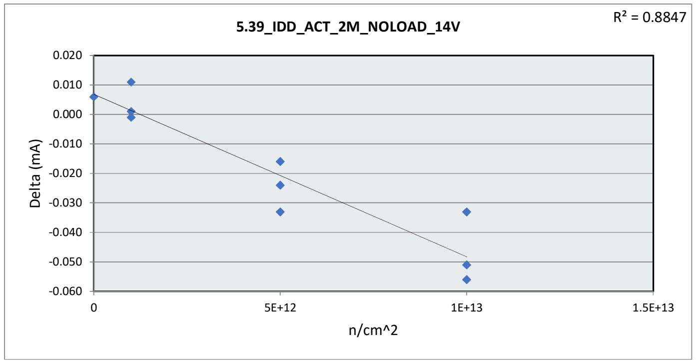


	5.38_IDD_ACT_2M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.846	7.789	7.963	7.785
Average	7.846	7.980	8.025	7.923
Max	7.846	8.139	8.068	8.090
UL	13.500	13.500	13.500	13.500

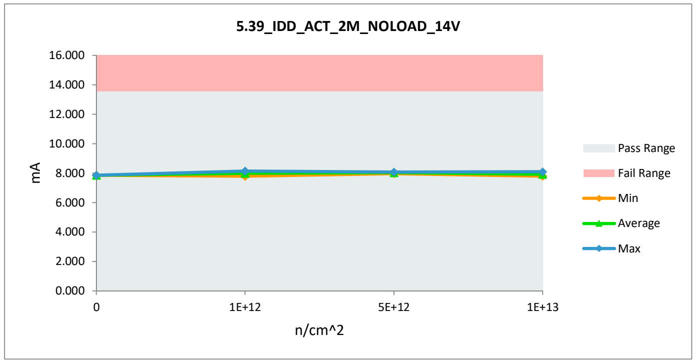


NDD Characterization Report
TPS7H5007-SEP

		5.39_IDD_ACT_2M_NOLOAD_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	12	13.5	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.847	7.853	0.006
1E+12	21	8.134	8.145	0.011
1E+12	22	8.016	8.015	-0.001
1E+12	23	7.793	7.794	0.001
5E+12	24	8.001	7.968	-0.033
5E+12	25	8.063	8.047	-0.016
5E+12	26	8.097	8.073	-0.024
1E+13	27	7.839	7.788	-0.051
1E+13	28	8.127	8.094	-0.033
1E+13	29	7.954	7.898	-0.056
	Max	8.134	8.145	0.011
	Average	7.987	7.968	-0.020
	Min	7.793	7.788	-0.056
	Std Dev	0.125	0.128	0.024



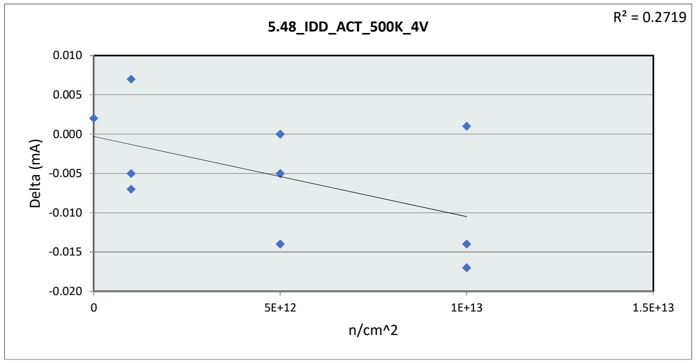
	5.39_IDD_ACT_2M_NOLOAD_1			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.853	7.794	7.968	7.788
Average	7.853	7.985	8.029	7.927
Max	7.853	8.145	8.073	8.094
UL	13.500	13.500	13.500	13.500



NDD Characterization Report
TPS7H5007-SEP

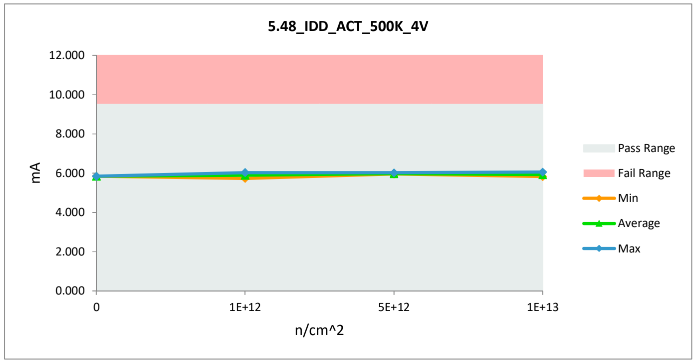
	5.48_IDD_ACT_500K_4V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	9.2	9.5
Min Limit	2	0

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.843	5.845	0.002
1E+12	21	6.027	6.034	0.007
1E+12	22	5.926	5.919	-0.007
1E+12	23	5.738	5.733	-0.005
5E+12	24	5.970	5.956	-0.014
5E+12	25	5.971	5.971	0.000
5E+12	26	6.023	6.018	-0.005
1E+13	27	5.840	5.826	-0.014
1E+13	28	6.055	6.056	0.001
1E+13	29	5.913	5.896	-0.017
	Max	6.055	6.056	0.007
	Average	5.931	5.925	-0.005
	Min	5.738	5.733	-0.017
	Std Dev	0.100	0.103	0.008



	5.48_IDD_ACT_500K_4V	
Test Site		
Tester		
Test Number		
Max Limit	9.5	mA
Min Limit	0	mA

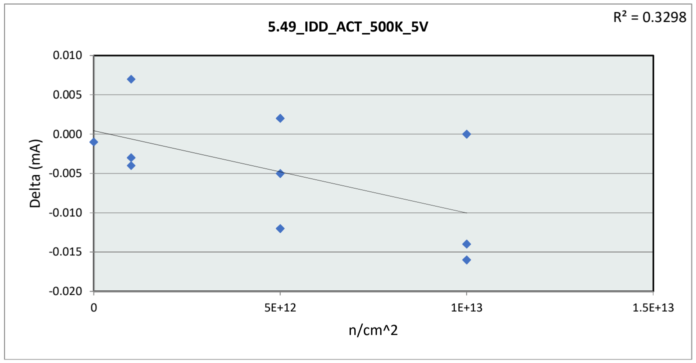
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	5.845	5.733	5.956	5.826
Average	5.845	5.895	5.982	5.926
Max	5.845	6.034	6.018	6.056
UL	9.500	9.500	9.500	9.500



NDD Characterization Report
TPS7H5007-SEP

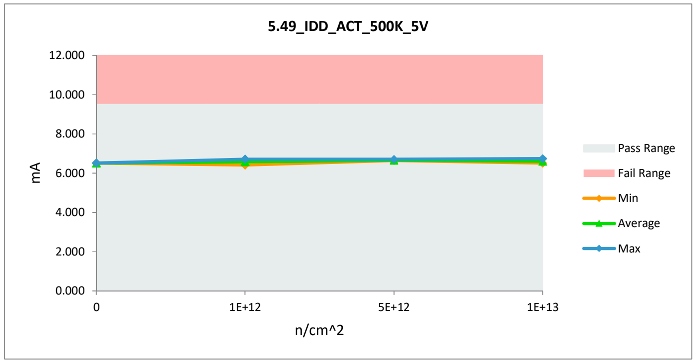
	5.49_IDD_ACT_500K_5V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	9.2	9.5
Min Limit	2	0

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	6.517	6.516	-0.001
1E+12	21	6.712	6.719	0.007
1E+12	22	6.611	6.608	-0.003
1E+12	23	6.412	6.408	-0.004
5E+12	24	6.651	6.639	-0.012
5E+12	25	6.656	6.658	0.002
5E+12	26	6.710	6.705	-0.005
1E+13	27	6.521	6.505	-0.016
1E+13	28	6.742	6.742	0.000
1E+13	29	6.594	6.580	-0.014
	Max	6.742	6.742	0.007
	Average	6.613	6.608	-0.005
	Min	6.412	6.408	-0.016
	Std Dev	0.104	0.107	0.007



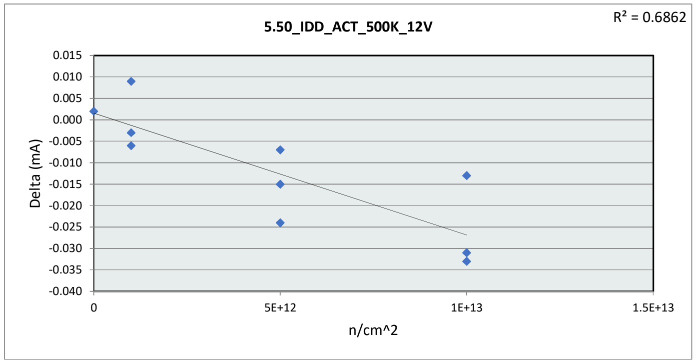
	5.49_IDD_ACT_500K_5V	
Test Site		
Tester		
Test Number		
Max Limit	9.5	mA
Min Limit	0	mA

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.516	6.408	6.639	6.505
Average	6.516	6.578	6.667	6.609
Max	6.516	6.719	6.705	6.742
UL	9.500	9.500	9.500	9.500

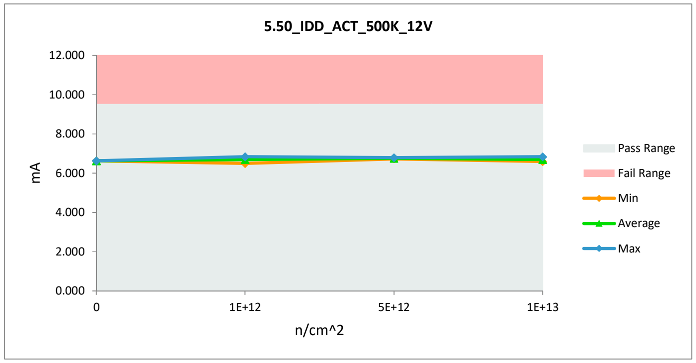


NDD Characterization Report
TPS7H5007-SEP

		5.50_IDD_ACT_500K_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	6.626	6.628	0.002
1E+12	21	6.823	6.832	0.009
1E+12	22	6.717	6.714	-0.003
1E+12	23	6.504	6.498	-0.006
5E+12	24	6.757	6.733	-0.024
5E+12	25	6.763	6.756	-0.007
5E+12	26	6.808	6.793	-0.015
1E+13	27	6.618	6.585	-0.033
1E+13	28	6.848	6.835	-0.013
1E+13	29	6.693	6.662	-0.031
	Max	6.848	6.835	0.009
	Average	6.716	6.704	-0.012
	Min	6.504	6.498	-0.033
	Std Dev	0.108	0.110	0.014

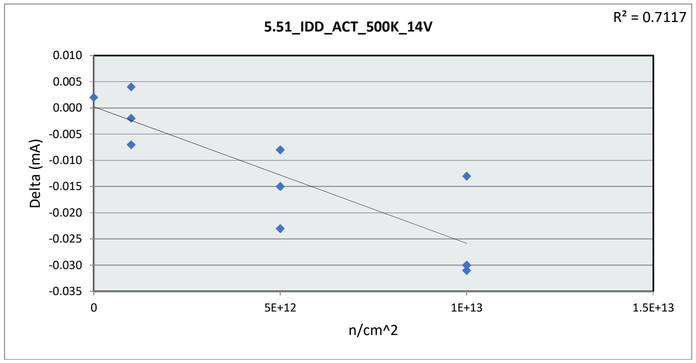


	5.50_IDD_ACT_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.628	6.498	6.733	6.585
Average	6.628	6.681	6.761	6.694
Max	6.628	6.832	6.793	6.835
UL	9.500	9.500	9.500	9.500

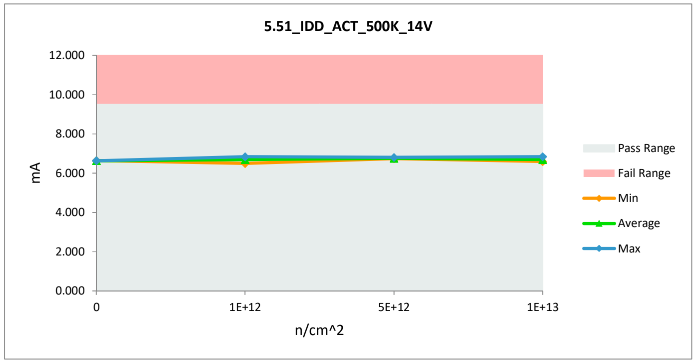


NDD Characterization Report
TPS7H5007-SEP

		5.51_IDD_ACT_500K_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	6.630	6.632	0.002
1E+12	21	6.830	6.834	0.004
1E+12	22	6.722	6.720	-0.002
1E+12	23	6.511	6.504	-0.007
5E+12	24	6.760	6.737	-0.023
5E+12	25	6.769	6.761	-0.008
5E+12	26	6.815	6.800	-0.015
1E+13	27	6.620	6.590	-0.030
1E+13	28	6.852	6.839	-0.013
1E+13	29	6.699	6.668	-0.031
	Max	6.852	6.839	0.004
	Average	6.721	6.709	-0.012
	Min	6.511	6.504	-0.031
	Std Dev	0.108	0.110	0.013

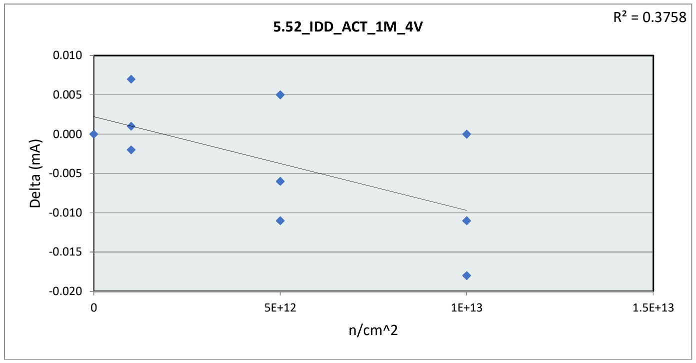


	5.51_IDD_ACT_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.632	6.504	6.737	6.590
Average	6.632	6.686	6.766	6.699
Max	6.632	6.834	6.800	6.839
UL	9.500	9.500	9.500	9.500

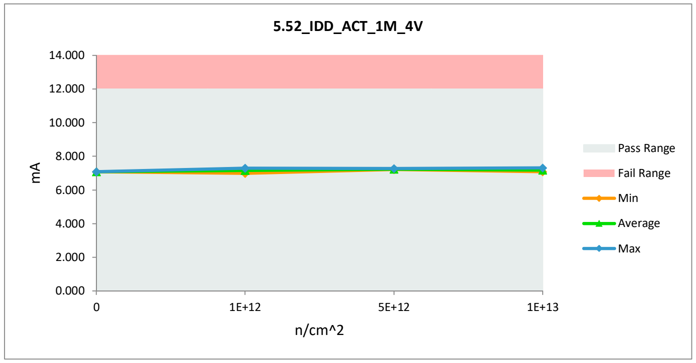


NDD Characterization Report
TPS7H5007-SEP

		5.52_IDD_ACT_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	11.7	12	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.086	7.086	0.000
1E+12	21	7.292	7.299	0.007
1E+12	22	7.184	7.182	-0.002
1E+12	23	6.993	6.994	0.001
5E+12	24	7.222	7.211	-0.011
5E+12	25	7.229	7.234	0.005
5E+12	26	7.282	7.276	-0.006
1E+13	27	7.089	7.078	-0.011
1E+13	28	7.310	7.310	0.000
1E+13	29	7.172	7.154	-0.018
	Max	7.310	7.310	0.007
	Average	7.186	7.182	-0.004
	Min	6.993	6.994	-0.018
	Std Dev	0.103	0.105	0.008

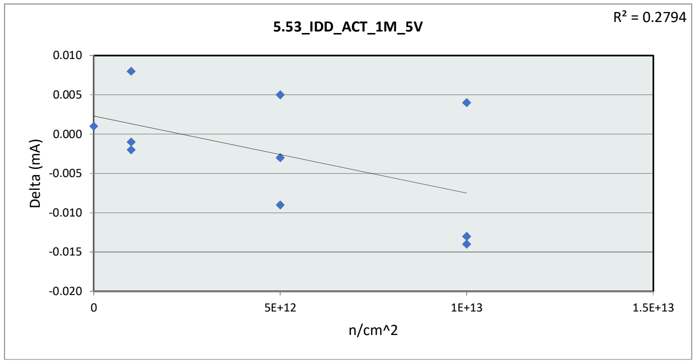


	5.52_IDD_ACT_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.086	6.994	7.211	7.078
Average	7.086	7.158	7.240	7.181
Max	7.086	7.299	7.276	7.310
UL	12.000	12.000	12.000	12.000

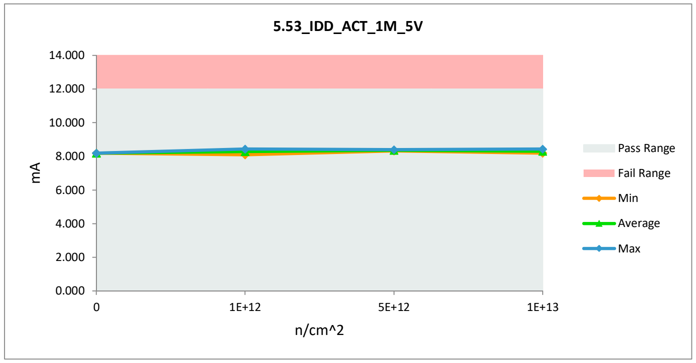


NDD Characterization Report
TPS7H5007-SEP

		5.53_IDD_ACT_1M_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.184	8.185	0.001
1E+12	21	8.416	8.424	0.008
1E+12	22	8.307	8.305	-0.002
1E+12	23	8.100	8.099	-0.001
5E+12	24	8.334	8.325	-0.009
5E+12	25	8.354	8.359	0.005
5E+12	26	8.400	8.397	-0.003
1E+13	27	8.201	8.188	-0.013
1E+13	28	8.428	8.432	0.004
1E+13	29	8.288	8.274	-0.014
	Max	8.428	8.432	0.008
	Average	8.301	8.299	-0.002
	Min	8.100	8.099	-0.014
	Std Dev	0.109	0.112	0.008

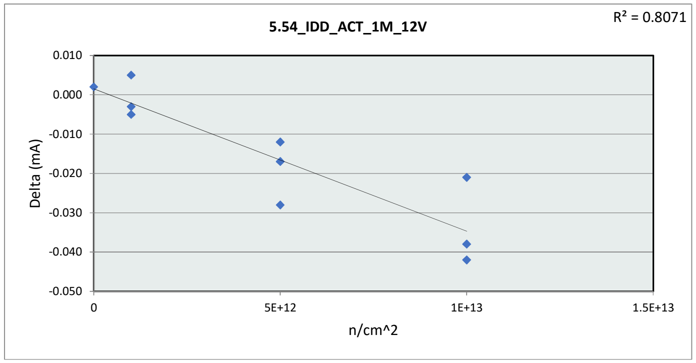


	5.53_IDD_ACT_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.185	8.099	8.325	8.188
Average	8.185	8.276	8.360	8.298
Max	8.185	8.424	8.397	8.432
UL	12.000	12.000	12.000	12.000

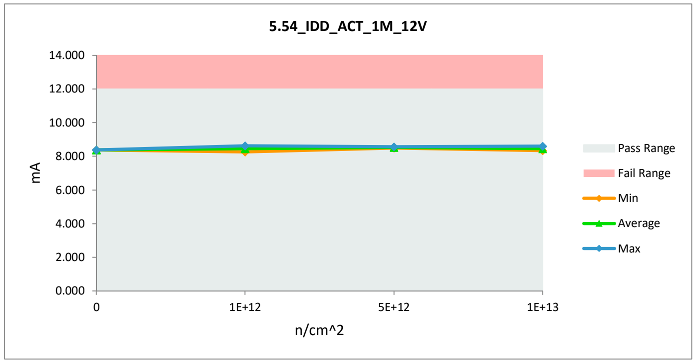


NDD Characterization Report
TPS7H5007-SEP

		5.54_IDD_ACT_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	11.7	12	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.382	8.384	0.002
1E+12	21	8.619	8.624	0.005
1E+12	22	8.503	8.498	-0.005
1E+12	23	8.272	8.269	-0.003
5E+12	24	8.526	8.498	-0.028
5E+12	25	8.547	8.535	-0.012
5E+12	26	8.579	8.562	-0.017
1E+13	27	8.377	8.339	-0.038
1E+13	28	8.623	8.602	-0.021
1E+13	29	8.468	8.426	-0.042
	Max	8.623	8.624	0.005
	Average	8.490	8.474	-0.016
	Min	8.272	8.269	-0.042
	Std Dev	0.115	0.117	0.016

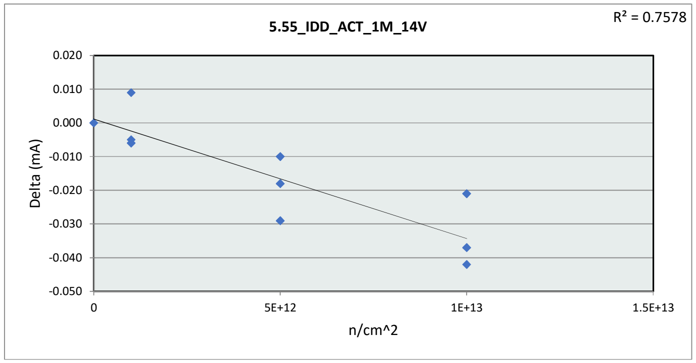


	5.54_IDD_ACT_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.384	8.269	8.498	8.339
Average	8.384	8.464	8.532	8.456
Max	8.384	8.624	8.562	8.602
UL	12.000	12.000	12.000	12.000

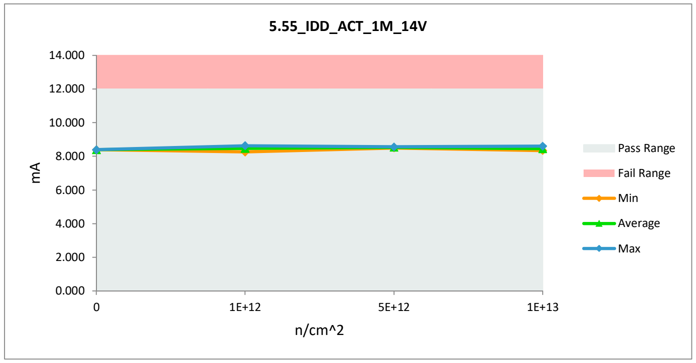


NDD Characterization Report
TPS7H5007-SEP

		5.55_IDD_ACT_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	11.7	12	
	Min Limit	5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.389	8.389	0.000
1E+12	21	8.622	8.631	0.009
1E+12	22	8.506	8.500	-0.006
1E+12	23	8.278	8.273	-0.005
5E+12	24	8.531	8.502	-0.029
5E+12	25	8.552	8.542	-0.010
5E+12	26	8.584	8.566	-0.018
1E+13	27	8.383	8.346	-0.037
1E+13	28	8.627	8.606	-0.021
1E+13	29	8.473	8.431	-0.042
	Max	8.627	8.631	0.009
	Average	8.494	8.479	-0.016
	Min	8.278	8.273	-0.042
	Std Dev	0.114	0.117	0.017

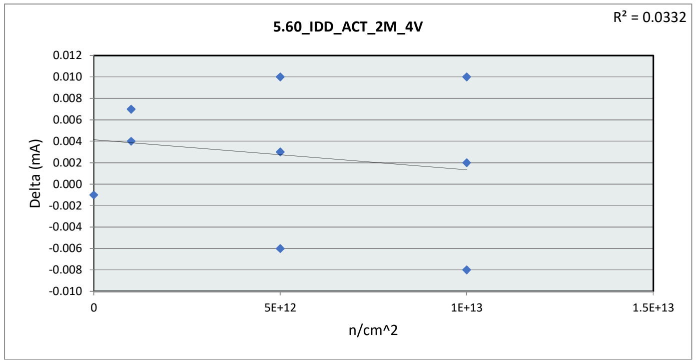


	5.55_IDD_ACT_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.389	8.273	8.502	8.346
Average	8.389	8.468	8.537	8.461
Max	8.389	8.631	8.566	8.606
UL	12.000	12.000	12.000	12.000

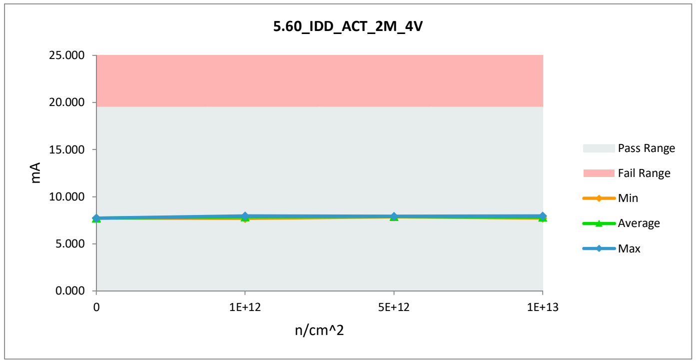


NDD Characterization Report
TPS7H5007-SEP

		5.60_IDD_ACT_2M_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		13	19.5	
Min Limit		5	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.739	7.738	-0.001
1E+12	21	7.958	7.965	0.007
1E+12	22	7.887	7.894	0.007
1E+12	23	7.685	7.689	0.004
5E+12	24	7.862	7.856	-0.006
5E+12	25	7.909	7.919	0.010
5E+12	26	7.914	7.917	0.003
1E+13	27	7.733	7.735	0.002
1E+13	28	7.954	7.964	0.010
1E+13	29	7.815	7.807	-0.008
	Max	7.958	7.965	0.010
	Average	7.846	7.848	0.003
	Min	7.685	7.689	-0.008
	Std Dev	0.098	0.101	0.006

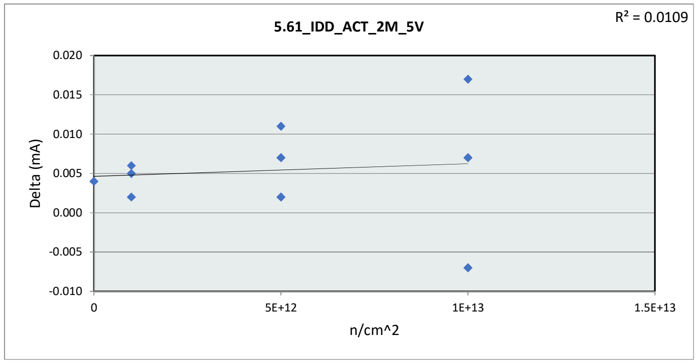


	5.60_IDD_ACT_2M_4V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.738	7.689	7.856	7.735
Average	7.738	7.849	7.897	7.835
Max	7.738	7.965	7.919	7.964
UL	19.500	19.500	19.500	19.500

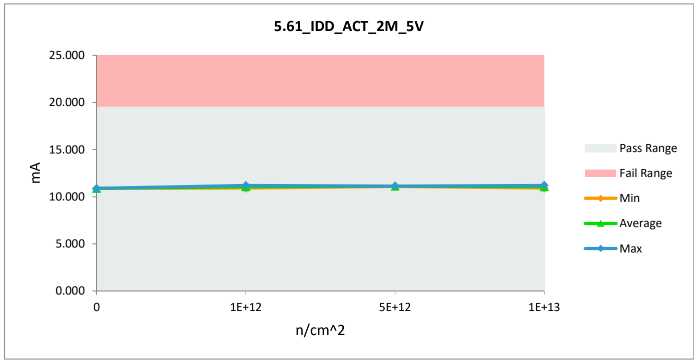


NDD Characterization Report
TPS7H5007-SEP

		5.61_IDD_ACT_2M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	18	19.5	
	Min Limit	10	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	10.877	10.881	0.004
1E+12	21	11.193	11.199	0.006
1E+12	22	11.083	11.085	0.002
1E+12	23	10.900	10.905	0.005
5E+12	24	11.092	11.094	0.002
5E+12	25	11.123	11.130	0.007
5E+12	26	11.106	11.117	0.011
1E+13	27	10.928	10.921	-0.007
1E+13	28	11.191	11.208	0.017
1E+13	29	11.044	11.051	0.007
	Max	11.193	11.208	0.017
	Average	11.054	11.059	0.005
	Min	10.877	10.881	-0.007
	Std Dev	0.115	0.119	0.006

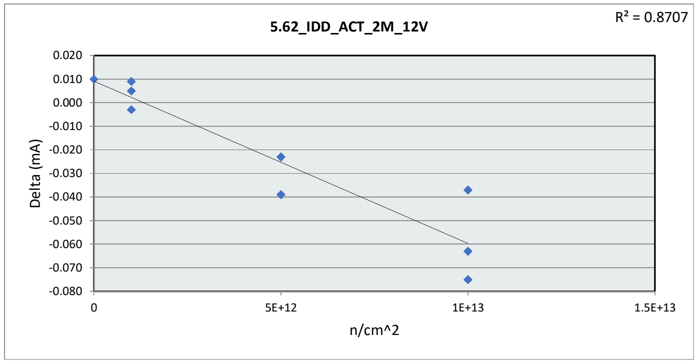


	5.61_IDD_ACT_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	10.881	10.905	11.094	10.921
Average	10.881	11.063	11.114	11.060
Max	10.881	11.199	11.130	11.208
UL	19.500	19.500	19.500	19.500

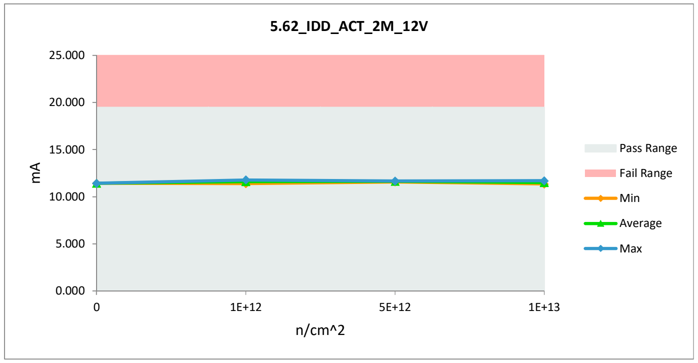


NDD Characterization Report
TPS7H5007-SEP

		5.62_IDD_ACT_2M_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		18	19.5	
Min Limit		10	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	11.413	11.423	0.010
1E+12	21	11.772	11.781	0.009
1E+12	22	11.624	11.621	-0.003
1E+12	23	11.397	11.402	0.005
5E+12	24	11.622	11.583	-0.039
5E+12	25	11.665	11.642	-0.023
5E+12	26	11.690	11.667	-0.023
1E+13	27	11.409	11.346	-0.063
1E+13	28	11.726	11.689	-0.037
1E+13	29	11.577	11.502	-0.075
	Max	11.772	11.781	0.010
	Average	11.589	11.566	-0.024
	Min	11.397	11.346	-0.075
	Std Dev	0.138	0.142	0.030

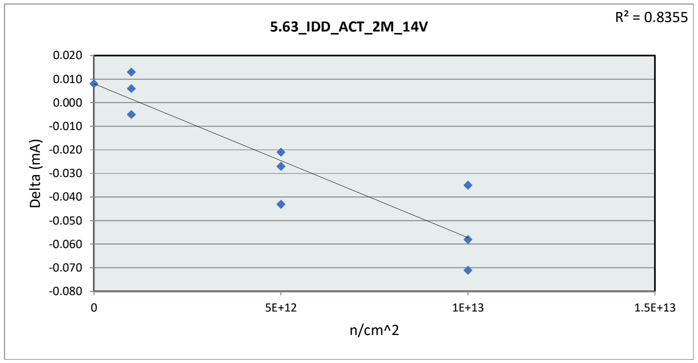


	5.62_IDD_ACT_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	11.423	11.402	11.583	11.346
Average	11.423	11.601	11.631	11.512
Max	11.423	11.781	11.667	11.689
UL	19.500	19.500	19.500	19.500

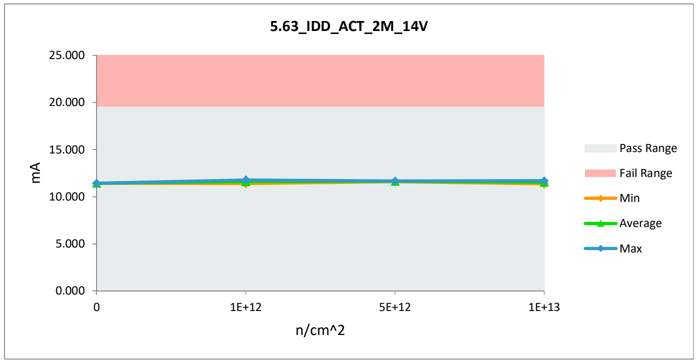


NDD Characterization Report
TPS7H5007-SEP

		5.63_IDD_ACT_2M_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		18	19.5	
Min Limit		10	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	11.419	11.427	0.008
1E+12	21	11.774	11.787	0.013
1E+12	22	11.629	11.624	-0.005
1E+12	23	11.399	11.405	0.006
5E+12	24	11.628	11.585	-0.043
5E+12	25	11.668	11.647	-0.021
5E+12	26	11.697	11.670	-0.027
1E+13	27	11.412	11.354	-0.058
1E+13	28	11.730	11.695	-0.035
1E+13	29	11.580	11.509	-0.071
	Max	11.774	11.787	0.013
	Average	11.594	11.570	-0.023
	Min	11.399	11.354	-0.071
	Std Dev	0.138	0.141	0.029

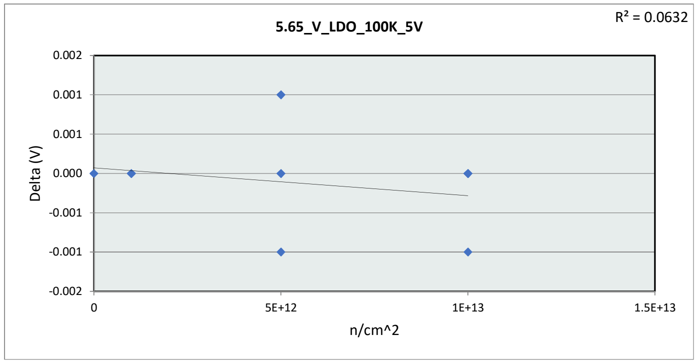


	5.63_IDD_ACT_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit	0	mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	11.427	11.405	11.585	11.354
Average	11.427	11.605	11.634	11.519
Max	11.427	11.787	11.670	11.695
UL	19.500	19.500	19.500	19.500

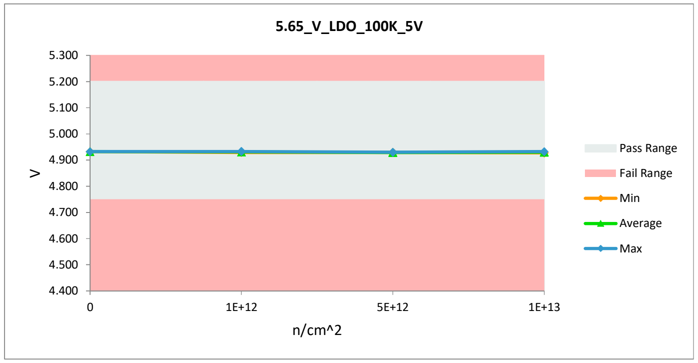


NDD Characterization Report
TPS7H5007-SEP

		5.65_V_LDO_100K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.1	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	4.932	4.932	0.000
1E+12	21	4.929	4.929	0.000
1E+12	22	4.930	4.930	0.000
1E+12	23	4.933	4.933	0.000
5E+12	24	4.930	4.929	-0.001
5E+12	25	4.930	4.930	0.000
5E+12	26	4.928	4.929	0.001
1E+13	27	4.932	4.932	0.000
1E+13	28	4.929	4.928	-0.001
1E+13	29	4.931	4.931	0.000
	Max	4.933	4.933	0.001
	Average	4.930	4.930	0.000
	Min	4.928	4.928	-0.001
	Std Dev	0.002	0.002	0.001

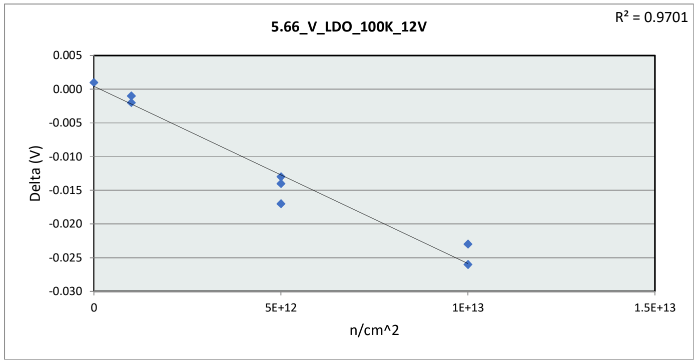


	5.65_V_LDO_100K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.932	4.929	4.929	4.928
Average	4.932	4.931	4.929	4.930
Max	4.932	4.933	4.930	4.932
UL	5.200	5.200	5.200	5.200

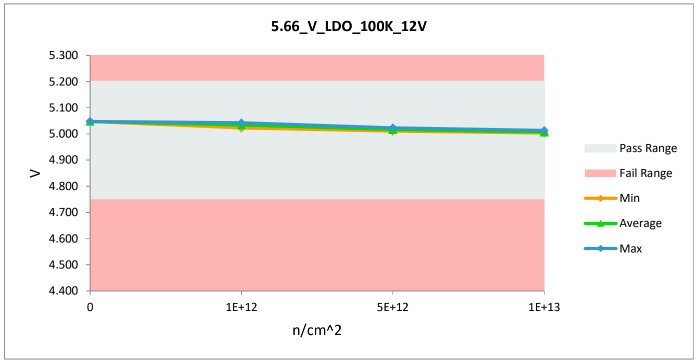


NDD Characterization Report
TPS7H5007-SEP

		5.66_V_LDO_100K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.047	5.048	0.001
1E+12	21	5.043	5.042	-0.001
1E+12	22	5.037	5.035	-0.002
1E+12	23	5.024	5.023	-0.001
5E+12	24	5.035	5.018	-0.017
5E+12	25	5.037	5.023	-0.014
5E+12	26	5.024	5.011	-0.013
1E+13	27	5.027	5.004	-0.023
1E+13	28	5.039	5.013	-0.026
1E+13	29	5.030	5.004	-0.026
	Max	5.047	5.048	0.001
	Average	5.034	5.022	-0.012
	Min	5.024	5.004	-0.026
	Std Dev	0.008	0.015	0.011

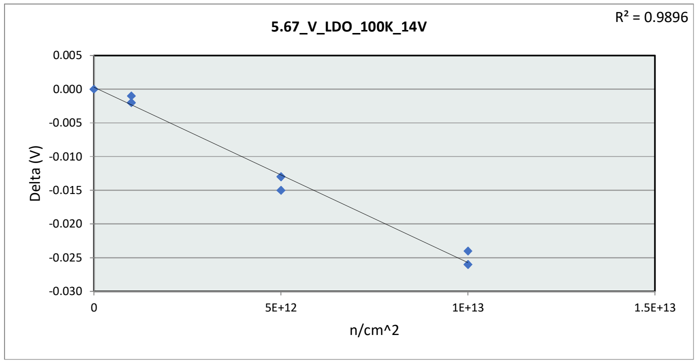


	5.66_V_LDO_100K_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.048	5.023	5.011	5.004
Average	5.048	5.033	5.017	5.007
Max	5.048	5.042	5.023	5.013
UL	5.200	5.200	5.200	5.200

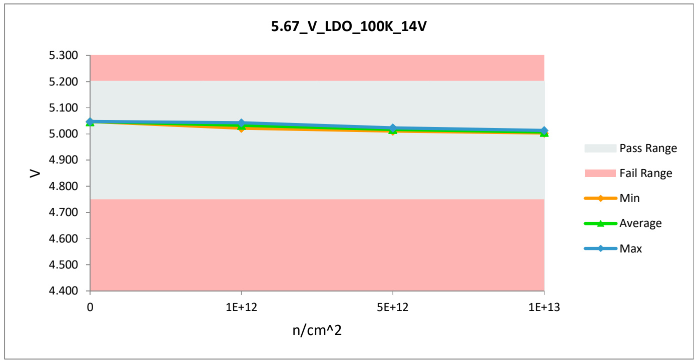


NDD Characterization Report
TPS7H5007-SEP

		5.67_V_LDO_100K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.047	5.047	0.000
1E+12	21	5.043	5.042	-0.001
1E+12	22	5.037	5.035	-0.002
1E+12	23	5.024	5.022	-0.002
5E+12	24	5.034	5.019	-0.015
5E+12	25	5.036	5.023	-0.013
5E+12	26	5.024	5.011	-0.013
1E+13	27	5.027	5.003	-0.024
1E+13	28	5.039	5.013	-0.026
1E+13	29	5.030	5.004	-0.026
	Max	5.047	5.047	0.000
	Average	5.034	5.022	-0.012
	Min	5.024	5.003	-0.026
	Std Dev	0.008	0.015	0.011

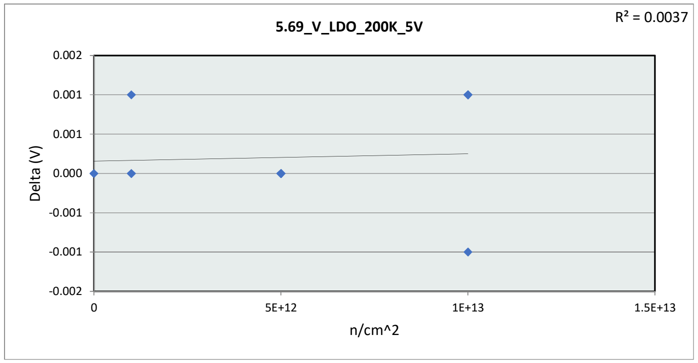


	5.67_V_LDO_100K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.047	5.022	5.011	5.003
Average	5.047	5.033	5.018	5.007
Max	5.047	5.042	5.023	5.013
UL	5.200	5.200	5.200	5.200

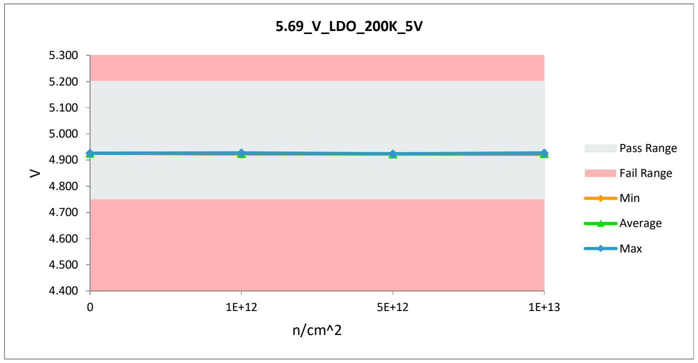


NDD Characterization Report
TPS7H5007-SEP

		5.69_V_LDO_200K_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.1	5.2	
Min Limit		4.84	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	4.926	4.926	0.000
1E+12	21	4.923	4.923	0.000
1E+12	22	4.925	4.925	0.000
1E+12	23	4.927	4.928	0.001
5E+12	24	4.924	4.924	0.000
5E+12	25	4.924	4.924	0.000
5E+12	26	4.923	4.923	0.000
1E+13	27	4.926	4.927	0.001
1E+13	28	4.923	4.922	-0.001
1E+13	29	4.925	4.926	0.001
	Max	4.927	4.928	0.001
	Average	4.925	4.925	0.000
	Min	4.923	4.922	-0.001
	Std Dev	0.001	0.002	0.001

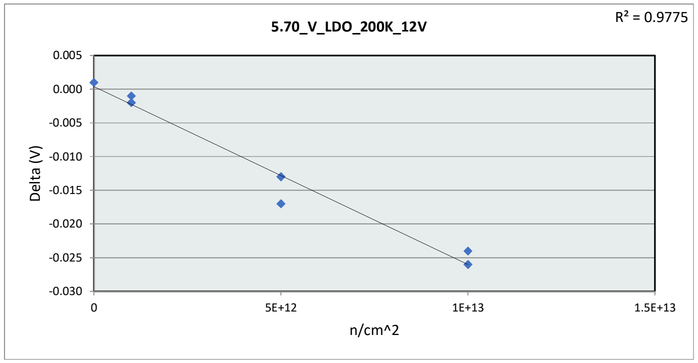


	5.69_V_LDO_200K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.926	4.923	4.923	4.922
Average	4.926	4.925	4.924	4.925
Max	4.926	4.928	4.924	4.927
UL	5.200	5.200	5.200	5.200

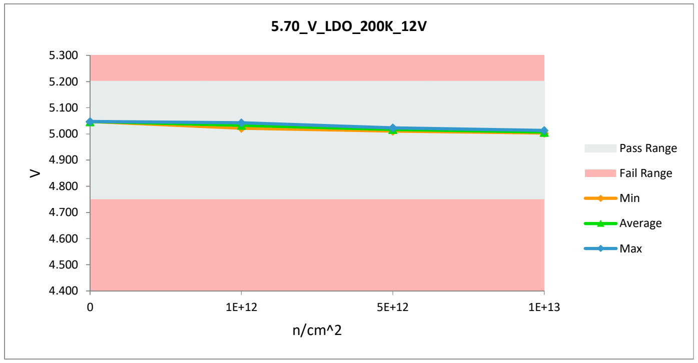


NDD Characterization Report
TPS7H5007-SEP

		5.70_V_LDO_200K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.84	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.046	5.047	0.001
1E+12	21	5.043	5.042	-0.001
1E+12	22	5.036	5.034	-0.002
1E+12	23	5.024	5.022	-0.002
5E+12	24	5.035	5.018	-0.017
5E+12	25	5.036	5.023	-0.013
5E+12	26	5.024	5.011	-0.013
1E+13	27	5.027	5.003	-0.024
1E+13	28	5.039	5.013	-0.026
1E+13	29	5.030	5.004	-0.026
	Max	5.046	5.047	0.001
	Average	5.034	5.022	-0.012
	Min	5.024	5.003	-0.026
	Std Dev	0.008	0.015	0.011

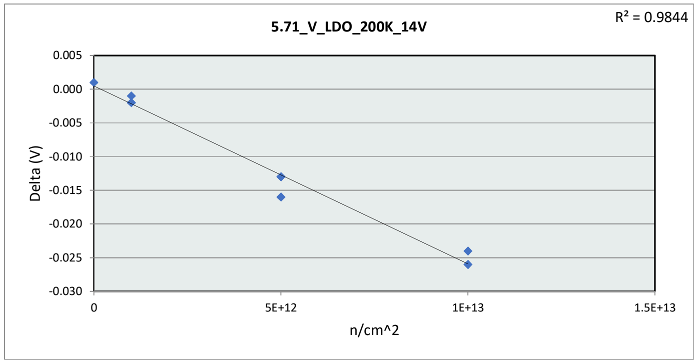


5.70_V_LDO_200K_12V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.047	5.022	5.011	5.003
Average	5.047	5.033	5.017	5.007
Max	5.047	5.042	5.023	5.013
UL	5.200	5.200	5.200	5.200

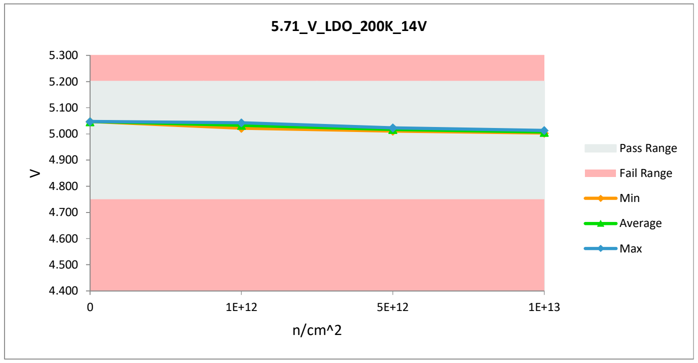


NDD Characterization Report
TPS7H5007-SEP

		5.71_V_LDO_200K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.84	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.046	5.047	0.001
1E+12	21	5.043	5.042	-0.001
1E+12	22	5.036	5.034	-0.002
1E+12	23	5.024	5.022	-0.002
5E+12	24	5.034	5.018	-0.016
5E+12	25	5.036	5.023	-0.013
5E+12	26	5.024	5.011	-0.013
1E+13	27	5.027	5.003	-0.024
1E+13	28	5.039	5.013	-0.026
1E+13	29	5.030	5.004	-0.026
	Max	5.046	5.047	0.001
	Average	5.034	5.022	-0.012
	Min	5.024	5.003	-0.026
	Std Dev	0.008	0.015	0.011

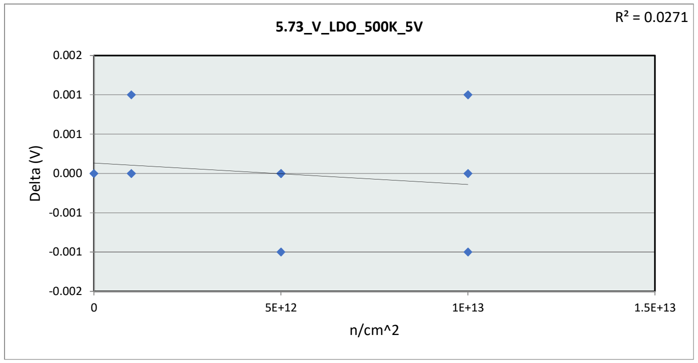


	5.71_V_LDO_200K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.047	5.022	5.011	5.003
Average	5.047	5.033	5.017	5.007
Max	5.047	5.042	5.023	5.013
UL	5.200	5.200	5.200	5.200

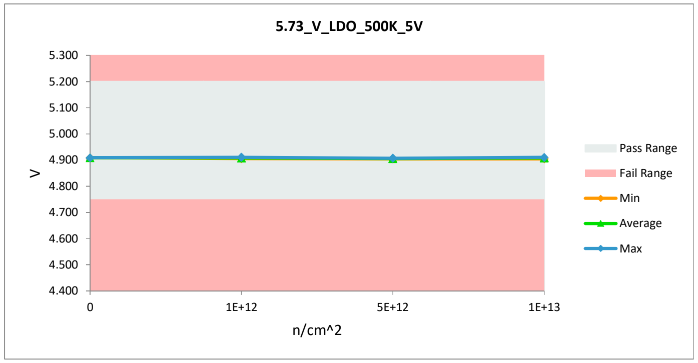


NDD Characterization Report
TPS7H5007-SEP

		5.73_V_LDO_500K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.1	5.2	
	Min Limit	4.81	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	4.909	4.909	0.000
1E+12	21	4.906	4.906	0.000
1E+12	22	4.907	4.907	0.000
1E+12	23	4.910	4.911	0.001
5E+12	24	4.907	4.907	0.000
5E+12	25	4.907	4.906	-0.001
5E+12	26	4.905	4.905	0.000
1E+13	27	4.909	4.910	0.001
1E+13	28	4.906	4.905	-0.001
1E+13	29	4.908	4.908	0.000
	Max	4.910	4.911	0.001
	Average	4.907	4.907	0.000
	Min	4.905	4.905	-0.001
	Std Dev	0.002	0.002	0.001

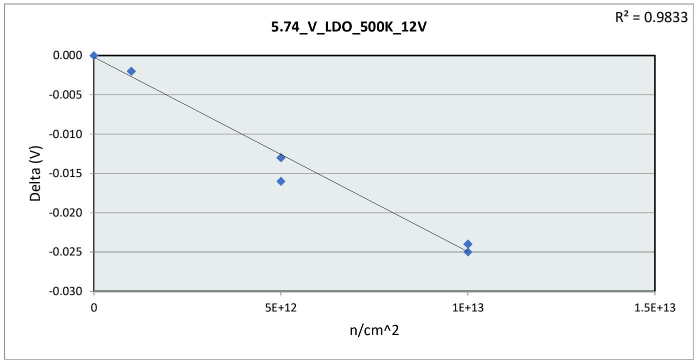


	5.73_V_LDO_500K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.909	4.906	4.905	4.905
Average	4.909	4.908	4.906	4.908
Max	4.909	4.911	4.907	4.910
UL	5.200	5.200	5.200	5.200

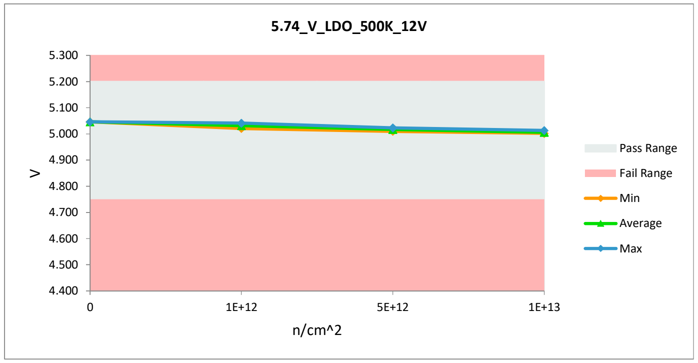


NDD Characterization Report
TPS7H5007-SEP

		5.74_V_LDO_500K_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.15	5.2	
Min Limit		4.81	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.046	5.046	0.000
1E+12	21	5.043	5.041	-0.002
1E+12	22	5.035	5.033	-0.002
1E+12	23	5.023	5.021	-0.002
5E+12	24	5.034	5.018	-0.016
5E+12	25	5.036	5.023	-0.013
5E+12	26	5.023	5.010	-0.013
1E+13	27	5.026	5.002	-0.024
1E+13	28	5.037	5.013	-0.024
1E+13	29	5.029	5.004	-0.025
	Max	5.046	5.046	0.000
	Average	5.033	5.021	-0.012
	Min	5.023	5.002	-0.025
	Std Dev	0.008	0.015	0.010



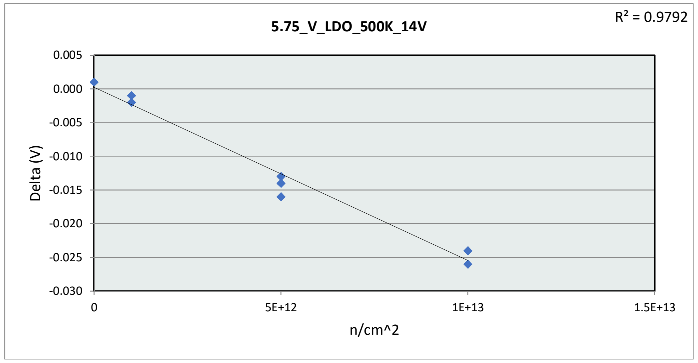
	5.74_V_LDO_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.046	5.021	5.010	5.002
Average	5.046	5.032	5.017	5.006
Max	5.046	5.041	5.023	5.013
UL	5.200	5.200	5.200	5.200



NDD Characterization Report
TPS7H5007-SEP

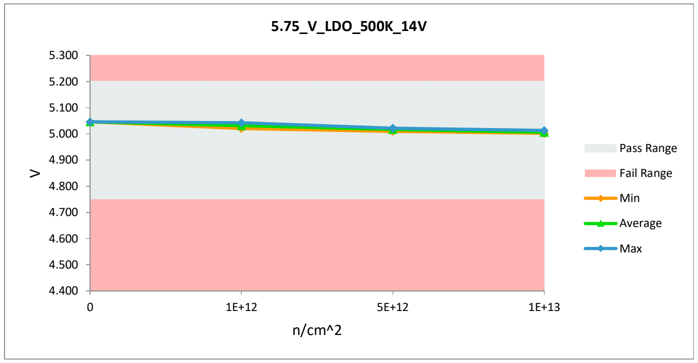
	5.75_V_LDO_500K_14V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	5.15	5.2
Min Limit	4.81	4.75

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.045	5.046	0.001
1E+12	21	5.043	5.042	-0.001
1E+12	22	5.035	5.033	-0.002
1E+12	23	5.023	5.021	-0.002
5E+12	24	5.034	5.018	-0.016
5E+12	25	5.036	5.022	-0.014
5E+12	26	5.023	5.010	-0.013
1E+13	27	5.026	5.002	-0.024
1E+13	28	5.037	5.013	-0.024
1E+13	29	5.029	5.003	-0.026
	Max	5.045	5.046	0.001
	Average	5.033	5.021	-0.012
	Min	5.023	5.002	-0.026
	Std Dev	0.008	0.015	0.011



	5.75_V_LDO_500K_14V	
Test Site		
Tester		
Test Number		
Max Limit	5.2	V
Min Limit	4.75	V

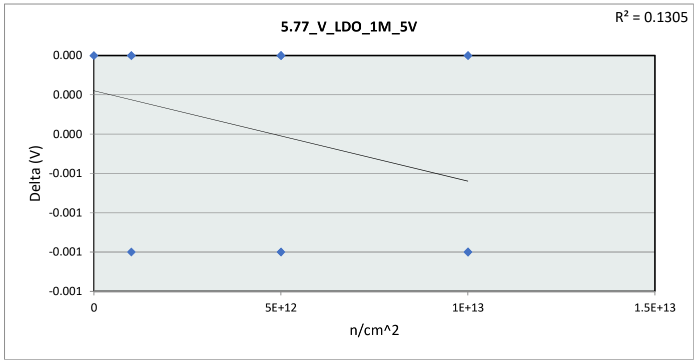
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.046	5.021	5.010	5.002
Average	5.046	5.032	5.017	5.006
Max	5.046	5.042	5.022	5.013
UL	5.200	5.200	5.200	5.200



NDD Characterization Report
TPS7H5007-SEP

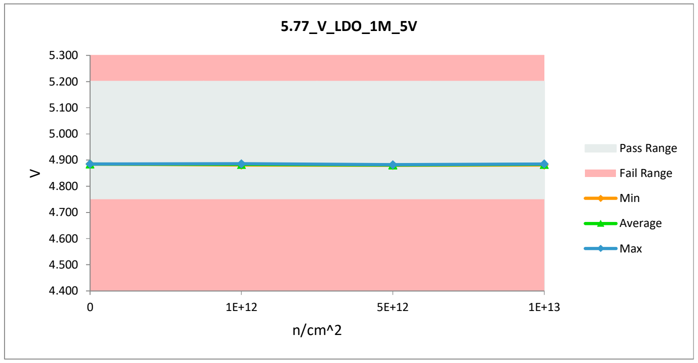
	5.77_V_LDO_1M_5V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	5.1	5.2
Min Limit	4.75	4.75

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	4.885	4.885	0.000
1E+12	21	4.881	4.881	0.000
1E+12	22	4.883	4.882	-0.001
1E+12	23	4.886	4.886	0.000
5E+12	24	4.882	4.882	0.000
5E+12	25	4.882	4.882	0.000
5E+12	26	4.881	4.880	-0.001
1E+13	27	4.885	4.885	0.000
1E+13	28	4.882	4.881	-0.001
1E+13	29	4.884	4.883	-0.001
	Max	4.886	4.886	0.000
	Average	4.883	4.883	0.000
	Min	4.881	4.880	-0.001
	Std Dev	0.002	0.002	0.001



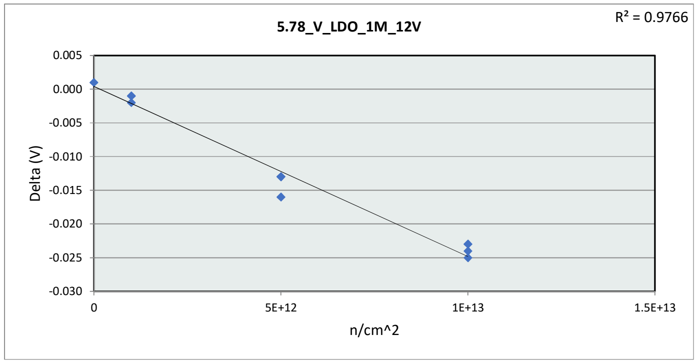
	5.77_V_LDO_1M_5V	
Test Site		
Tester		
Test Number		
Max Limit	5.2	V
Min Limit	4.75	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.885	4.881	4.880	4.881
Average	4.885	4.883	4.881	4.883
Max	4.885	4.886	4.882	4.885
UL	5.200	5.200	5.200	5.200

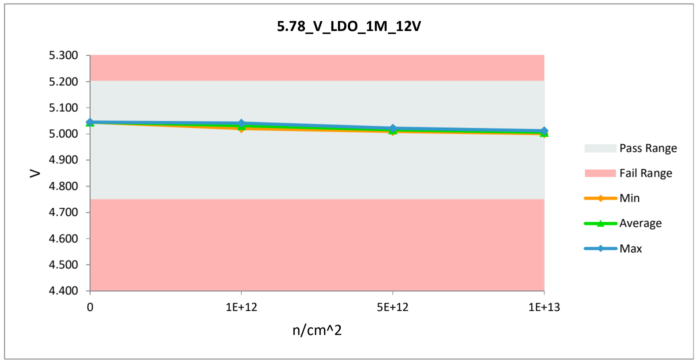


NDD Characterization Report
TPS7H5007-SEP

		5.78_V_LDO_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.044	5.045	0.001
1E+12	21	5.042	5.041	-0.001
1E+12	22	5.034	5.032	-0.002
1E+12	23	5.021	5.020	-0.001
5E+12	24	5.033	5.017	-0.016
5E+12	25	5.035	5.022	-0.013
5E+12	26	5.022	5.009	-0.013
1E+13	27	5.024	5.001	-0.023
1E+13	28	5.036	5.012	-0.024
1E+13	29	5.028	5.003	-0.025
	Max	5.044	5.045	0.001
	Average	5.032	5.020	-0.012
	Min	5.021	5.001	-0.025
	Std Dev	0.008	0.015	0.010

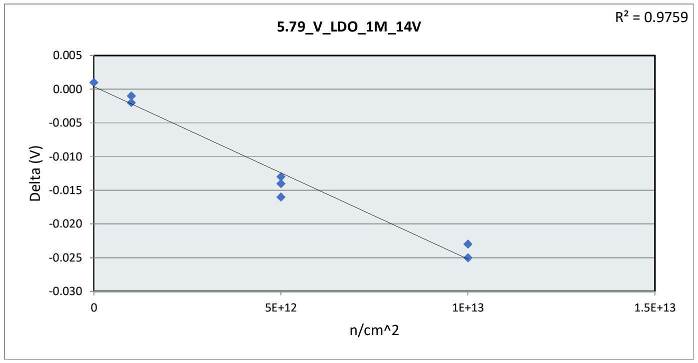


	5.78_V_LDO_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.045	5.020	5.009	5.001
Average	5.045	5.031	5.016	5.005
Max	5.045	5.041	5.022	5.012
UL	5.200	5.200	5.200	5.200

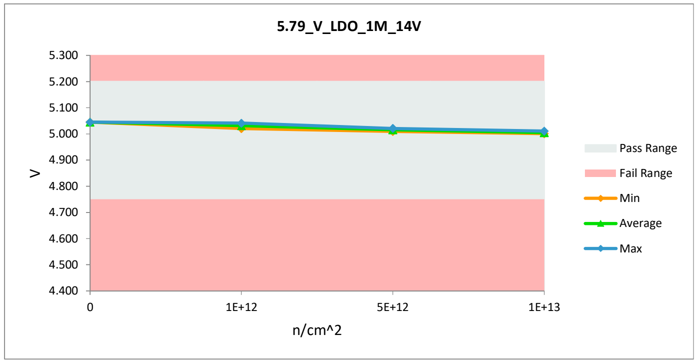


NDD Characterization Report
TPS7H5007-SEP

		5.79_V_LDO_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.044	5.045	0.001
1E+12	21	5.042	5.041	-0.001
1E+12	22	5.034	5.032	-0.002
1E+12	23	5.021	5.020	-0.001
5E+12	24	5.033	5.017	-0.016
5E+12	25	5.035	5.021	-0.014
5E+12	26	5.022	5.009	-0.013
1E+13	27	5.024	5.001	-0.023
1E+13	28	5.036	5.011	-0.025
1E+13	29	5.027	5.002	-0.025
	Max	5.044	5.045	0.001
	Average	5.032	5.020	-0.012
	Min	5.021	5.001	-0.025
	Std Dev	0.008	0.015	0.010

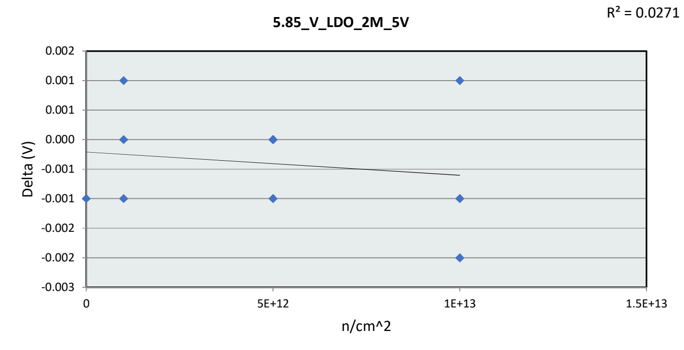


	5.79_V_LDO_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.045	5.020	5.009	5.001
Average	5.045	5.031	5.016	5.005
Max	5.045	5.041	5.021	5.011
UL	5.200	5.200	5.200	5.200

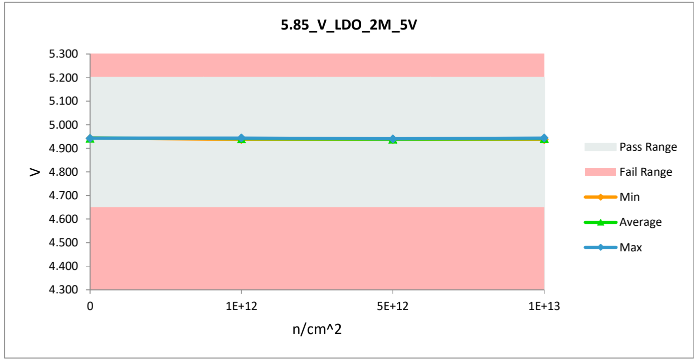


NDD Characterization Report
TPS7H5007-SEP

		5.85_V_LDO_2M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.1	5.2	
	Min Limit	4.8	4.65	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	4.944	4.943	-0.001
1E+12	21	4.938	4.938	0.000
1E+12	22	4.940	4.939	-0.001
1E+12	23	4.943	4.944	0.001
5E+12	24	4.940	4.940	0.000
5E+12	25	4.939	4.939	0.000
5E+12	26	4.939	4.938	-0.001
1E+13	27	4.943	4.944	0.001
1E+13	28	4.940	4.938	-0.002
1E+13	29	4.942	4.941	-0.001
	Max	4.944	4.944	0.001
	Average	4.941	4.940	0.000
	Min	4.938	4.938	-0.002
	Std Dev	0.002	0.002	0.001

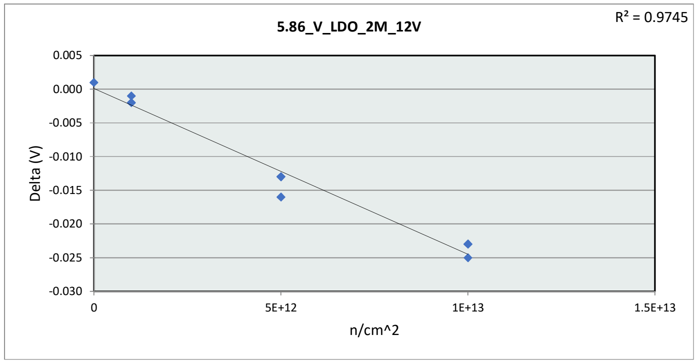


	5.85_V_LDO_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	4.943	4.938	4.938	4.938
Average	4.943	4.940	4.939	4.941
Max	4.943	4.944	4.940	4.944
UL	5.200	5.200	5.200	5.200

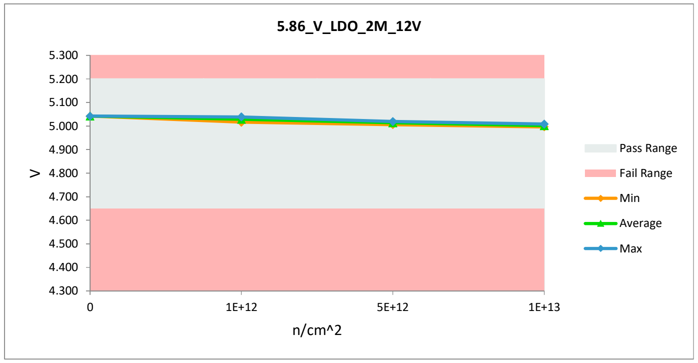


NDD Characterization Report
TPS7H5007-SEP

		5.86_V_LDO_2M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.8	4.65	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.041	5.042	0.001
1E+12	21	5.040	5.039	-0.001
1E+12	22	5.030	5.028	-0.002
1E+12	23	5.019	5.017	-0.002
5E+12	24	5.031	5.015	-0.016
5E+12	25	5.032	5.019	-0.013
5E+12	26	5.019	5.006	-0.013
1E+13	27	5.020	4.997	-0.023
1E+13	28	5.032	5.009	-0.023
1E+13	29	5.024	4.999	-0.025
	Max	5.041	5.042	0.001
	Average	5.029	5.017	-0.012
	Min	5.019	4.997	-0.025
	Std Dev	0.008	0.015	0.010

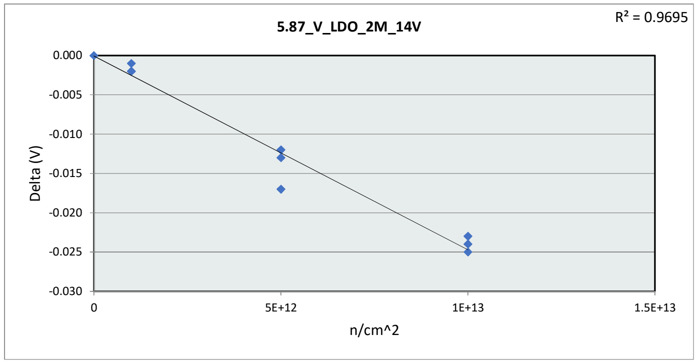


	5.86_V_LDO_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.042	5.017	5.006	4.997
Average	5.042	5.028	5.013	5.002
Max	5.042	5.039	5.019	5.009
UL	5.200	5.200	5.200	5.200

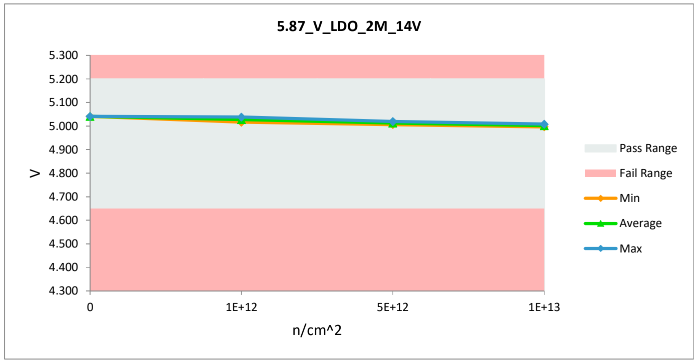


NDD Characterization Report
TPS7H5007-SEP

		5.87_V_LDO_2M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.8	4.65	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.041	5.041	0.000
1E+12	21	5.040	5.038	-0.002
1E+12	22	5.030	5.028	-0.002
1E+12	23	5.018	5.017	-0.001
5E+12	24	5.031	5.014	-0.017
5E+12	25	5.032	5.019	-0.013
5E+12	26	5.018	5.006	-0.012
1E+13	27	5.020	4.997	-0.023
1E+13	28	5.032	5.008	-0.024
1E+13	29	5.024	4.999	-0.025
	Max	5.041	5.041	0.000
	Average	5.029	5.017	-0.012
	Min	5.018	4.997	-0.025
	Std Dev	0.008	0.015	0.010

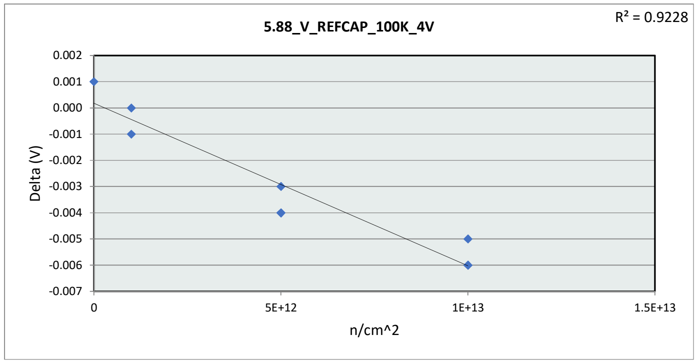


	5.87_V_LDO_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.041	5.017	5.006	4.997
Average	5.041	5.028	5.013	5.001
Max	5.041	5.038	5.019	5.008
UL	5.200	5.200	5.200	5.200

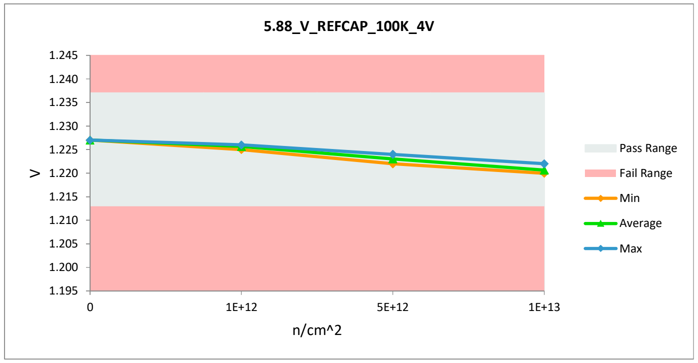


NDD Characterization Report
TPS7H5007-SEP

		5.88_V_REFCAP_100K_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.226	1.227	0.001
1E+12	21	1.226	1.226	0.000
1E+12	22	1.226	1.226	0.000
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.222	-0.004
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.220	-0.006
1E+13	29	1.226	1.220	-0.006
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.006
	Std Dev	0.000	0.003	0.003

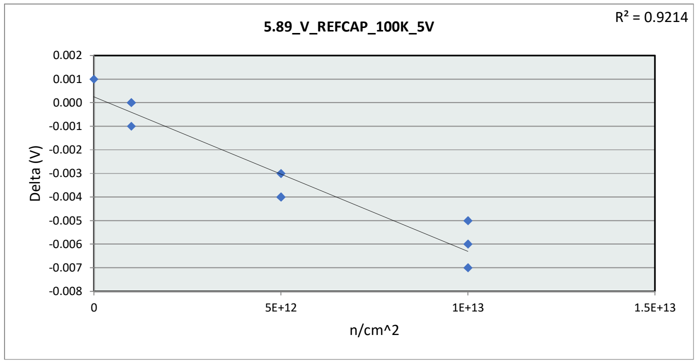


	5.88_V_REFCAP_100K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.222	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

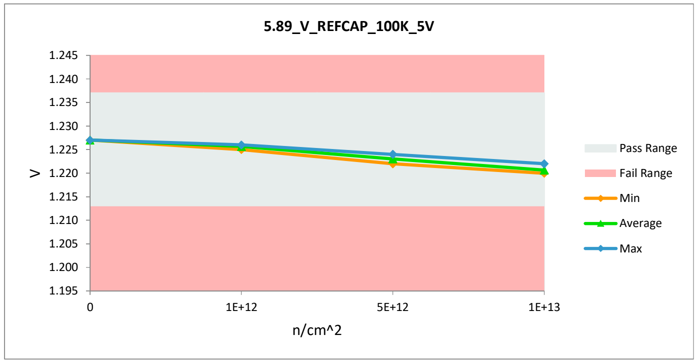


NDD Characterization Report
TPS7H5007-SEP

		5.89_V_REFCAP_100K_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.226	1.227	0.001
1E+12	21	1.226	1.226	0.000
1E+12	22	1.226	1.226	0.000
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.222	-0.004
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.220	-0.006
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

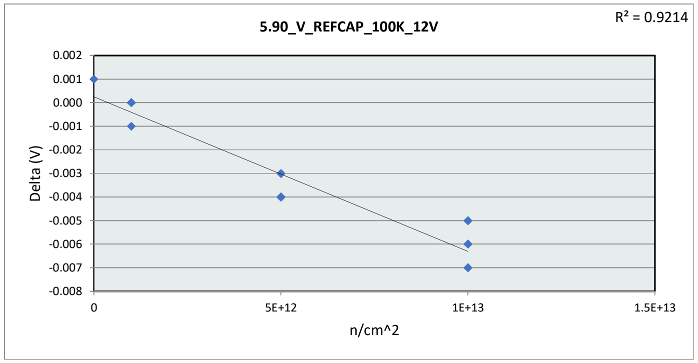


	5.89_V_REFCAP_100K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.222	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

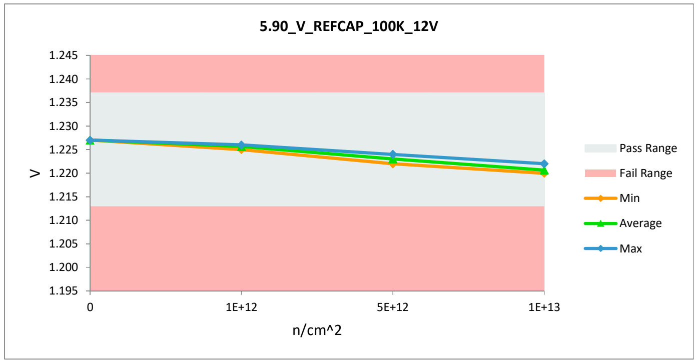


NDD Characterization Report
TPS7H5007-SEP

		5.90_V_REFCAP_100K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.226	1.227	0.001
1E+12	21	1.226	1.226	0.000
1E+12	22	1.226	1.226	0.000
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.222	-0.004
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.220	-0.006
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

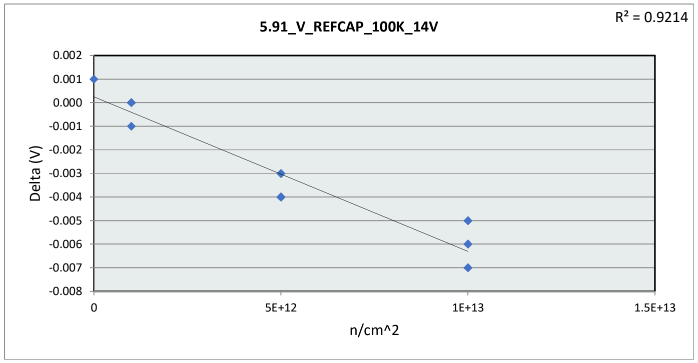


	5.90_V_REFCAP_100K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.222	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

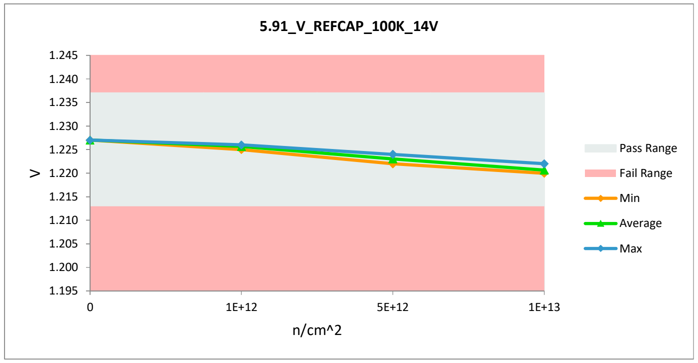


NDD Characterization Report
TPS7H5007-SEP

		5.91_V_REFCAP_100K_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.226	1.227	0.001
1E+12	21	1.226	1.226	0.000
1E+12	22	1.226	1.226	0.000
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.222	-0.004
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.220	-0.006
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

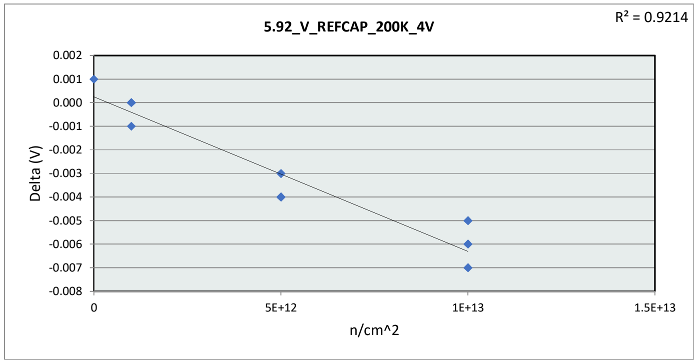


	5.91_V_REFCAP_100K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.222	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

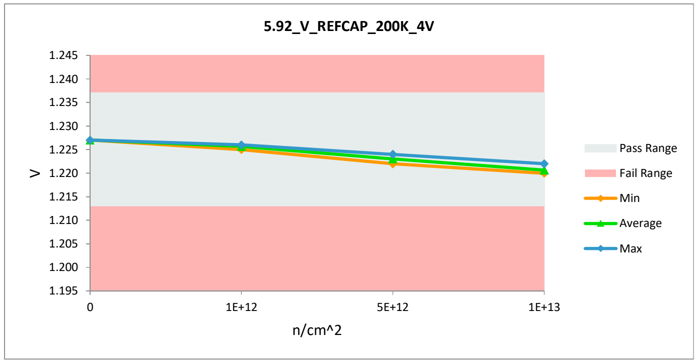


NDD Characterization Report
TPS7H5007-SEP

		5.92_V_REFCAP_200K_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.226	1.227	0.001
1E+12	21	1.226	1.226	0.000
1E+12	22	1.226	1.226	0.000
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.222	-0.004
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.220	-0.006
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

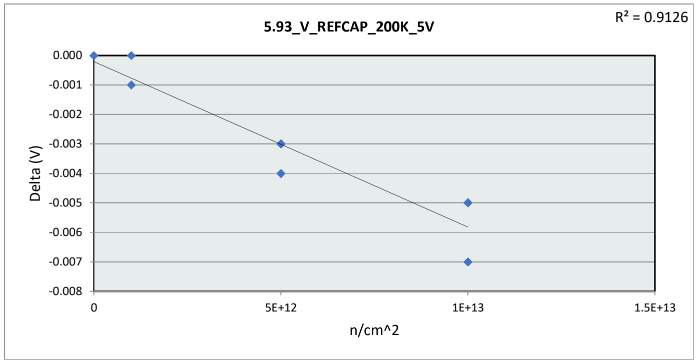


	5.92_V_REFCAP_200K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.222	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

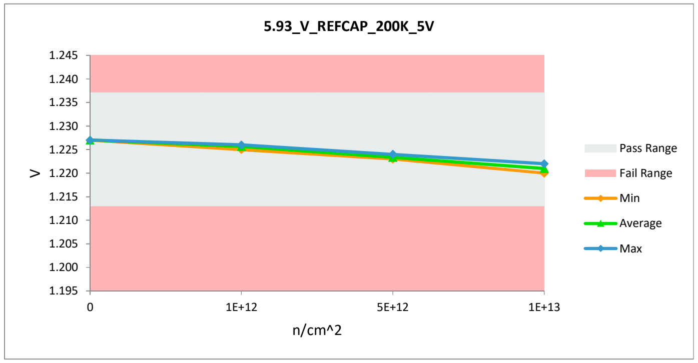


NDD Characterization Report
TPS7H5007-SEP

		5.93_V_REFCAP_200K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.226	1.226	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.002	0.002



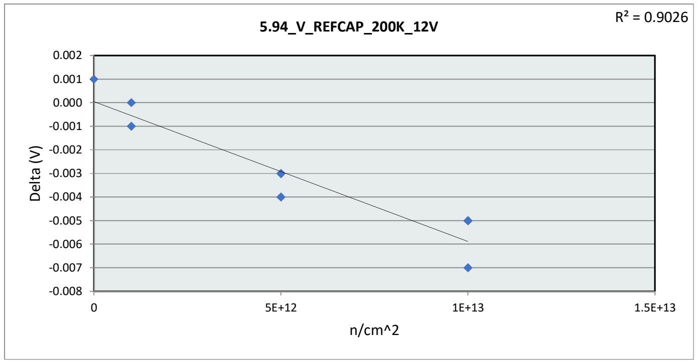
	5.93_V_REFCAP_200K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237



NDD Characterization Report
TPS7H5007-SEP

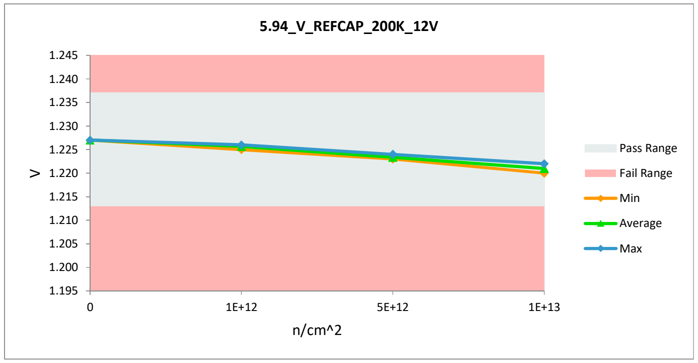
	5.94_V_REFCAP_200K_12V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.237	1.237
Min Limit	1.213	1.213

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.226	1.227	0.001
1E+12	21	1.226	1.226	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.002	0.003



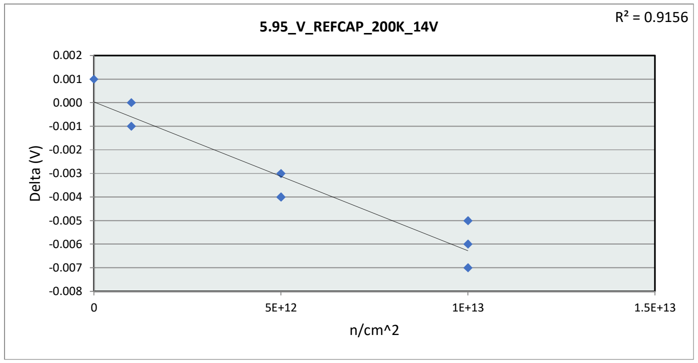
	5.94_V_REFCAP_200K_12V	
Test Site		
Tester		
Test Number		
Max Limit	1.237	V
Min Limit	1.213	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

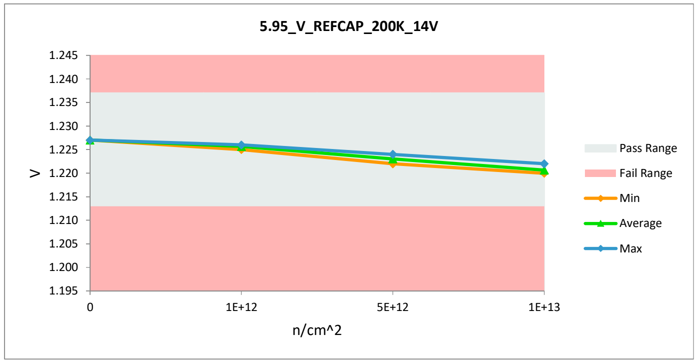


NDD Characterization Report
TPS7H5007-SEP

		5.95_V_REFCAP_200K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.226	1.227	0.001
1E+12	21	1.226	1.226	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.222	-0.004
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.220	-0.006
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

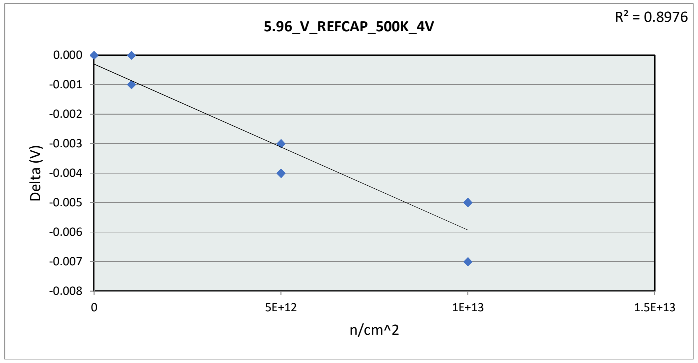


	5.95_V_REFCAP_200K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.222	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

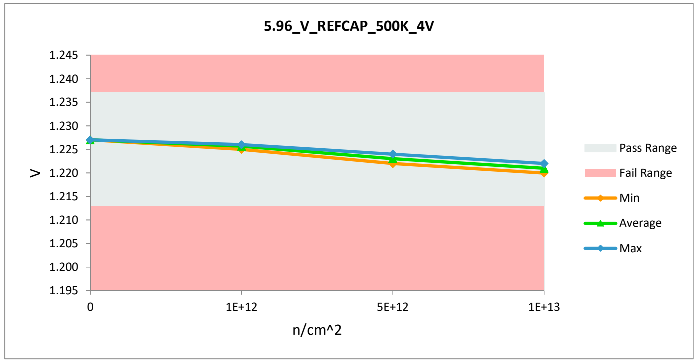


NDD Characterization Report
TPS7H5007-SEP

		5.96_V_REFCAP_500K_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.226	1.226	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.223	-0.004
5E+12	25	1.226	1.222	-0.004
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.002	0.002

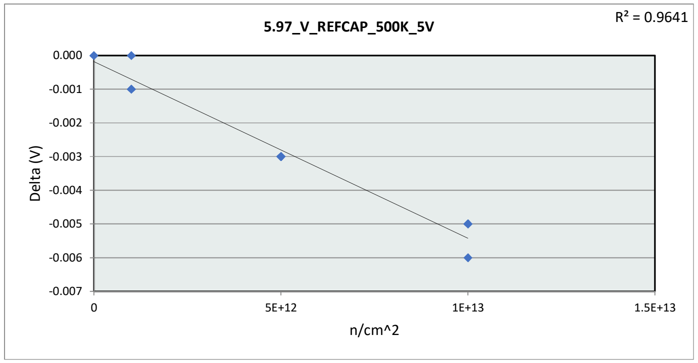


	5.96_V_REFCAP_500K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.222	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

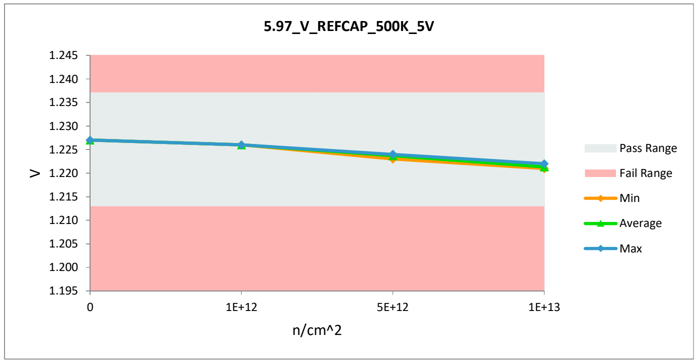


NDD Characterization Report
TPS7H5007-SEP

		5.97_V_REFCAP_500K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.226	-0.001
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.227	1.224	-0.003
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.000	0.002	0.002

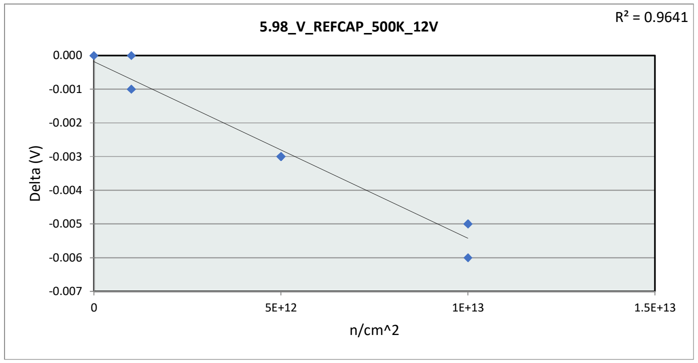


	5.97_V_REFCAP_500K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

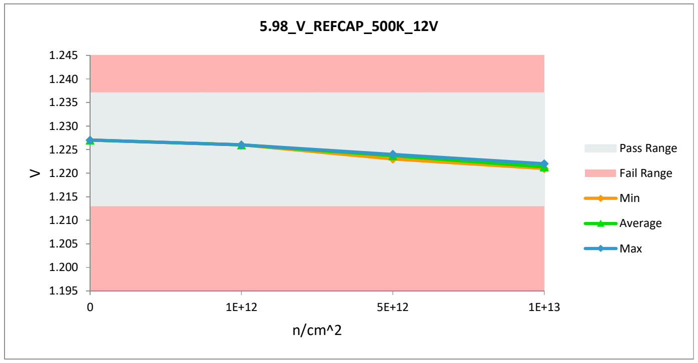


NDD Characterization Report
TPS7H5007-SEP

		5.98_V_REFCAP_500K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.226	-0.001
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.227	1.224	-0.003
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.000	0.002	0.002

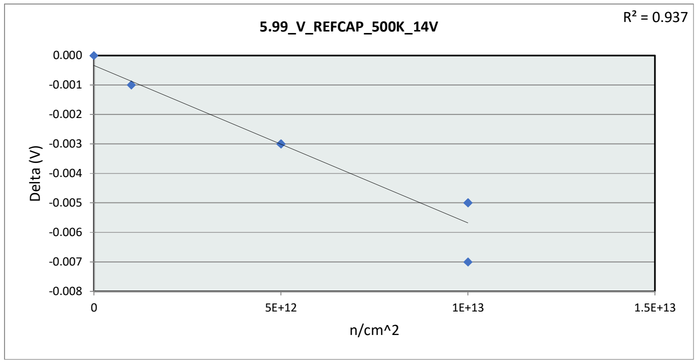


	5.98_V_REFCAP_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

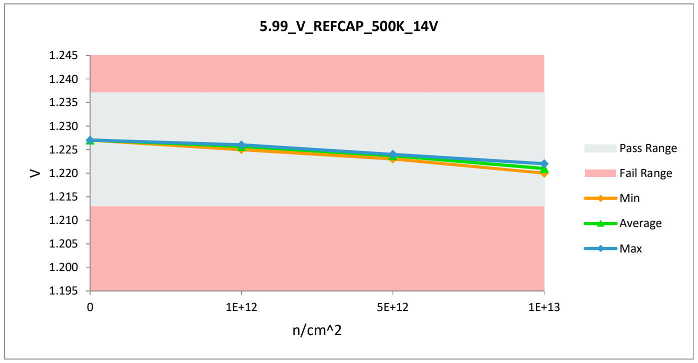


NDD Characterization Report
TPS7H5007-SEP

		5.99_V_REFCAP_500K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.226	-0.001
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.225	-0.001
5E+12	24	1.227	1.224	-0.003
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.220	-0.007
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.000	0.002	0.002

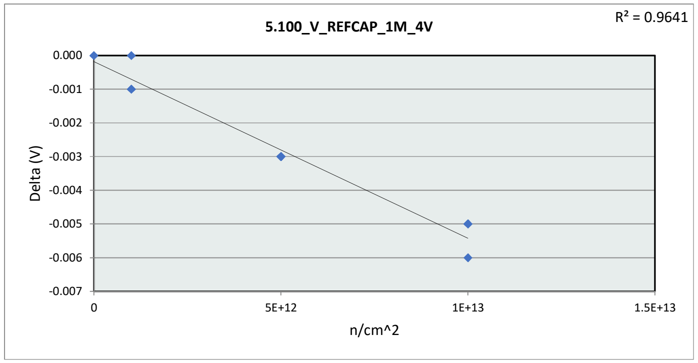


	5.99_V_REFCAP_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.225	1.223	1.220
Average	1.227	1.226	1.224	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

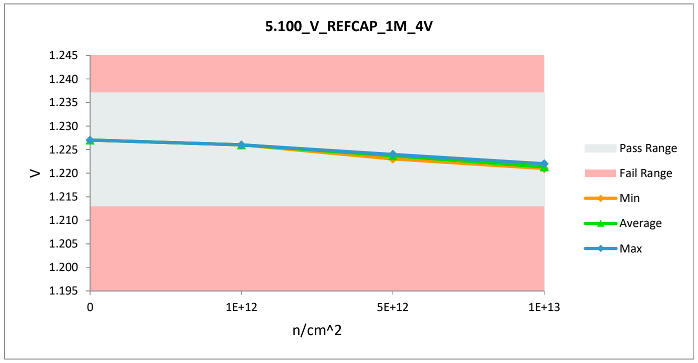


NDD Characterization Report
TPS7H5007-SEP

		5.100_V_REFCAP_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.226	-0.001
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.227	1.224	-0.003
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.000	0.002	0.002

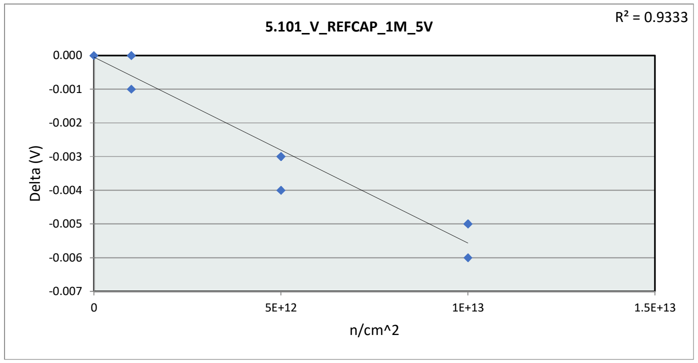


	5.100_V_REFCAP_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

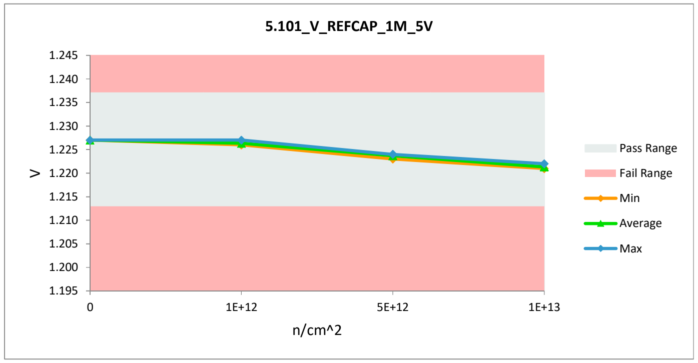


NDD Characterization Report
TPS7H5007-SEP

		5.101_V_REFCAP_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.227	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.228	1.224	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

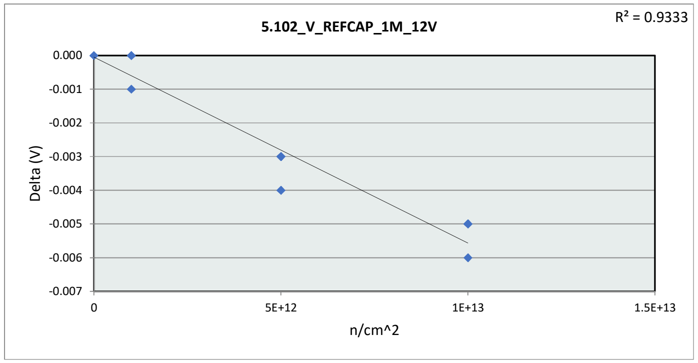


	5.101_V_REFCAP_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.221
Max	1.227	1.227	1.224	1.222
UL	1.237	1.237	1.237	1.237

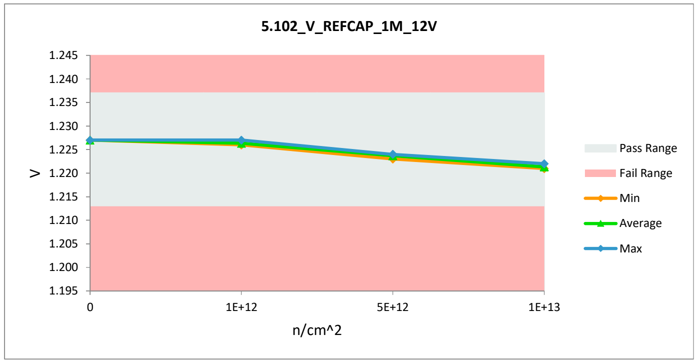


NDD Characterization Report
TPS7H5007-SEP

		5.102_V_REFCAP_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.227	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.228	1.224	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

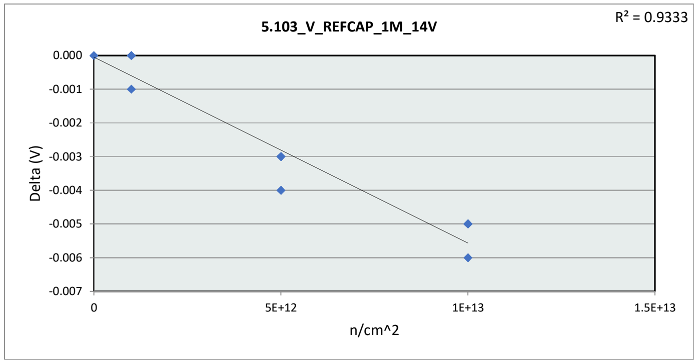


	5.102_V_REFCAP_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.221
Max	1.227	1.227	1.224	1.222
UL	1.237	1.237	1.237	1.237

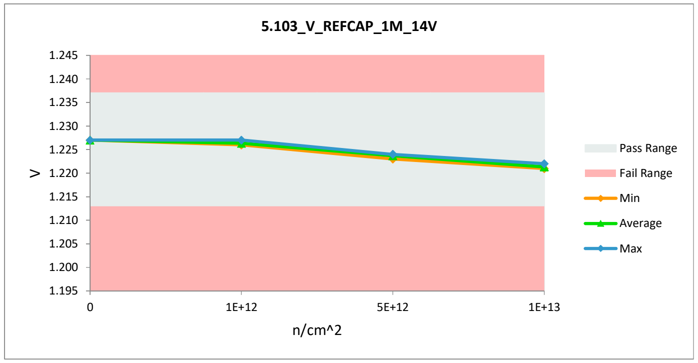


NDD Characterization Report
TPS7H5007-SEP

		5.103_V_REFCAP_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.227	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.228	1.224	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

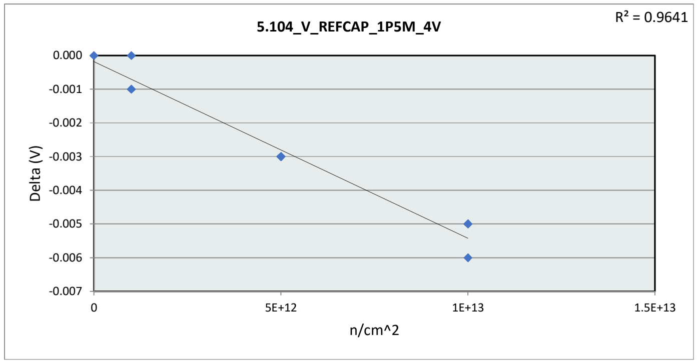


	5.103_V_REFCAP_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.221
Max	1.227	1.227	1.224	1.222
UL	1.237	1.237	1.237	1.237

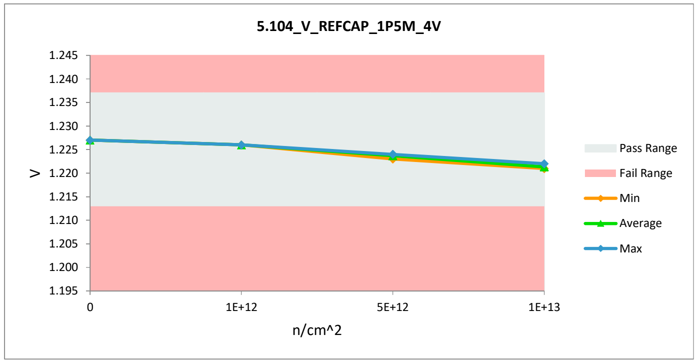


NDD Characterization Report
TPS7H5007-SEP

		5.104_V_REFCAP_1P5M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.226	-0.001
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.227	1.224	-0.003
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.000	0.002	0.002

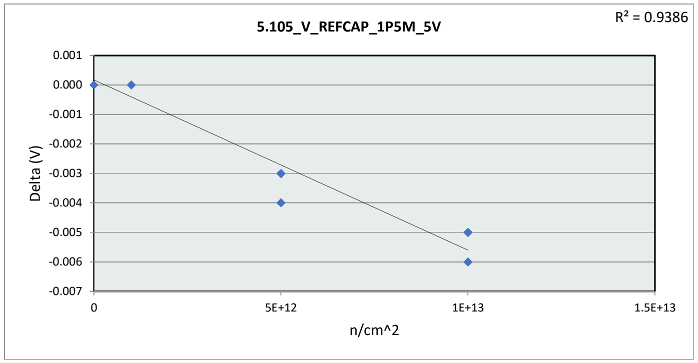


	5.104_V_REFCAP_1P5M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.221
Max	1.227	1.226	1.224	1.222
UL	1.237	1.237	1.237	1.237

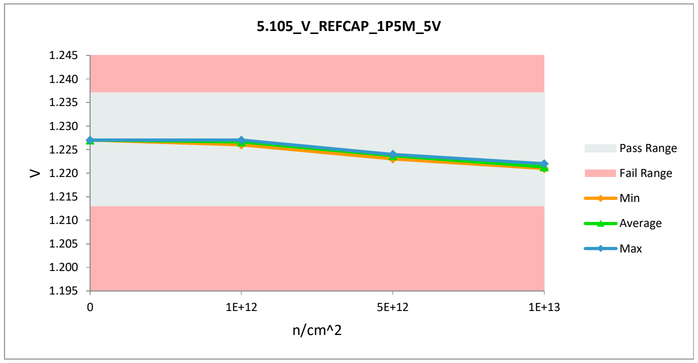


NDD Characterization Report
TPS7H5007-SEP

		5.105_V_REFCAP_1P5M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.227	0.000
1E+12	22	1.227	1.227	0.000
1E+12	23	1.226	1.226	0.000
5E+12	24	1.228	1.224	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

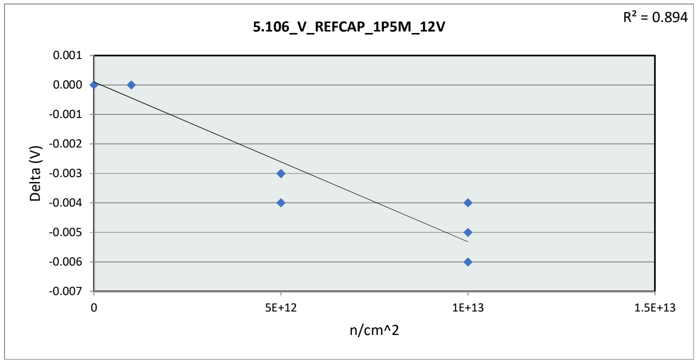


	5.105_V_REFCAP_1P5M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.227	1.224	1.221
Max	1.227	1.227	1.224	1.222
UL	1.237	1.237	1.237	1.237

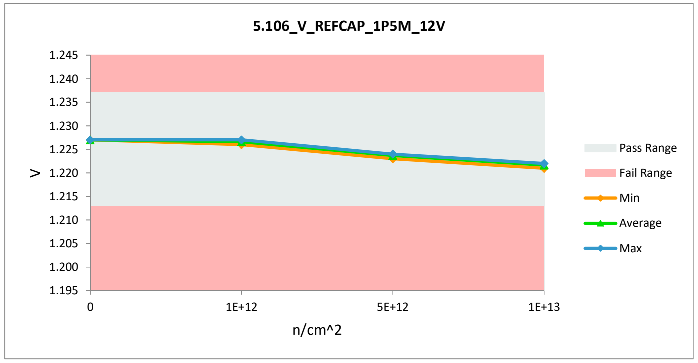


NDD Characterization Report
TPS7H5007-SEP

		5.106_V_REFCAP_1P5M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.227	0.000
1E+12	22	1.227	1.227	0.000
1E+12	23	1.226	1.226	0.000
5E+12	24	1.228	1.224	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.222	-0.004
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.002
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

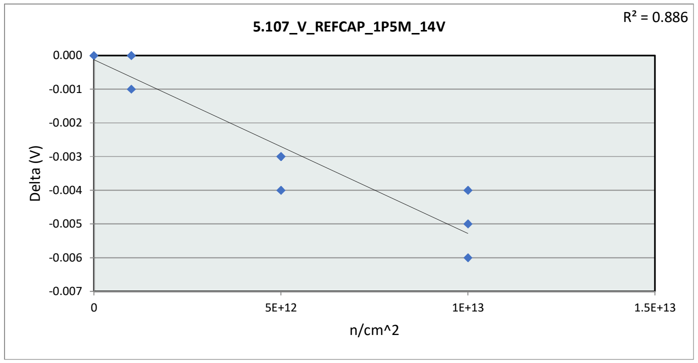


	5.106_V_REFCAP_1P5M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.227	1.224	1.222
Max	1.227	1.227	1.224	1.222
UL	1.237	1.237	1.237	1.237

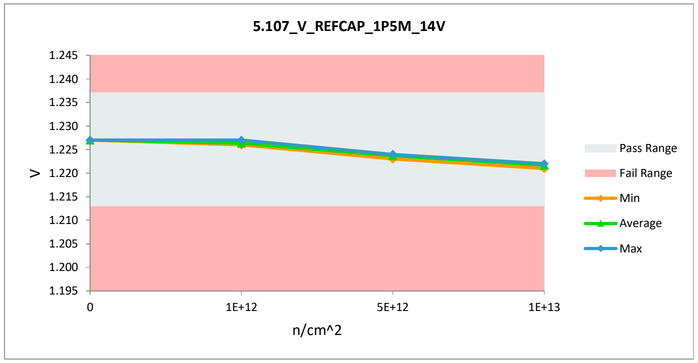


NDD Characterization Report
TPS7H5007-SEP

		5.107_V_REFCAP_1P5M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.227	0.000
1E+12	22	1.227	1.226	-0.001
1E+12	23	1.226	1.226	0.000
5E+12	24	1.228	1.224	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.222	-0.004
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

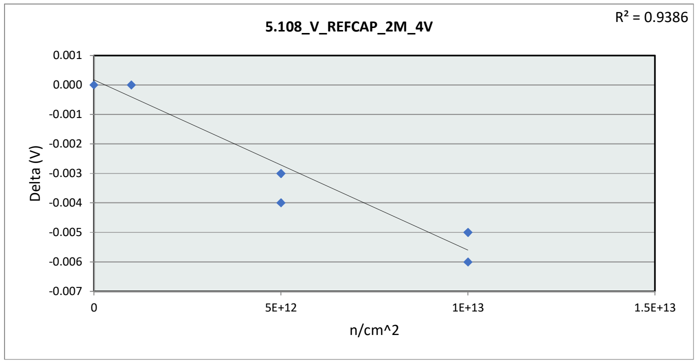


	5.107_V_REFCAP_1P5M_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.226	1.224	1.222
Max	1.227	1.227	1.224	1.222
UL	1.237	1.237	1.237	1.237

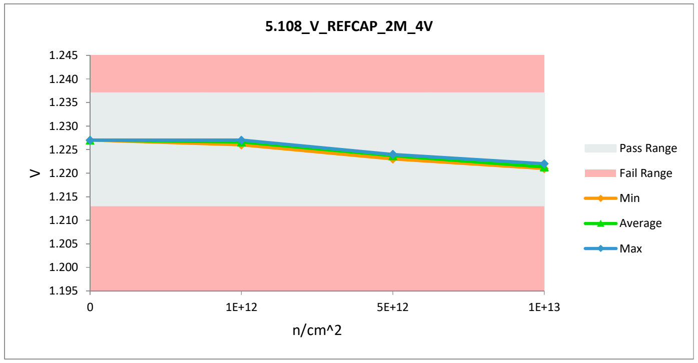


NDD Characterization Report
TPS7H5007-SEP

		5.108_V_REFCAP_2M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.227	1.227	0.000
1E+12	22	1.227	1.227	0.000
1E+12	23	1.226	1.226	0.000
5E+12	24	1.228	1.224	-0.004
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.224	-0.003
1E+13	27	1.227	1.222	-0.005
1E+13	28	1.226	1.221	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

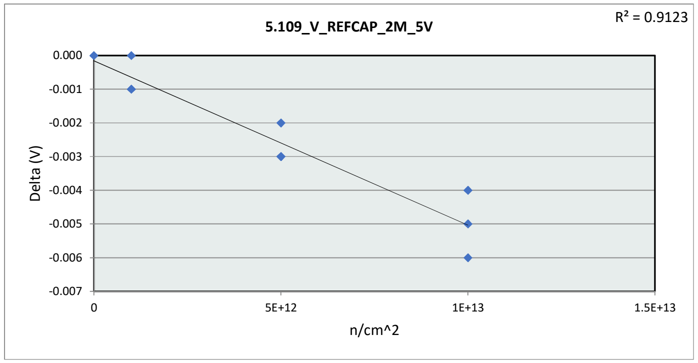


	5.108_V_REFCAP_2M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.227	1.224	1.221
Max	1.227	1.227	1.224	1.222
UL	1.237	1.237	1.237	1.237

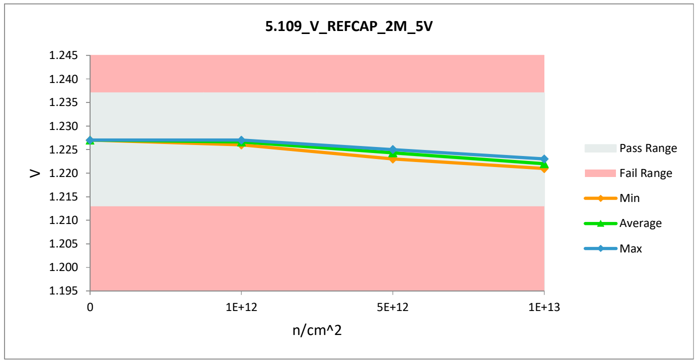


NDD Characterization Report
TPS7H5007-SEP

		5.109_V_REFCAP_2M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.228	1.227	-0.001
1E+12	22	1.227	1.227	0.000
1E+12	23	1.227	1.226	-0.001
5E+12	24	1.228	1.225	-0.003
5E+12	25	1.226	1.223	-0.003
5E+12	26	1.227	1.225	-0.002
1E+13	27	1.227	1.223	-0.004
1E+13	28	1.227	1.222	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.225	-0.002
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002



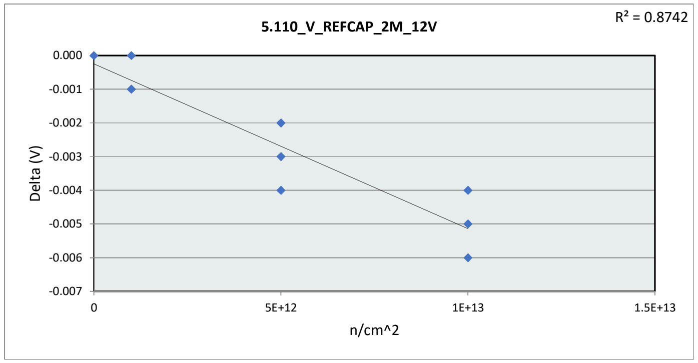
	5.109_V_REFCAP_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.227	1.224	1.222
Max	1.227	1.227	1.225	1.223
UL	1.237	1.237	1.237	1.237



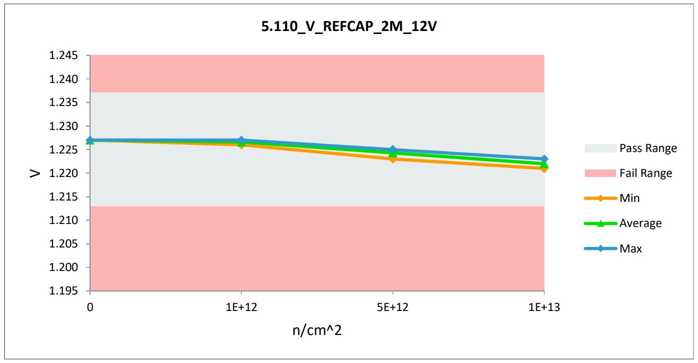
NDD Characterization Report
TPS7H5007-SEP

	5.110_V_REFCAP_2M_12V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.237	1.237
Min Limit	1.213	1.213

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.228	1.227	-0.001
1E+12	22	1.227	1.227	0.000
1E+12	23	1.227	1.226	-0.001
5E+12	24	1.228	1.225	-0.003
5E+12	25	1.227	1.223	-0.004
5E+12	26	1.227	1.225	-0.002
1E+13	27	1.227	1.223	-0.004
1E+13	28	1.227	1.222	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.225	-0.003
	Min	1.227	1.221	-0.006
	Std Dev	0.000	0.002	0.002

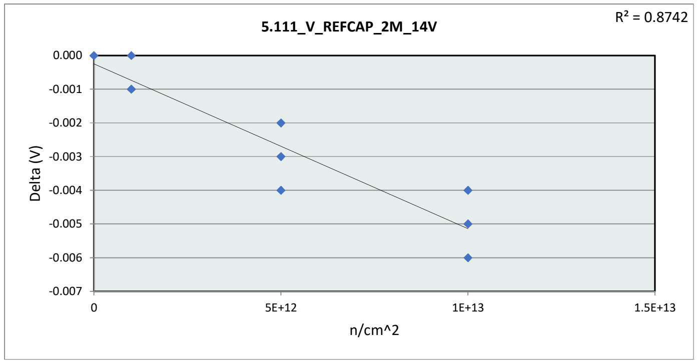


	5.110_V_REFCAP_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.227	1.224	1.222
Max	1.227	1.227	1.225	1.223
UL	1.237	1.237	1.237	1.237

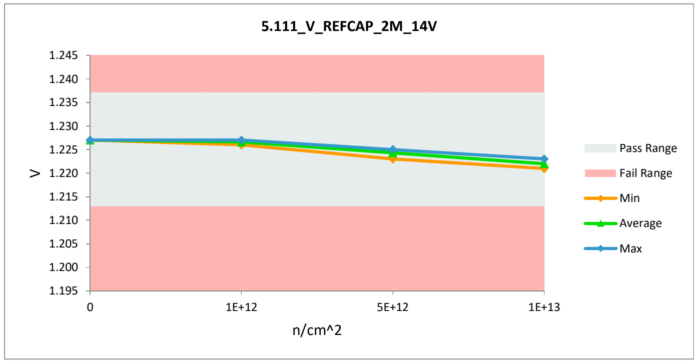


NDD Characterization Report
TPS7H5007-SEP

		5.111_V_REFCAP_2M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.227	1.227	0.000
1E+12	21	1.228	1.227	-0.001
1E+12	22	1.227	1.227	0.000
1E+12	23	1.227	1.226	-0.001
5E+12	24	1.228	1.225	-0.003
5E+12	25	1.227	1.223	-0.004
5E+12	26	1.227	1.225	-0.002
1E+13	27	1.227	1.223	-0.004
1E+13	28	1.227	1.222	-0.005
1E+13	29	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.225	-0.003
	Min	1.227	1.221	-0.006
	Std Dev	0.000	0.002	0.002

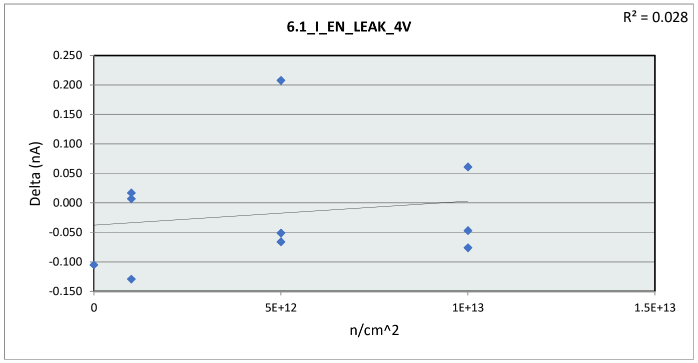


	5.111_V_REFCAP_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.226	1.223	1.221
Average	1.227	1.227	1.224	1.222
Max	1.227	1.227	1.225	1.223
UL	1.237	1.237	1.237	1.237

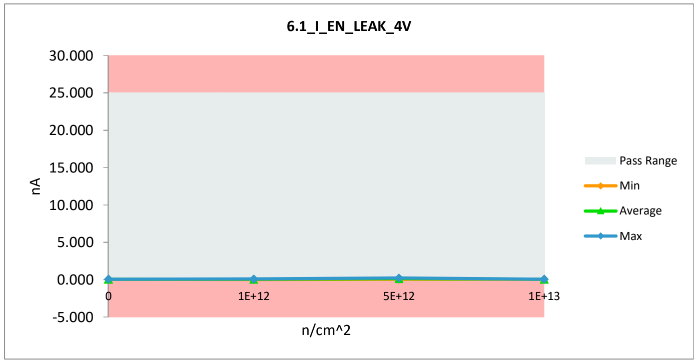


NDD Characterization Report
TPS7H5007-SEP

		6.1_I_EN_LEAK_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	nA	nA	
	Max Limit	5	25	
	Min Limit	-0.1	-0.1	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.171	0.066	-0.105
1E+12	21	0.015	0.022	0.007
1E+12	22	0.093	0.110	0.017
1E+12	23	0.161	0.032	-0.129
5E+12	24	0.034	0.242	0.208
5E+12	25	0.142	0.076	-0.066
5E+12	26	0.190	0.139	-0.051
1E+13	27	0.122	0.046	-0.076
1E+13	28	0.015	0.076	0.061
1E+13	29	0.093	0.046	-0.047
	Max	0.190	0.242	0.208
	Average	0.104	0.085	-0.018
	Min	0.015	0.022	-0.129
	Std Dev	0.065	0.065	0.098

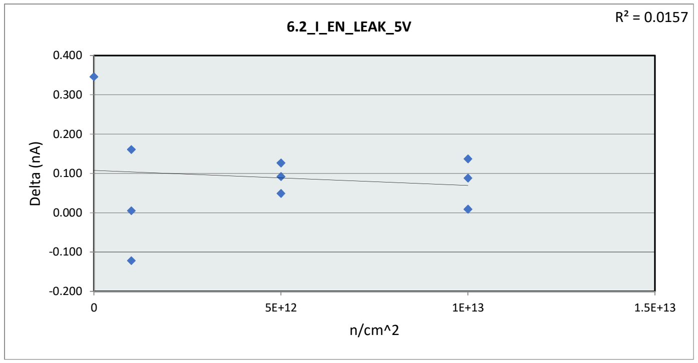


	6.1_I_EN_LEAK_4V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit	-0.1	nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-0.100	-0.100	-0.100	-0.100
Min	0.066	0.022	0.076	0.046
Average	0.066	0.055	0.152	0.056
Max	0.066	0.110	0.242	0.076
UL	25.000	25.000	25.000	25.000

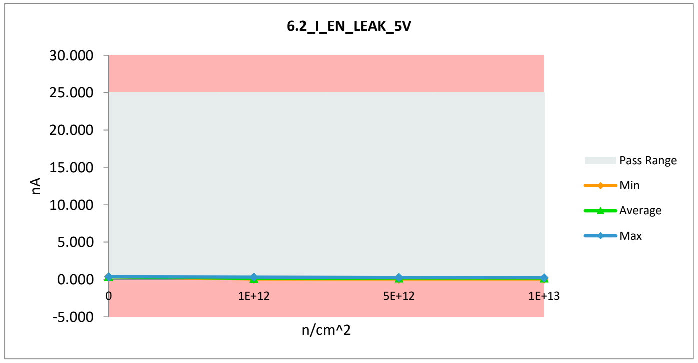


NDD Characterization Report
TPS7H5007-SEP

		6.2_I_EN_LEAK_5V		
Test Site				
Tester				
Test Number				
Unit		nA	nA	
Max Limit		5	25	
Min Limit		-0.1	-0.1	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.027	0.373	0.346
1E+12	21	0.154	0.315	0.161
1E+12	22	0.115	0.120	0.005
1E+12	23	0.173	0.051	-0.122
5E+12	24	0.159	0.286	0.127
5E+12	25	0.115	0.207	0.092
5E+12	26	0.002	0.051	0.049
1E+13	27	0.100	0.237	0.137
1E+13	28	0.081	0.090	0.009
1E+13	29	0.129	0.217	0.088
	Max	0.173	0.373	0.346
	Average	0.105	0.195	0.089
	Min	0.002	0.051	-0.122
	Std Dev	0.056	0.113	0.122

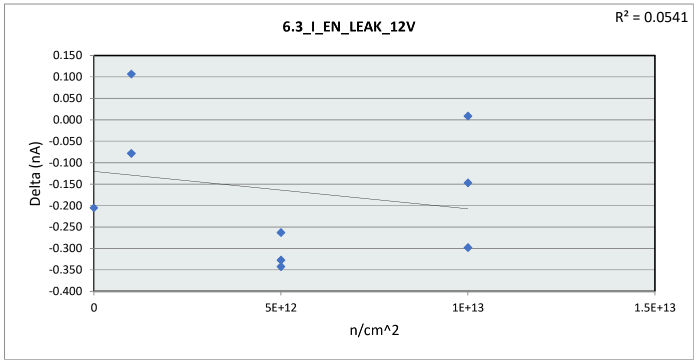


	6.2_I_EN_LEAK_5V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit	-0.1	nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-0.100	-0.100	-0.100	-0.100
Min	0.373	0.051	0.051	0.090
Average	0.373	0.162	0.181	0.181
Max	0.373	0.315	0.286	0.237
UL	25.000	25.000	25.000	25.000

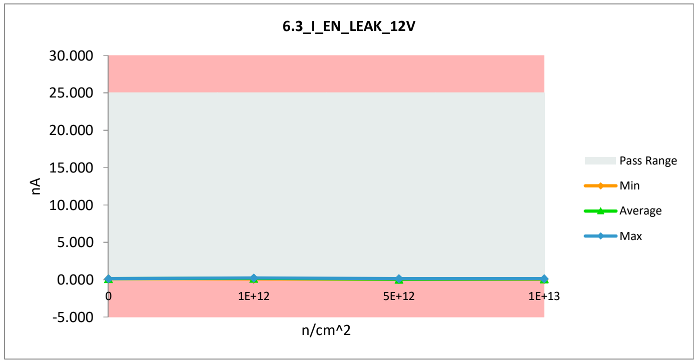


NDD Characterization Report
TPS7H5007-SEP

		6.3_I_EN_LEAK_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	nA	nA	
	Max Limit	5	25	
	Min Limit	-0.1	-0.1	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.334	0.129	-0.205
1E+12	21	0.120	0.227	0.107
1E+12	22	0.188	0.110	-0.078
1E+12	23	0.295	0.217	-0.078
5E+12	24	0.393	0.051	-0.342
5E+12	25	0.383	0.056	-0.327
5E+12	26	0.412	0.149	-0.263
1E+13	27	0.354	0.056	-0.298
1E+13	28	0.237	0.090	-0.147
1E+13	29	0.120	0.129	0.009
	Max	0.412	0.227	0.107
	Average	0.284	0.121	-0.162
	Min	0.120	0.051	-0.342
	Std Dev	0.111	0.063	0.151

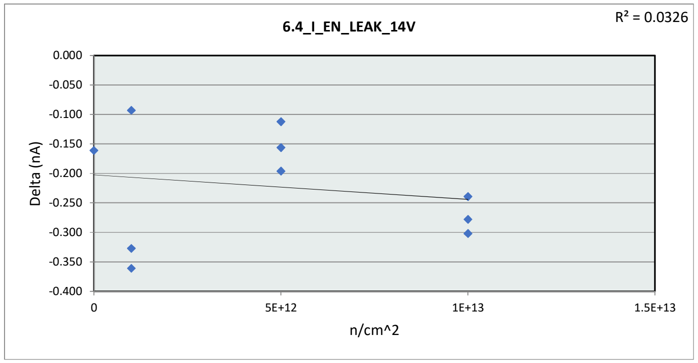


	6.3_I_EN_LEAK_12V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit	-0.1	nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-0.100	-0.100	-0.100	-0.100
Min	0.129	0.110	0.051	0.056
Average	0.129	0.185	0.085	0.092
Max	0.129	0.227	0.149	0.129
UL	25.000	25.000	25.000	25.000

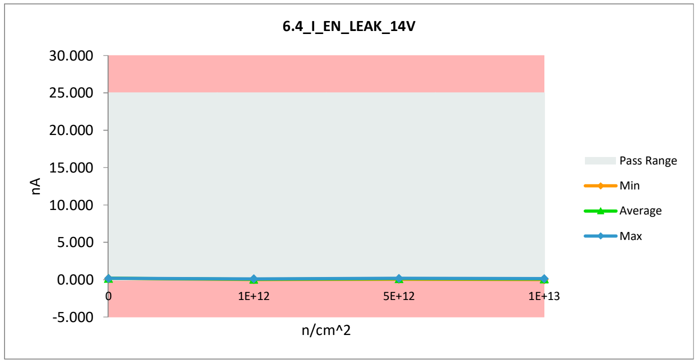


NDD Characterization Report
TPS7H5007-SEP

		6.4_I_EN_LEAK_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	nA	nA	
	Max Limit	5	25	
	Min Limit	-0.1	-0.1	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.344	0.183	-0.161
1E+12	21	0.383	0.022	-0.361
1E+12	22	0.383	0.056	-0.327
1E+12	23	0.217	0.124	-0.093
5E+12	24	0.276	0.120	-0.156
5E+12	25	0.305	0.193	-0.112
5E+12	26	0.286	0.090	-0.196
1E+13	27	0.315	0.037	-0.278
1E+13	28	0.422	0.120	-0.302
1E+13	29	0.393	0.154	-0.239
	Max	0.422	0.193	-0.093
	Average	0.332	0.110	-0.222
	Min	0.217	0.022	-0.361
	Std Dev	0.064	0.059	0.093



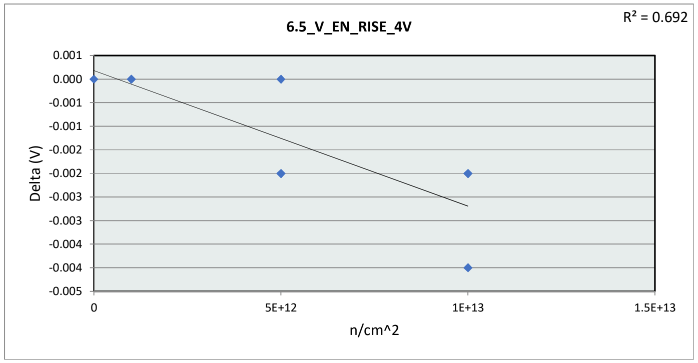
	6.4_I_EN_LEAK_14V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit	-0.1	nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-0.100	-0.100	-0.100	-0.100
Min	0.183	0.022	0.090	0.037
Average	0.183	0.067	0.134	0.104
Max	0.183	0.124	0.193	0.154
UL	25.000	25.000	25.000	25.000



NDD Characterization Report
TPS7H5007-SEP

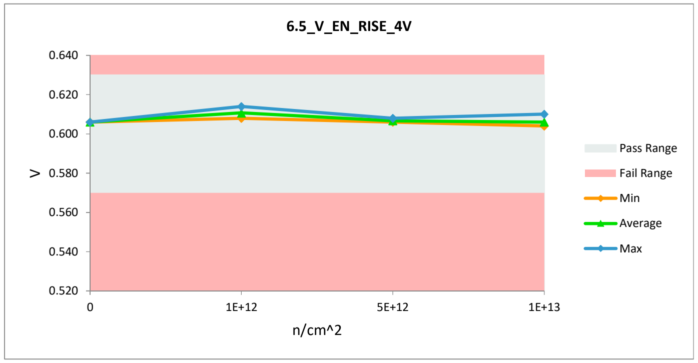
	6.5_V_EN_RISE_4V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.63	0.63
Min Limit	0.58	0.57

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.606	0.606	0.000
1E+12	21	0.614	0.614	0.000
1E+12	22	0.610	0.610	0.000
1E+12	23	0.608	0.608	0.000
5E+12	24	0.608	0.606	-0.002
5E+12	25	0.606	0.606	0.000
5E+12	26	0.610	0.608	-0.002
1E+13	27	0.612	0.610	-0.002
1E+13	28	0.606	0.604	-0.002
1E+13	29	0.608	0.604	-0.004
	Max	0.614	0.614	0.000
	Average	0.609	0.608	-0.001
	Min	0.606	0.604	-0.004
	Std Dev	0.003	0.003	0.001



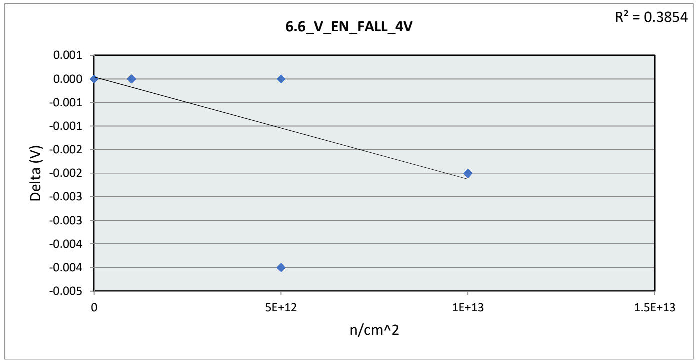
	6.5_V_EN_RISE_4V	
Test Site		
Tester		
Test Number		
Max Limit	0.63	V
Min Limit	0.57	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.608	0.606	0.604
Average	0.606	0.611	0.607	0.606
Max	0.606	0.614	0.608	0.610
UL	0.630	0.630	0.630	0.630

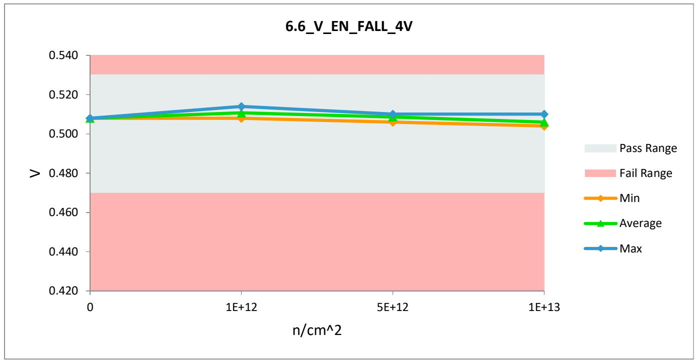


NDD Characterization Report
TPS7H5007-SEP

		6.6_V_EN_FALL_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.508	0.508	0.000
1E+12	21	0.514	0.514	0.000
1E+12	22	0.510	0.510	0.000
1E+12	23	0.508	0.508	0.000
5E+12	24	0.510	0.510	0.000
5E+12	25	0.510	0.506	-0.004
5E+12	26	0.510	0.510	0.000
1E+13	27	0.512	0.510	-0.002
1E+13	28	0.506	0.504	-0.002
1E+13	29	0.506	0.504	-0.002
	Max	0.514	0.514	0.000
	Average	0.509	0.508	-0.001
	Min	0.506	0.504	-0.004
	Std Dev	0.003	0.003	0.001

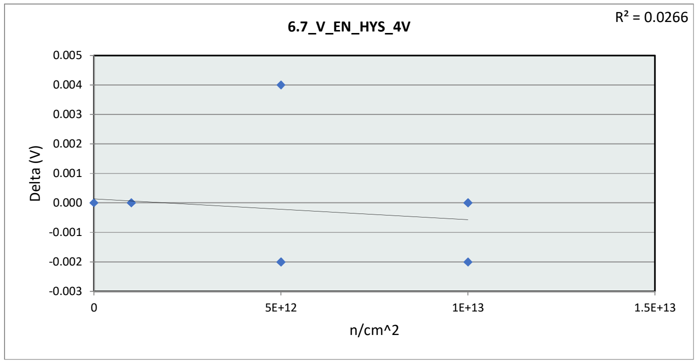


	6.6_V_EN_FALL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.506	0.504
Average	0.508	0.511	0.509	0.506
Max	0.508	0.514	0.510	0.510
UL	0.530	0.530	0.530	0.530

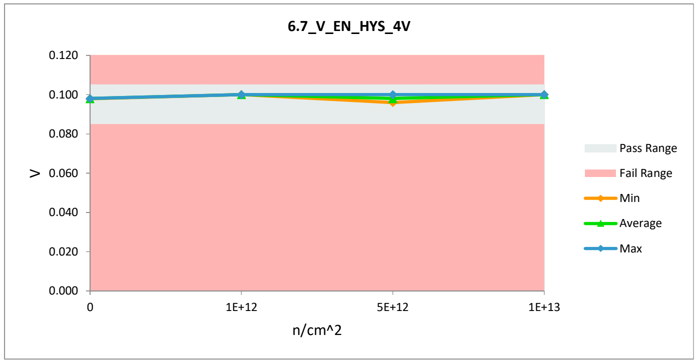


NDD Characterization Report
TPS7H5007-SEP

		6.7_V_EN_HYS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.098	0.098	0.000
1E+12	21	0.100	0.100	0.000
1E+12	22	0.100	0.100	0.000
1E+12	23	0.100	0.100	0.000
5E+12	24	0.098	0.096	-0.002
5E+12	25	0.096	0.100	0.004
5E+12	26	0.100	0.098	-0.002
1E+13	27	0.100	0.100	0.000
1E+13	28	0.100	0.100	0.000
1E+13	29	0.102	0.100	-0.002
	Max	0.102	0.100	0.004
	Average	0.099	0.099	0.000
	Min	0.096	0.096	-0.002
	Std Dev	0.002	0.001	0.002

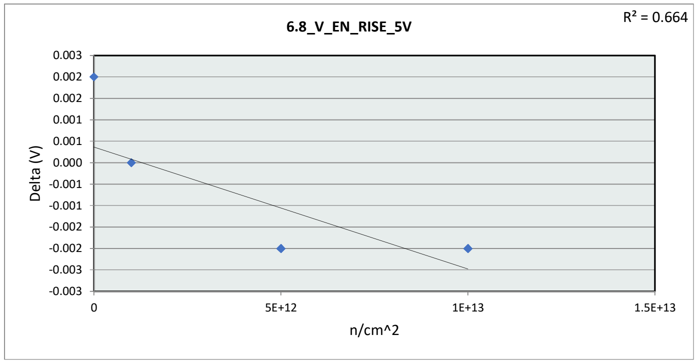


	6.7_V_EN_HYS_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.098	0.100	0.096	0.100
Average	0.098	0.100	0.098	0.100
Max	0.098	0.100	0.100	0.100
UL	0.105	0.105	0.105	0.105

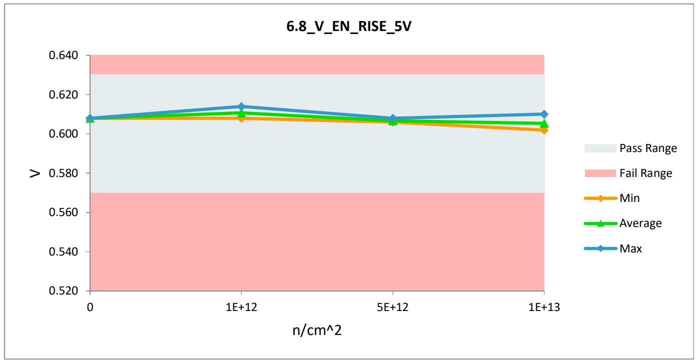


NDD Characterization Report
TPS7H5007-SEP

		6.8_V_EN_RISE_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.606	0.608	0.002
1E+12	21	0.614	0.614	0.000
1E+12	22	0.610	0.610	0.000
1E+12	23	0.608	0.608	0.000
5E+12	24	0.608	0.606	-0.002
5E+12	25	0.608	0.606	-0.002
5E+12	26	0.610	0.608	-0.002
1E+13	27	0.612	0.610	-0.002
1E+13	28	0.606	0.604	-0.002
1E+13	29	0.604	0.602	-0.002
	Max	0.614	0.614	0.002
	Average	0.609	0.608	-0.001
	Min	0.604	0.602	-0.002
	Std Dev	0.003	0.003	0.001

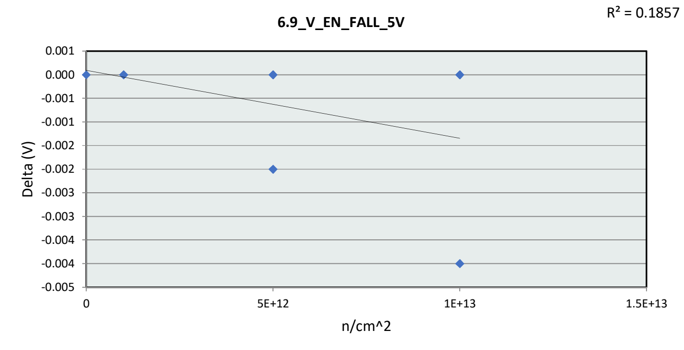


6.8_V_EN_RISE_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.608	0.608	0.606	0.602
Average	0.608	0.611	0.607	0.605
Max	0.608	0.614	0.608	0.610
UL	0.630	0.630	0.630	0.630

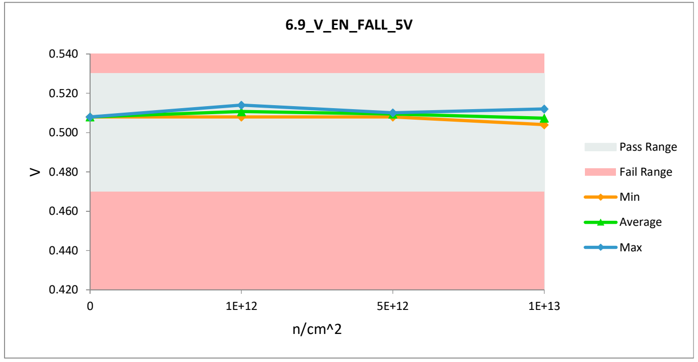


NDD Characterization Report
TPS7H5007-SEP

		6.9_V_EN_FALL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.508	0.508	0.000
1E+12	21	0.514	0.514	0.000
1E+12	22	0.510	0.510	0.000
1E+12	23	0.508	0.508	0.000
5E+12	24	0.510	0.510	0.000
5E+12	25	0.510	0.508	-0.002
5E+12	26	0.510	0.510	0.000
1E+13	27	0.512	0.512	0.000
1E+13	28	0.506	0.506	0.000
1E+13	29	0.508	0.504	-0.004
	Max	0.514	0.514	0.000
	Average	0.510	0.509	-0.001
	Min	0.506	0.504	-0.004
	Std Dev	0.002	0.003	0.001

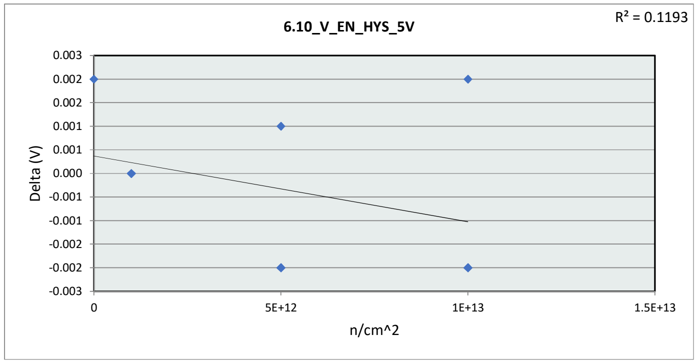


	6.9_V_EN_FALL_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.508	0.504
Average	0.508	0.511	0.509	0.507
Max	0.508	0.514	0.510	0.512
UL	0.530	0.530	0.530	0.530

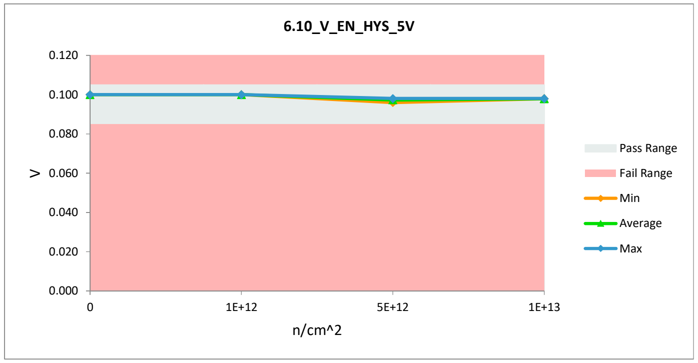


NDD Characterization Report
TPS7H5007-SEP

		6.10_V_EN_HYS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.098	0.100	0.002
1E+12	21	0.100	0.100	0.000
1E+12	22	0.100	0.100	0.000
1E+12	23	0.100	0.100	0.000
5E+12	24	0.098	0.096	-0.002
5E+12	25	0.097	0.098	0.001
5E+12	26	0.100	0.098	-0.002
1E+13	27	0.100	0.098	-0.002
1E+13	28	0.100	0.098	-0.002
1E+13	29	0.096	0.098	0.002
	Max	0.100	0.100	0.002
	Average	0.099	0.099	0.000
	Min	0.096	0.096	-0.002
	Std Dev	0.002	0.001	0.002

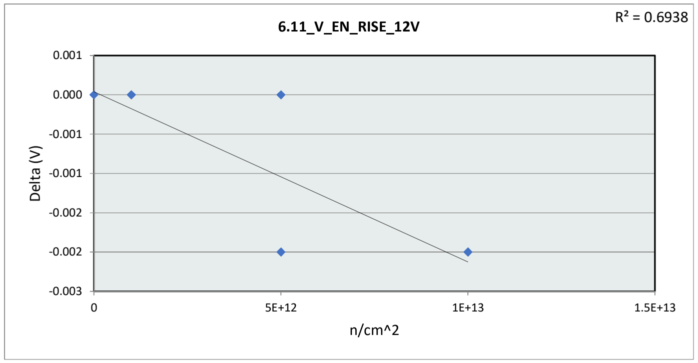


	6.10_V_EN_HYS_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.100	0.100	0.096	0.098
Average	0.100	0.100	0.097	0.098
Max	0.100	0.100	0.098	0.098
UL	0.105	0.105	0.105	0.105

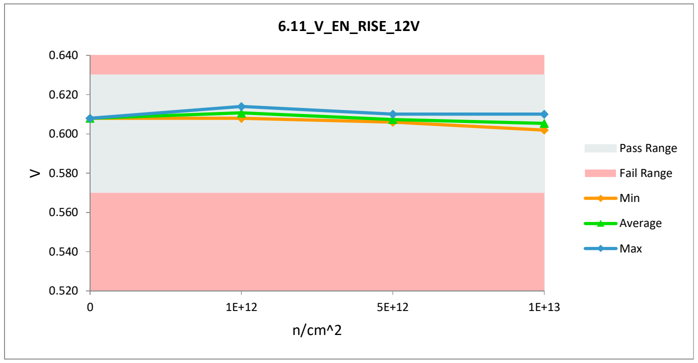


NDD Characterization Report
TPS7H5007-SEP

		6.11_V_EN_RISE_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.608	0.608	0.000
1E+12	21	0.614	0.614	0.000
1E+12	22	0.610	0.610	0.000
1E+12	23	0.608	0.608	0.000
5E+12	24	0.608	0.606	-0.002
5E+12	25	0.608	0.606	-0.002
5E+12	26	0.610	0.610	0.000
1E+13	27	0.612	0.610	-0.002
1E+13	28	0.606	0.604	-0.002
1E+13	29	0.604	0.602	-0.002
	Max	0.614	0.614	0.000
	Average	0.609	0.608	-0.001
	Min	0.604	0.602	-0.002
	Std Dev	0.003	0.003	0.001

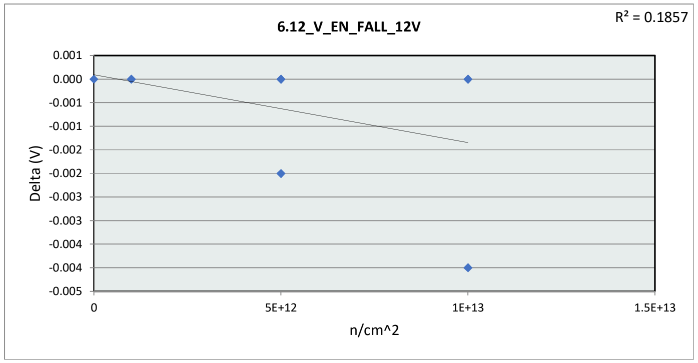


	6.11_V_EN_RISE_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.608	0.608	0.606	0.602
Average	0.608	0.611	0.607	0.605
Max	0.608	0.614	0.610	0.610
UL	0.630	0.630	0.630	0.630

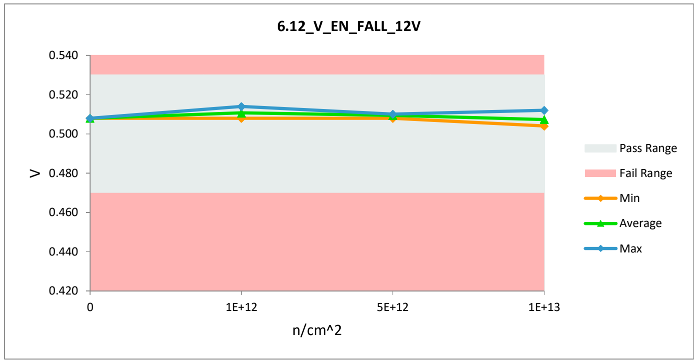


NDD Characterization Report
TPS7H5007-SEP

		6.12_V_EN_FALL_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.508	0.508	0.000
1E+12	21	0.514	0.514	0.000
1E+12	22	0.510	0.510	0.000
1E+12	23	0.508	0.508	0.000
5E+12	24	0.510	0.510	0.000
5E+12	25	0.510	0.508	-0.002
5E+12	26	0.510	0.510	0.000
1E+13	27	0.512	0.512	0.000
1E+13	28	0.506	0.506	0.000
1E+13	29	0.508	0.504	-0.004
	Max	0.514	0.514	0.000
	Average	0.510	0.509	-0.001
	Min	0.506	0.504	-0.004
	Std Dev	0.002	0.003	0.001

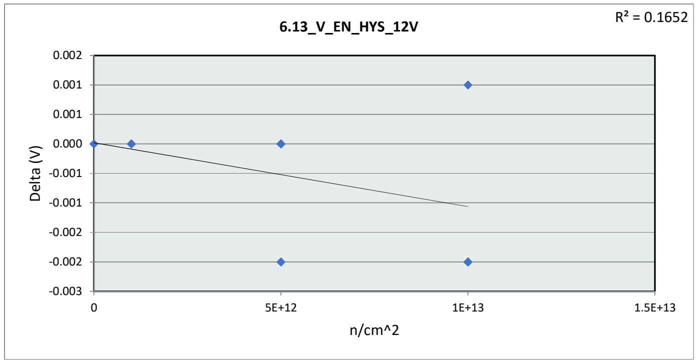


	6.12_V_EN_FALL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.508	0.504
Average	0.508	0.511	0.509	0.507
Max	0.508	0.514	0.510	0.512
UL	0.530	0.530	0.530	0.530

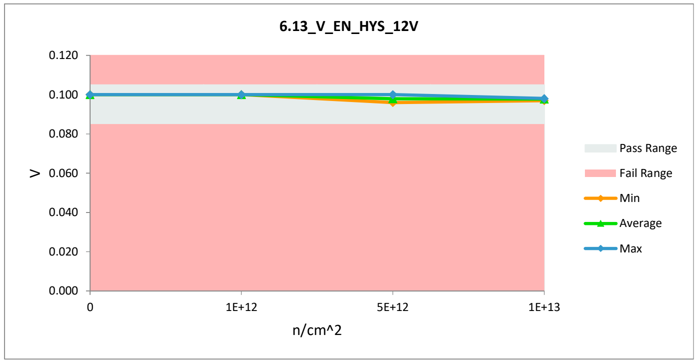


NDD Characterization Report
TPS7H5007-SEP

		6.13_V_EN_HYS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.100	0.100	0.000
1E+12	21	0.100	0.100	0.000
1E+12	22	0.100	0.100	0.000
1E+12	23	0.100	0.100	0.000
5E+12	24	0.098	0.096	-0.002
5E+12	25	0.098	0.098	0.000
5E+12	26	0.100	0.100	0.000
1E+13	27	0.100	0.098	-0.002
1E+13	28	0.100	0.098	-0.002
1E+13	29	0.096	0.097	0.001
	Max	0.100	0.100	0.001
	Average	0.099	0.099	-0.001
	Min	0.096	0.096	-0.002
	Std Dev	0.001	0.001	0.001

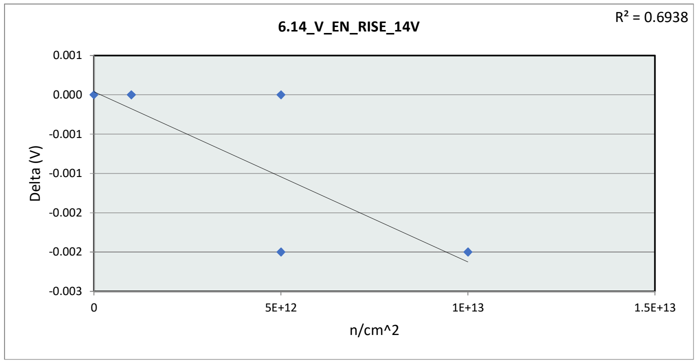


	6.13_V_EN_HYS_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.100	0.100	0.096	0.097
Average	0.100	0.100	0.098	0.098
Max	0.100	0.100	0.100	0.098
UL	0.105	0.105	0.105	0.105

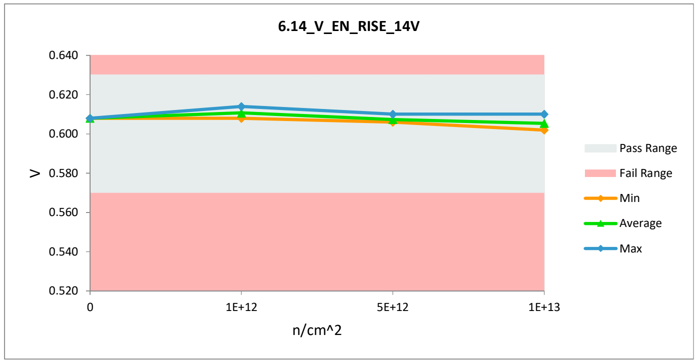


NDD Characterization Report
TPS7H5007-SEP

		6.14_V_EN_RISE_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.608	0.608	0.000
1E+12	21	0.614	0.614	0.000
1E+12	22	0.610	0.610	0.000
1E+12	23	0.608	0.608	0.000
5E+12	24	0.608	0.606	-0.002
5E+12	25	0.608	0.606	-0.002
5E+12	26	0.610	0.610	0.000
1E+13	27	0.612	0.610	-0.002
1E+13	28	0.606	0.604	-0.002
1E+13	29	0.604	0.602	-0.002
	Max	0.614	0.614	0.000
	Average	0.609	0.608	-0.001
	Min	0.604	0.602	-0.002
	Std Dev	0.003	0.003	0.001

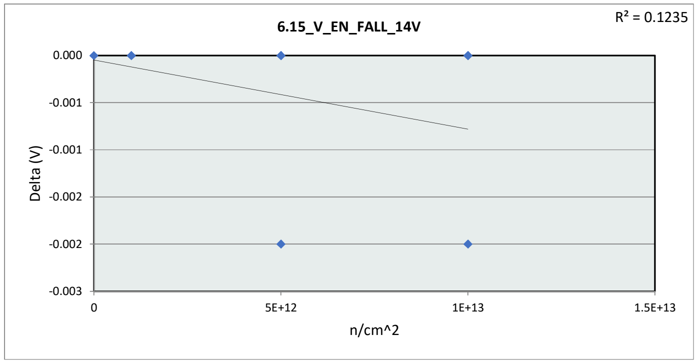


	6.14_V_EN_RISE_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.608	0.608	0.606	0.602
Average	0.608	0.611	0.607	0.605
Max	0.608	0.614	0.610	0.610
UL	0.630	0.630	0.630	0.630

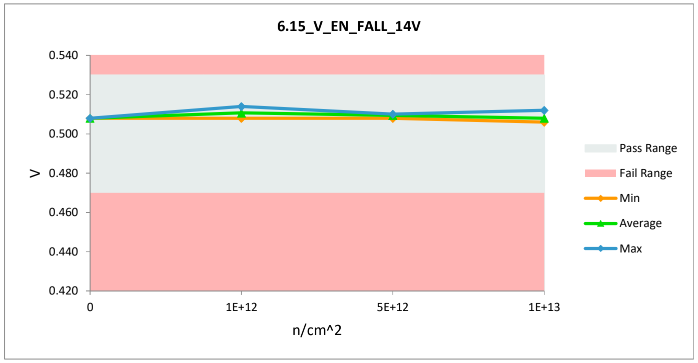


NDD Characterization Report
TPS7H5007-SEP

		6.15_V_EN_FALL_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.508	0.508	0.000
1E+12	21	0.514	0.514	0.000
1E+12	22	0.510	0.510	0.000
1E+12	23	0.508	0.508	0.000
5E+12	24	0.510	0.510	0.000
5E+12	25	0.510	0.508	-0.002
5E+12	26	0.510	0.510	0.000
1E+13	27	0.512	0.512	0.000
1E+13	28	0.506	0.506	0.000
1E+13	29	0.508	0.506	-0.002
	Max	0.514	0.514	0.000
	Average	0.510	0.509	0.000
	Min	0.506	0.506	-0.002
	Std Dev	0.002	0.003	0.001

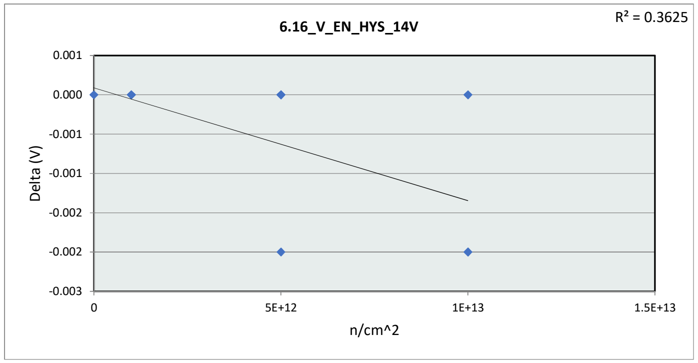


	6.15_V_EN_FALL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.508	0.506
Average	0.508	0.511	0.509	0.508
Max	0.508	0.514	0.510	0.512
UL	0.530	0.530	0.530	0.530

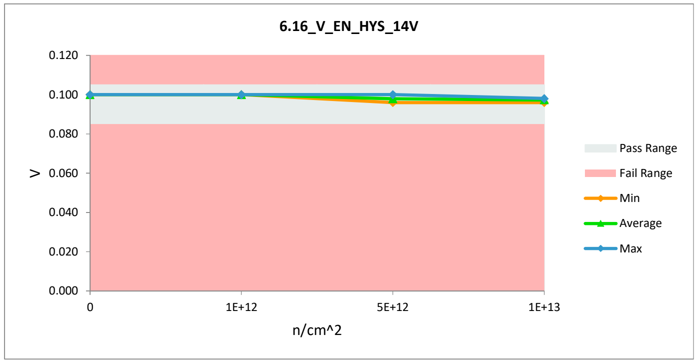


NDD Characterization Report
TPS7H5007-SEP

		6.16_V_EN_HYS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.100	0.100	0.000
1E+12	21	0.100	0.100	0.000
1E+12	22	0.100	0.100	0.000
1E+12	23	0.100	0.100	0.000
5E+12	24	0.098	0.096	-0.002
5E+12	25	0.098	0.098	0.000
5E+12	26	0.100	0.100	0.000
1E+13	27	0.100	0.098	-0.002
1E+13	28	0.100	0.098	-0.002
1E+13	29	0.096	0.096	0.000
	Max	0.100	0.100	0.000
	Average	0.099	0.099	-0.001
	Min	0.096	0.096	-0.002
	Std Dev	0.001	0.002	0.001



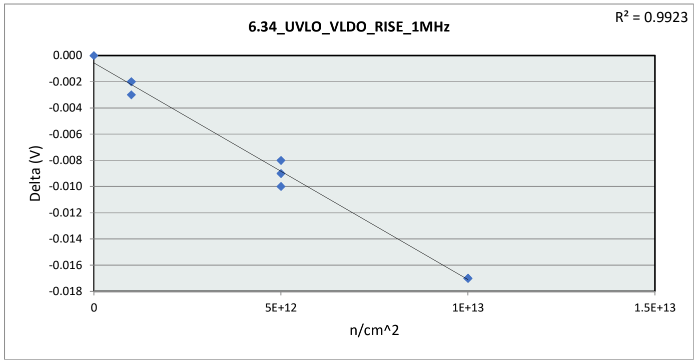
	6.16_V_EN_HYS_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.100	0.100	0.096	0.096
Average	0.100	0.100	0.098	0.097
Max	0.100	0.100	0.100	0.098
UL	0.105	0.105	0.105	0.105



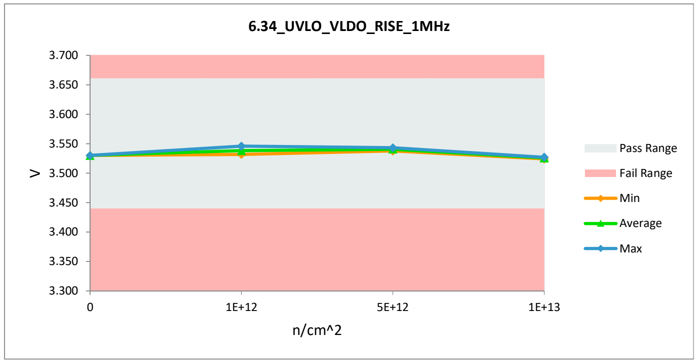
NDD Characterization Report
TPS7H5007-SEP

	6.34_UVLO_VLDO_RISE_1MHz	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.66	3.66
Min Limit	3.44	3.44

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.530	3.530	0.000
1E+12	21	3.549	3.546	-0.003
1E+12	22	3.539	3.537	-0.002
1E+12	23	3.534	3.532	-0.002
5E+12	24	3.547	3.538	-0.009
5E+12	25	3.553	3.543	-0.010
5E+12	26	3.549	3.541	-0.008
1E+13	27	3.541	3.524	-0.017
1E+13	28	3.544	3.527	-0.017
1E+13	29	3.543	3.526	-0.017
	Max	3.553	3.546	0.000
	Average	3.543	3.534	-0.008
	Min	3.530	3.524	-0.017
	Std Dev	0.007	0.008	0.007

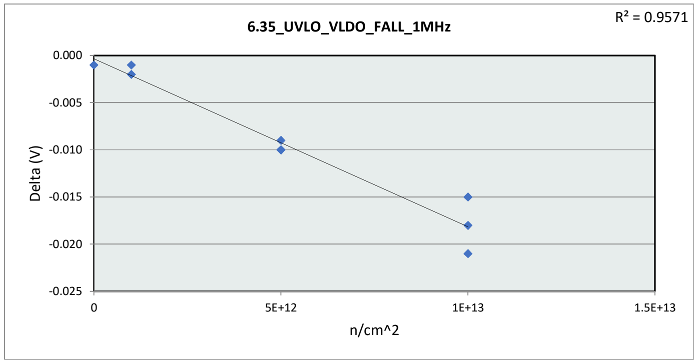


	6.34_UVLO_VLDO_RISE_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.530	3.532	3.538	3.524
Average	3.530	3.538	3.541	3.526
Max	3.530	3.546	3.543	3.527
UL	3.660	3.660	3.660	3.660

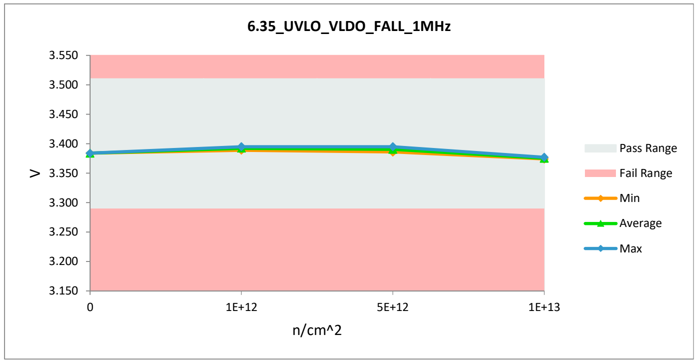


NDD Characterization Report
TPS7H5007-SEP

		6.35_UVLO_VLDO_FALL_1MHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.51	3.51	
Min Limit		3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.385	3.384	-0.001
1E+12	21	3.397	3.395	-0.002
1E+12	22	3.390	3.389	-0.001
1E+12	23	3.395	3.393	-0.002
5E+12	24	3.396	3.386	-0.010
5E+12	25	3.405	3.395	-0.010
5E+12	26	3.399	3.390	-0.009
1E+13	27	3.392	3.377	-0.015
1E+13	28	3.396	3.375	-0.021
1E+13	29	3.392	3.374	-0.018
	Max	3.405	3.395	-0.001
	Average	3.395	3.386	-0.009
	Min	3.385	3.374	-0.021
	Std Dev	0.005	0.008	0.007

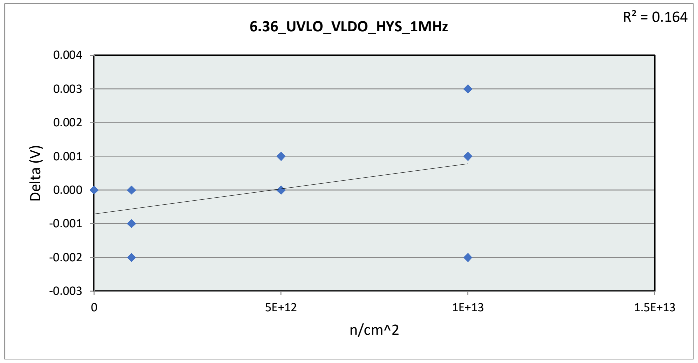


	6.35_UVLO_VLDO_FALL_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.384	3.389	3.386	3.374
Average	3.384	3.392	3.390	3.375
Max	3.384	3.395	3.395	3.377
UL	3.510	3.510	3.510	3.510

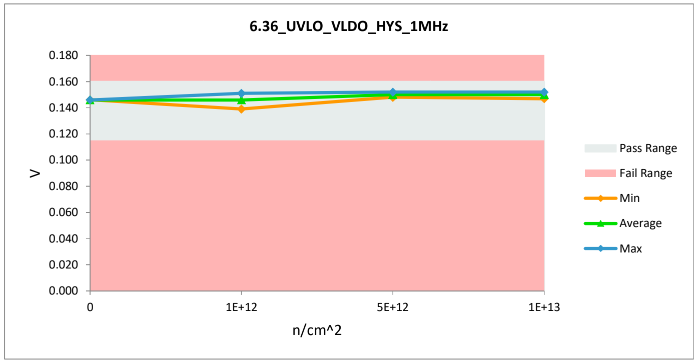


NDD Characterization Report
TPS7H5007-SEP

		6.36_UVLO_VLDO_HYS_1MHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.158	0.16	
Min Limit		0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.146	0.146	0.000
1E+12	21	0.152	0.151	-0.001
1E+12	22	0.150	0.148	-0.002
1E+12	23	0.139	0.139	0.000
5E+12	24	0.152	0.152	0.000
5E+12	25	0.147	0.148	0.001
5E+12	26	0.150	0.150	0.000
1E+13	27	0.149	0.147	-0.002
1E+13	28	0.148	0.151	0.003
1E+13	29	0.151	0.152	0.001
	Max	0.152	0.152	0.003
	Average	0.148	0.148	0.000
	Min	0.139	0.139	-0.002
	Std Dev	0.004	0.004	0.001

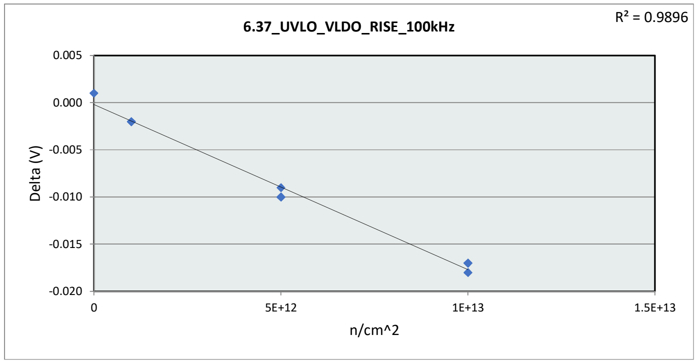


	6.36_UVLO_VLDO_HYS_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.146	0.139	0.148	0.147
Average	0.146	0.146	0.150	0.150
Max	0.146	0.151	0.152	0.152
UL	0.160	0.160	0.160	0.160

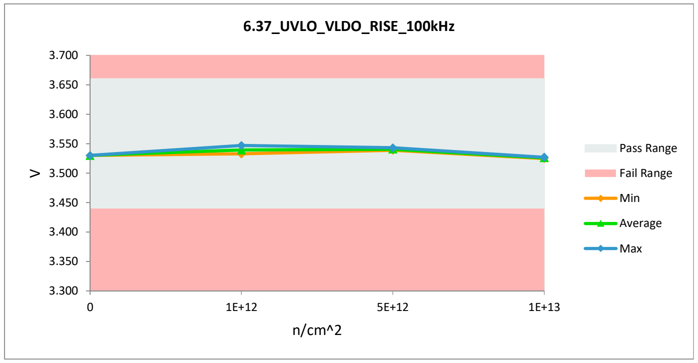


NDD Characterization Report
TPS7H5007-SEP

		6.37_UVLO_VLDO_RISE_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.529	3.530	0.001
1E+12	21	3.549	3.547	-0.002
1E+12	22	3.540	3.538	-0.002
1E+12	23	3.535	3.533	-0.002
5E+12	24	3.548	3.539	-0.009
5E+12	25	3.553	3.543	-0.010
5E+12	26	3.550	3.540	-0.010
1E+13	27	3.542	3.525	-0.017
1E+13	28	3.545	3.527	-0.018
1E+13	29	3.543	3.526	-0.017
	Max	3.553	3.547	0.001
	Average	3.543	3.535	-0.009
	Min	3.529	3.525	-0.018
	Std Dev	0.007	0.008	0.007

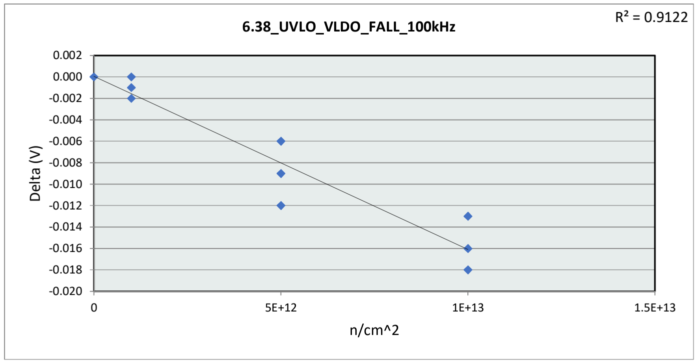


	6.37_UVLO_VLDO_RISE_100k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.530	3.533	3.539	3.525
Average	3.530	3.539	3.541	3.526
Max	3.530	3.547	3.543	3.527
UL	3.660	3.660	3.660	3.660

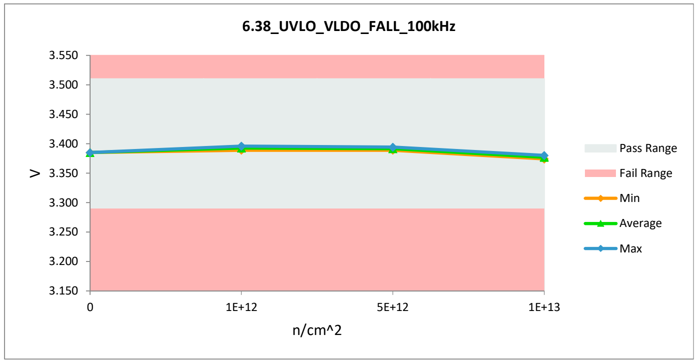


NDD Characterization Report
TPS7H5007-SEP

		6.38_UVLO_VLDO_FALL_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.385	3.385	0.000
1E+12	21	3.396	3.396	0.000
1E+12	22	3.390	3.389	-0.001
1E+12	23	3.395	3.393	-0.002
5E+12	24	3.395	3.389	-0.006
5E+12	25	3.406	3.394	-0.012
5E+12	26	3.400	3.391	-0.009
1E+13	27	3.393	3.377	-0.016
1E+13	28	3.393	3.380	-0.013
1E+13	29	3.392	3.374	-0.018
	Max	3.406	3.396	0.000
	Average	3.394	3.387	-0.008
	Min	3.385	3.374	-0.018
	Std Dev	0.006	0.008	0.007

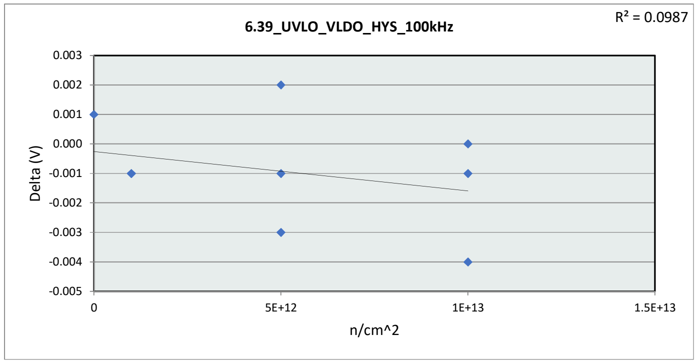


	6.38_UVLO_VLDO_FALL_100k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.385	3.389	3.389	3.374
Average	3.385	3.393	3.391	3.377
Max	3.385	3.396	3.394	3.380
UL	3.510	3.510	3.510	3.510

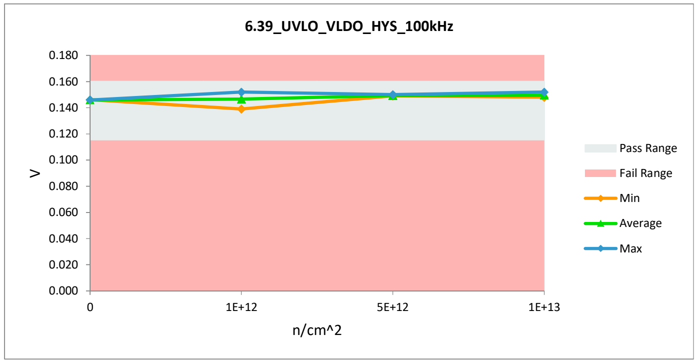


NDD Characterization Report
TPS7H5007-SEP

		6.39_UVLO_VLDO_HYS_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.145	0.146	0.001
1E+12	21	0.153	0.152	-0.001
1E+12	22	0.150	0.149	-0.001
1E+12	23	0.140	0.139	-0.001
5E+12	24	0.153	0.150	-0.003
5E+12	25	0.147	0.149	0.002
5E+12	26	0.150	0.149	-0.001
1E+13	27	0.150	0.149	-0.001
1E+13	28	0.152	0.148	-0.004
1E+13	29	0.152	0.152	0.000
	Max	0.153	0.152	0.002
	Average	0.149	0.148	-0.001
	Min	0.140	0.139	-0.004
	Std Dev	0.004	0.004	0.002

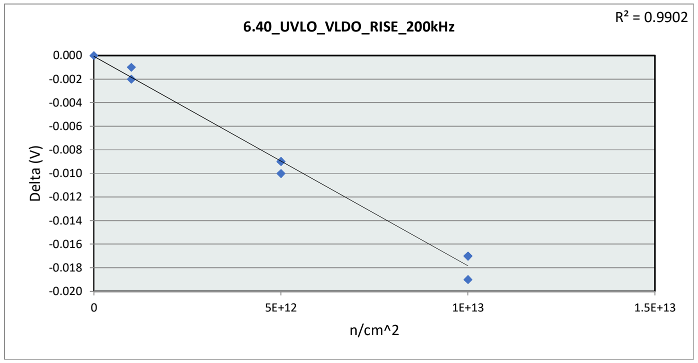


	6.39_UVLO_VLDO_HYS_100kHz			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.146	0.139	0.149	0.148
Average	0.146	0.147	0.149	0.150
Max	0.146	0.152	0.150	0.152
UL	0.160	0.160	0.160	0.160

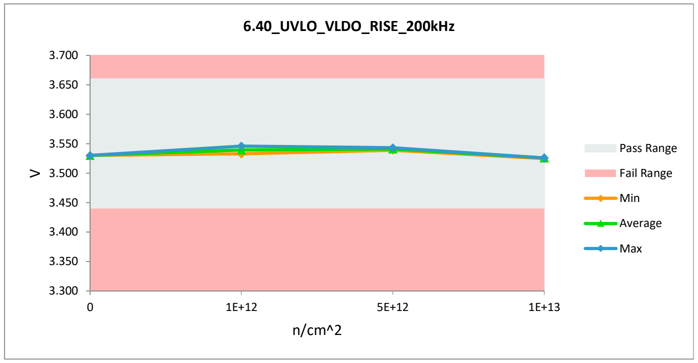


NDD Characterization Report
TPS7H5007-SEP

		6.40_UVLO_VLDO_RISE_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.530	3.530	0.000
1E+12	21	3.548	3.546	-0.002
1E+12	22	3.539	3.538	-0.001
1E+12	23	3.535	3.533	-0.002
5E+12	24	3.548	3.539	-0.009
5E+12	25	3.553	3.543	-0.010
5E+12	26	3.550	3.541	-0.009
1E+13	27	3.542	3.525	-0.017
1E+13	28	3.545	3.526	-0.019
1E+13	29	3.543	3.526	-0.017
	Max	3.553	3.546	0.000
	Average	3.543	3.535	-0.009
	Min	3.530	3.525	-0.019
	Std Dev	0.007	0.008	0.007

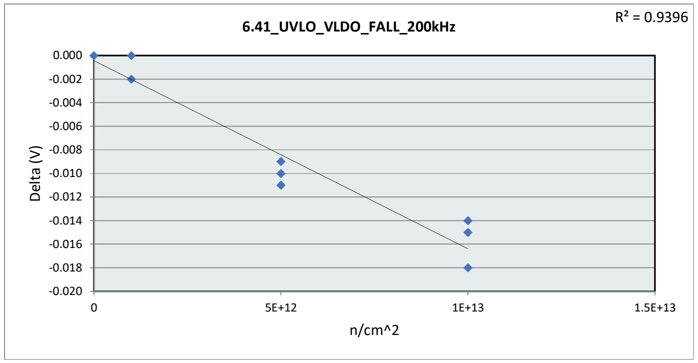


	6.40_UVLO_VLDO_RISE_200k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.530	3.533	3.539	3.525
Average	3.530	3.539	3.541	3.526
Max	3.530	3.546	3.543	3.526
UL	3.660	3.660	3.660	3.660

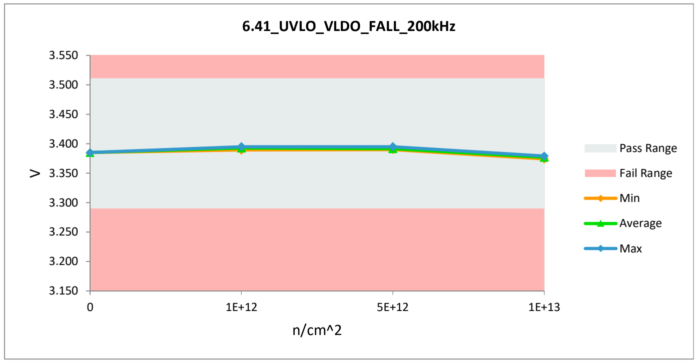


NDD Characterization Report
TPS7H5007-SEP

		6.41_UVLO_VLDO_FALL_200kHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.51	3.51	
Min Limit		3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.385	3.385	0.000
1E+12	21	3.397	3.395	-0.002
1E+12	22	3.391	3.389	-0.002
1E+12	23	3.394	3.394	0.000
5E+12	24	3.399	3.390	-0.009
5E+12	25	3.406	3.395	-0.011
5E+12	26	3.400	3.390	-0.010
1E+13	27	3.392	3.377	-0.015
1E+13	28	3.393	3.379	-0.014
1E+13	29	3.392	3.374	-0.018
	Max	3.406	3.395	0.000
	Average	3.395	3.387	-0.008
	Min	3.385	3.374	-0.018
	Std Dev	0.006	0.008	0.007

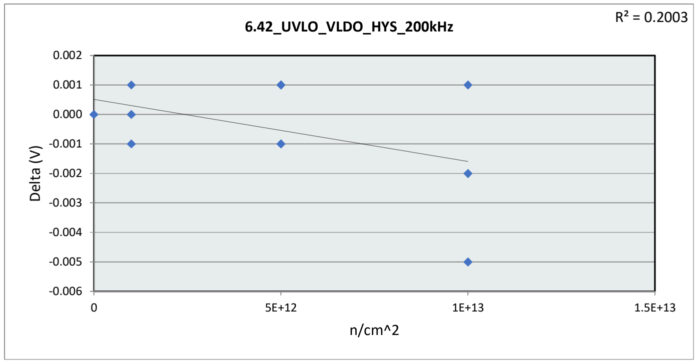


	6.41_UVLO_VLDO_FALL_200k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.385	3.389	3.390	3.374
Average	3.385	3.393	3.392	3.377
Max	3.385	3.395	3.395	3.379
UL	3.510	3.510	3.510	3.510

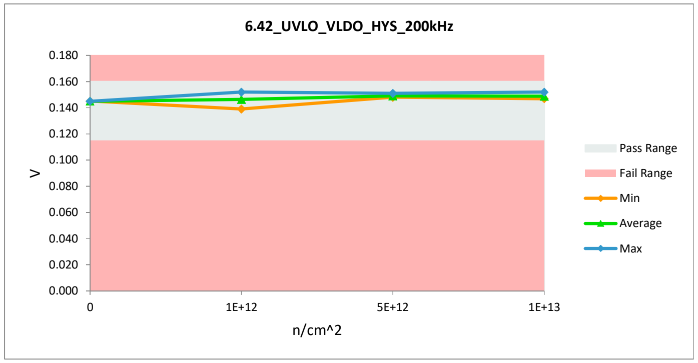


NDD Characterization Report
TPS7H5007-SEP

		6.42_UVLO_VLDO_HYS_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.145	0.145	0.000
1E+12	21	0.151	0.152	0.001
1E+12	22	0.148	0.148	0.000
1E+12	23	0.140	0.139	-0.001
5E+12	24	0.149	0.148	-0.001
5E+12	25	0.147	0.148	0.001
5E+12	26	0.150	0.151	0.001
1E+13	27	0.149	0.147	-0.002
1E+13	28	0.152	0.147	-0.005
1E+13	29	0.151	0.152	0.001
	Max	0.152	0.152	0.001
	Average	0.148	0.148	-0.001
	Min	0.140	0.139	-0.005
	Std Dev	0.004	0.004	0.002

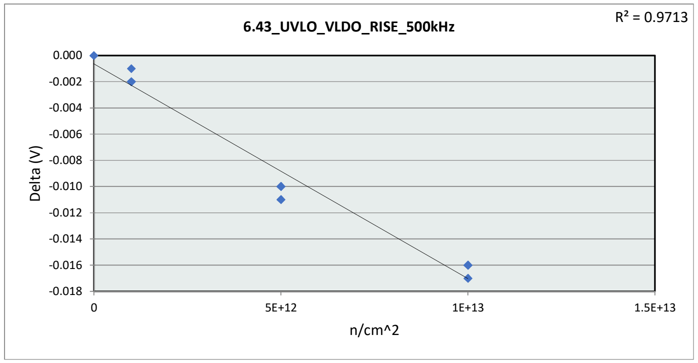


	6.42_UVLO_VLDO_HYS_200kH			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.145	0.139	0.148	0.147
Average	0.145	0.146	0.149	0.149
Max	0.145	0.152	0.151	0.152
UL	0.160	0.160	0.160	0.160

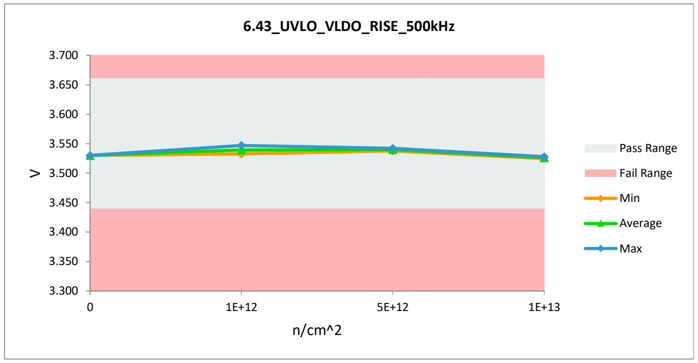


NDD Characterization Report
TPS7H5007-SEP

		6.43_UVLO_VLDO_RISE_500kHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.66	3.66	
Min Limit		3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.530	3.530	0.000
1E+12	21	3.549	3.547	-0.002
1E+12	22	3.540	3.538	-0.002
1E+12	23	3.534	3.533	-0.001
5E+12	24	3.548	3.538	-0.010
5E+12	25	3.553	3.542	-0.011
5E+12	26	3.550	3.540	-0.010
1E+13	27	3.541	3.525	-0.016
1E+13	28	3.544	3.528	-0.016
1E+13	29	3.543	3.526	-0.017
	Max	3.553	3.547	0.000
	Average	3.543	3.535	-0.008
	Min	3.530	3.525	-0.017
	Std Dev	0.007	0.007	0.007

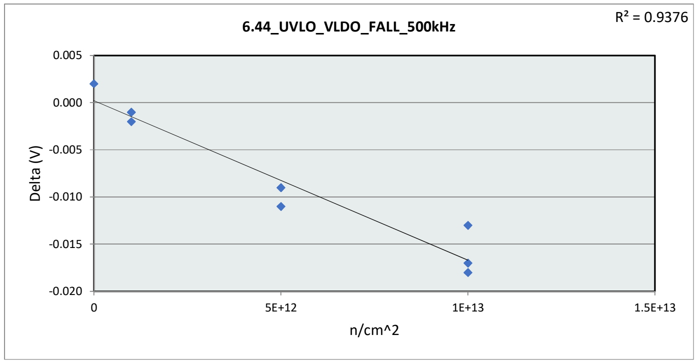


	6.43_UVLO_VLDO_RISE_500k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.530	3.533	3.538	3.525
Average	3.530	3.539	3.540	3.526
Max	3.530	3.547	3.542	3.528
UL	3.660	3.660	3.660	3.660

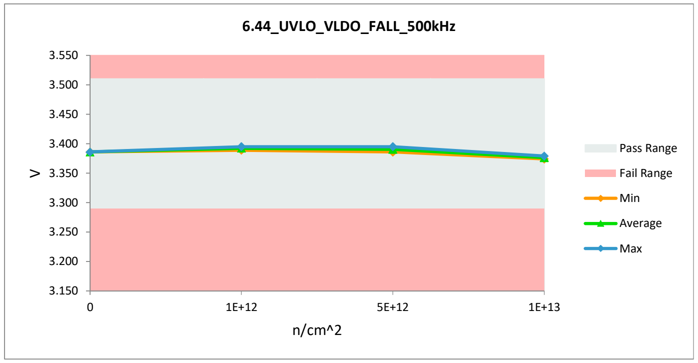


NDD Characterization Report
TPS7H5007-SEP

		6.44_UVLO_VLDO_FALL_500kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.384	3.386	0.002
1E+12	21	3.396	3.395	-0.001
1E+12	22	3.390	3.389	-0.001
1E+12	23	3.395	3.393	-0.002
5E+12	24	3.395	3.386	-0.009
5E+12	25	3.406	3.395	-0.011
5E+12	26	3.399	3.390	-0.009
1E+13	27	3.394	3.376	-0.018
1E+13	28	3.392	3.379	-0.013
1E+13	29	3.391	3.374	-0.017
	Max	3.406	3.395	0.002
	Average	3.394	3.386	-0.008
	Min	3.384	3.374	-0.018
	Std Dev	0.006	0.008	0.007

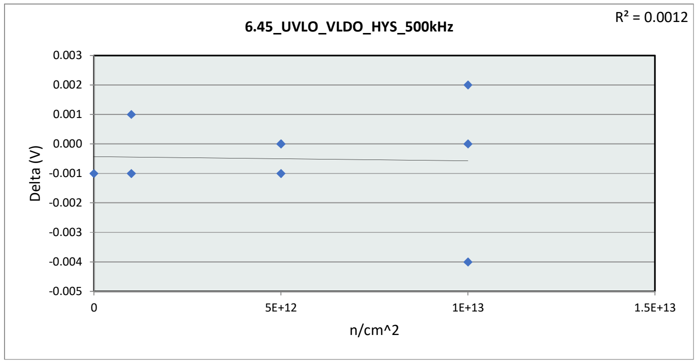


	6.44_UVLO_VLDO_FALL_500k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.386	3.389	3.386	3.374
Average	3.386	3.392	3.390	3.376
Max	3.386	3.395	3.395	3.379
UL	3.510	3.510	3.510	3.510

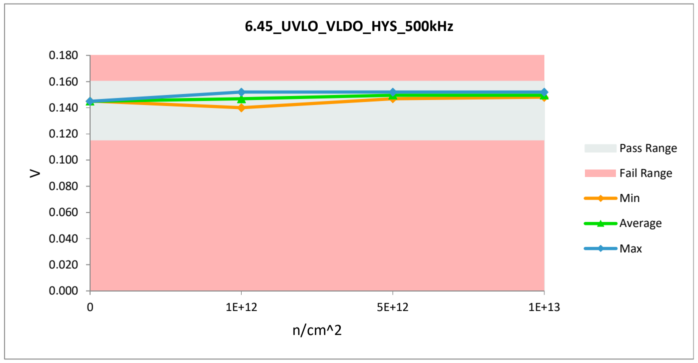


NDD Characterization Report
TPS7H5007-SEP

		6.45_UVLO_VLDO_HYS_500kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.146	0.145	-0.001
1E+12	21	0.153	0.152	-0.001
1E+12	22	0.150	0.149	-0.001
1E+12	23	0.139	0.140	0.001
5E+12	24	0.153	0.152	-0.001
5E+12	25	0.147	0.147	0.000
5E+12	26	0.150	0.150	0.000
1E+13	27	0.147	0.149	0.002
1E+13	28	0.152	0.148	-0.004
1E+13	29	0.152	0.152	0.000
	Max	0.153	0.152	0.002
	Average	0.149	0.148	0.000
	Min	0.139	0.140	-0.004
	Std Dev	0.004	0.004	0.002

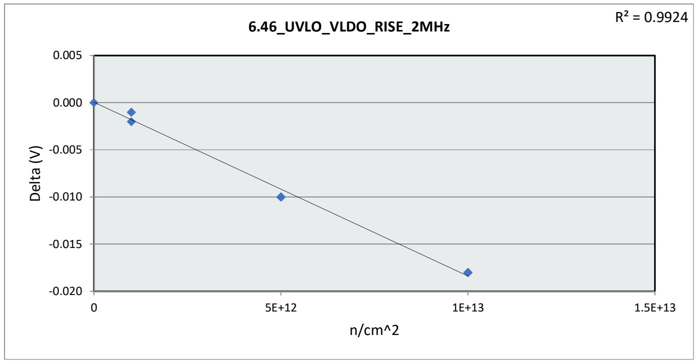


6.45_UVLO_VLDO_HYS_500kH				
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.145	0.140	0.147	0.148
Average	0.145	0.147	0.150	0.150
Max	0.145	0.152	0.152	0.152
UL	0.160	0.160	0.160	0.160

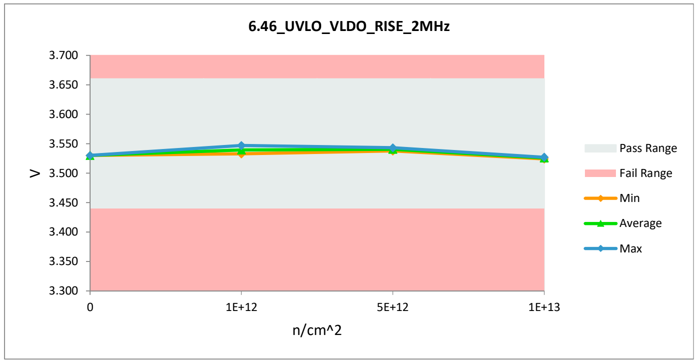


NDD Characterization Report
TPS7H5007-SEP

		6.46_UVLO_VLDO_RISE_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.530	3.530	0.000
1E+12	21	3.548	3.547	-0.001
1E+12	22	3.540	3.538	-0.002
1E+12	23	3.534	3.533	-0.001
5E+12	24	3.548	3.538	-0.010
5E+12	25	3.553	3.543	-0.010
5E+12	26	3.550	3.540	-0.010
1E+13	27	3.542	3.524	-0.018
1E+13	28	3.545	3.527	-0.018
1E+13	29	3.544	3.526	-0.018
	Max	3.553	3.547	0.000
	Average	3.543	3.535	-0.009
	Min	3.530	3.524	-0.018
	Std Dev	0.007	0.008	0.007

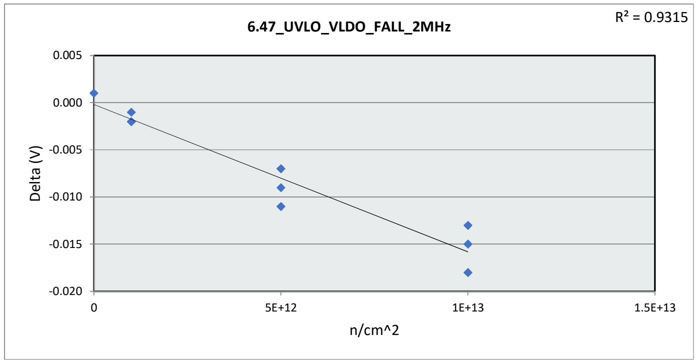


	6.46_UVLO_VLDO_RISE_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.530	3.533	3.538	3.524
Average	3.530	3.539	3.540	3.526
Max	3.530	3.547	3.543	3.527
UL	3.660	3.660	3.660	3.660

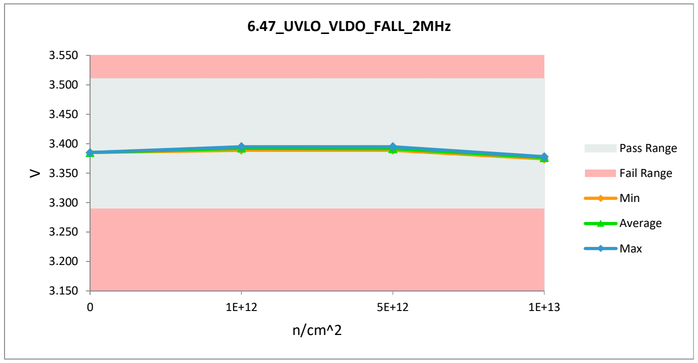


NDD Characterization Report
TPS7H5007-SEP

		6.47_UVLO_VLDO_FALL_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	3.384	3.385	0.001
1E+12	21	3.396	3.395	-0.001
1E+12	22	3.391	3.389	-0.002
1E+12	23	3.395	3.393	-0.002
5E+12	24	3.396	3.389	-0.007
5E+12	25	3.406	3.395	-0.011
5E+12	26	3.399	3.390	-0.009
1E+13	27	3.392	3.377	-0.015
1E+13	28	3.391	3.378	-0.013
1E+13	29	3.392	3.374	-0.018
	Max	3.406	3.395	0.001
	Average	3.394	3.387	-0.008
	Min	3.384	3.374	-0.018
	Std Dev	0.006	0.008	0.007

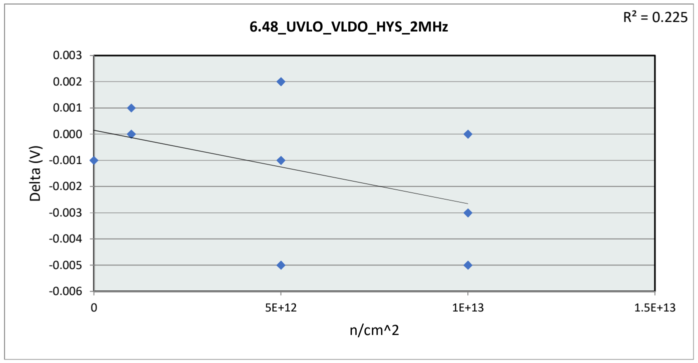


	6.47_UVLO_VLDO_FALL_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.385	3.389	3.389	3.374
Average	3.385	3.392	3.391	3.376
Max	3.385	3.395	3.395	3.378
UL	3.510	3.510	3.510	3.510

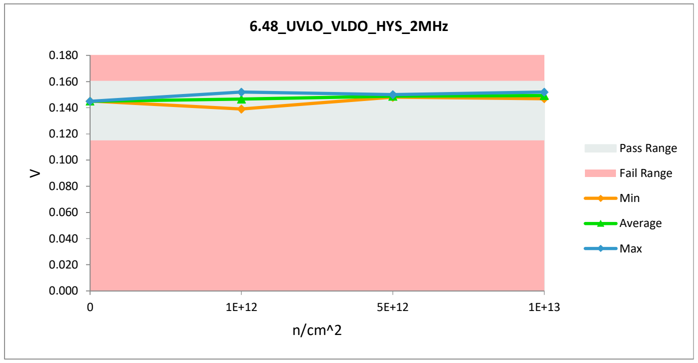


NDD Characterization Report
TPS7H5007-SEP

		6.48_UVLO_VLDO_HYS_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.146	0.145	-0.001
1E+12	21	0.152	0.152	0.000
1E+12	22	0.149	0.149	0.000
1E+12	23	0.138	0.139	0.001
5E+12	24	0.153	0.148	-0.005
5E+12	25	0.146	0.148	0.002
5E+12	26	0.151	0.150	-0.001
1E+13	27	0.150	0.147	-0.003
1E+13	28	0.154	0.149	-0.005
1E+13	29	0.152	0.152	0.000
	Max	0.154	0.152	0.002
	Average	0.149	0.148	-0.001
	Min	0.138	0.139	-0.005
	Std Dev	0.005	0.004	0.002



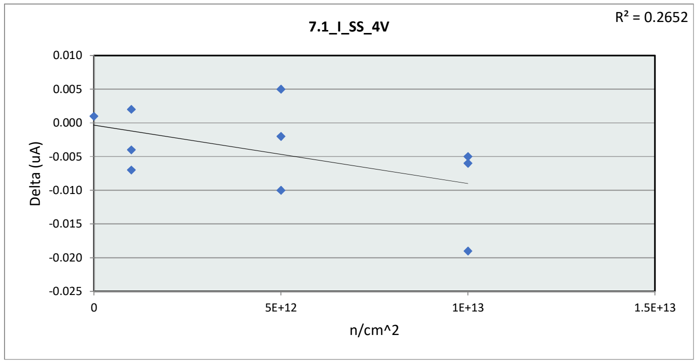
	6.48_UVLO_VLDO_HYS_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.145	0.139	0.148	0.147
Average	0.145	0.147	0.149	0.149
Max	0.145	0.152	0.150	0.152
UL	0.160	0.160	0.160	0.160



NDD Characterization Report
TPS7H5007-SEP

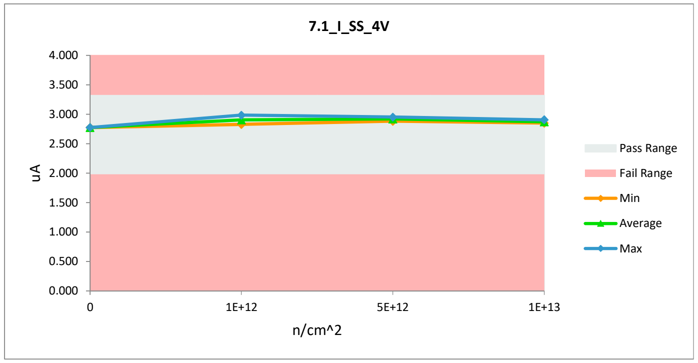
	7.1_I_SS_4V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	3.2	3.32
Min Limit	2.2	1.98

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.774	2.775	0.001
1E+12	21	2.984	2.986	0.002
1E+12	22	2.904	2.897	-0.007
1E+12	23	2.832	2.828	-0.004
5E+12	24	2.933	2.923	-0.010
5E+12	25	2.877	2.882	0.005
5E+12	26	2.956	2.954	-0.002
1E+13	27	2.855	2.850	-0.005
1E+13	28	2.913	2.907	-0.006
1E+13	29	2.873	2.854	-0.019
	Max	2.984	2.986	0.005
	Average	2.890	2.886	-0.004
	Min	2.774	2.775	-0.019
	Std Dev	0.062	0.062	0.007



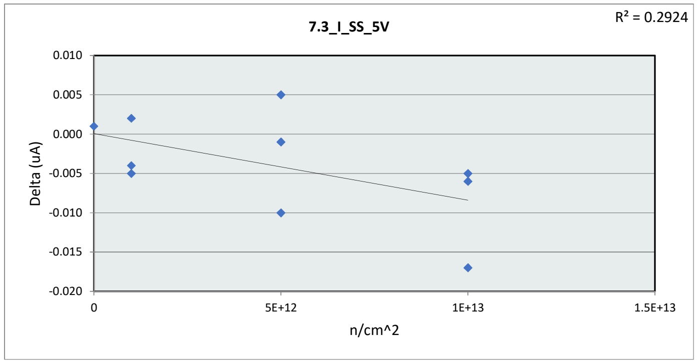
	7.1_I_SS_4V	
Test Site		
Tester		
Test Number		
Max Limit	3.32	uA
Min Limit	1.98	uA

n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.775	2.828	2.882	2.850
Average	2.775	2.904	2.920	2.870
Max	2.775	2.986	2.954	2.907
UL	3.320	3.320	3.320	3.320

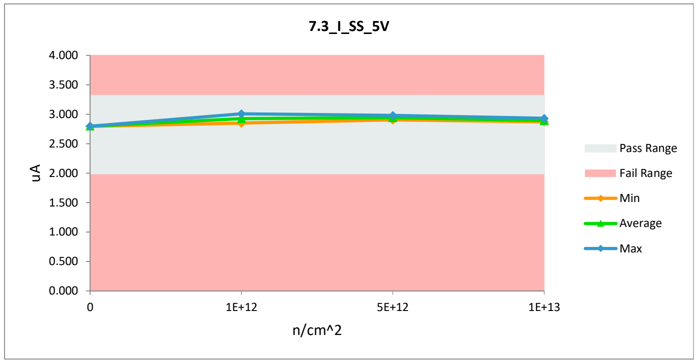


NDD Characterization Report
TPS7H5007-SEP

		7.3_I_SS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.2	3.32	
	Min Limit	2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.797	2.798	0.001
1E+12	21	3.007	3.009	0.002
1E+12	22	2.926	2.921	-0.005
1E+12	23	2.854	2.850	-0.004
5E+12	24	2.955	2.945	-0.010
5E+12	25	2.900	2.905	0.005
5E+12	26	2.979	2.978	-0.001
1E+13	27	2.878	2.873	-0.005
1E+13	28	2.936	2.930	-0.006
1E+13	29	2.894	2.877	-0.017
	Max	3.007	3.009	0.005
	Average	2.913	2.909	-0.004
	Min	2.797	2.798	-0.017
	Std Dev	0.062	0.062	0.006

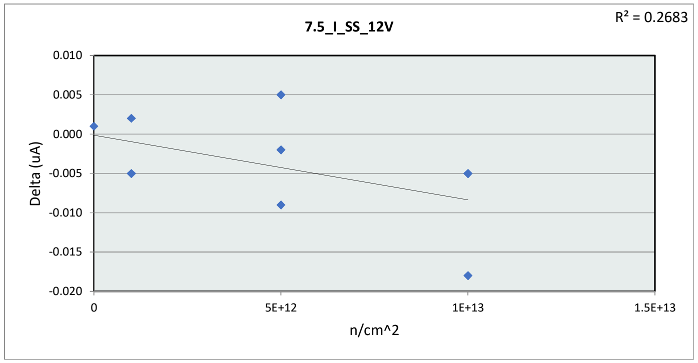


	7.3_I_SS_5V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.798	2.850	2.905	2.873
Average	2.798	2.927	2.943	2.893
Max	2.798	3.009	2.978	2.930
UL	3.320	3.320	3.320	3.320

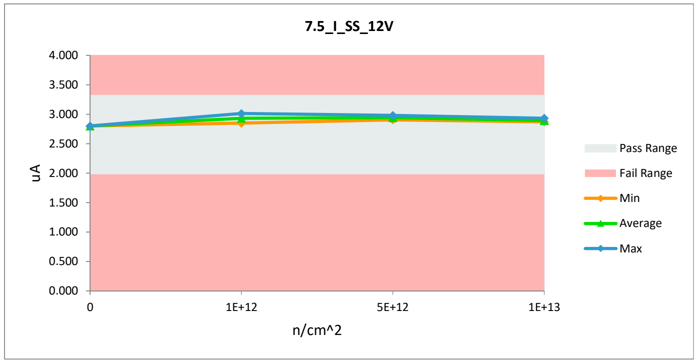


NDD Characterization Report
TPS7H5007-SEP

		7.5_I_SS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.2	3.32	
	Min Limit	2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.799	2.800	0.001
1E+12	21	3.009	3.011	0.002
1E+12	22	2.928	2.923	-0.005
1E+12	23	2.856	2.851	-0.005
5E+12	24	2.956	2.947	-0.009
5E+12	25	2.902	2.907	0.005
5E+12	26	2.980	2.978	-0.002
1E+13	27	2.879	2.874	-0.005
1E+13	28	2.937	2.932	-0.005
1E+13	29	2.896	2.878	-0.018
	Max	3.009	3.011	0.005
	Average	2.914	2.910	-0.004
	Min	2.799	2.800	-0.018
	Std Dev	0.062	0.062	0.006

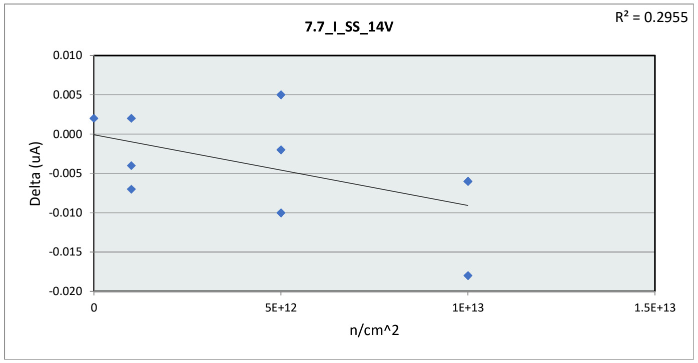


	7.5_I_SS_12V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.800	2.851	2.907	2.874
Average	2.800	2.928	2.944	2.895
Max	2.800	3.011	2.978	2.932
UL	3.320	3.320	3.320	3.320

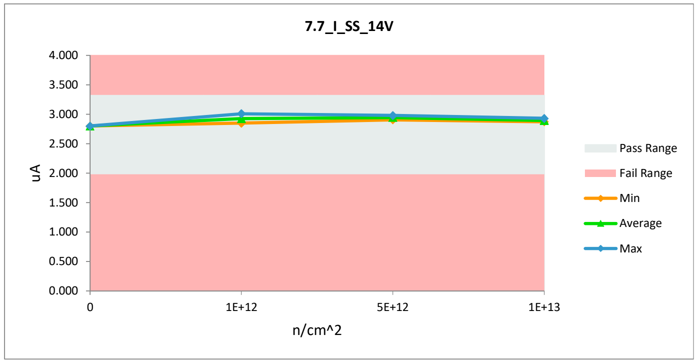


NDD Characterization Report
TPS7H5007-SEP

		7.7_I_SS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.2	3.32	
	Min Limit	2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.798	2.800	0.002
1E+12	21	3.008	3.010	0.002
1E+12	22	2.929	2.922	-0.007
1E+12	23	2.855	2.851	-0.004
5E+12	24	2.957	2.947	-0.010
5E+12	25	2.902	2.907	0.005
5E+12	26	2.981	2.979	-0.002
1E+13	27	2.880	2.874	-0.006
1E+13	28	2.937	2.931	-0.006
1E+13	29	2.896	2.878	-0.018
	Max	3.008	3.010	0.005
	Average	2.914	2.910	-0.004
	Min	2.798	2.800	-0.018
	Std Dev	0.062	0.062	0.007



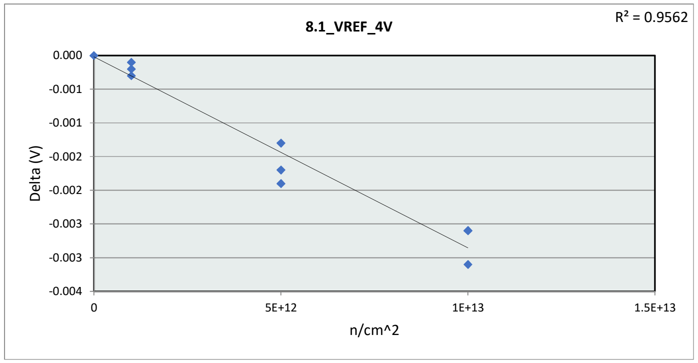
	7.7_I_SS_14V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.800	2.851	2.907	2.874
Average	2.800	2.928	2.944	2.894
Max	2.800	3.010	2.979	2.931
UL	3.320	3.320	3.320	3.320



NDD Characterization Report
TPS7H5007-SEP

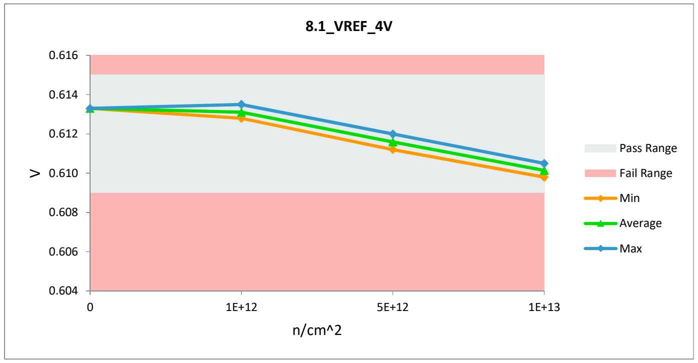
	8.1_VREF_4V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.615	0.615
Min Limit	0.611	0.609

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.613	0.613	0.000
1E+12	21	0.614	0.613	0.000
1E+12	22	0.613	0.613	0.000
1E+12	23	0.613	0.613	0.000
5E+12	24	0.613	0.612	-0.002
5E+12	25	0.613	0.611	-0.002
5E+12	26	0.613	0.612	-0.001
1E+13	27	0.613	0.610	-0.003
1E+13	28	0.613	0.610	-0.003
1E+13	29	0.613	0.610	-0.003
	Max	0.614	0.613	0.000
	Average	0.613	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.000	0.001	0.001



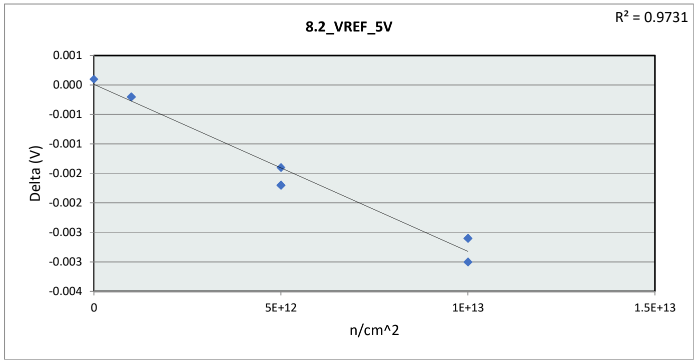
	8.1_VREF_4V	
Test Site		
Tester		
Test Number		
Max Limit	0.615	V
Min Limit	0.609	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.613	0.611	0.610
Average	0.613	0.613	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

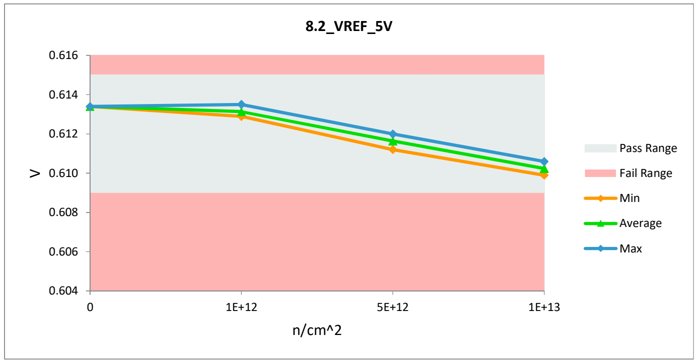


NDD Characterization Report
TPS7H5007-SEP

		8.2_VREF_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.611	0.609	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.613	0.613	0.000
1E+12	21	0.614	0.613	0.000
1E+12	22	0.613	0.613	0.000
1E+12	23	0.613	0.613	0.000
5E+12	24	0.613	0.612	-0.002
5E+12	25	0.613	0.611	-0.002
5E+12	26	0.613	0.612	-0.001
1E+13	27	0.613	0.610	-0.003
1E+13	28	0.613	0.611	-0.003
1E+13	29	0.613	0.610	-0.003
	Max	0.614	0.613	0.000
	Average	0.613	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.000	0.001	0.001

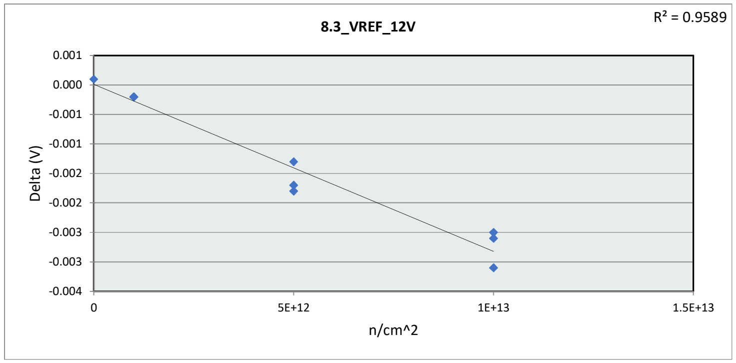


8.2_VREF_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.613	0.611	0.610
Average	0.613	0.613	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

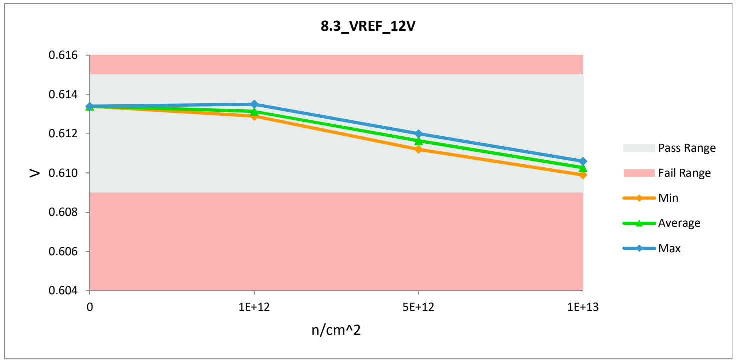


NDD Characterization Report
TPS7H5007-SEP

		8.3_VREF_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.611	0.609	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.613	0.613	0.000
1E+12	21	0.614	0.613	0.000
1E+12	22	0.613	0.613	0.000
1E+12	23	0.613	0.613	0.000
5E+12	24	0.613	0.612	-0.002
5E+12	25	0.613	0.611	-0.002
5E+12	26	0.613	0.612	-0.001
1E+13	27	0.613	0.610	-0.002
1E+13	28	0.613	0.611	-0.003
1E+13	29	0.613	0.610	-0.003
	Max	0.614	0.613	0.000
	Average	0.613	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.000	0.001	0.001

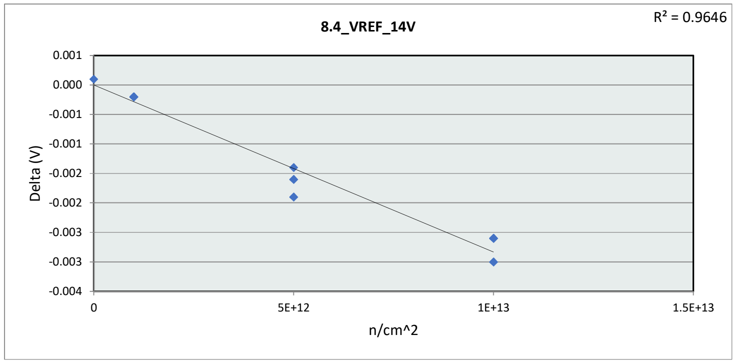


	8.3_VREF_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.613	0.611	0.610
Average	0.613	0.613	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

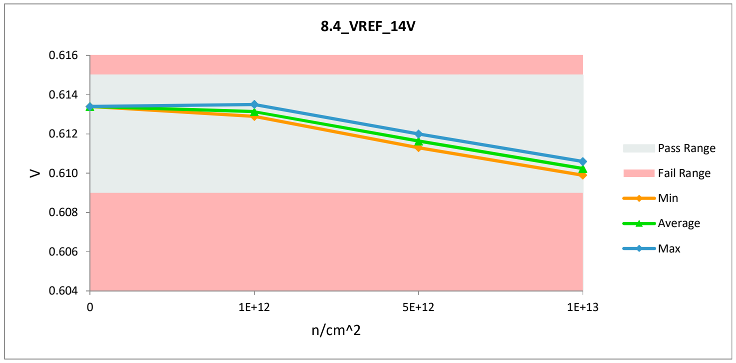


NDD Characterization Report
TPS7H5007-SEP

		8.4_VREF_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.615	0.615	
Min Limit		0.611	0.609	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.613	0.613	0.000
1E+12	21	0.614	0.613	0.000
1E+12	22	0.613	0.613	0.000
1E+12	23	0.613	0.613	0.000
5E+12	24	0.613	0.612	-0.002
5E+12	25	0.613	0.611	-0.002
5E+12	26	0.613	0.612	-0.001
1E+13	27	0.613	0.610	-0.003
1E+13	28	0.613	0.611	-0.003
1E+13	29	0.613	0.610	-0.003
	Max	0.614	0.613	0.000
	Average	0.613	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.000	0.001	0.001

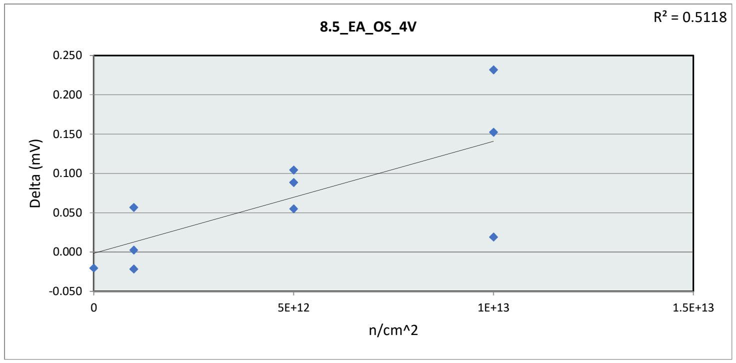


	8.4_VREF_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.613	0.611	0.610
Average	0.613	0.613	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

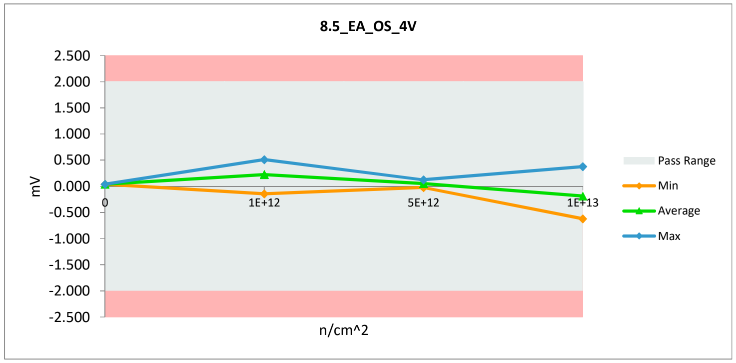


NDD Characterization Report
TPS7H5007-SEP

		8.5_EA_OS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mV	mV	
	Max Limit	1.9	2	
	Min Limit	-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.060	0.039	-0.021
1E+12	21	0.453	0.510	0.057
1E+12	22	-0.124	-0.145	-0.022
1E+12	23	0.308	0.311	0.003
5E+12	24	-0.077	-0.022	0.055
5E+12	25	-0.060	0.044	0.104
5E+12	26	0.035	0.123	0.088
1E+13	27	-0.773	-0.621	0.153
1E+13	28	0.145	0.377	0.232
1E+13	29	-0.336	-0.317	0.019
	Max	0.453	0.510	0.232
	Average	-0.037	0.030	0.067
	Min	-0.773	-0.621	-0.022
	Std Dev	0.341	0.336	0.081

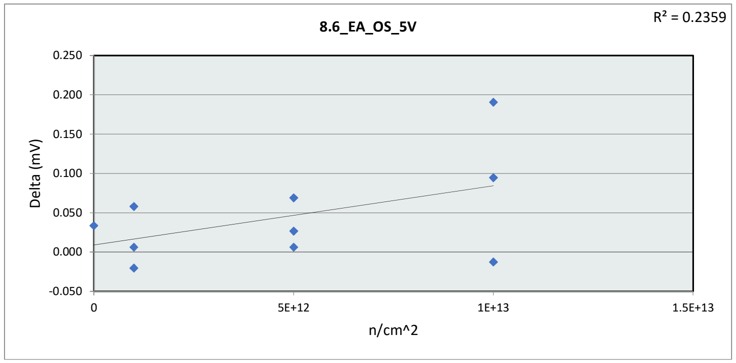


	8.5_EA_OS_4V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.039	-0.145	-0.022	-0.621
Average	0.039	0.225	0.048	-0.187
Max	0.039	0.510	0.123	0.377
UL	2.000	2.000	2.000	2.000

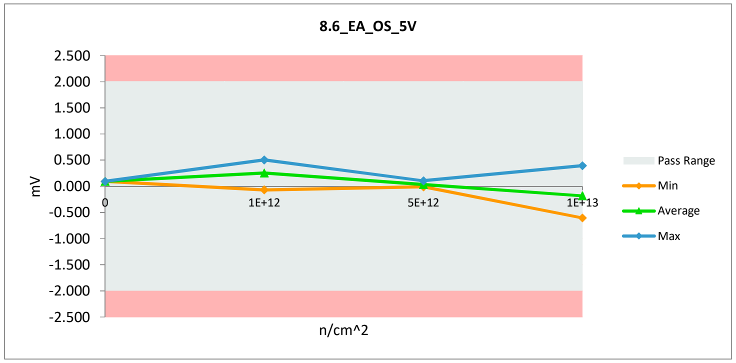


NDD Characterization Report
TPS7H5007-SEP

		8.6_EA_OS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mV	mV	
	Max Limit	1.9	2	
	Min Limit	-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.060	0.094	0.033
1E+12	21	0.524	0.504	-0.020
1E+12	22	-0.127	-0.069	0.058
1E+12	23	0.320	0.327	0.006
5E+12	24	-0.034	-0.007	0.027
5E+12	25	-0.001	0.006	0.006
5E+12	26	0.036	0.105	0.069
1E+13	27	-0.699	-0.604	0.095
1E+13	28	0.204	0.394	0.191
1E+13	29	-0.326	-0.338	-0.012
	Max	0.524	0.504	0.191
	Average	-0.004	0.041	0.045
	Min	-0.699	-0.604	-0.020
	Std Dev	0.339	0.334	0.063

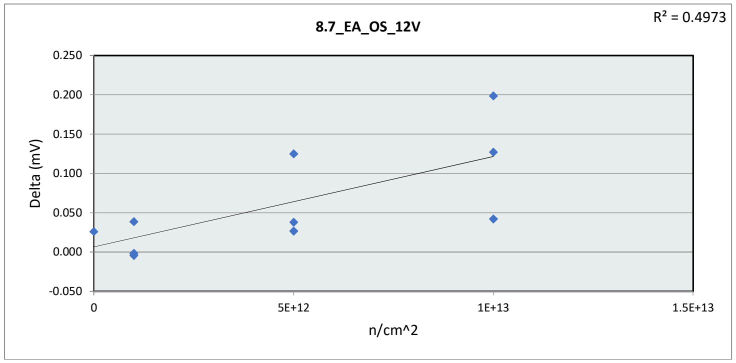


8.6_EA_OS_5V				
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.094	-0.069	-0.007	-0.605
Average	0.094	0.254	0.035	-0.183
Max	0.094	0.504	0.105	0.394
UL	2.000	2.000	2.000	2.000

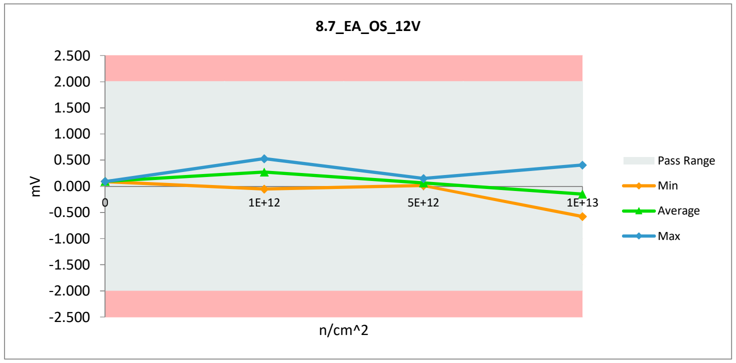


NDD Characterization Report
TPS7H5007-SEP

		8.7_EA_OS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mV	mV	
	Max Limit	1.9	2	
	Min Limit	-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.066	0.092	0.026
1E+12	21	0.533	0.529	-0.004
1E+12	22	-0.093	-0.055	0.039
1E+12	23	0.341	0.340	-0.001
5E+12	24	-0.026	0.012	0.038
5E+12	25	0.001	0.027	0.027
5E+12	26	0.025	0.150	0.125
1E+13	27	-0.703	-0.576	0.127
1E+13	28	0.208	0.407	0.199
1E+13	29	-0.323	-0.281	0.042
	Max	0.533	0.529	0.199
	Average	0.003	0.064	0.062
	Min	-0.703	-0.576	-0.004
	Std Dev	0.343	0.327	0.066

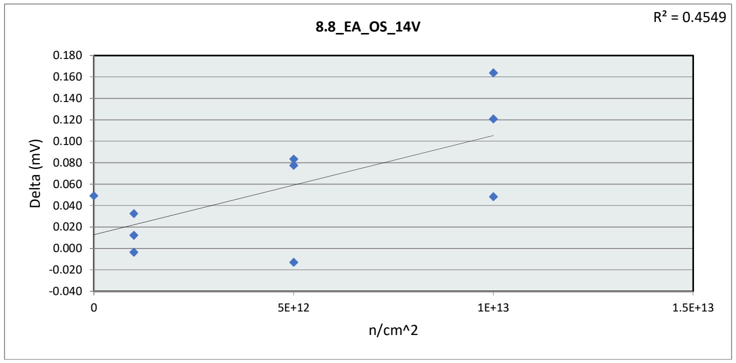


	8.7_EA_OS_12V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.092	-0.055	0.012	-0.576
Average	0.092	0.271	0.063	-0.150
Max	0.092	0.529	0.150	0.407
UL	2.000	2.000	2.000	2.000

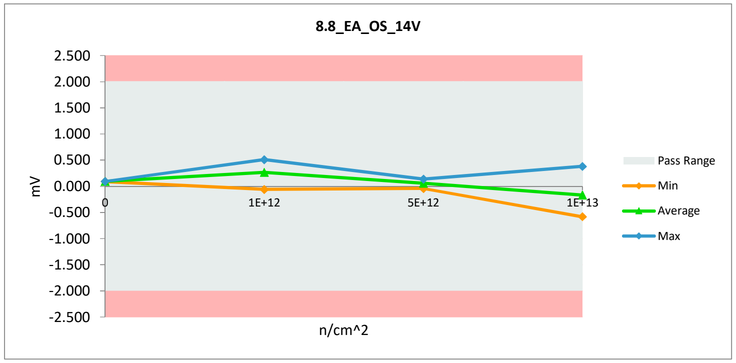


NDD Characterization Report
TPS7H5007-SEP

		8.8_EA_OS_14V		
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		1.9	2	
Min Limit		-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.043	0.092	0.049
1E+12	21	0.513	0.509	-0.003
1E+12	22	-0.092	-0.060	0.033
1E+12	23	0.341	0.353	0.012
5E+12	24	-0.028	-0.041	-0.013
5E+12	25	-0.002	0.082	0.083
5E+12	26	0.060	0.138	0.078
1E+13	27	-0.703	-0.582	0.121
1E+13	28	0.215	0.379	0.164
1E+13	29	-0.341	-0.293	0.048
	Max	0.513	0.509	0.164
	Average	0.001	0.058	0.057
	Min	-0.703	-0.582	-0.013
	Std Dev	0.342	0.326	0.056

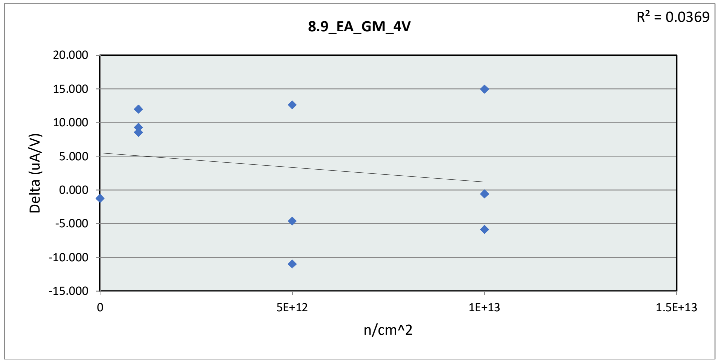


	8.8_EA_OS_14V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.092	-0.060	-0.041	-0.582
Average	0.092	0.268	0.059	-0.165
Max	0.092	0.509	0.138	0.379
UL	2.000	2.000	2.000	2.000

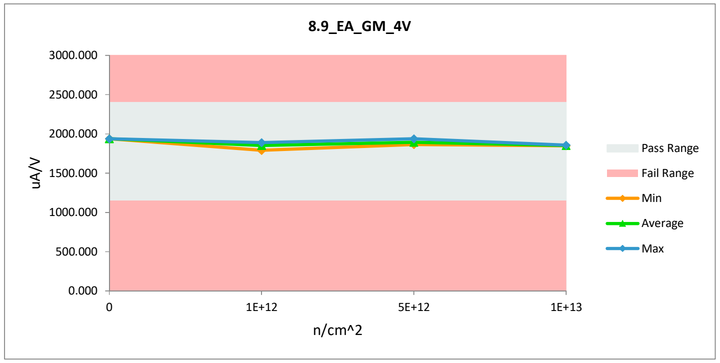


NDD Characterization Report
TPS7H5007-SEP

		8.9_EA_GM_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA/V	uA/V	
	Max Limit	2350	2400	
	Min Limit	1200	1150	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1938.856	1937.614	-1.242
1E+12	21	1873.346	1881.909	8.563
1E+12	22	1875.912	1887.934	12.022
1E+12	23	1780.529	1789.837	9.308
5E+12	24	1924.964	1937.614	12.650
5E+12	25	1868.641	1864.042	-4.599
5E+12	26	1892.897	1881.909	-10.988
1E+13	27	1833.866	1848.831	14.965
1E+13	28	1858.158	1852.311	-5.847
1E+13	29	1858.745	1858.158	-0.587
	Max	1938.856	1937.614	14.965
	Average	1870.591	1874.016	3.425
	Min	1780.529	1789.837	-10.988
	Std Dev	44.608	43.398	9.124

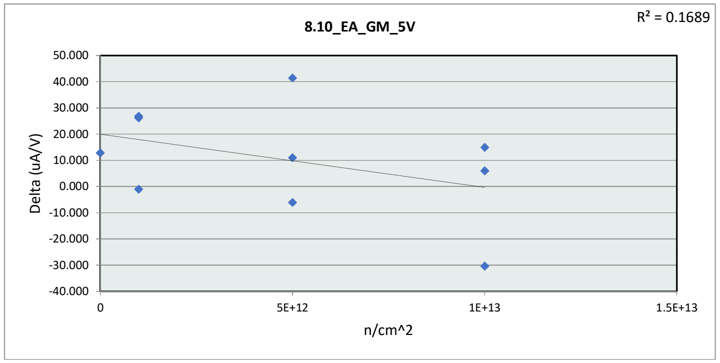


	8.9_EA_GM_4V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1937.614	1789.837	1864.042	1848.831
Average	1937.614	1853.227	1894.522	1853.100
Max	1937.614	1887.934	1937.614	1858.158
UL	2400.000	2400.000	2400.000	2400.000

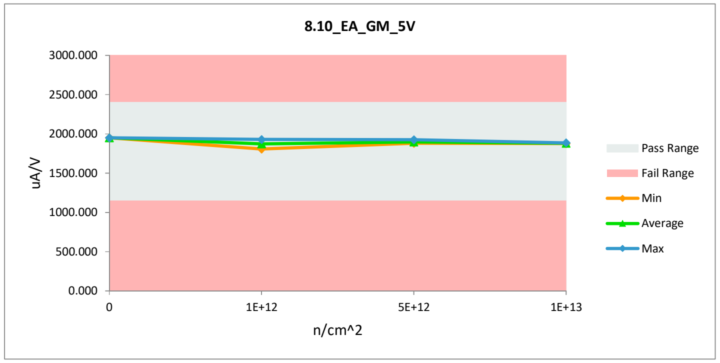


NDD Characterization Report
TPS7H5007-SEP

		8.10_EA_GM_5V		
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2350	2400	
Min Limit		1200	1150	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1937.625	1950.454	12.829
1E+12	21	1862.263	1888.539	26.276
1E+12	22	1900.670	1927.485	26.815
1E+12	23	1809.635	1808.630	-1.005
5E+12	24	1915.207	1926.213	11.006
5E+12	25	1846.511	1887.934	41.423
5E+12	26	1887.934	1881.898	-6.036
1E+13	27	1875.912	1881.909	5.997
1E+13	28	1870.557	1885.504	14.947
1E+13	29	1906.274	1875.912	-30.362
	Max	1937.625	1950.454	41.423
	Average	1881.259	1891.448	10.189
	Min	1809.635	1808.630	-30.362
	Std Dev	36.845	38.482	19.977

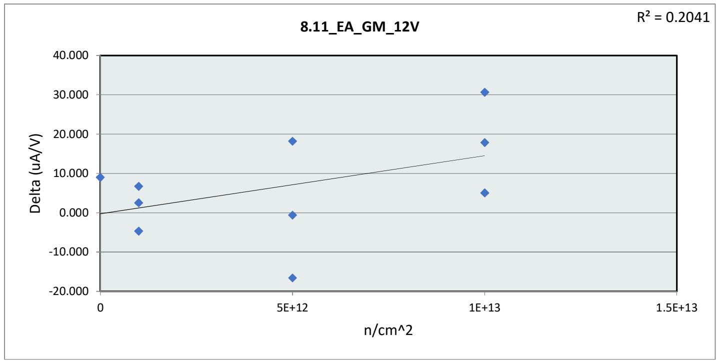


	8.10_EA_GM_5V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1950.454	1808.630	1881.898	1875.912
Average	1950.454	1874.885	1898.682	1881.108
Max	1950.454	1927.485	1926.213	1885.504
UL	2400.000	2400.000	2400.000	2400.000

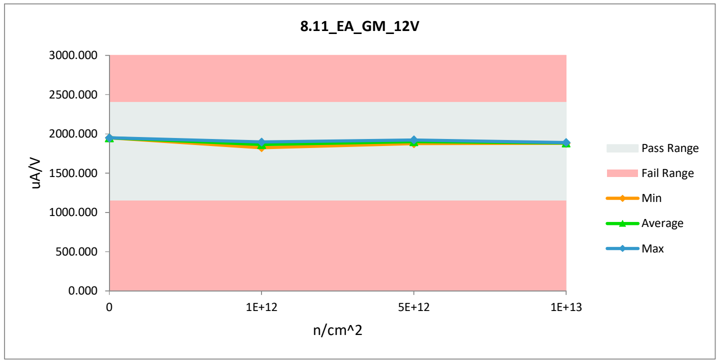


NDD Characterization Report
TPS7H5007-SEP

		8.11_EA_GM_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA/V	uA/V	
	Max Limit	2350	2400	
	Min Limit	1200	1150	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1941.459	1950.454	8.995
1E+12	21	1867.413	1874.130	6.717
1E+12	22	1902.168	1897.499	-4.669
1E+12	23	1822.244	1824.771	2.527
5E+12	24	1924.953	1924.368	-0.585
5E+12	25	1892.491	1875.912	-16.579
5E+12	26	1881.909	1900.121	18.212
1E+13	27	1864.042	1881.898	17.856
1E+13	28	1858.158	1888.816	30.658
1E+13	29	1885.917	1890.966	5.049
	Max	1941.459	1950.454	30.658
	Average	1884.075	1890.893	6.818
	Min	1822.244	1824.771	-16.579
	Std Dev	34.228	32.930	13.252



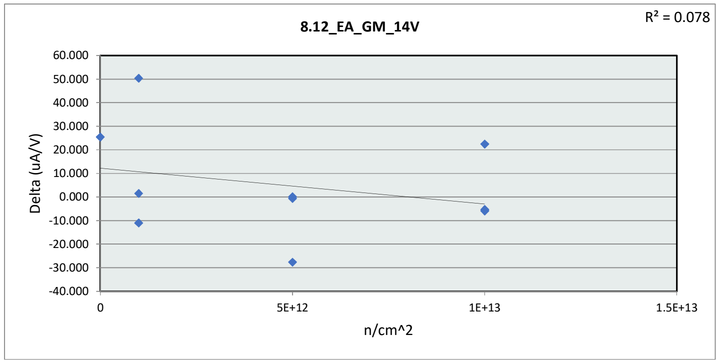
8.11_EA_GM_12V				
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1950.454	1824.771	1875.912	1881.898
Average	1950.454	1865.467	1900.134	1887.227
Max	1950.454	1897.499	1924.368	1890.966
UL	2400.000	2400.000	2400.000	2400.000



NDD Characterization Report
TPS7H5007-SEP

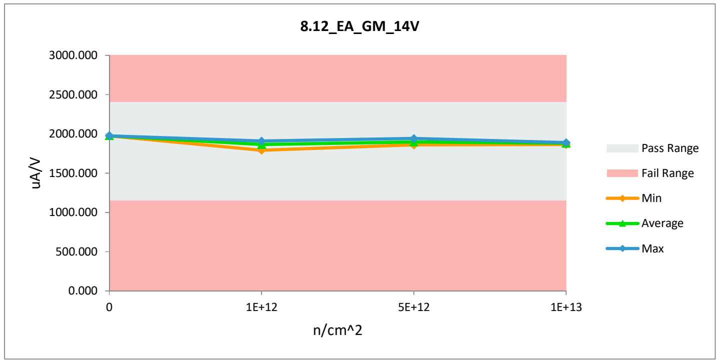
	8.12_EA_GM_14V	
Test Site		
Tester		
Test Number		
Unit	uA/V	uA/V
Max Limit	2350	2400
Min Limit	1200	1150

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1951.202	1976.627	25.425
1E+12	21	1858.158	1908.519	50.361
1E+12	22	1894.008	1895.527	1.519
1E+12	23	1804.099	1793.108	-10.991
5E+12	24	1940.179	1940.348	0.169
5E+12	25	1891.318	1890.753	-0.565
5E+12	26	1887.944	1860.291	-27.653
1E+13	27	1869.963	1864.042	-5.921
1E+13	28	1865.514	1887.934	22.420
1E+13	29	1894.896	1889.592	-5.304
	Max	1951.202	1976.627	50.361
	Average	1885.728	1890.674	4.946
	Min	1804.099	1793.108	-27.653
	Std Dev	41.528	48.714	22.091



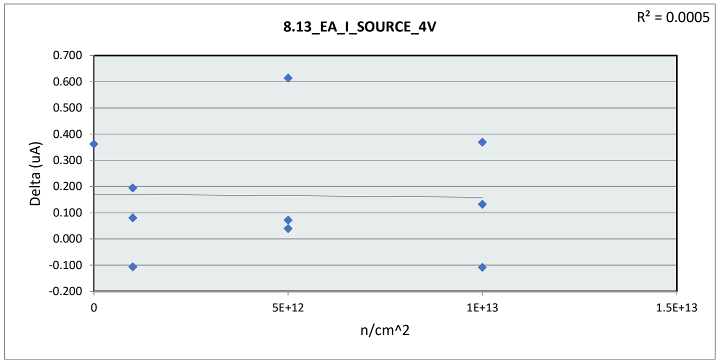
	8.12_EA_GM_14V	
Test Site		
Tester		
Test Number		
Max Limit	2400	uA/V
Min Limit	1150	uA/V

n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1976.627	1793.108	1860.291	1864.042
Average	1976.627	1865.718	1897.131	1880.523
Max	1976.627	1908.519	1940.348	1889.592
UL	2400.000	2400.000	2400.000	2400.000

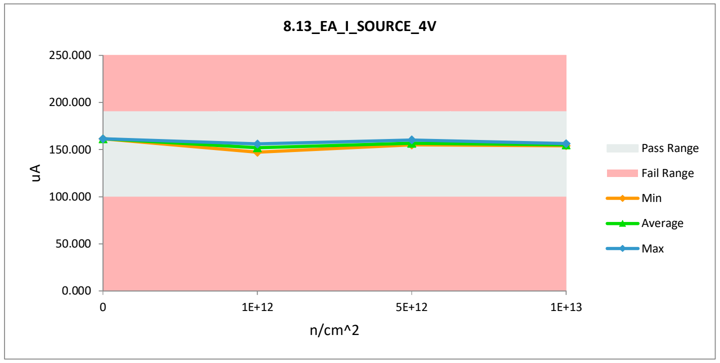


NDD Characterization Report
TPS7H5007-SEP

		8.13_EA_I_SOURCE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	161.132	161.494	0.362
1E+12	21	152.748	152.943	0.195
1E+12	22	156.171	156.065	-0.106
1E+12	23	147.184	147.265	0.081
5E+12	24	160.205	160.245	0.040
5E+12	25	154.263	154.877	0.614
5E+12	26	155.526	155.598	0.072
1E+13	27	154.974	155.107	0.133
1E+13	28	153.748	154.117	0.369
1E+13	29	156.494	156.386	-0.108
	Max	161.132	161.494	0.614
	Average	155.245	155.410	0.165
	Min	147.184	147.265	-0.108
	Std Dev	3.891	3.891	0.227

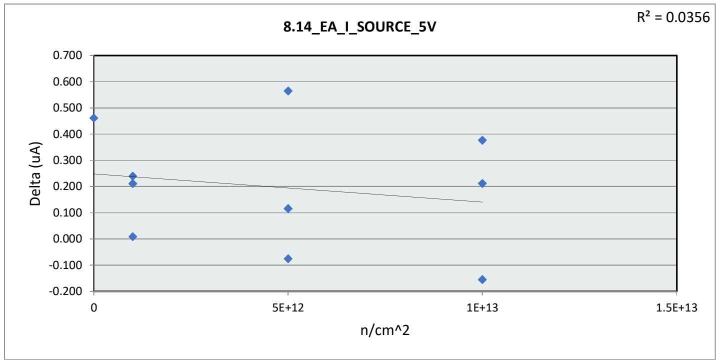


	8.13_EA_I_SOURCE_4V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	161.494	147.265	154.877	154.117
Average	161.494	152.091	156.907	155.203
Max	161.494	156.065	160.245	156.386
UL	190.000	190.000	190.000	190.000

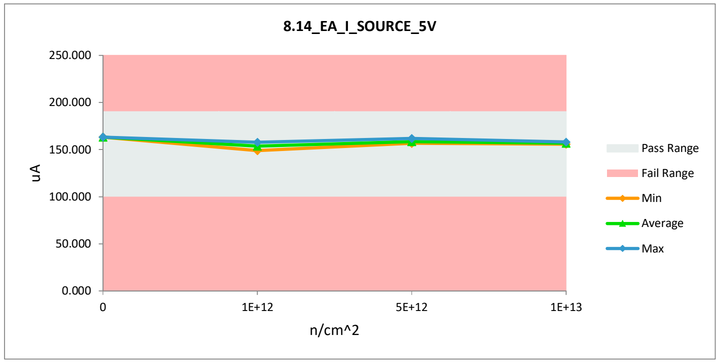


NDD Characterization Report
TPS7H5007-SEP

		8.14_EA_I_SOURCE_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	162.829	163.291	0.462
1E+12	21	154.243	154.483	0.240
1E+12	22	157.812	157.821	0.009
1E+12	23	148.689	148.900	0.211
5E+12	24	161.756	161.872	0.116
5E+12	25	155.987	156.552	0.565
5E+12	26	157.070	156.995	-0.075
1E+13	27	156.528	156.740	0.212
1E+13	28	155.505	155.882	0.377
1E+13	29	158.117	157.962	-0.155
	Max	162.829	163.291	0.565
	Average	156.854	157.050	0.196
	Min	148.689	148.900	-0.155
	Std Dev	3.922	3.921	0.231

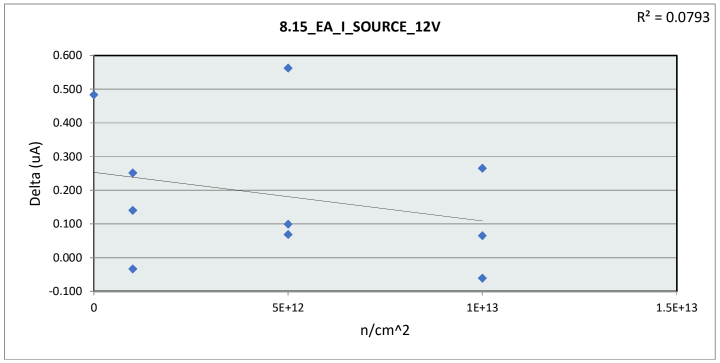


	8.14_EA_I_SOURCE_5V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	163.291	148.900	156.552	155.882
Average	163.291	153.735	158.473	156.861
Max	163.291	157.821	161.872	157.962
UL	190.000	190.000	190.000	190.000

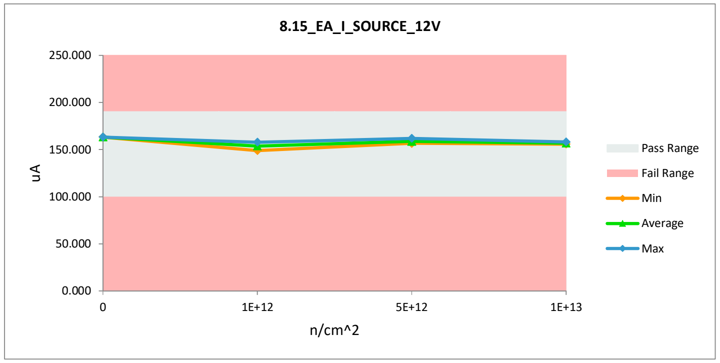


NDD Characterization Report
TPS7H5007-SEP

		8.15_EA_I_SOURCE_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	162.821	163.304	0.483
1E+12	21	154.293	154.544	0.251
1E+12	22	157.821	157.787	-0.034
1E+12	23	148.768	148.908	0.140
5E+12	24	161.935	162.003	0.068
5E+12	25	156.023	156.585	0.562
5E+12	26	157.033	157.132	0.099
1E+13	27	156.633	156.698	0.065
1E+13	28	155.554	155.819	0.265
1E+13	29	158.121	158.060	-0.061
	Max	162.821	163.304	0.562
	Average	156.900	157.084	0.184
	Min	148.768	148.908	-0.061
	Std Dev	3.921	3.939	0.208

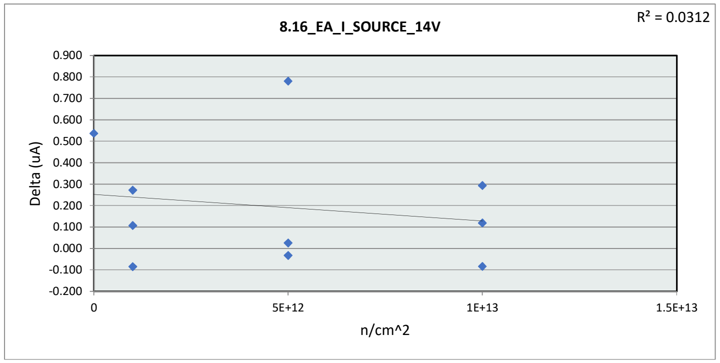


	8.15_EA_I_SOURCE_12V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	163.304	148.908	156.585	155.819
Average	163.304	153.746	158.573	156.859
Max	163.304	157.787	162.003	158.060
UL	190.000	190.000	190.000	190.000

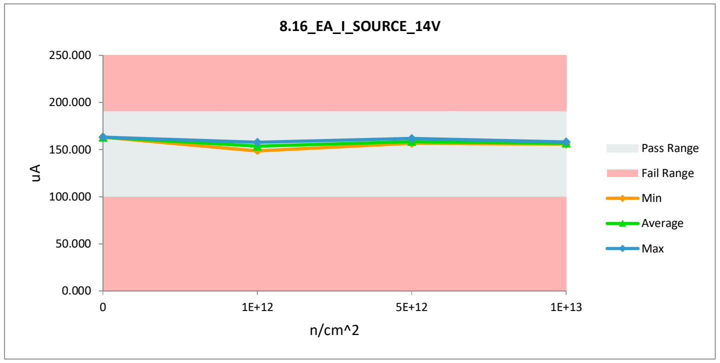


NDD Characterization Report
TPS7H5007-SEP

		8.16_EA_I_SOURCE_14V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	162.677	163.213	0.536
1E+12	21	154.190	154.461	0.271
1E+12	22	157.699	157.614	-0.085
1E+12	23	148.661	148.767	0.106
5E+12	24	161.731	161.698	-0.033
5E+12	25	155.894	156.674	0.780
5E+12	26	156.924	156.949	0.025
1E+13	27	156.514	156.632	0.118
1E+13	28	155.388	155.681	0.293
1E+13	29	158.023	157.939	-0.084
	Max	162.677	163.213	0.780
	Average	156.770	156.963	0.193
	Min	148.661	148.767	-0.085
	Std Dev	3.903	3.918	0.284

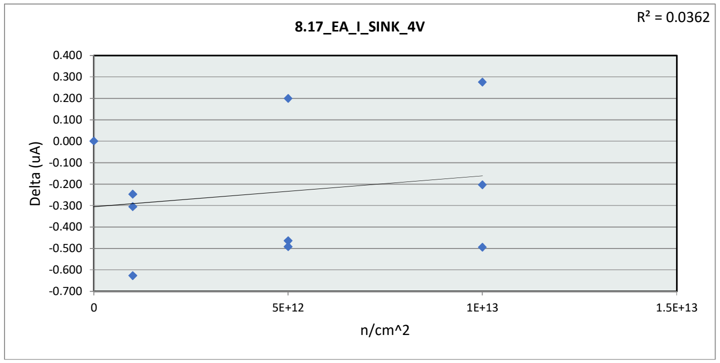


	8.16_EA_I_SOURCE_14V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	163.213	148.767	156.674	155.681
Average	163.213	153.614	158.440	156.751
Max	163.213	157.614	161.698	157.939
UL	190.000	190.000	190.000	190.000

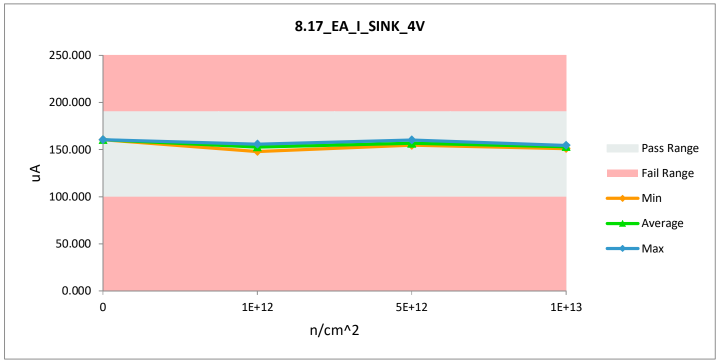


NDD Characterization Report
TPS7H5007-SEP

		8.17_EA_I_SINK_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	160.509	160.509	0.000
1E+12	21	154.658	154.352	-0.306
1E+12	22	156.514	155.887	-0.627
1E+12	23	148.300	148.052	-0.248
5E+12	24	160.439	159.975	-0.464
5E+12	25	154.284	154.483	0.199
5E+12	26	155.912	155.420	-0.492
1E+13	27	151.398	151.194	-0.204
1E+13	28	154.262	154.537	0.275
1E+13	29	154.344	153.849	-0.495
	Max	160.509	160.509	0.275
	Average	155.062	154.826	-0.236
	Min	148.300	148.052	-0.627
	Std Dev	3.689	3.663	0.307

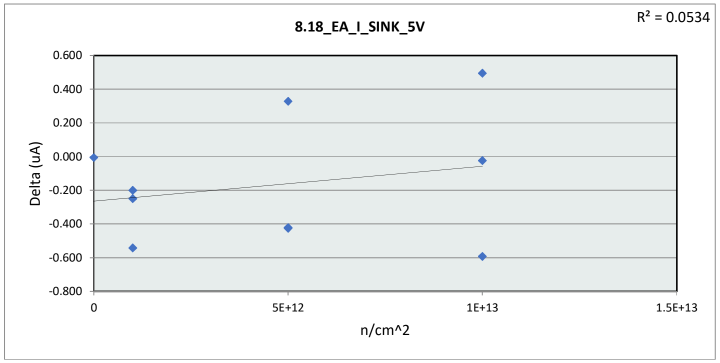


	8.17_EA_I_SINK_4V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	160.509	148.052	154.483	151.194
Average	160.509	152.764	156.626	153.193
Max	160.509	155.887	159.975	154.537
UL	190.000	190.000	190.000	190.000

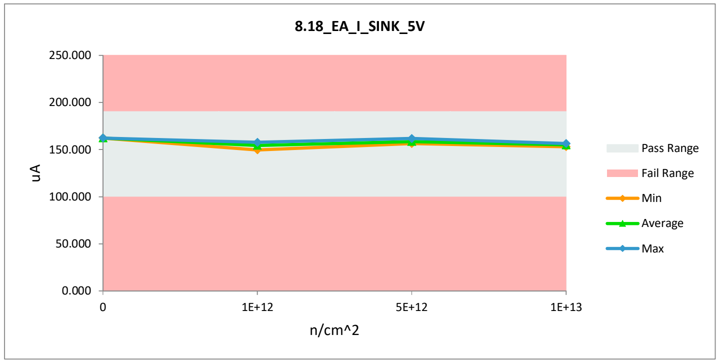


NDD Characterization Report
TPS7H5007-SEP

		8.18_EA_I_SINK_5V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	162.343	162.336	-0.007
1E+12	21	156.221	156.020	-0.201
1E+12	22	158.224	157.680	-0.544
1E+12	23	149.914	149.663	-0.251
5E+12	24	162.182	161.759	-0.423
5E+12	25	156.047	156.374	0.327
5E+12	26	157.582	157.156	-0.426
1E+13	27	152.993	152.968	-0.025
1E+13	28	155.948	156.442	0.494
1E+13	29	156.154	155.560	-0.594
	Max	162.343	162.336	0.494
	Average	156.761	156.596	-0.165
	Min	149.914	149.663	-0.594
	Std Dev	3.746	3.709	0.364

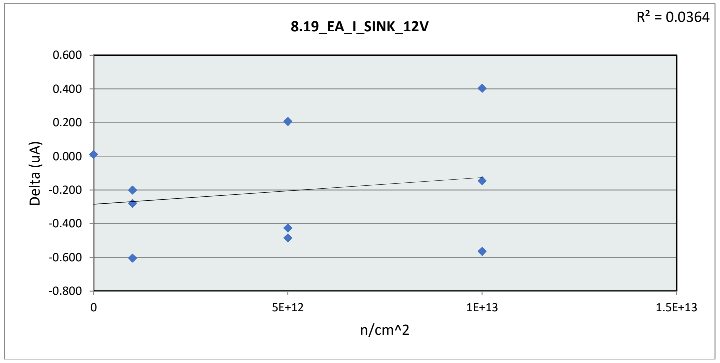


	8.18_EA_I_SINK_5V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	162.336	149.663	156.374	152.968
Average	162.336	154.454	158.430	154.990
Max	162.336	157.680	161.759	156.442
UL	190.000	190.000	190.000	190.000

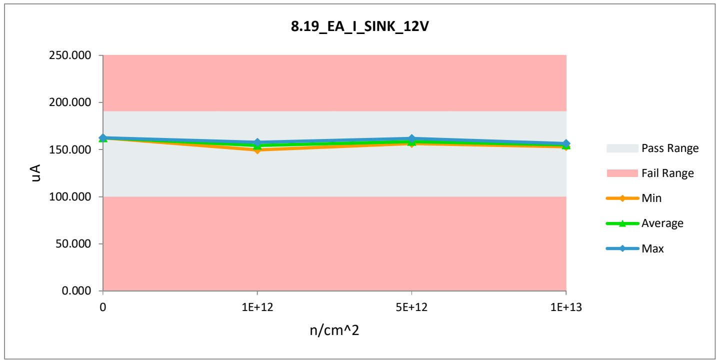


NDD Characterization Report
TPS7H5007-SEP

		8.19_EA_I_SINK_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	162.395	162.406	0.011
1E+12	21	156.331	156.130	-0.201
1E+12	22	158.317	157.712	-0.605
1E+12	23	149.969	149.689	-0.280
5E+12	24	162.229	161.744	-0.485
5E+12	25	156.102	156.308	0.206
5E+12	26	157.581	157.155	-0.426
1E+13	27	153.056	152.910	-0.146
1E+13	28	156.076	156.479	0.403
1E+13	29	156.191	155.626	-0.565
	Max	162.395	162.406	0.403
	Average	156.825	156.616	-0.209
	Min	149.969	149.689	-0.605
	Std Dev	3.741	3.717	0.335

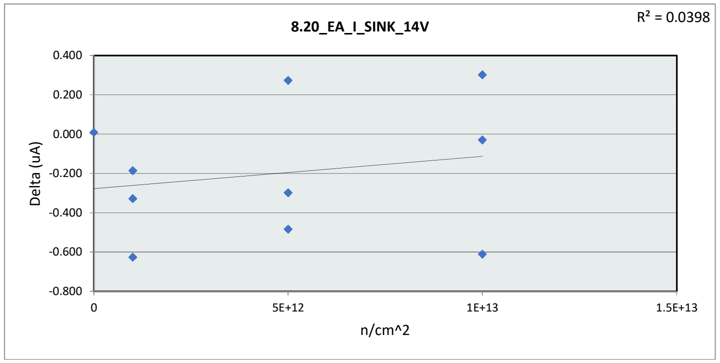


	8.19_EA_I_SINK_12V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	162.406	149.689	156.308	152.910
Average	162.406	154.510	158.402	155.005
Max	162.406	157.712	161.744	156.479
UL	190.000	190.000	190.000	190.000

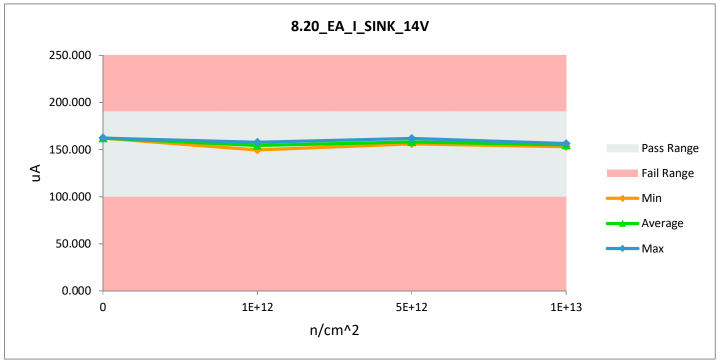


NDD Characterization Report
TPS7H5007-SEP

		8.20_EA_I_SINK_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	162.264	162.272	0.008
1E+12	21	156.193	156.007	-0.186
1E+12	22	158.227	157.600	-0.627
1E+12	23	149.920	149.591	-0.329
5E+12	24	162.098	161.614	-0.484
5E+12	25	155.939	156.212	0.273
5E+12	26	157.335	157.036	-0.299
1E+13	27	152.931	152.901	-0.030
1E+13	28	155.962	156.263	0.301
1E+13	29	156.082	155.471	-0.611
	Max	162.264	162.272	0.301
	Average	156.695	156.497	-0.198
	Min	149.920	149.591	-0.627
	Std Dev	3.723	3.698	0.334

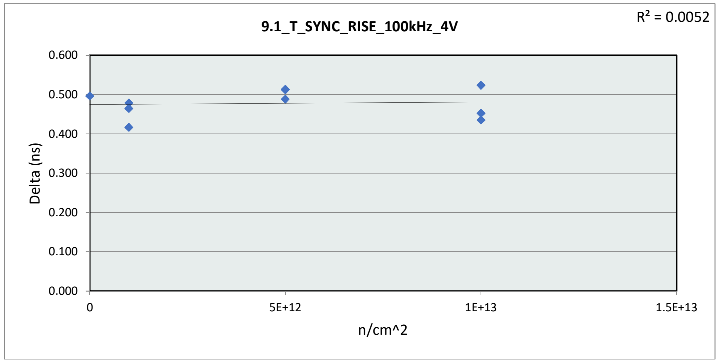


	8.20_EA_I_SINK_14V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	162.272	149.591	156.212	152.901
Average	162.272	154.399	158.287	154.878
Max	162.272	157.600	161.614	156.263
UL	190.000	190.000	190.000	190.000

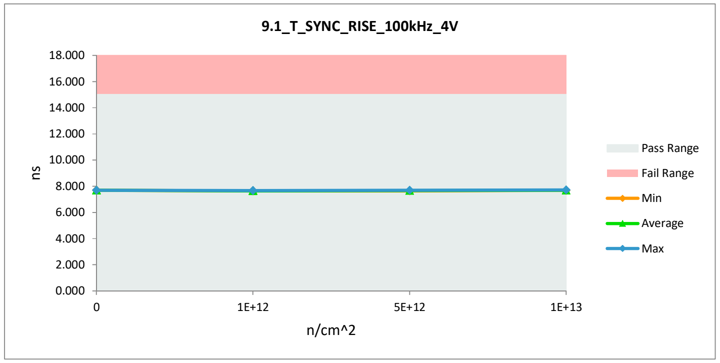


NDD Characterization Report
TPS7H5007-SEP

		9.1_T_SYNC_RISE_100kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14.5	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.196	7.692	0.496
1E+12	21	7.222	7.638	0.416
1E+12	22	7.183	7.661	0.478
1E+12	23	7.198	7.662	0.464
5E+12	24	7.122	7.634	0.512
5E+12	25	7.159	7.672	0.513
5E+12	26	7.201	7.689	0.488
1E+13	27	7.262	7.714	0.452
1E+13	28	7.160	7.683	0.523
1E+13	29	7.239	7.674	0.435
	Max	7.262	7.714	0.523
	Average	7.194	7.672	0.478
	Min	7.122	7.634	0.416
	Std Dev	0.041	0.024	0.036

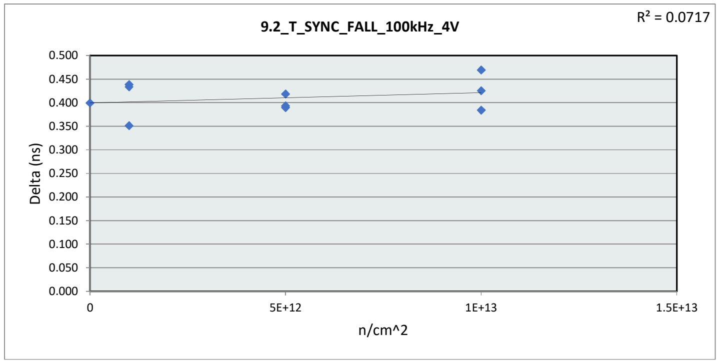


	9.1_T_SYNC_RISE_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.692	7.638	7.634	7.674
Average	7.692	7.654	7.665	7.690
Max	7.692	7.662	7.689	7.714
UL	15.000	15.000	15.000	15.000

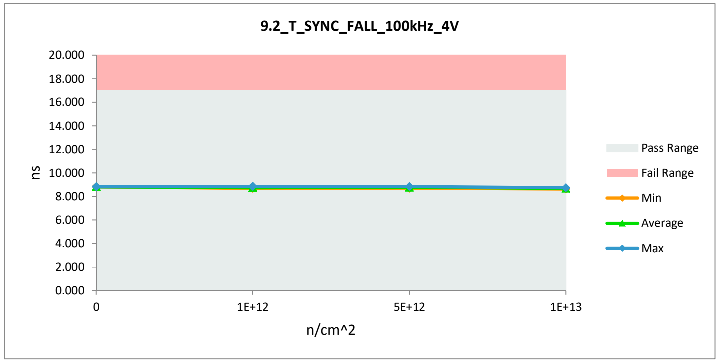


NDD Characterization Report
TPS7H5007-SEP

		9.2_T_SYNC_FALL_100kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14.5	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.423	8.822	0.399
1E+12	21	8.267	8.700	0.433
1E+12	22	8.336	8.687	0.351
1E+12	23	8.417	8.855	0.438
5E+12	24	8.307	8.696	0.389
5E+12	25	8.448	8.841	0.393
5E+12	26	8.396	8.814	0.418
1E+13	27	8.200	8.669	0.469
1E+13	28	8.299	8.724	0.425
1E+13	29	8.241	8.625	0.384
	Max	8.448	8.855	0.469
	Average	8.333	8.743	0.410
	Min	8.200	8.625	0.351
	Std Dev	0.085	0.082	0.033

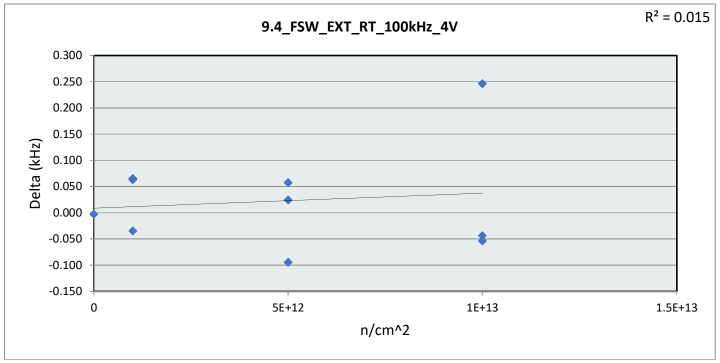


	9.2_T_SYNC_FALL_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.822	8.687	8.696	8.625
Average	8.822	8.747	8.784	8.673
Max	8.822	8.855	8.841	8.724
UL	17.000	17.000	17.000	17.000

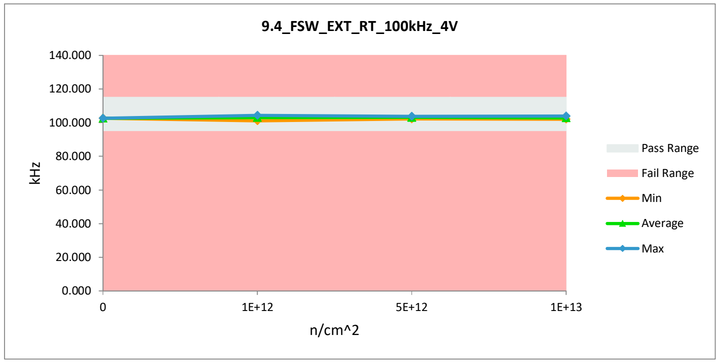


NDD Characterization Report
TPS7H5007-SEP

		9.4_FSW_EXT_RT_100kHz_4V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	102.671	102.668	-0.003
1E+12	21	104.405	104.370	-0.035
1E+12	22	103.656	103.719	0.063
1E+12	23	101.073	101.138	0.065
5E+12	24	103.343	103.248	-0.095
5E+12	25	103.746	103.770	0.024
5E+12	26	102.108	102.165	0.057
1E+13	27	102.162	102.118	-0.044
1E+13	28	102.497	102.743	0.246
1E+13	29	103.945	103.891	-0.054
	Max	104.405	104.370	0.246
	Average	102.961	102.983	0.022
	Min	101.073	101.138	-0.095
	Std Dev	1.029	0.998	0.096

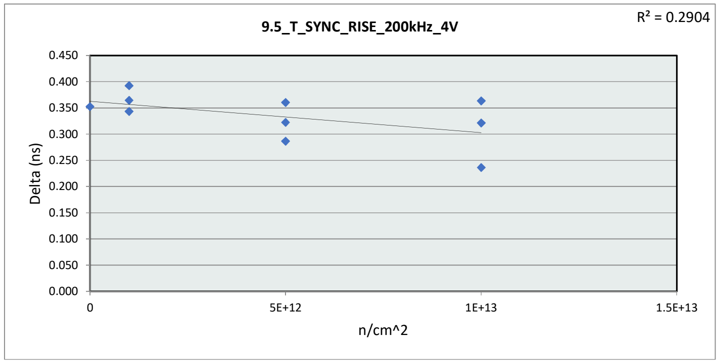


	9.4_FSW_EXT_RT_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	102.668	101.138	102.165	102.118
Average	102.668	103.076	103.061	102.917
Max	102.668	104.370	103.770	103.891
UL	115.000	115.000	115.000	115.000

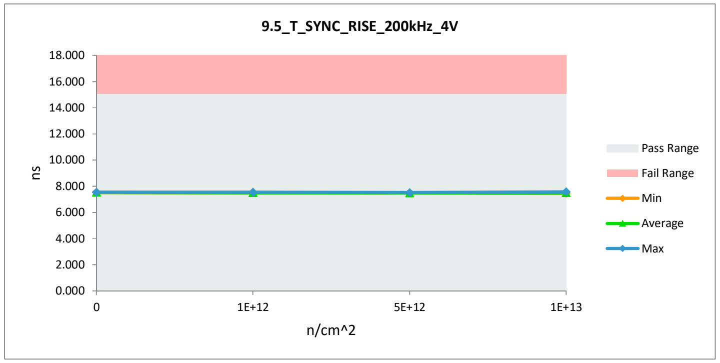


NDD Characterization Report
TPS7H5007-SEP

		9.5_T_SYNC_RISE_200kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14.5	15	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.180	7.532	0.352
1E+12	21	7.142	7.506	0.364
1E+12	22	7.159	7.502	0.343
1E+12	23	7.135	7.527	0.392
5E+12	24	7.146	7.468	0.322
5E+12	25	7.119	7.479	0.360
5E+12	26	7.223	7.509	0.286
1E+13	27	7.242	7.563	0.321
1E+13	28	7.215	7.451	0.236
1E+13	29	7.124	7.487	0.363
	Max	7.242	7.563	0.392
	Average	7.169	7.502	0.334
	Min	7.119	7.451	0.236
	Std Dev	0.044	0.033	0.045

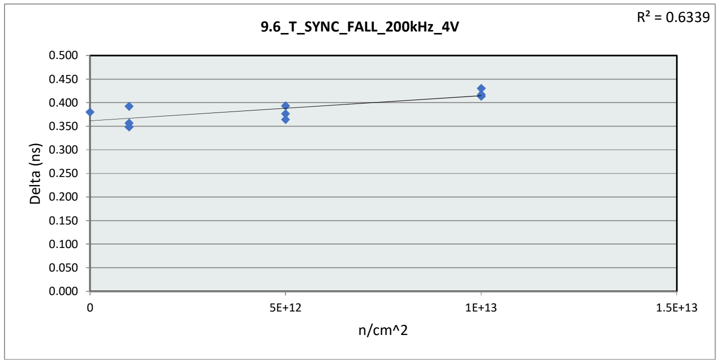


9.5_T_SYNC_RISE_200kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.532	7.502	7.468	7.451
Average	7.532	7.512	7.485	7.500
Max	7.532	7.527	7.509	7.563
UL	15.000	15.000	15.000	15.000

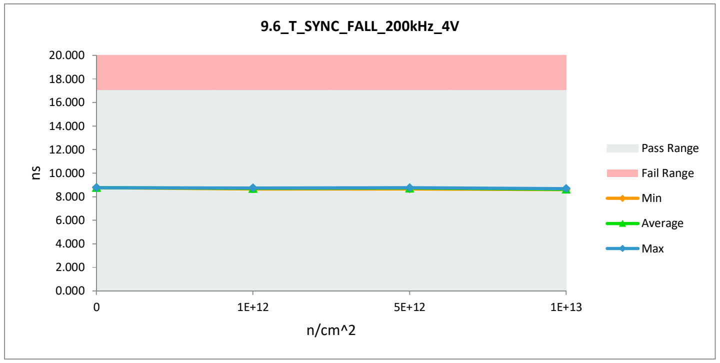


NDD Characterization Report
TPS7H5007-SEP

		9.6_T_SYNC_FALL_200kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.396	8.776	0.380
1E+12	21	8.293	8.685	0.392
1E+12	22	8.312	8.660	0.348
1E+12	23	8.387	8.743	0.356
5E+12	24	8.263	8.656	0.393
5E+12	25	8.401	8.765	0.364
5E+12	26	8.377	8.753	0.376
1E+13	27	8.194	8.607	0.413
1E+13	28	8.260	8.690	0.430
1E+13	29	8.199	8.616	0.417
	Max	8.401	8.776	0.430
	Average	8.308	8.695	0.387
	Min	8.194	8.607	0.348
	Std Dev	0.079	0.061	0.027

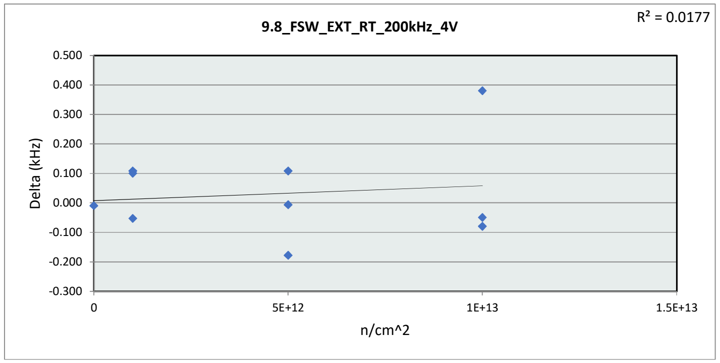


	9.6_T_SYNC_FALL_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.776	8.660	8.656	8.607
Average	8.776	8.696	8.725	8.638
Max	8.776	8.743	8.765	8.690
UL	17.000	17.000	17.000	17.000

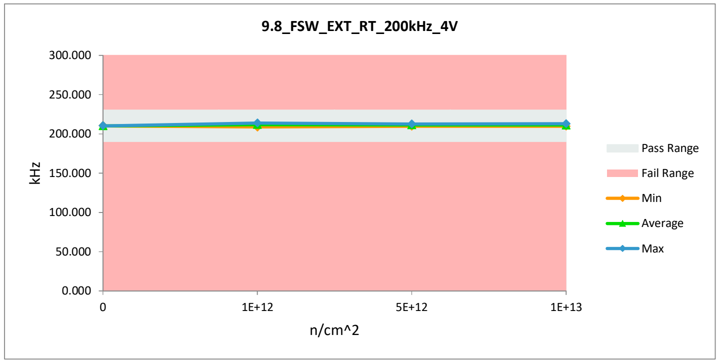


NDD Characterization Report
TPS7H5007-SEP

		9.8_FSW_EXT_RT_200kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	230	230	
	Min Limit	190	190	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	210.328	210.318	-0.010
1E+12	21	213.826	213.773	-0.053
1E+12	22	212.784	212.892	0.108
1E+12	23	208.676	208.776	0.100
5E+12	24	212.172	211.994	-0.178
5E+12	25	212.570	212.563	-0.007
5E+12	26	209.650	209.758	0.108
1E+13	27	209.841	209.791	-0.050
1E+13	28	210.403	210.783	0.380
1E+13	29	212.960	212.880	-0.080
	Max	213.826	213.773	0.380
	Average	211.321	211.353	0.032
	Min	208.676	208.776	-0.178
	Std Dev	1.738	1.682	0.153

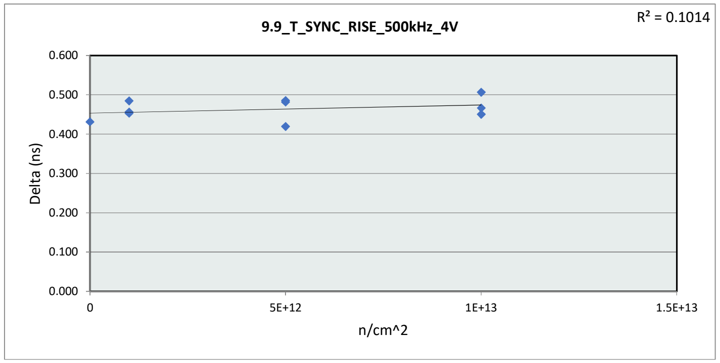


	9.8_FSW_EXT_RT_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	210.318	208.776	209.758	209.791
Average	210.318	211.814	211.438	211.151
Max	210.318	213.773	212.563	212.880
UL	230.000	230.000	230.000	230.000

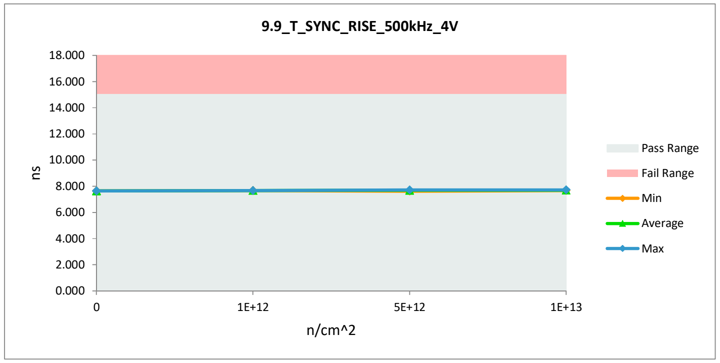


NDD Characterization Report
TPS7H5007-SEP

		9.9_T_SYNC_RISE_500kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14.5	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.206	7.637	0.431
1E+12	21	7.205	7.661	0.456
1E+12	22	7.212	7.665	0.453
1E+12	23	7.177	7.661	0.484
5E+12	24	7.208	7.627	0.419
5E+12	25	7.207	7.692	0.485
5E+12	26	7.232	7.713	0.481
1E+13	27	7.209	7.675	0.466
1E+13	28	7.216	7.722	0.506
1E+13	29	7.234	7.684	0.450
	Max	7.234	7.722	0.506
	Average	7.211	7.674	0.463
	Min	7.177	7.627	0.419
	Std Dev	0.016	0.030	0.027

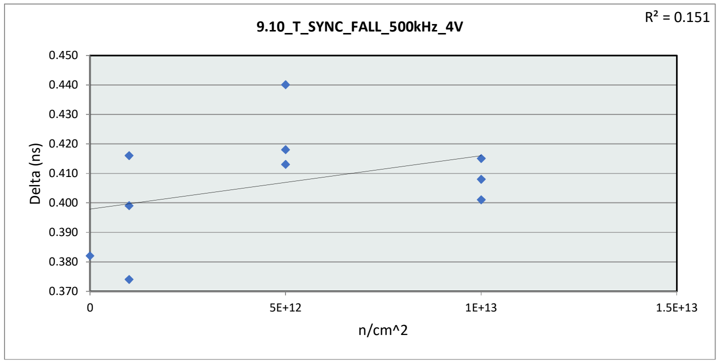


	9.9_T_SYNC_RISE_500kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.637	7.661	7.627	7.675
Average	7.637	7.662	7.677	7.694
Max	7.637	7.665	7.713	7.722
UL	15.000	15.000	15.000	15.000

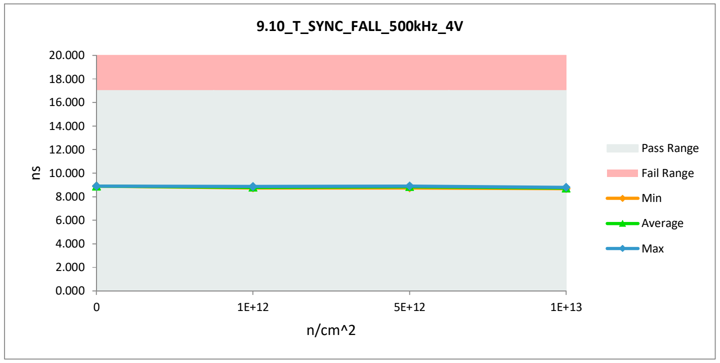


NDD Characterization Report
TPS7H5007-SEP

		9.10_T_SYNC_FALL_500kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.517	8.899	0.382
1E+12	21	8.329	8.745	0.416
1E+12	22	8.400	8.774	0.374
1E+12	23	8.468	8.867	0.399
5E+12	24	8.322	8.735	0.413
5E+12	25	8.487	8.905	0.418
5E+12	26	8.445	8.885	0.440
1E+13	27	8.278	8.679	0.401
1E+13	28	8.386	8.801	0.415
1E+13	29	8.299	8.707	0.408
	Max	8.517	8.905	0.440
	Average	8.393	8.800	0.407
	Min	8.278	8.679	0.374
	Std Dev	0.084	0.084	0.019

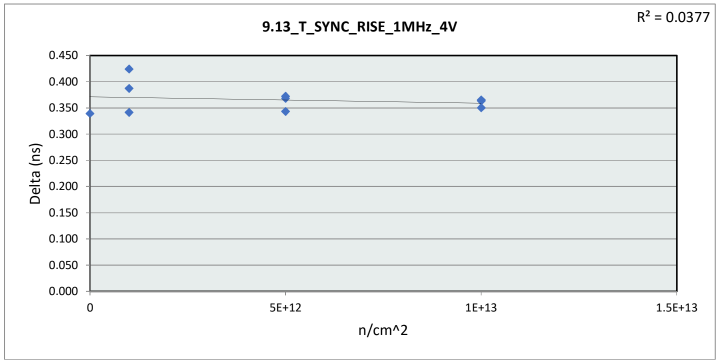


	9.10_T_SYNC_FALL_500kHz_4			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.899	8.745	8.735	8.679
Average	8.899	8.795	8.842	8.729
Max	8.899	8.867	8.905	8.801
UL	17.000	17.000	17.000	17.000

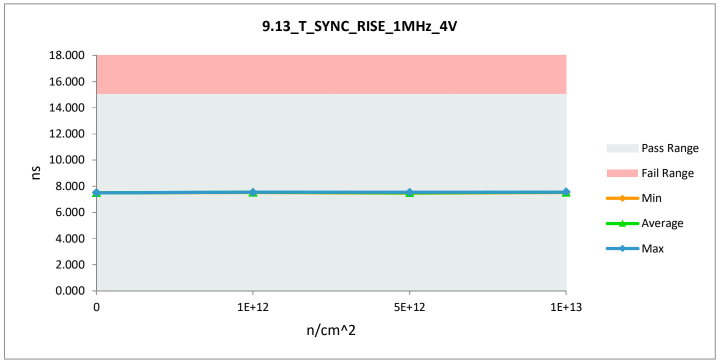


NDD Characterization Report
TPS7H5007-SEP

		9.13_T_SYNC_RISE_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14.5	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.163	7.502	0.339
1E+12	21	7.192	7.533	0.341
1E+12	22	7.115	7.539	0.424
1E+12	23	7.131	7.518	0.387
5E+12	24	7.133	7.476	0.343
5E+12	25	7.151	7.519	0.368
5E+12	26	7.162	7.534	0.372
1E+13	27	7.192	7.557	0.365
1E+13	28	7.151	7.514	0.363
1E+13	29	7.184	7.534	0.350
	Max	7.192	7.557	0.424
	Average	7.157	7.523	0.365
	Min	7.115	7.476	0.339
	Std Dev	0.027	0.022	0.026

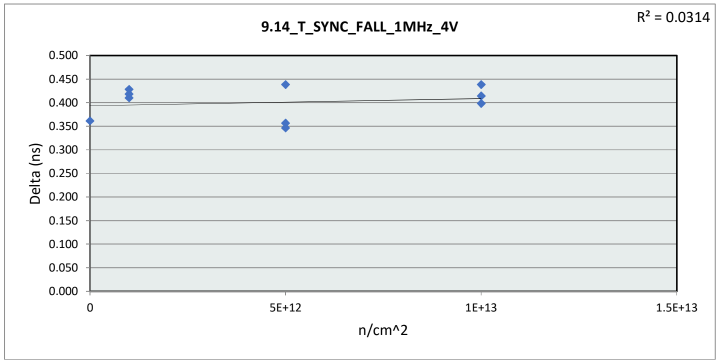


	9.13_T_SYNC_RISE_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.502	7.518	7.476	7.514
Average	7.502	7.530	7.510	7.535
Max	7.502	7.539	7.534	7.557
UL	15.000	15.000	15.000	15.000

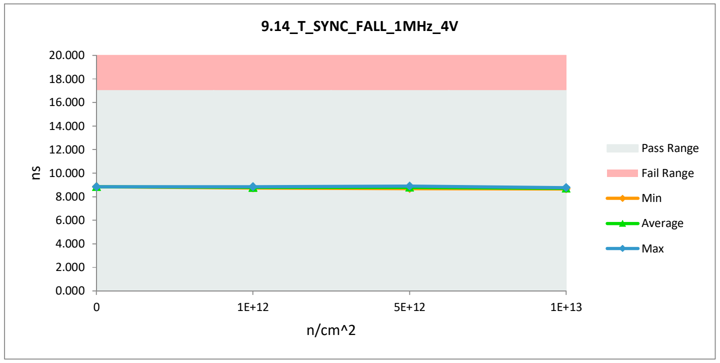


NDD Characterization Report
TPS7H5007-SEP

		9.14_T_SYNC_FALL_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.489	8.850	0.361
1E+12	21	8.332	8.750	0.418
1E+12	22	8.332	8.760	0.428
1E+12	23	8.438	8.848	0.410
5E+12	24	8.330	8.686	0.356
5E+12	25	8.453	8.891	0.438
5E+12	26	8.468	8.814	0.346
1E+13	27	8.261	8.659	0.398
1E+13	28	8.358	8.772	0.414
1E+13	29	8.263	8.701	0.438
	Max	8.489	8.891	0.438
	Average	8.372	8.773	0.401
	Min	8.261	8.659	0.346
	Std Dev	0.084	0.077	0.034

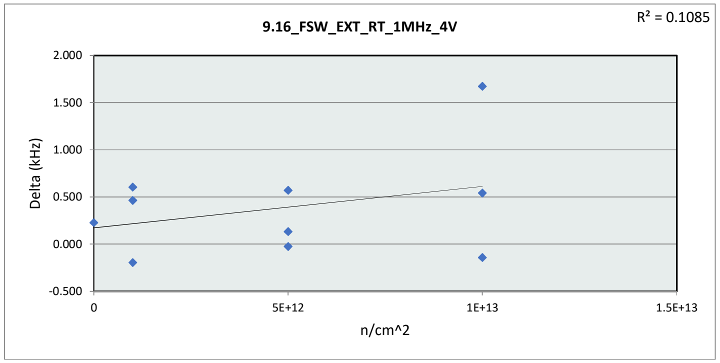


	9.14_T_SYNC_FALL_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.850	8.750	8.686	8.659
Average	8.850	8.786	8.797	8.711
Max	8.850	8.848	8.891	8.772
UL	17.000	17.000	17.000	17.000

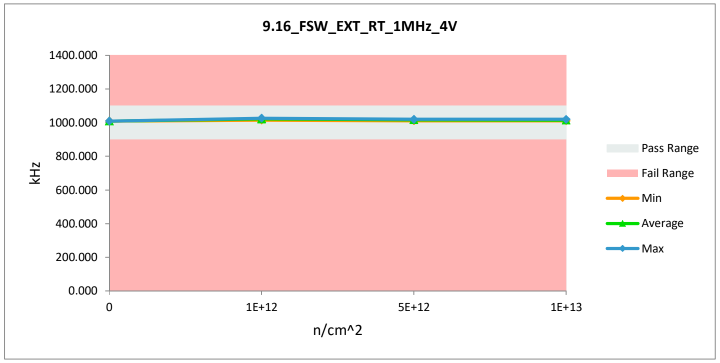


NDD Characterization Report
TPS7H5007-SEP

		9.16_FSW_EXT_RT_1MHz_4V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1008.918	1009.144	0.226
1E+12	21	1026.689	1026.492	-0.197
1E+12	22	1023.089	1023.552	0.463
1E+12	23	1014.493	1015.096	0.603
5E+12	24	1019.330	1019.305	-0.025
5E+12	25	1019.471	1019.603	0.132
5E+12	26	1011.522	1012.091	0.569
1E+13	27	1009.633	1010.173	0.540
1E+13	28	1013.006	1014.677	1.671
1E+13	29	1019.767	1019.624	-0.143
	Max	1026.689	1026.492	1.671
	Average	1016.592	1016.976	0.384
	Min	1008.918	1009.144	-0.197
	Std Dev	5.966	5.710	0.542

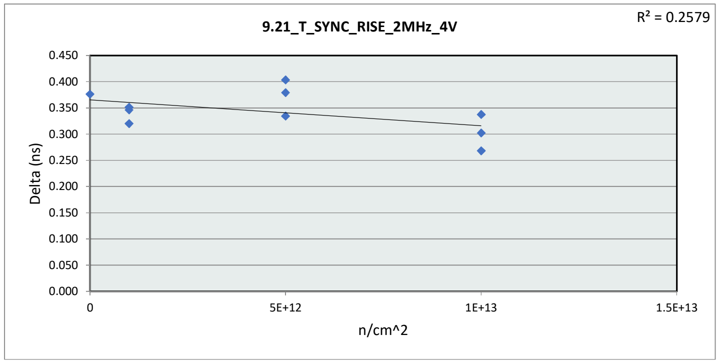


	9.16_FSW_EXT_RT_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1009.144	1015.096	1012.091	1010.173
Average	1009.144	1021.713	1017.000	1014.825
Max	1009.144	1026.492	1019.603	1019.624
UL	1100.000	1100.000	1100.000	1100.000

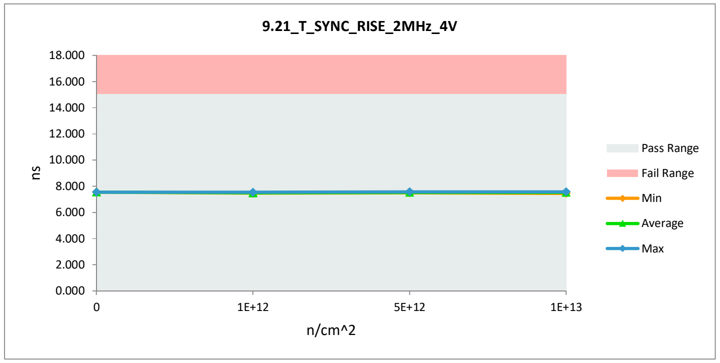


NDD Characterization Report
TPS7H5007-SEP

		9.21_T_SYNC_RISE_2MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.167	7.543	0.376
1E+12	21	7.129	7.475	0.346
1E+12	22	7.185	7.536	0.351
1E+12	23	7.147	7.467	0.320
5E+12	24	7.119	7.498	0.379
5E+12	25	7.155	7.489	0.334
5E+12	26	7.172	7.575	0.403
1E+13	27	7.243	7.580	0.337
1E+13	28	7.186	7.454	0.268
1E+13	29	7.233	7.535	0.302
	Max	7.243	7.580	0.403
	Average	7.174	7.515	0.342
	Min	7.119	7.454	0.268
	Std Dev	0.040	0.045	0.039

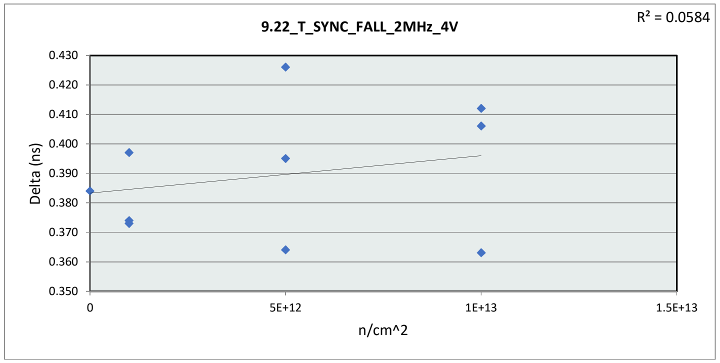


	9.21_T_SYNC_RISE_2MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.543	7.467	7.489	7.454
Average	7.543	7.493	7.521	7.523
Max	7.543	7.536	7.575	7.580
UL	15.000	15.000	15.000	15.000

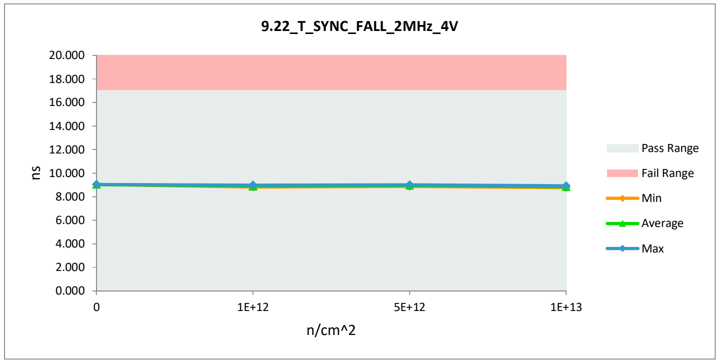


NDD Characterization Report
TPS7H5007-SEP

		9.22_T_SYNC_FALL_2MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.663	9.047	0.384
1E+12	21	8.461	8.834	0.373
1E+12	22	8.484	8.858	0.374
1E+12	23	8.585	8.982	0.397
5E+12	24	8.458	8.853	0.395
5E+12	25	8.629	8.993	0.364
5E+12	26	8.587	9.013	0.426
1E+13	27	8.397	8.760	0.363
1E+13	28	8.512	8.918	0.406
1E+13	29	8.438	8.850	0.412
	Max	8.663	9.047	0.426
	Average	8.521	8.911	0.389
	Min	8.397	8.760	0.363
	Std Dev	0.089	0.094	0.021

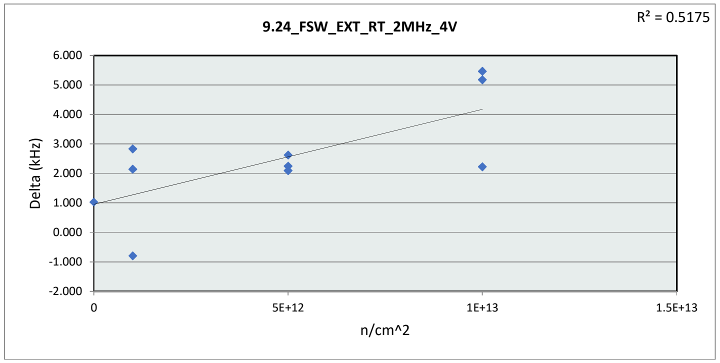


	9.22_T_SYNC_FALL_2MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	9.047	8.834	8.853	8.760
Average	9.047	8.891	8.953	8.843
Max	9.047	8.982	9.013	8.918
UL	17.000	17.000	17.000	17.000

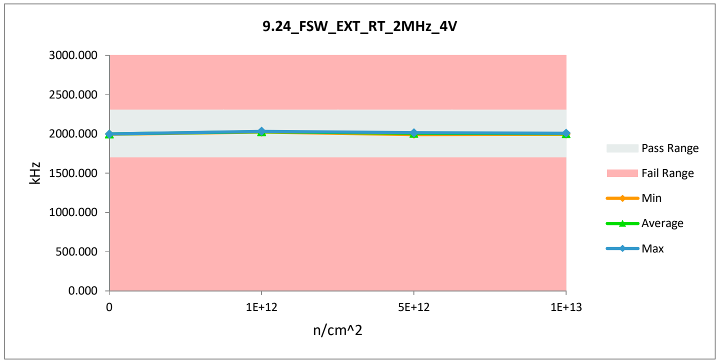


NDD Characterization Report
TPS7H5007-SEP

		9.24_FSW_EXT_RT_2MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1996.811	1997.833	1.022
1E+12	21	2026.956	2026.156	-0.800
1E+12	22	2030.631	2033.456	2.825
1E+12	23	2019.679	2021.818	2.139
5E+12	24	2010.097	2012.188	2.091
5E+12	25	2012.000	2014.619	2.619
5E+12	26	1990.982	1993.225	2.243
1E+13	27	1991.171	1996.631	5.460
1E+13	28	1997.359	2002.527	5.168
1E+13	29	2005.836	2008.058	2.222
	Max	2030.631	2033.456	5.460
	Average	2008.152	2010.651	2.499
	Min	1990.982	1993.225	-0.800
	Std Dev	14.314	13.501	1.811

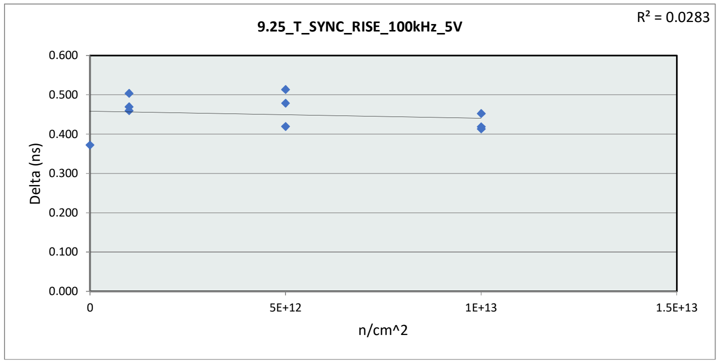


9.24_FSW_EXT_RT_2MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1997.833	2021.818	1993.225	1996.631
Average	1997.833	2027.143	2006.677	2002.405
Max	1997.833	2033.456	2014.619	2008.058
UL	2300.000	2300.000	2300.000	2300.000

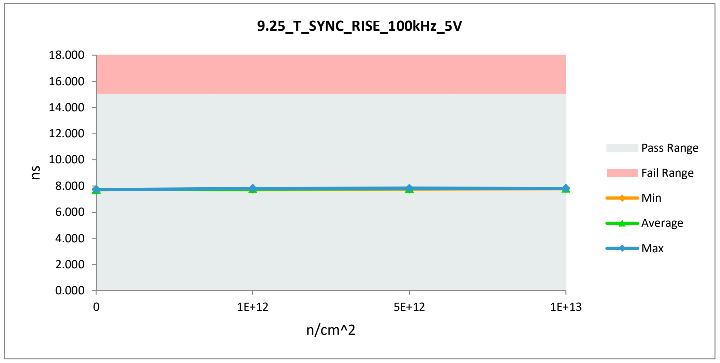


NDD Characterization Report
TPS7H5007-SEP

		9.25_T_SYNC_RISE_100kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.350	7.722	0.372
1E+12	21	7.300	7.769	0.469
1E+12	22	7.304	7.807	0.503
1E+12	23	7.286	7.745	0.459
5E+12	24	7.284	7.797	0.513
5E+12	25	7.338	7.757	0.419
5E+12	26	7.351	7.829	0.478
1E+13	27	7.379	7.792	0.413
1E+13	28	7.355	7.807	0.452
1E+13	29	7.399	7.817	0.418
	Max	7.399	7.829	0.513
	Average	7.335	7.784	0.450
	Min	7.284	7.722	0.372
	Std Dev	0.040	0.035	0.044

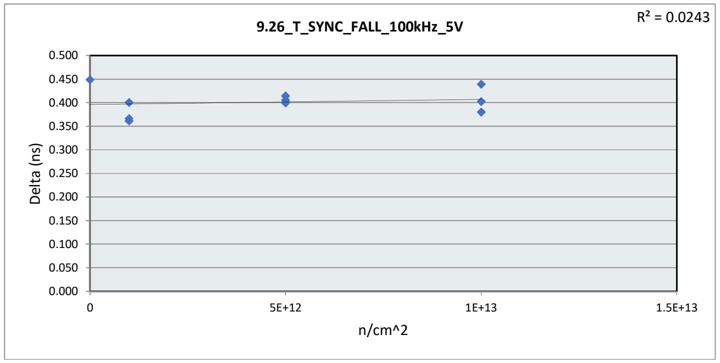


	9.25_T_SYNC_RISE_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.722	7.745	7.757	7.792
Average	7.722	7.774	7.794	7.805
Max	7.722	7.807	7.829	7.817
UL	15.000	15.000	15.000	15.000

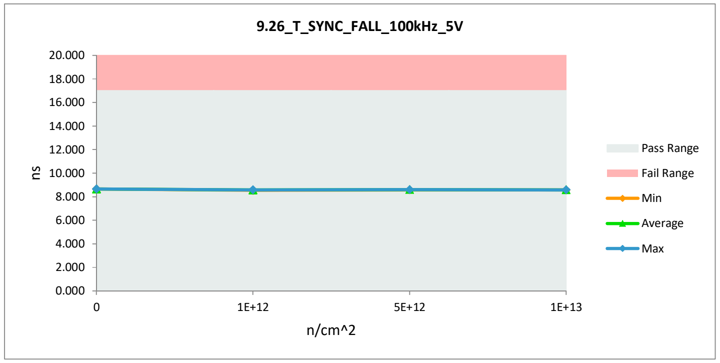


NDD Characterization Report
TPS7H5007-SEP

		9.26_T_SYNC_FALL_100kHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.206	8.654	0.448
1E+12	21	8.183	8.583	0.400
1E+12	22	8.170	8.536	0.366
1E+12	23	8.211	8.572	0.361
5E+12	24	8.184	8.589	0.405
5E+12	25	8.204	8.603	0.399
5E+12	26	8.183	8.597	0.414
1E+13	27	8.148	8.587	0.439
1E+13	28	8.187	8.567	0.380
1E+13	29	8.180	8.582	0.402
	Max	8.211	8.654	0.448
	Average	8.186	8.587	0.401
	Min	8.148	8.536	0.361
	Std Dev	0.019	0.030	0.028

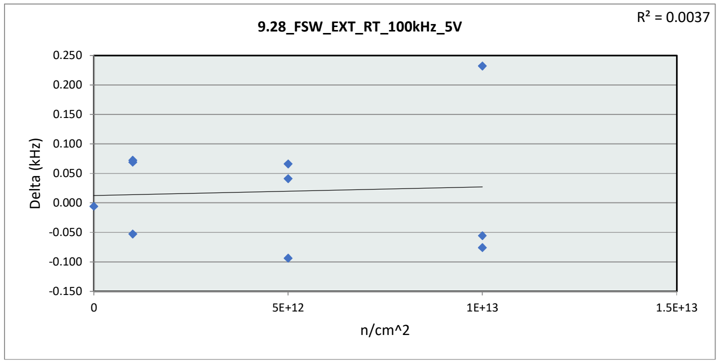


	9.26_T_SYNC_FALL_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.654	8.536	8.589	8.567
Average	8.654	8.564	8.596	8.579
Max	8.654	8.583	8.603	8.587
UL	17.000	17.000	17.000	17.000

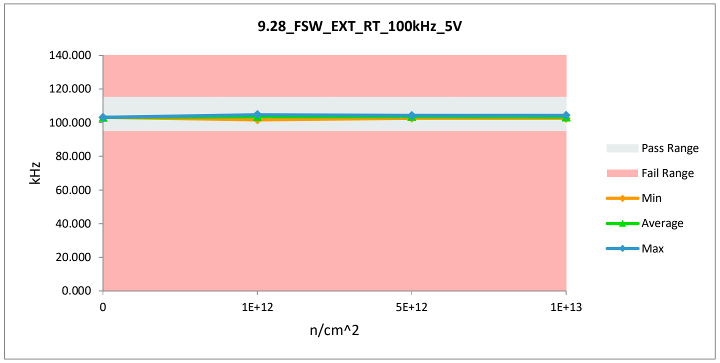


NDD Characterization Report
TPS7H5007-SEP

		9.28_FSW_EXT_RT_100kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	103.147	103.141	-0.006
1E+12	21	104.850	104.797	-0.053
1E+12	22	104.110	104.182	0.072
1E+12	23	101.541	101.610	0.069
5E+12	24	103.798	103.704	-0.094
5E+12	25	104.187	104.228	0.041
5E+12	26	102.560	102.626	0.066
1E+13	27	102.619	102.563	-0.056
1E+13	28	102.986	103.218	0.232
1E+13	29	104.426	104.350	-0.076
	Max	104.850	104.797	0.232
	Average	103.422	103.442	0.019
	Min	101.541	101.610	-0.094
	Std Dev	1.024	0.991	0.098

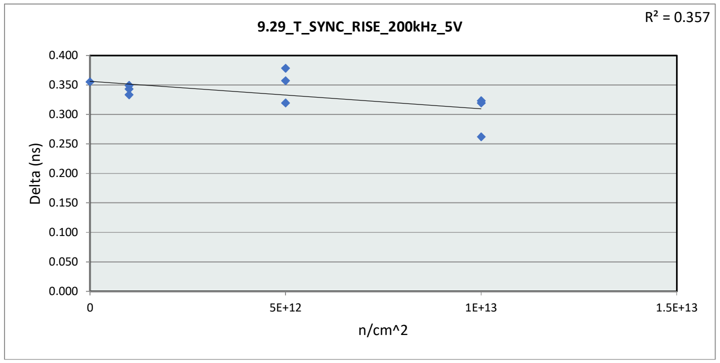


	9.28_FSW_EXT_RT_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.141	101.610	102.626	102.563
Average	103.141	103.530	103.519	103.377
Max	103.141	104.797	104.228	104.350
UL	115.000	115.000	115.000	115.000

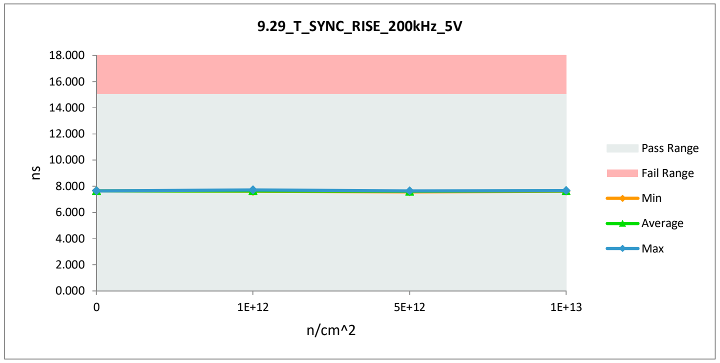


NDD Characterization Report
TPS7H5007-SEP

		9.29_T_SYNC_RISE_200kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.299	7.654	0.355
1E+12	21	7.365	7.708	0.343
1E+12	22	7.296	7.645	0.349
1E+12	23	7.278	7.611	0.333
5E+12	24	7.251	7.570	0.319
5E+12	25	7.250	7.628	0.378
5E+12	26	7.286	7.643	0.357
1E+13	27	7.400	7.662	0.262
1E+13	28	7.298	7.617	0.319
1E+13	29	7.336	7.659	0.323
	Max	7.400	7.708	0.378
	Average	7.306	7.640	0.334
	Min	7.250	7.570	0.262
	Std Dev	0.048	0.037	0.032

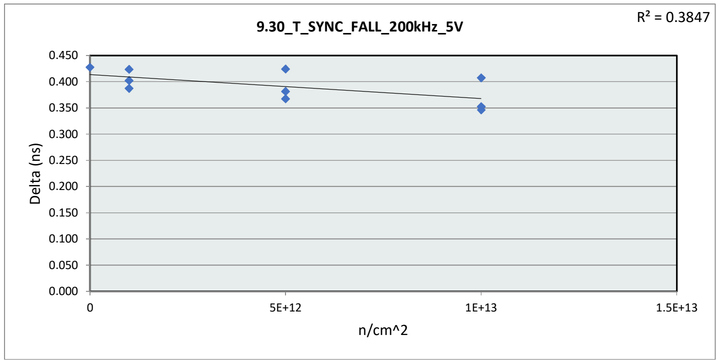


	9.29_T_SYNC_RISE_200kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.654	7.611	7.570	7.617
Average	7.654	7.655	7.614	7.646
Max	7.654	7.708	7.643	7.662
UL	15.000	15.000	15.000	15.000

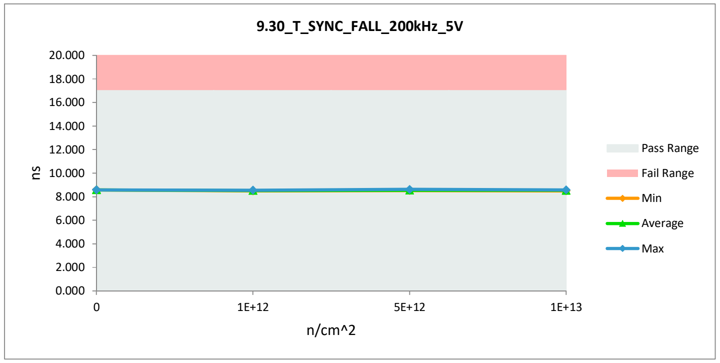


NDD Characterization Report
TPS7H5007-SEP

		9.30_T_SYNC_FALL_200kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.151	8.578	0.427
1E+12	21	8.070	8.493	0.423
1E+12	22	8.146	8.548	0.402
1E+12	23	8.147	8.534	0.387
5E+12	24	8.130	8.511	0.381
5E+12	25	8.191	8.615	0.424
5E+12	26	8.160	8.527	0.367
1E+13	27	8.157	8.509	0.352
1E+13	28	8.172	8.518	0.346
1E+13	29	8.153	8.560	0.407
	Max	8.191	8.615	0.427
	Average	8.148	8.539	0.392
	Min	8.070	8.493	0.346
	Std Dev	0.032	0.037	0.030

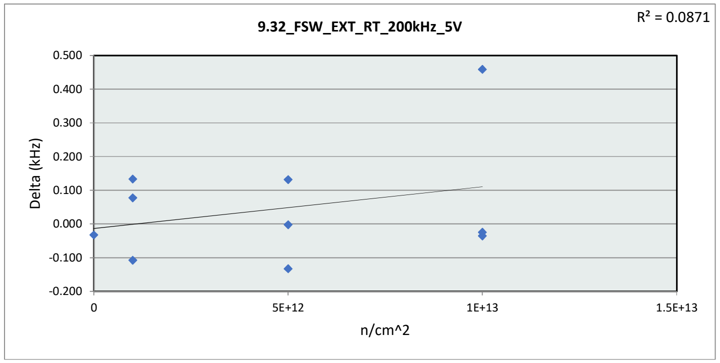


	9.30_T_SYNC_FALL_200kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.578	8.493	8.511	8.509
Average	8.578	8.525	8.551	8.529
Max	8.578	8.548	8.615	8.560
UL	17.000	17.000	17.000	17.000

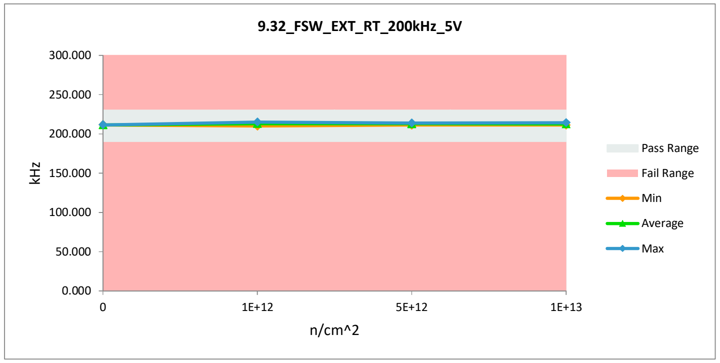


NDD Characterization Report
TPS7H5007-SEP

		9.32_FSW_EXT_RT_200kHz_5V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	211.582	211.549	-0.033
1E+12	21	215.122	215.014	-0.108
1E+12	22	214.049	214.182	0.133
1E+12	23	209.932	210.009	0.077
5E+12	24	213.483	213.350	-0.133
5E+12	25	213.902	213.899	-0.003
5E+12	26	210.993	211.124	0.131
1E+13	27	211.100	211.075	-0.025
1E+13	28	211.702	212.160	0.458
1E+13	29	214.317	214.281	-0.036
	Max	215.122	215.014	0.458
	Average	212.618	212.664	0.046
	Min	209.932	210.009	-0.133
	Std Dev	1.754	1.696	0.171

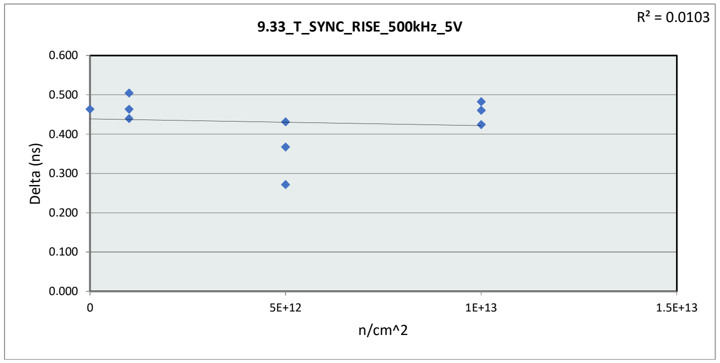


	9.32_FSW_EXT_RT_200kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	211.549	210.009	211.124	211.075
Average	211.549	213.068	212.791	212.505
Max	211.549	215.014	213.899	214.281
UL	230.000	230.000	230.000	230.000

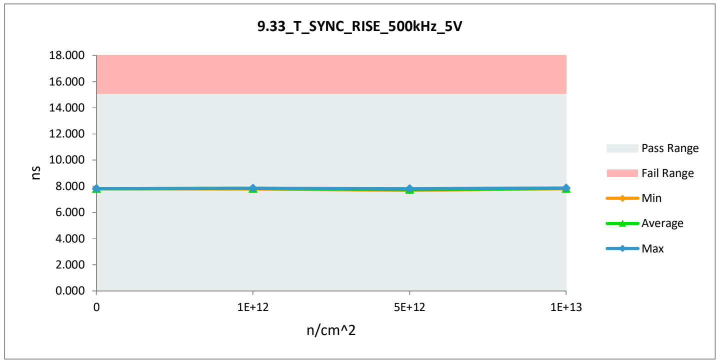


NDD Characterization Report
TPS7H5007-SEP

		9.33_T_SYNC_RISE_500kHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.346	7.809	0.463
1E+12	21	7.356	7.819	0.463
1E+12	22	7.341	7.845	0.504
1E+12	23	7.363	7.802	0.439
5E+12	24	7.428	7.699	0.271
5E+12	25	7.382	7.749	0.367
5E+12	26	7.380	7.811	0.431
1E+13	27	7.379	7.861	0.482
1E+13	28	7.390	7.814	0.424
1E+13	29	7.362	7.822	0.460
	Max	7.428	7.861	0.504
	Average	7.373	7.803	0.430
	Min	7.341	7.699	0.271
	Std Dev	0.025	0.047	0.067



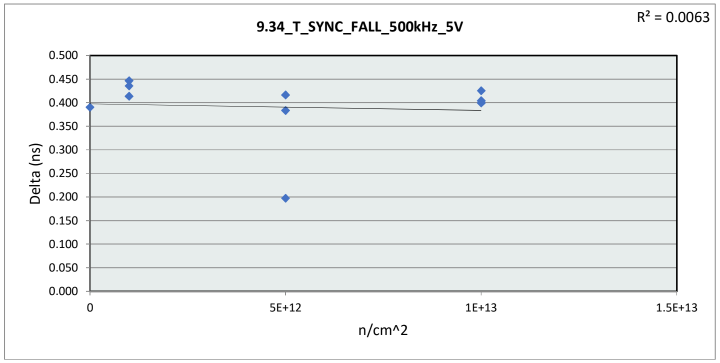
	9.33_T_SYNC_RISE_500kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.809	7.802	7.699	7.814
Average	7.809	7.822	7.753	7.832
Max	7.809	7.845	7.811	7.861
UL	15.000	15.000	15.000	15.000



NDD Characterization Report
TPS7H5007-SEP

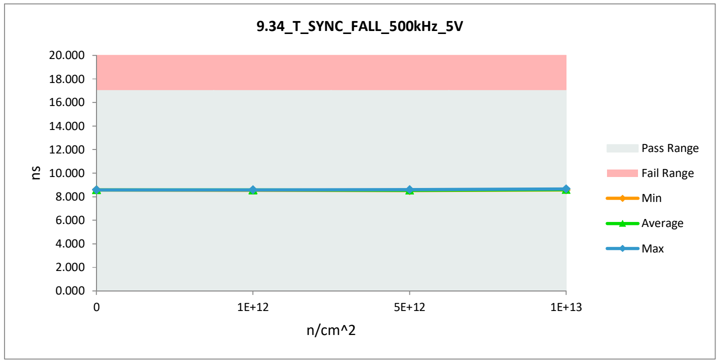
	9.34_T_SYNC_FALL_500kHz_5V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	14	17
Min Limit	0	0

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.197	8.587	0.390
1E+12	21	8.154	8.589	0.435
1E+12	22	8.100	8.546	0.446
1E+12	23	8.143	8.556	0.413
5E+12	24	8.148	8.531	0.383
5E+12	25	8.310	8.507	0.197
5E+12	26	8.179	8.595	0.416
1E+13	27	8.134	8.559	0.425
1E+13	28	8.171	8.570	0.399
1E+13	29	8.257	8.661	0.404
	Max	8.310	8.661	0.446
	Average	8.179	8.570	0.391
	Min	8.100	8.507	0.197
	Std Dev	0.062	0.042	0.071



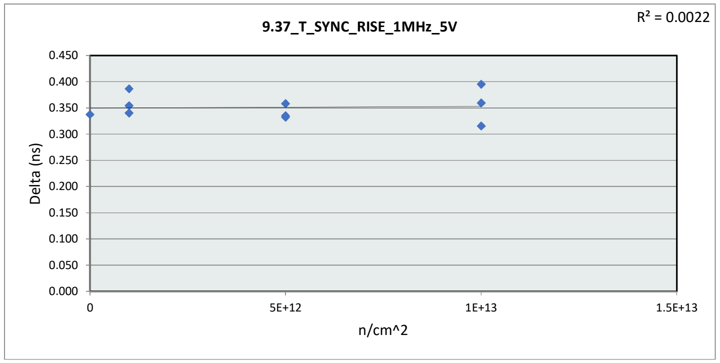
	9.34_T_SYNC_FALL_500kHz_5	
Test Site		
Tester		
Test Number		
Max Limit	17	ns
Min Limit	0	ns

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.587	8.546	8.507	8.559
Average	8.587	8.564	8.544	8.597
Max	8.587	8.589	8.595	8.661
UL	17.000	17.000	17.000	17.000

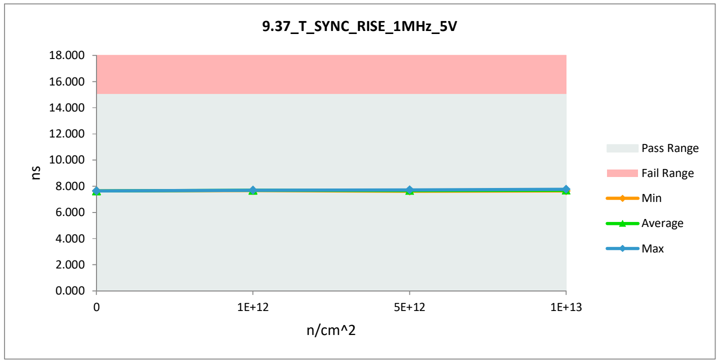


NDD Characterization Report
TPS7H5007-SEP

		9.37_T_SYNC_RISE_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.303	7.640	0.337
1E+12	21	7.315	7.701	0.386
1E+12	22	7.329	7.669	0.340
1E+12	23	7.313	7.667	0.354
5E+12	24	7.284	7.616	0.332
5E+12	25	7.331	7.666	0.335
5E+12	26	7.373	7.731	0.358
1E+13	27	7.373	7.768	0.395
1E+13	28	7.319	7.678	0.359
1E+13	29	7.317	7.632	0.315
	Max	7.373	7.768	0.395
	Average	7.326	7.677	0.351
	Min	7.284	7.616	0.315
	Std Dev	0.028	0.046	0.025

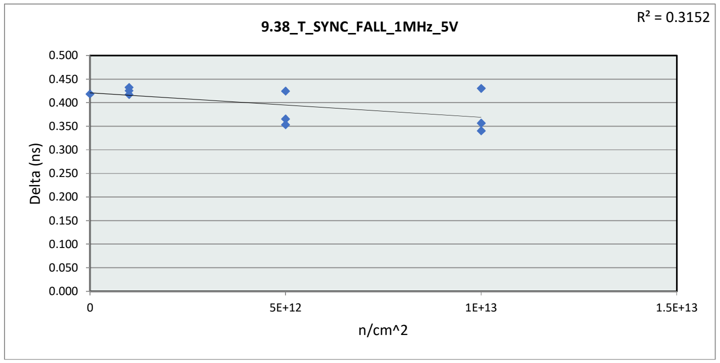


9.37_T_SYNC_RISE_1MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.640	7.667	7.616	7.632
Average	7.640	7.679	7.671	7.693
Max	7.640	7.701	7.731	7.768
UL	15.000	15.000	15.000	15.000

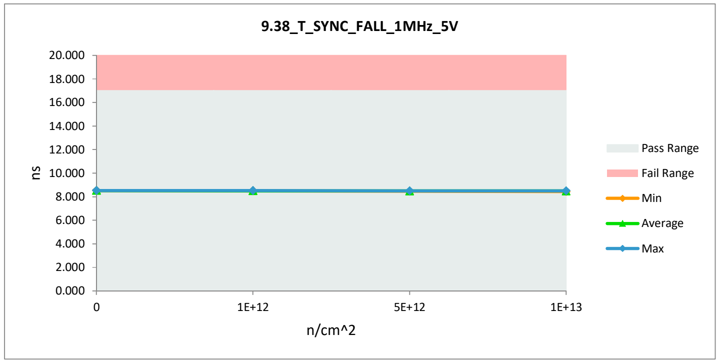


NDD Characterization Report
TPS7H5007-SEP

		9.38_T_SYNC_FALL_1MHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.115	8.533	0.418
1E+12	21	8.083	8.508	0.425
1E+12	22	8.063	8.495	0.432
1E+12	23	8.107	8.524	0.417
5E+12	24	8.097	8.462	0.365
5E+12	25	8.070	8.494	0.424
5E+12	26	8.143	8.496	0.353
1E+13	27	8.075	8.505	0.430
1E+13	28	8.153	8.509	0.356
1E+13	29	8.088	8.428	0.340
	Max	8.153	8.533	0.432
	Average	8.099	8.495	0.396
	Min	8.063	8.428	0.340
	Std Dev	0.030	0.030	0.037

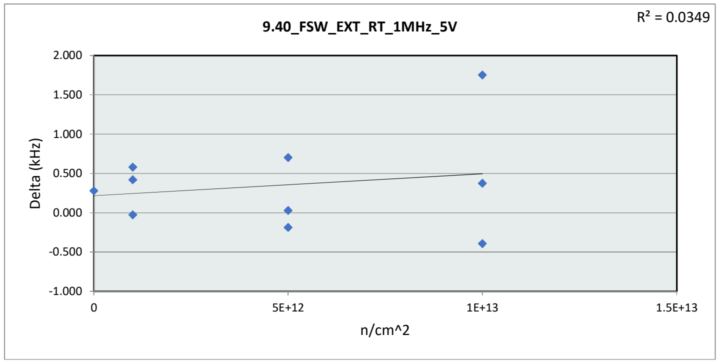


	9.38_T_SYNC_FALL_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.533	8.495	8.462	8.428
Average	8.533	8.509	8.484	8.481
Max	8.533	8.524	8.496	8.509
UL	17.000	17.000	17.000	17.000

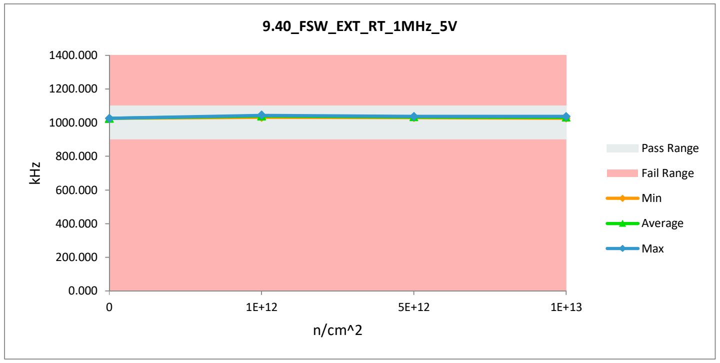


NDD Characterization Report
TPS7H5007-SEP

		9.40_FSW_EXT_RT_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1025.100	1025.377	0.277
1E+12	21	1044.230	1044.202	-0.028
1E+12	22	1039.827	1040.243	0.416
1E+12	23	1031.007	1031.586	0.579
5E+12	24	1037.202	1037.012	-0.190
5E+12	25	1035.954	1035.980	0.026
5E+12	26	1028.732	1029.432	0.700
1E+13	27	1026.576	1026.949	0.373
1E+13	28	1030.397	1032.147	1.750
1E+13	29	1037.417	1037.022	-0.395
	Max	1044.230	1044.202	1.750
	Average	1033.644	1033.995	0.351
	Min	1025.100	1025.377	-0.395
	Std Dev	6.210	5.957	0.600



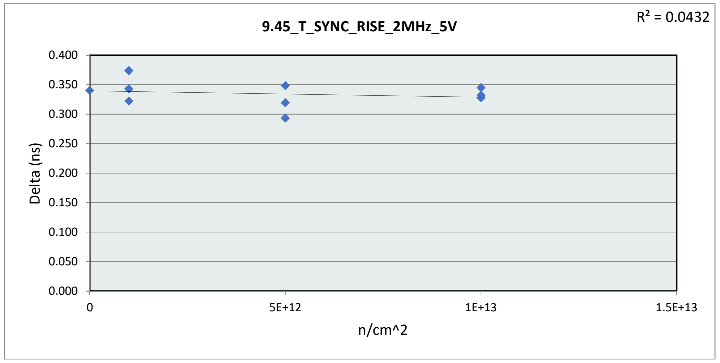
	9.40_FSW_EXT_RT_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1025.377	1031.586	1029.432	1026.949
Average	1025.377	1038.677	1034.141	1032.039
Max	1025.377	1044.202	1037.012	1037.022
UL	1100.000	1100.000	1100.000	1100.000



NDD Characterization Report
TPS7H5007-SEP

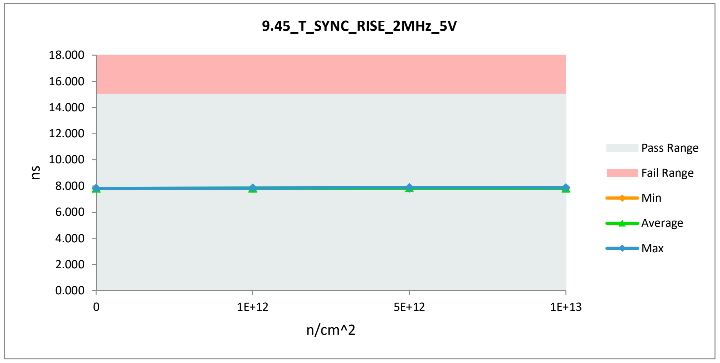
	9.45_T_SYNC_RISE_2MHz_5V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	14	15
Min Limit	0	0

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.467	7.807	0.340
1E+12	21	7.496	7.818	0.322
1E+12	22	7.463	7.837	0.374
1E+12	23	7.482	7.825	0.343
5E+12	24	7.521	7.814	0.293
5E+12	25	7.484	7.832	0.348
5E+12	26	7.566	7.885	0.319
1E+13	27	7.466	7.811	0.345
1E+13	28	7.477	7.809	0.332
1E+13	29	7.542	7.870	0.328
	Max	7.566	7.885	0.374
	Average	7.496	7.831	0.334
	Min	7.463	7.807	0.293
	Std Dev	0.035	0.027	0.021



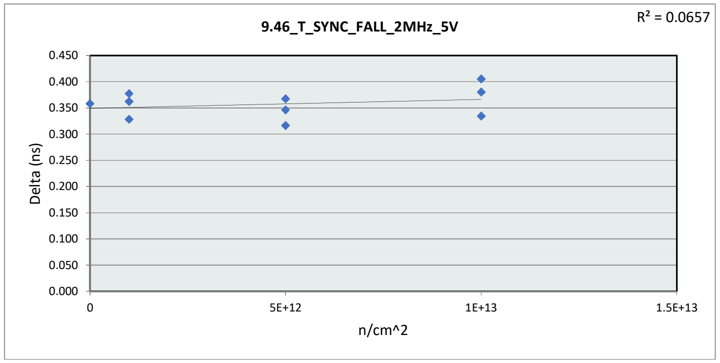
	9.45_T_SYNC_RISE_2MHz_5V	
Test Site		
Tester		
Test Number		
Max Limit	15	ns
Min Limit	0	ns

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.807	7.818	7.814	7.809
Average	7.807	7.827	7.844	7.830
Max	7.807	7.837	7.885	7.870
UL	15.000	15.000	15.000	15.000

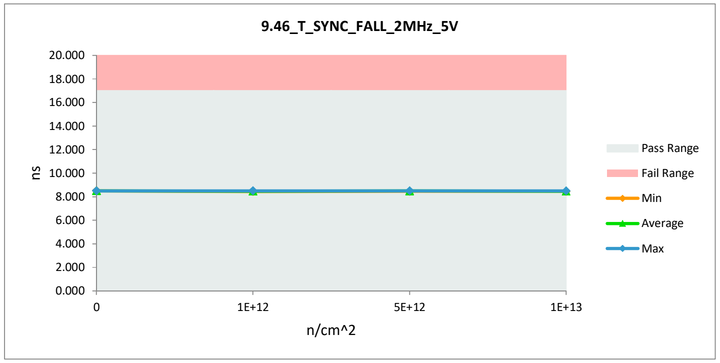


NDD Characterization Report
TPS7H5007-SEP

		9.46_T_SYNC_FALL_2MHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.146	8.504	0.358
1E+12	21	8.095	8.457	0.362
1E+12	22	8.106	8.434	0.328
1E+12	23	8.128	8.505	0.377
5E+12	24	8.137	8.504	0.367
5E+12	25	8.136	8.452	0.316
5E+12	26	8.137	8.483	0.346
1E+13	27	8.113	8.447	0.334
1E+13	28	8.085	8.490	0.405
1E+13	29	8.108	8.488	0.380
	Max	8.146	8.505	0.405
	Average	8.119	8.476	0.357
	Min	8.085	8.434	0.316
	Std Dev	0.021	0.027	0.027

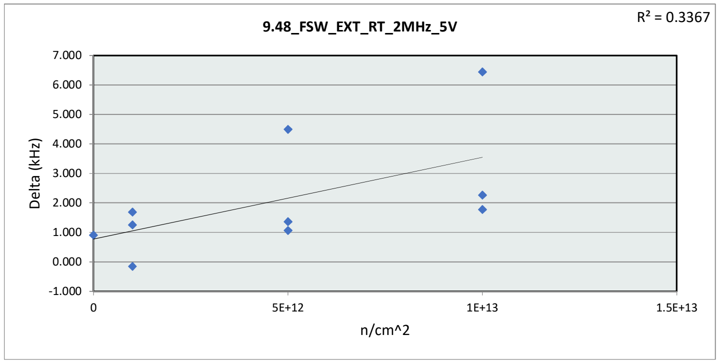


	9.46_T_SYNC_FALL_2MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.504	8.434	8.452	8.447
Average	8.504	8.465	8.480	8.475
Max	8.504	8.505	8.504	8.490
UL	17.000	17.000	17.000	17.000

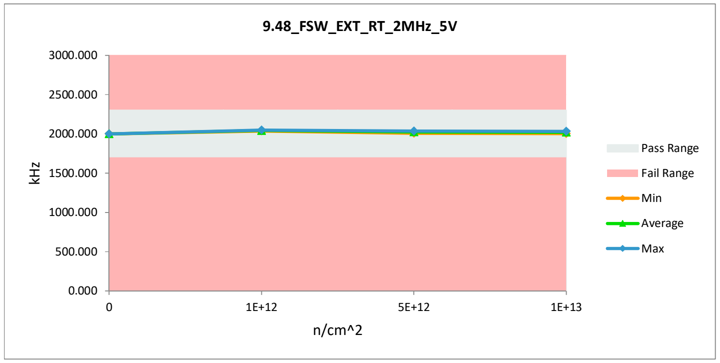


NDD Characterization Report
TPS7H5007-SEP

		9.48_FSW_EXT_RT_2MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1999.799	2000.699	0.900
1E+12	21	2049.775	2049.613	-0.162
1E+12	22	2040.349	2041.598	1.249
1E+12	23	2036.316	2038.001	1.685
5E+12	24	2033.611	2034.668	1.057
5E+12	25	2024.057	2025.418	1.361
5E+12	26	2003.282	2007.774	4.492
1E+13	27	2002.598	2004.857	2.259
1E+13	28	2019.034	2025.475	6.441
1E+13	29	2031.577	2033.348	1.771
	Max	2049.775	2049.613	6.441
	Average	2024.040	2026.145	2.105
	Min	1999.799	2000.699	-0.162
	Std Dev	17.419	16.646	1.938

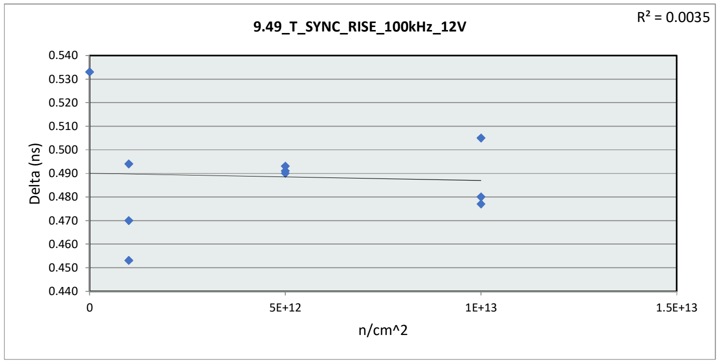


9.48_FSW_EXT_RT_2MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	2000.699	2038.001	2007.774	2004.857
Average	2000.699	2043.071	2022.620	2021.227
Max	2000.699	2049.613	2034.668	2033.348
UL	2300.000	2300.000	2300.000	2300.000

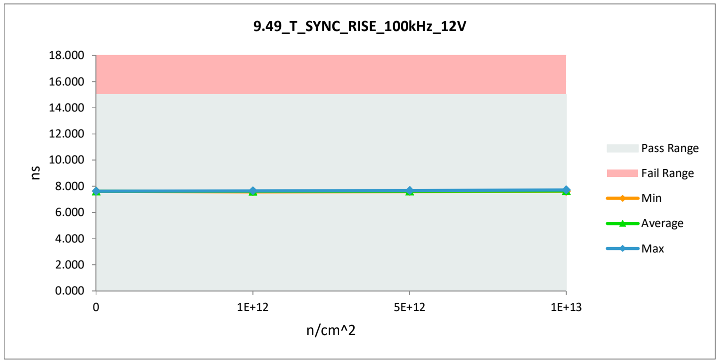


NDD Characterization Report
TPS7H5007-SEP

		9.49_T_SYNC_RISE_100kHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.088	7.621	0.533
1E+12	21	7.117	7.570	0.453
1E+12	22	7.153	7.647	0.494
1E+12	23	7.139	7.609	0.470
5E+12	24	7.101	7.594	0.493
5E+12	25	7.129	7.619	0.490
5E+12	26	7.177	7.668	0.491
1E+13	27	7.212	7.717	0.505
1E+13	28	7.134	7.614	0.480
1E+13	29	7.149	7.626	0.477
	Max	7.212	7.717	0.533
	Average	7.140	7.628	0.489
	Min	7.088	7.570	0.453
	Std Dev	0.036	0.041	0.021

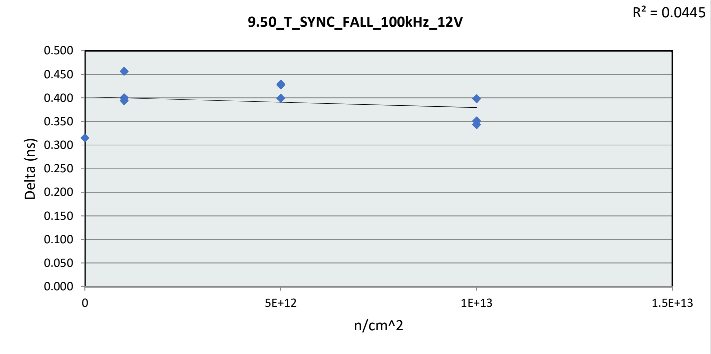


	9.49_T_SYNC_RISE_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.621	7.570	7.594	7.614
Average	7.621	7.609	7.627	7.652
Max	7.621	7.647	7.668	7.717
UL	15.000	15.000	15.000	15.000

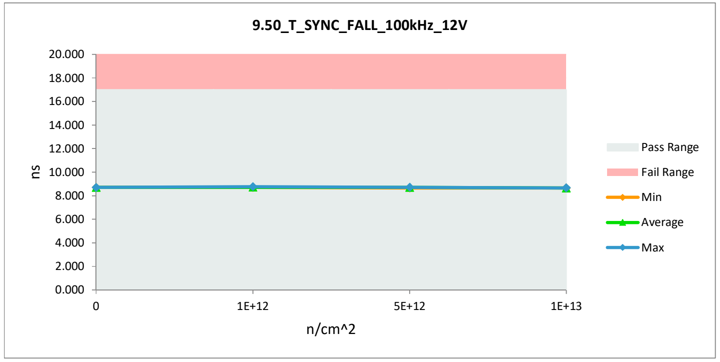


NDD Characterization Report
TPS7H5007-SEP

		9.50_T_SYNC_FALL_100kHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.383	8.698	0.315
1E+12	21	8.310	8.704	0.394
1E+12	22	8.299	8.755	0.456
1E+12	23	8.302	8.702	0.400
5E+12	24	8.286	8.715	0.429
5E+12	25	8.288	8.715	0.427
5E+12	26	8.249	8.648	0.399
1E+13	27	8.268	8.666	0.398
1E+13	28	8.301	8.652	0.351
1E+13	29	8.303	8.646	0.343
	Max	8.383	8.755	0.456
	Average	8.299	8.690	0.391
	Min	8.249	8.646	0.315
	Std Dev	0.035	0.036	0.043

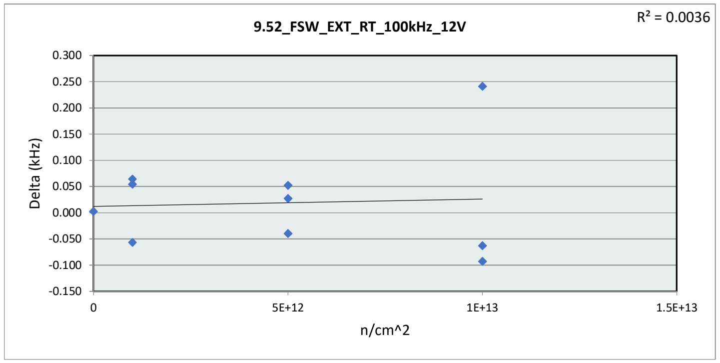


	9.50_T_SYNC_FALL_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.698	8.702	8.648	8.646
Average	8.698	8.720	8.693	8.655
Max	8.698	8.755	8.715	8.666
UL	17.000	17.000	17.000	17.000

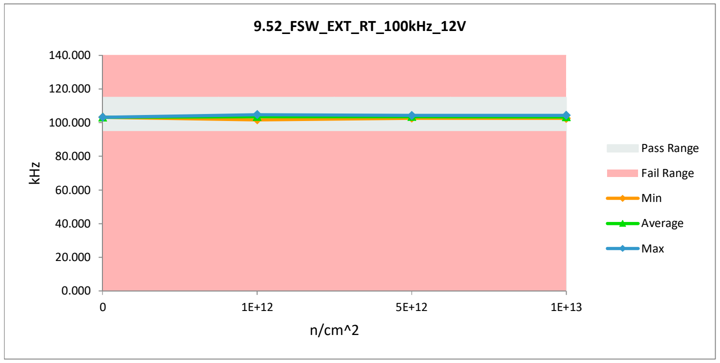


NDD Characterization Report
TPS7H5007-SEP

		9.52_FSW_EXT_RT_100kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	103.165	103.167	0.002
1E+12	21	104.867	104.810	-0.057
1E+12	22	104.116	104.180	0.064
1E+12	23	101.568	101.622	0.054
5E+12	24	103.818	103.778	-0.040
5E+12	25	104.224	104.251	0.027
5E+12	26	102.598	102.650	0.052
1E+13	27	102.636	102.573	-0.063
1E+13	28	103.010	103.251	0.241
1E+13	29	104.447	104.354	-0.093
	Max	104.867	104.810	0.241
	Average	103.445	103.464	0.019
	Min	101.568	101.622	-0.093
	Std Dev	1.021	0.990	0.096

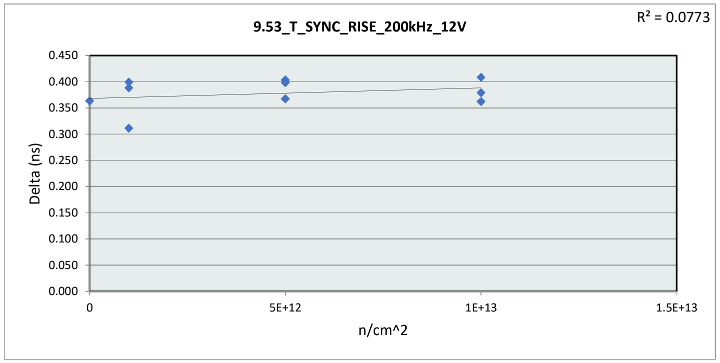


	9.52_FSW_EXT_RT_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.167	101.622	102.650	102.573
Average	103.167	103.537	103.560	103.393
Max	103.167	104.810	104.251	104.354
UL	115.000	115.000	115.000	115.000

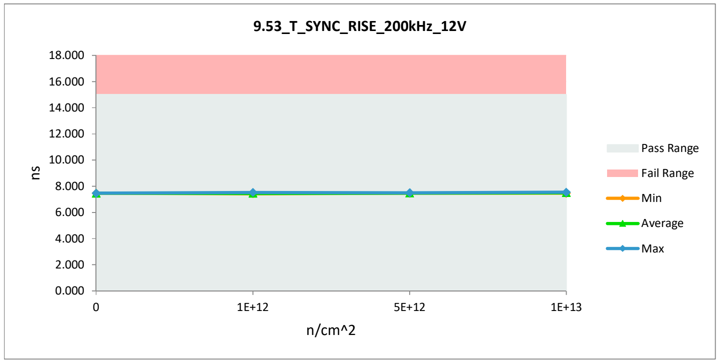


NDD Characterization Report
TPS7H5007-SEP

		9.53_T_SYNC_RISE_200kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.103	7.466	0.363
1E+12	21	7.020	7.419	0.399
1E+12	22	7.113	7.424	0.311
1E+12	23	7.137	7.525	0.388
5E+12	24	7.082	7.485	0.403
5E+12	25	7.088	7.455	0.367
5E+12	26	7.088	7.486	0.398
1E+13	27	7.141	7.520	0.379
1E+13	28	7.104	7.466	0.362
1E+13	29	7.130	7.538	0.408
	Max	7.141	7.538	0.408
	Average	7.101	7.478	0.378
	Min	7.020	7.419	0.311
	Std Dev	0.035	0.041	0.029

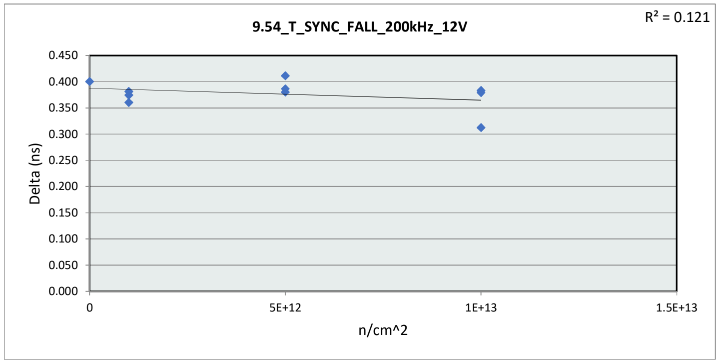


	9.53_T_SYNC_RISE_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.466	7.419	7.455	7.466
Average	7.466	7.456	7.475	7.508
Max	7.466	7.525	7.486	7.538
UL	15.000	15.000	15.000	15.000

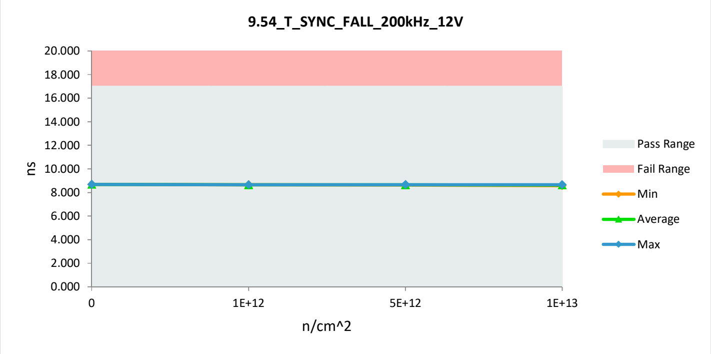


NDD Characterization Report
TPS7H5007-SEP

		9.54_T_SYNC_FALL_200kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.285	8.685	0.400
1E+12	21	8.268	8.649	0.381
1E+12	22	8.279	8.653	0.374
1E+12	23	8.281	8.641	0.360
5E+12	24	8.245	8.631	0.386
5E+12	25	8.281	8.661	0.380
5E+12	26	8.254	8.665	0.411
1E+13	27	8.272	8.584	0.312
1E+13	28	8.260	8.639	0.379
1E+13	29	8.270	8.653	0.383
	Max	8.285	8.685	0.411
	Average	8.270	8.646	0.377
	Min	8.245	8.584	0.312
	Std Dev	0.013	0.027	0.027

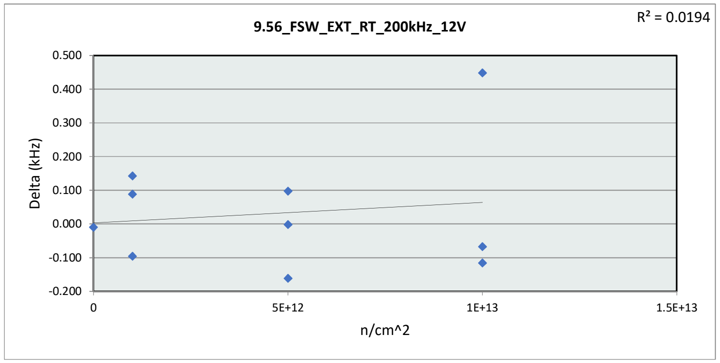


	9.54_T_SYNC_FALL_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.685	8.641	8.631	8.584
Average	8.685	8.648	8.652	8.625
Max	8.685	8.653	8.665	8.653
UL	17.000	17.000	17.000	17.000

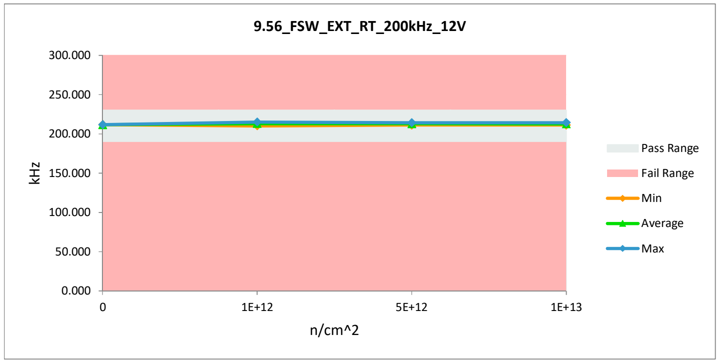


NDD Characterization Report
TPS7H5007-SEP

		9.56_FSW_EXT_RT_200kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	230	230	
	Min Limit	190	190	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	211.697	211.687	-0.010
1E+12	21	215.190	215.094	-0.096
1E+12	22	214.139	214.281	0.142
1E+12	23	210.021	210.109	0.088
5E+12	24	213.562	213.400	-0.162
5E+12	25	213.985	213.983	-0.002
5E+12	26	211.069	211.166	0.097
1E+13	27	211.202	211.086	-0.116
1E+13	28	211.781	212.229	0.448
1E+13	29	214.394	214.326	-0.068
	Max	215.190	215.094	0.448
	Average	212.704	212.736	0.032
	Min	210.021	210.109	-0.162
	Std Dev	1.747	1.697	0.177

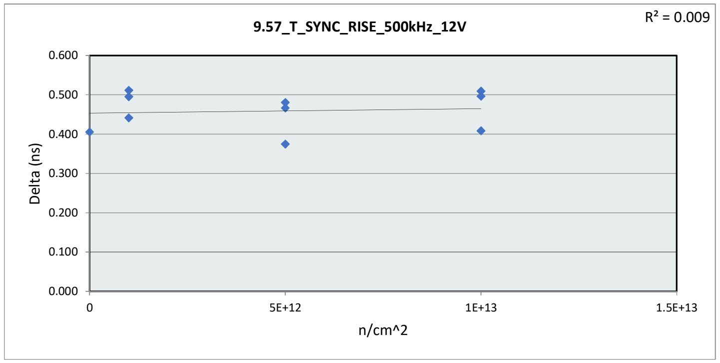


	9.56_FSW_EXT_RT_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	211.687	210.109	211.166	211.086
Average	211.687	213.161	212.850	212.547
Max	211.687	215.094	213.983	214.326
UL	230.000	230.000	230.000	230.000

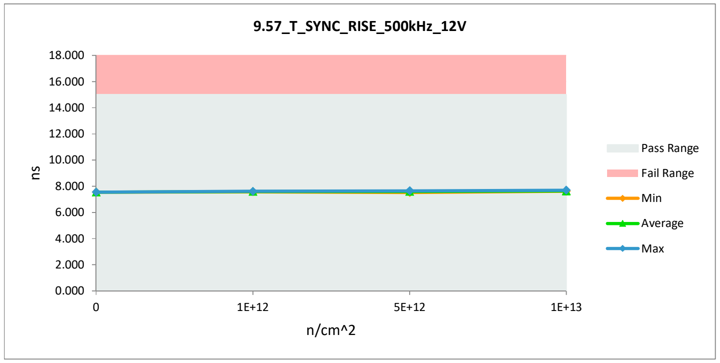


NDD Characterization Report
TPS7H5007-SEP

		9.57_T_SYNC_RISE_500kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.145	7.550	0.405
1E+12	21	7.081	7.592	0.511
1E+12	22	7.136	7.577	0.441
1E+12	23	7.112	7.607	0.495
5E+12	24	7.151	7.525	0.374
5E+12	25	7.134	7.600	0.466
5E+12	26	7.165	7.645	0.480
1E+13	27	7.192	7.688	0.496
1E+13	28	7.110	7.619	0.509
1E+13	29	7.211	7.619	0.408
	Max	7.211	7.688	0.511
	Average	7.144	7.602	0.459
	Min	7.081	7.525	0.374
	Std Dev	0.039	0.046	0.049



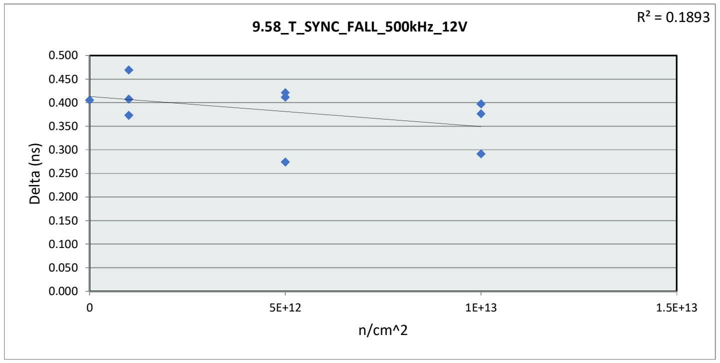
	9.57_T_SYNC_RISE_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.550	7.577	7.525	7.619
Average	7.550	7.592	7.590	7.642
Max	7.550	7.607	7.645	7.688
UL	15.000	15.000	15.000	15.000



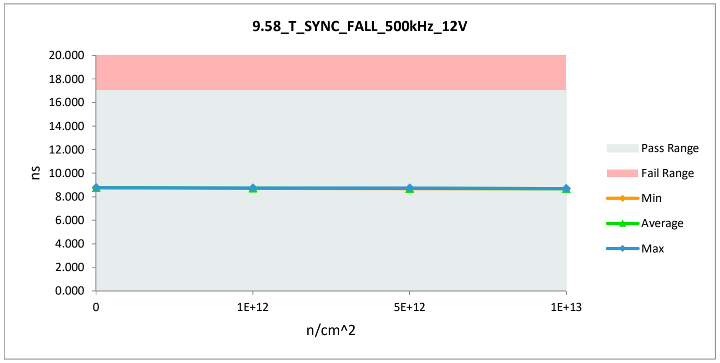
NDD Characterization Report
TPS7H5007-SEP

	9.58_T_SYNC_FALL_500kHz_12V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	14	17
Min Limit	0	0

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.356	8.761	0.405
1E+12	21	8.344	8.717	0.373
1E+12	22	8.271	8.740	0.469
1E+12	23	8.316	8.723	0.407
5E+12	24	8.319	8.730	0.411
5E+12	25	8.403	8.677	0.274
5E+12	26	8.276	8.697	0.421
1E+13	27	8.291	8.688	0.397
1E+13	28	8.318	8.694	0.376
1E+13	29	8.384	8.675	0.291
Max		8.403	8.761	0.469
Average		8.328	8.710	0.382
Min		8.271	8.675	0.274
Std Dev		0.044	0.029	0.059

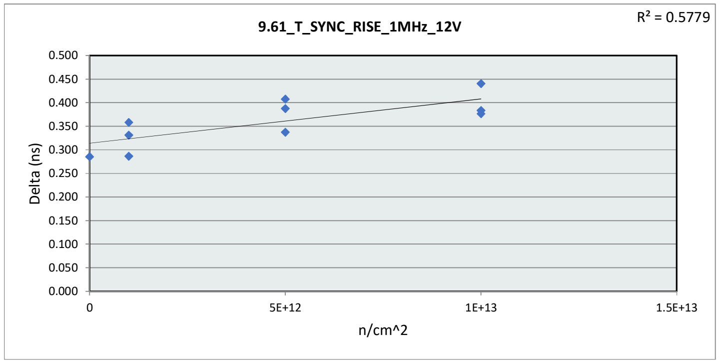


	9.58_T_SYNC_FALL_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.761	8.717	8.677	8.675
Average	8.761	8.727	8.701	8.686
Max	8.761	8.740	8.730	8.694
UL	17.000	17.000	17.000	17.000

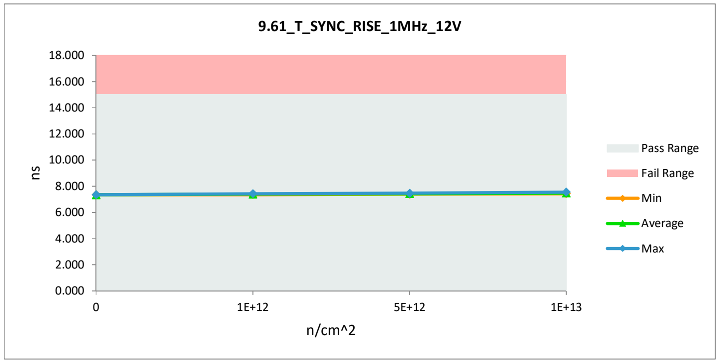


NDD Characterization Report
TPS7H5007-SEP

		9.61_T_SYNC_RISE_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.065	7.350	0.285
1E+12	21	7.013	7.371	0.358
1E+12	22	7.064	7.350	0.286
1E+12	23	7.093	7.424	0.331
5E+12	24	7.007	7.394	0.387
5E+12	25	7.035	7.442	0.407
5E+12	26	7.125	7.462	0.337
1E+13	27	7.171	7.547	0.376
1E+13	28	6.995	7.435	0.440
1E+13	29	7.062	7.445	0.383
	Max	7.171	7.547	0.440
	Average	7.063	7.422	0.359
	Min	6.995	7.350	0.285
	Std Dev	0.055	0.060	0.050

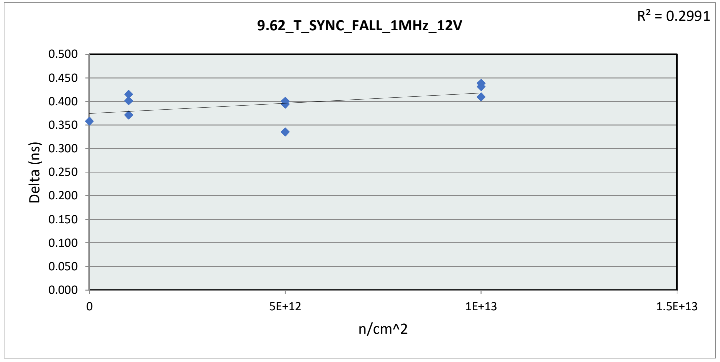


9.61_T_SYNC_RISE_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.350	7.350	7.394	7.435
Average	7.350	7.382	7.433	7.476
Max	7.350	7.424	7.462	7.547
UL	15.000	15.000	15.000	15.000

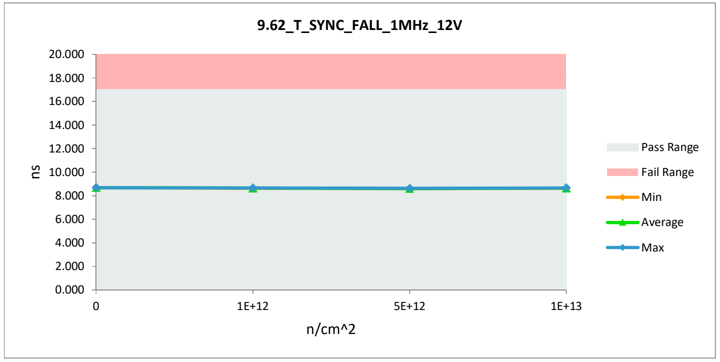


NDD Characterization Report
TPS7H5007-SEP

		9.62_T_SYNC_FALL_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.326	8.684	0.358
1E+12	21	8.244	8.659	0.415
1E+12	22	8.267	8.668	0.401
1E+12	23	8.263	8.634	0.371
5E+12	24	8.213	8.607	0.394
5E+12	25	8.261	8.596	0.335
5E+12	26	8.218	8.618	0.400
1E+13	27	8.258	8.667	0.409
1E+13	28	8.227	8.658	0.431
1E+13	29	8.196	8.634	0.438
	Max	8.326	8.684	0.438
	Average	8.247	8.643	0.395
	Min	8.196	8.596	0.335
	Std Dev	0.037	0.029	0.032

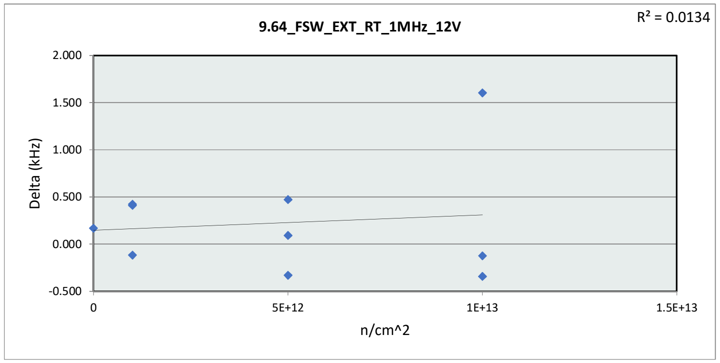


	9.62_T_SYNC_FALL_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.684	8.634	8.596	8.634
Average	8.684	8.654	8.607	8.653
Max	8.684	8.668	8.618	8.667
UL	17.000	17.000	17.000	17.000

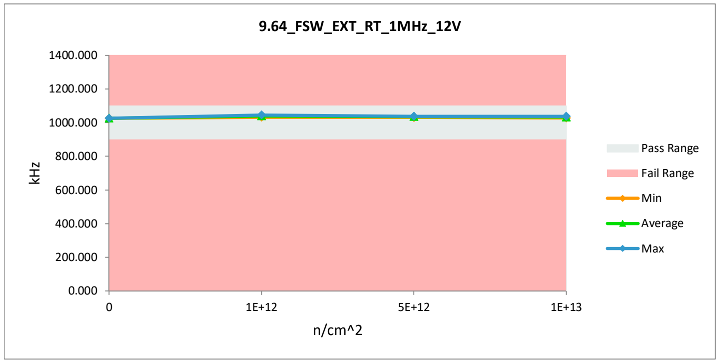


NDD Characterization Report
TPS7H5007-SEP

		9.64_FSW_EXT_RT_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1026.498	1026.666	0.168
1E+12	21	1045.697	1045.580	-0.117
1E+12	22	1041.089	1041.499	0.410
1E+12	23	1032.217	1032.640	0.423
5E+12	24	1038.659	1038.329	-0.330
5E+12	25	1037.197	1037.288	0.091
5E+12	26	1030.220	1030.691	0.471
1E+13	27	1028.010	1027.884	-0.126
1E+13	28	1031.883	1033.485	1.602
1E+13	29	1038.601	1038.257	-0.344
	Max	1045.697	1045.580	1.602
	Average	1035.007	1035.232	0.225
	Min	1026.498	1026.666	-0.344
	Std Dev	6.184	6.028	0.570

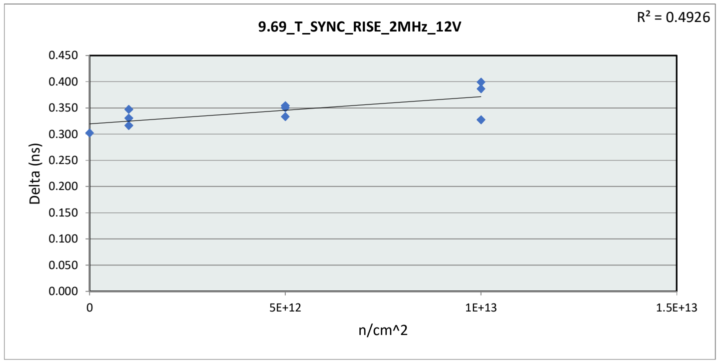


9.64_FSW_EXT_RT_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1026.666	1032.640	1030.691	1027.884
Average	1026.666	1039.906	1035.436	1033.209
Max	1026.666	1045.580	1038.329	1038.257
UL	1100.000	1100.000	1100.000	1100.000

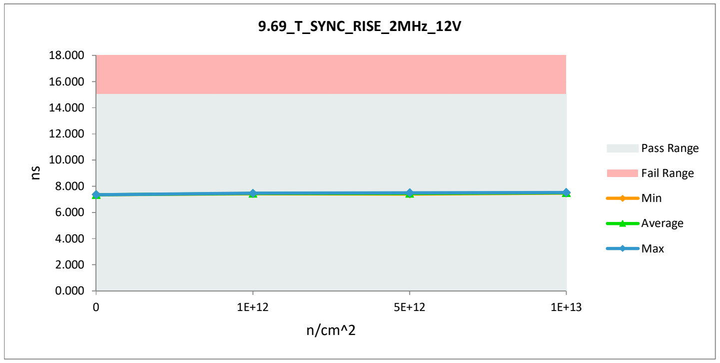


NDD Characterization Report
TPS7H5007-SEP

		9.69_T_SYNC_RISE_2MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.051	7.353	0.302
1E+12	21	7.117	7.433	0.316
1E+12	22	7.099	7.446	0.347
1E+12	23	7.134	7.464	0.330
5E+12	24	7.057	7.407	0.350
5E+12	25	7.101	7.455	0.354
5E+12	26	7.151	7.484	0.333
1E+13	27	7.125	7.524	0.399
1E+13	28	7.082	7.468	0.386
1E+13	29	7.195	7.522	0.327
	Max	7.195	7.524	0.399
	Average	7.111	7.456	0.344
	Min	7.051	7.353	0.302
	Std Dev	0.043	0.051	0.030

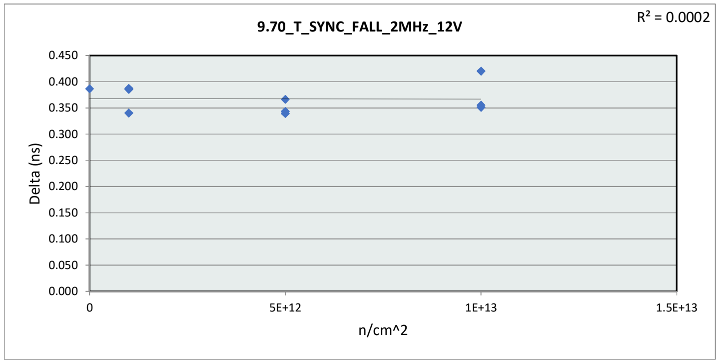


	9.69_T_SYNC_RISE_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.353	7.433	7.407	7.468
Average	7.353	7.448	7.449	7.505
Max	7.353	7.464	7.484	7.524
UL	15.000	15.000	15.000	15.000

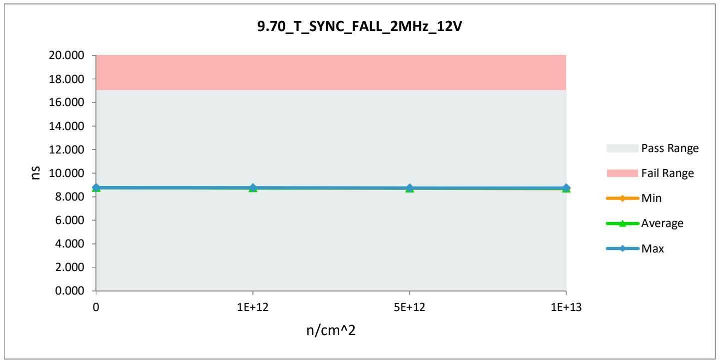


NDD Characterization Report
TPS7H5007-SEP

		9.70_T_SYNC_FALL_2MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.387	8.773	0.386
1E+12	21	8.345	8.732	0.387
1E+12	22	8.367	8.752	0.385
1E+12	23	8.430	8.770	0.340
5E+12	24	8.380	8.723	0.343
5E+12	25	8.388	8.727	0.339
5E+12	26	8.351	8.717	0.366
1E+13	27	8.323	8.674	0.351
1E+13	28	8.352	8.707	0.355
1E+13	29	8.325	8.745	0.420
	Max	8.430	8.773	0.420
	Average	8.365	8.732	0.367
	Min	8.323	8.674	0.339
	Std Dev	0.033	0.030	0.027

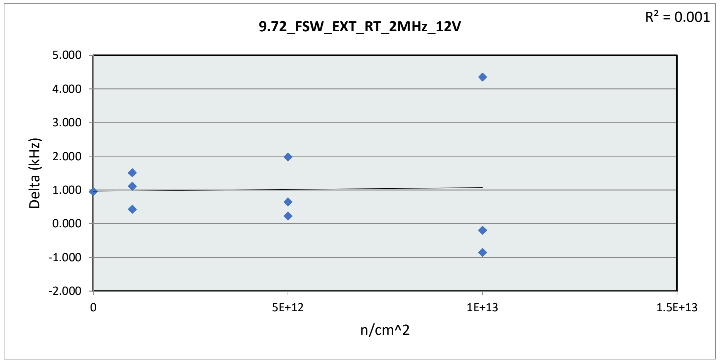


	9.70_T_SYNC_FALL_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.773	8.732	8.717	8.674
Average	8.773	8.751	8.722	8.709
Max	8.773	8.770	8.727	8.745
UL	17.000	17.000	17.000	17.000

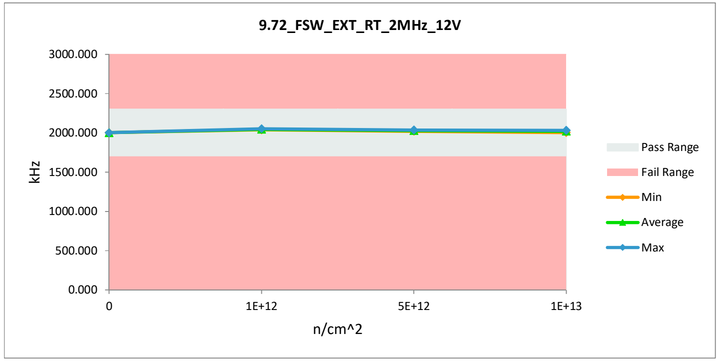


NDD Characterization Report
TPS7H5007-SEP

		9.72_FSW_EXT_RT_2MHz_12V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2001.621	2002.569	0.948
1E+12	21	2052.861	2053.282	0.421
1E+12	22	2041.222	2042.329	1.107
1E+12	23	2037.015	2038.518	1.503
5E+12	24	2035.848	2036.071	0.223
5E+12	25	2025.908	2026.554	0.646
5E+12	26	2019.774	2021.752	1.978
1E+13	27	2004.528	2004.332	-0.196
1E+13	28	2023.174	2027.525	4.351
1E+13	29	2032.853	2031.995	-0.858
	Max	2052.861	2053.282	4.351
	Average	2027.480	2028.493	1.012
	Min	2001.621	2002.569	-0.858
	Std Dev	15.982	15.924	1.430

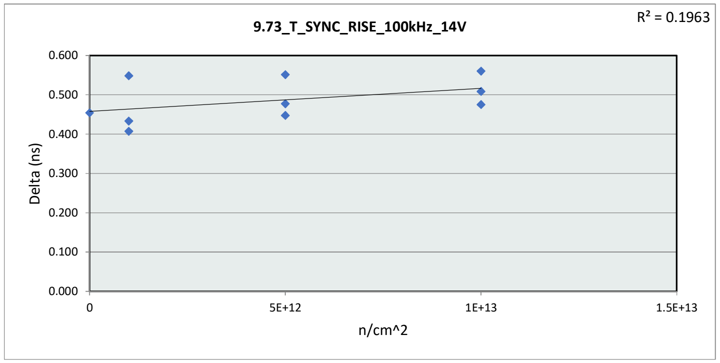


	9.72_FSW_EXT_RT_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	2002.569	2038.518	2021.752	2004.332
Average	2002.569	2044.710	2028.126	2021.284
Max	2002.569	2053.282	2036.071	2031.995
UL	2300.000	2300.000	2300.000	2300.000

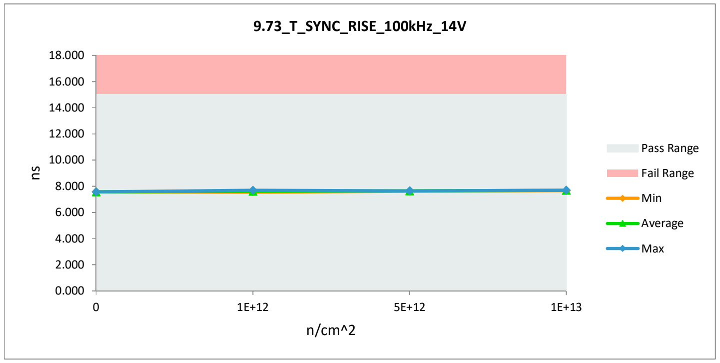


NDD Characterization Report
TPS7H5007-SEP

		9.73_T_SYNC_RISE_100kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.114	7.568	0.454
1E+12	21	7.149	7.556	0.407
1E+12	22	7.148	7.581	0.433
1E+12	23	7.141	7.689	0.548
5E+12	24	7.082	7.633	0.551
5E+12	25	7.150	7.627	0.477
5E+12	26	7.199	7.646	0.447
1E+13	27	7.220	7.695	0.475
1E+13	28	7.109	7.669	0.560
1E+13	29	7.180	7.688	0.508
	Max	7.220	7.695	0.560
	Average	7.149	7.635	0.486
	Min	7.082	7.556	0.407
	Std Dev	0.042	0.052	0.054

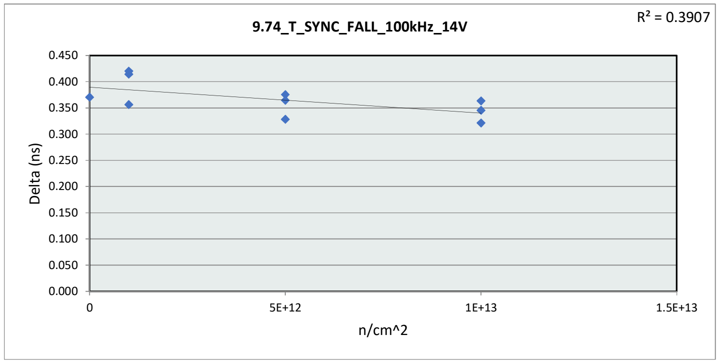


	9.73_T_SYNC_RISE_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.568	7.556	7.627	7.669
Average	7.568	7.609	7.635	7.684
Max	7.568	7.689	7.646	7.695
UL	15.000	15.000	15.000	15.000

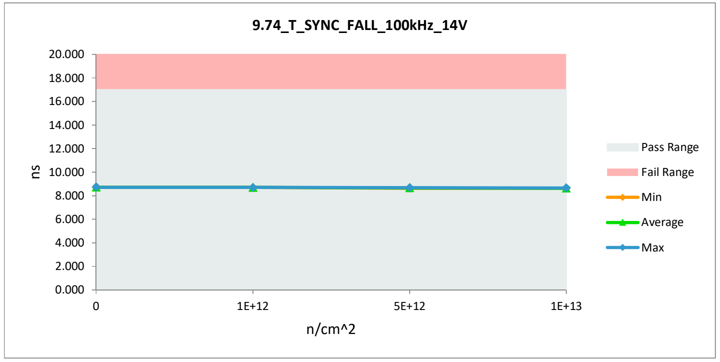


NDD Characterization Report
TPS7H5007-SEP

		9.74_T_SYNC_FALL_100kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.353	8.723	0.370
1E+12	21	8.285	8.705	0.420
1E+12	22	8.341	8.697	0.356
1E+12	23	8.280	8.694	0.414
5E+12	24	8.309	8.637	0.328
5E+12	25	8.310	8.674	0.364
5E+12	26	8.302	8.677	0.375
1E+13	27	8.263	8.626	0.363
1E+13	28	8.320	8.665	0.345
1E+13	29	8.305	8.626	0.321
	Max	8.353	8.723	0.420
	Average	8.307	8.672	0.366
	Min	8.263	8.626	0.321
	Std Dev	0.027	0.034	0.032

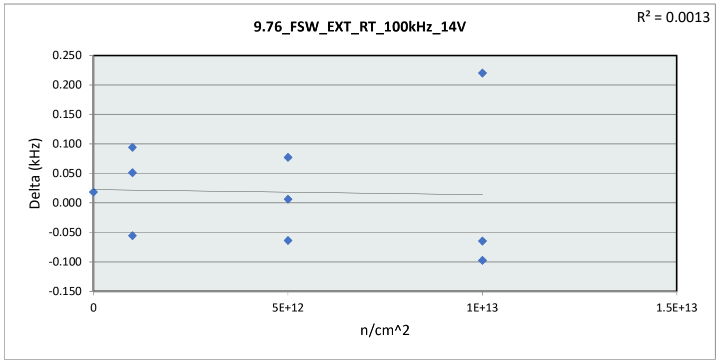


	9.74_T_SYNC_FALL_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.723	8.694	8.637	8.626
Average	8.723	8.699	8.663	8.639
Max	8.723	8.705	8.677	8.665
UL	17.000	17.000	17.000	17.000

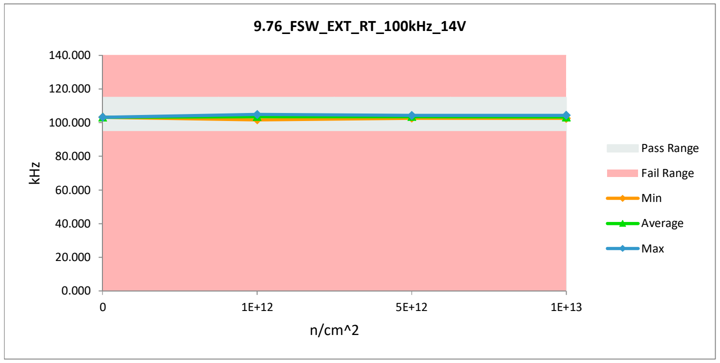


NDD Characterization Report
TPS7H5007-SEP

		9.76_FSW_EXT_RT_100kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	103.173	103.191	0.018
1E+12	21	104.877	104.821	-0.056
1E+12	22	104.107	104.201	0.094
1E+12	23	101.564	101.615	0.051
5E+12	24	103.819	103.755	-0.064
5E+12	25	104.230	104.236	0.006
5E+12	26	102.579	102.656	0.077
1E+13	27	102.637	102.572	-0.065
1E+13	28	103.016	103.236	0.220
1E+13	29	104.437	104.339	-0.098
	Max	104.877	104.821	0.220
	Average	103.444	103.462	0.018
	Min	101.564	101.615	-0.098
	Std Dev	1.024	0.990	0.097

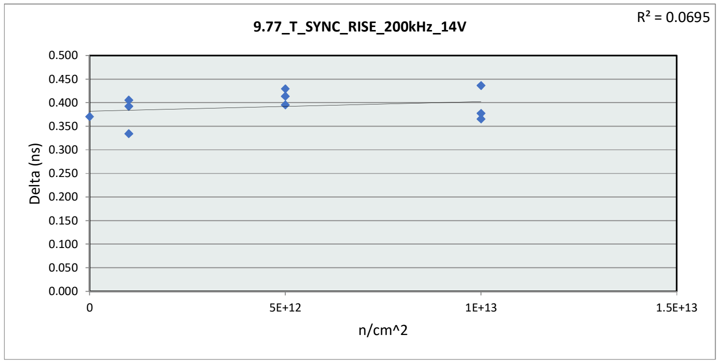


	9.76_FSW_EXT_RT_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.191	101.615	102.656	102.572
Average	103.191	103.546	103.549	103.382
Max	103.191	104.821	104.236	104.339
UL	115.000	115.000	115.000	115.000

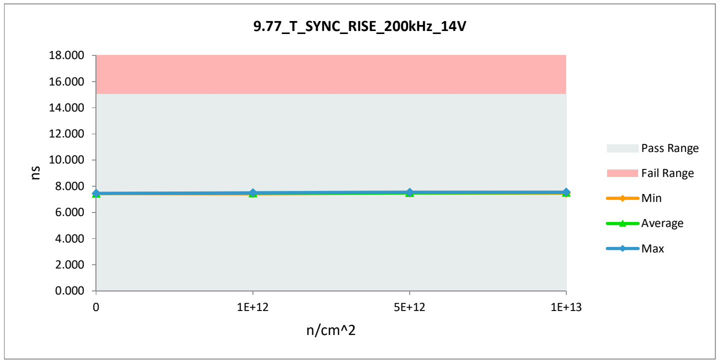


NDD Characterization Report
TPS7H5007-SEP

		9.77_T_SYNC_RISE_200kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.081	7.451	0.370
1E+12	21	7.076	7.481	0.405
1E+12	22	7.094	7.428	0.334
1E+12	23	7.117	7.509	0.392
5E+12	24	7.082	7.477	0.395
5E+12	25	7.081	7.494	0.413
5E+12	26	7.108	7.537	0.429
1E+13	27	7.179	7.544	0.365
1E+13	28	7.087	7.464	0.377
1E+13	29	7.103	7.539	0.436
	Max	7.179	7.544	0.436
	Average	7.101	7.492	0.392
	Min	7.076	7.428	0.334
	Std Dev	0.031	0.040	0.031

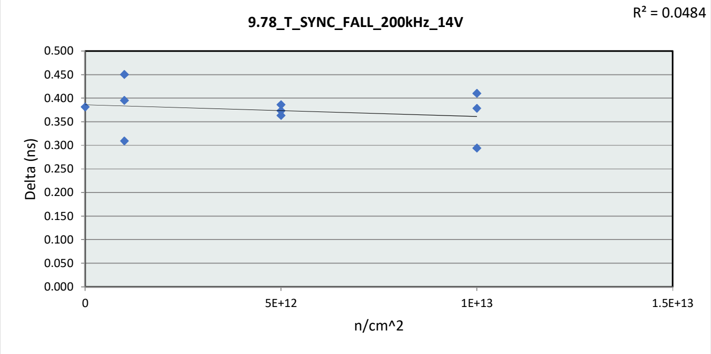


	9.77_T_SYNC_RISE_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.451	7.428	7.477	7.464
Average	7.451	7.473	7.503	7.516
Max	7.451	7.509	7.537	7.544
UL	15.000	15.000	15.000	15.000

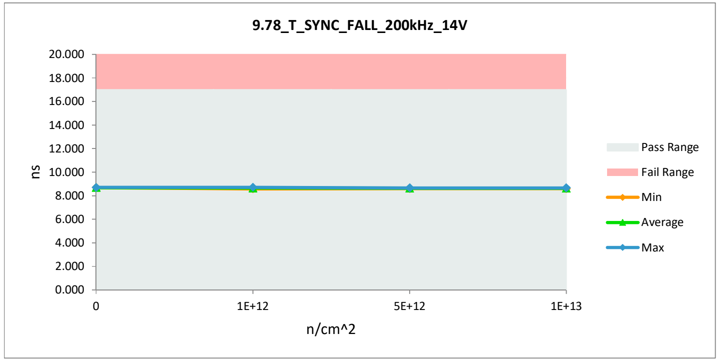


NDD Characterization Report
TPS7H5007-SEP

		9.78_T_SYNC_FALL_200kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.310	8.691	0.381
1E+12	21	8.257	8.707	0.450
1E+12	22	8.260	8.655	0.395
1E+12	23	8.272	8.581	0.309
5E+12	24	8.241	8.604	0.363
5E+12	25	8.283	8.669	0.386
5E+12	26	8.262	8.635	0.373
1E+13	27	8.304	8.598	0.294
1E+13	28	8.250	8.660	0.410
1E+13	29	8.242	8.620	0.378
	Max	8.310	8.707	0.450
	Average	8.268	8.642	0.374
	Min	8.241	8.581	0.294
	Std Dev	0.024	0.041	0.045

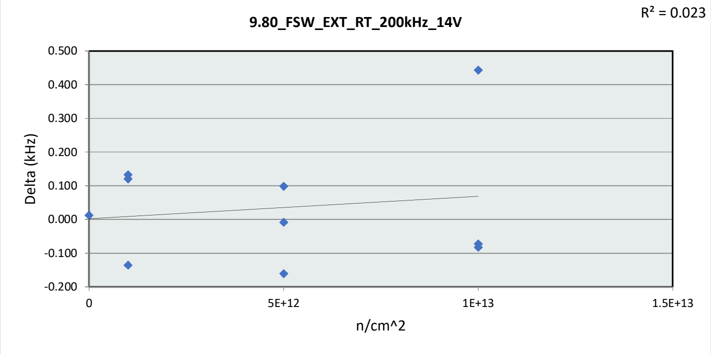


	9.78_T_SYNC_FALL_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.691	8.581	8.604	8.598
Average	8.691	8.648	8.636	8.626
Max	8.691	8.707	8.669	8.660
UL	17.000	17.000	17.000	17.000

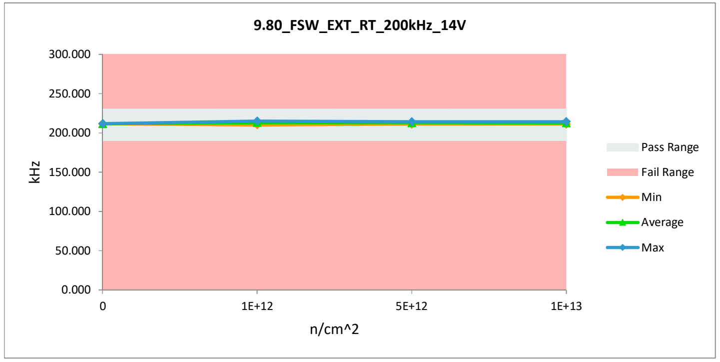


NDD Characterization Report
TPS7H5007-SEP

		9.80_FSW_EXT_RT_200kHz_14V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	211.677	211.689	0.012
1E+12	21	215.174	215.038	-0.136
1E+12	22	214.097	214.229	0.132
1E+12	23	210.004	210.124	0.120
5E+12	24	213.590	213.429	-0.161
5E+12	25	213.979	213.970	-0.009
5E+12	26	211.085	211.183	0.098
1E+13	27	211.187	211.114	-0.073
1E+13	28	211.783	212.226	0.443
1E+13	29	214.372	214.289	-0.083
	Max	215.174	215.038	0.443
	Average	212.695	212.729	0.034
	Min	210.004	210.124	-0.161
	Std Dev	1.743	1.672	0.177

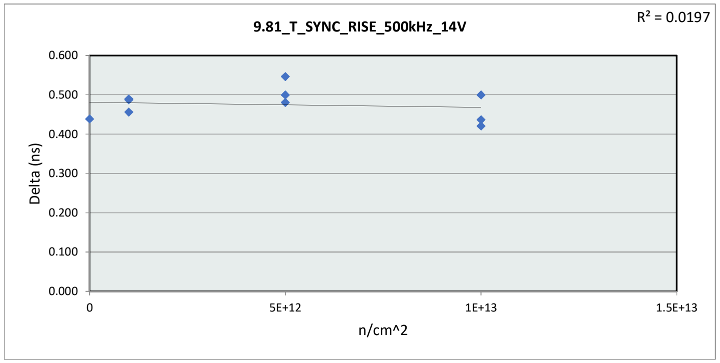


	9.80_FSW_EXT_RT_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	211.689	210.124	211.183	211.114
Average	211.689	213.130	212.861	212.543
Max	211.689	215.038	213.970	214.289
UL	230.000	230.000	230.000	230.000

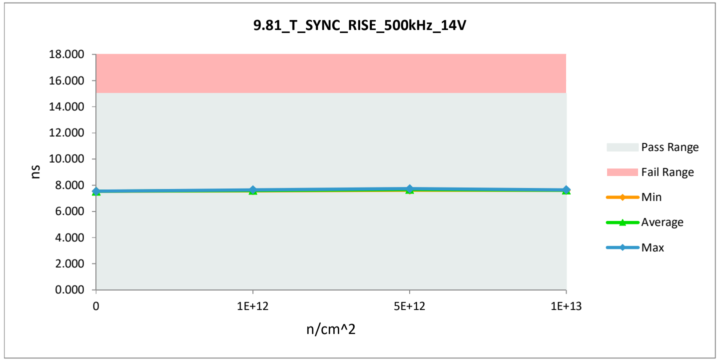


NDD Characterization Report
TPS7H5007-SEP

		9.81_T_SYNC_RISE_500kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.101	7.539	0.438
1E+12	21	7.115	7.571	0.456
1E+12	22	7.089	7.576	0.487
1E+12	23	7.161	7.650	0.489
5E+12	24	7.117	7.616	0.499
5E+12	25	7.185	7.731	0.546
5E+12	26	7.182	7.662	0.480
1E+13	27	7.238	7.658	0.420
1E+13	28	7.113	7.612	0.499
1E+13	29	7.179	7.615	0.436
	Max	7.238	7.731	0.546
	Average	7.148	7.623	0.475
	Min	7.089	7.539	0.420
	Std Dev	0.048	0.055	0.038

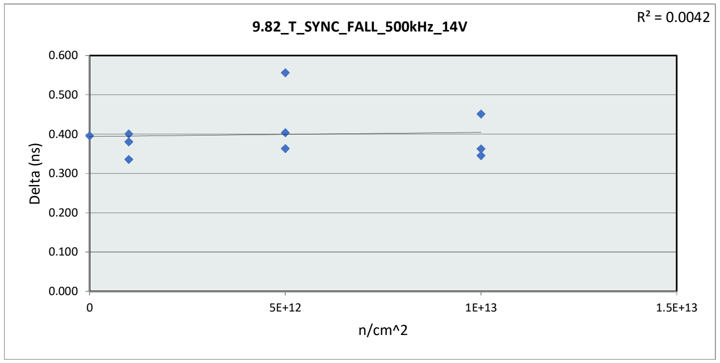


	9.81_T_SYNC_RISE_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.539	7.571	7.616	7.612
Average	7.539	7.599	7.670	7.628
Max	7.539	7.650	7.731	7.658
UL	15.000	15.000	15.000	15.000

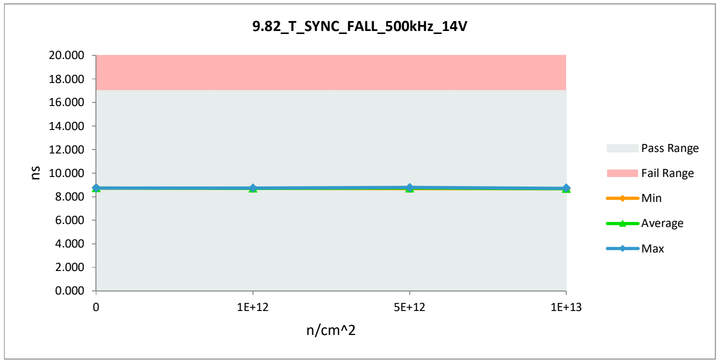


NDD Characterization Report
TPS7H5007-SEP

		9.82_T_SYNC_FALL_500kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.349	8.744	0.395
1E+12	21	8.339	8.719	0.380
1E+12	22	8.357	8.692	0.335
1E+12	23	8.328	8.728	0.400
5E+12	24	8.310	8.713	0.403
5E+12	25	8.227	8.783	0.556
5E+12	26	8.318	8.681	0.363
1E+13	27	8.310	8.672	0.362
1E+13	28	8.330	8.675	0.345
1E+13	29	8.271	8.722	0.451
	Max	8.357	8.783	0.556
	Average	8.314	8.713	0.399
	Min	8.227	8.672	0.335
	Std Dev	0.039	0.035	0.064

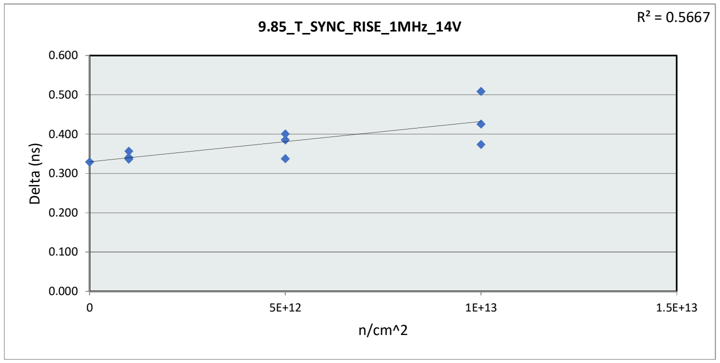


	9.82_T_SYNC_FALL_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.744	8.692	8.681	8.672
Average	8.744	8.713	8.726	8.690
Max	8.744	8.728	8.783	8.722
UL	17.000	17.000	17.000	17.000

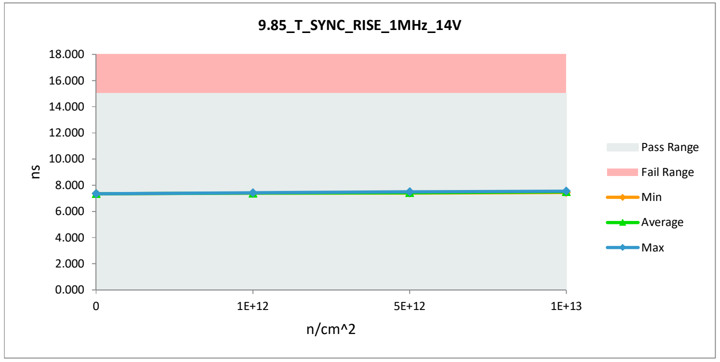


NDD Characterization Report
TPS7H5007-SEP

		9.85_T_SYNC_RISE_1MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.029	7.358	0.329
1E+12	21	7.025	7.381	0.356
1E+12	22	7.045	7.381	0.336
1E+12	23	7.078	7.418	0.340
5E+12	24	7.017	7.402	0.385
5E+12	25	7.027	7.427	0.400
5E+12	26	7.146	7.483	0.337
1E+13	27	7.130	7.555	0.425
1E+13	28	6.987	7.495	0.508
1E+13	29	7.072	7.445	0.373
	Max	7.146	7.555	0.508
	Average	7.056	7.434	0.379
	Min	6.987	7.358	0.329
	Std Dev	0.051	0.061	0.055



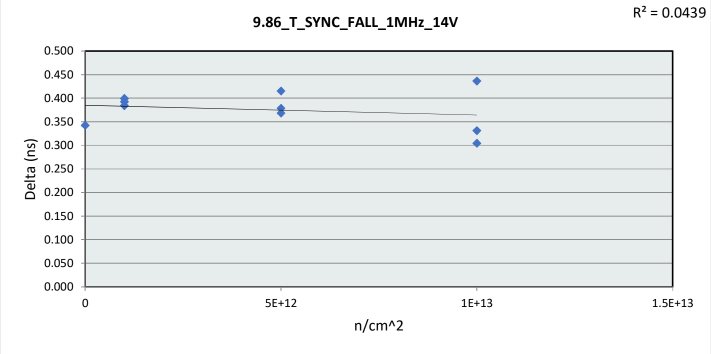
9.85_T_SYNC_RISE_1MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.358	7.381	7.402	7.445
Average	7.358	7.393	7.437	7.498
Max	7.358	7.418	7.483	7.555
UL	15.000	15.000	15.000	15.000



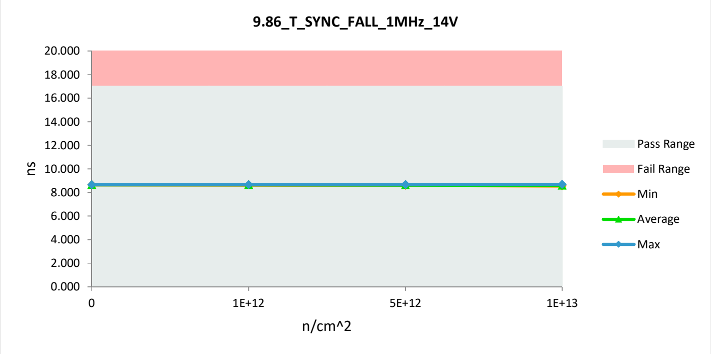
NDD Characterization Report
TPS7H5007-SEP

	9.86_T_SYNC_FALL_1MHz_14V		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	14	17	
Min Limit	0	0	

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.306	8.648	0.342
1E+12	21	8.274	8.666	0.392
1E+12	22	8.226	8.625	0.399
1E+12	23	8.264	8.648	0.384
5E+12	24	8.222	8.600	0.378
5E+12	25	8.265	8.633	0.368
5E+12	26	8.244	8.659	0.415
1E+13	27	8.228	8.559	0.331
1E+13	28	8.243	8.679	0.436
1E+13	29	8.241	8.545	0.304
	Max	8.306	8.679	0.436
	Average	8.251	8.626	0.375
	Min	8.222	8.545	0.304
	Std Dev	0.026	0.045	0.040

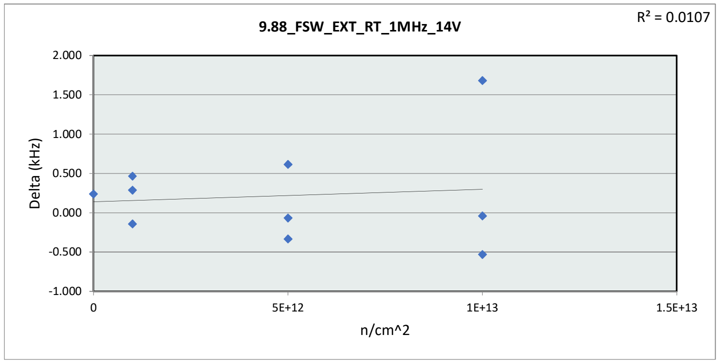


	9.86_T_SYNC_FALL_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.648	8.625	8.600	8.545
Average	8.648	8.646	8.631	8.594
Max	8.648	8.666	8.659	8.679
UL	17.000	17.000	17.000	17.000

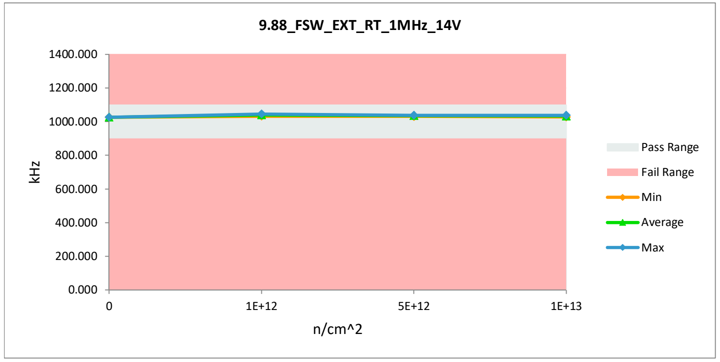


NDD Characterization Report
TPS7H5007-SEP

		9.88_FSW_EXT_RT_1MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1026.492	1026.728	0.236
1E+12	21	1045.676	1045.531	-0.145
1E+12	22	1041.073	1041.357	0.284
1E+12	23	1032.241	1032.705	0.464
5E+12	24	1038.677	1038.341	-0.336
5E+12	25	1037.166	1037.097	-0.069
5E+12	26	1029.990	1030.603	0.613
1E+13	27	1027.911	1027.869	-0.042
1E+13	28	1031.743	1033.423	1.680
1E+13	29	1038.649	1038.115	-0.534
	Max	1045.676	1045.531	1.680
	Average	1034.962	1035.177	0.215
	Min	1026.492	1026.728	-0.534
	Std Dev	6.221	5.987	0.625

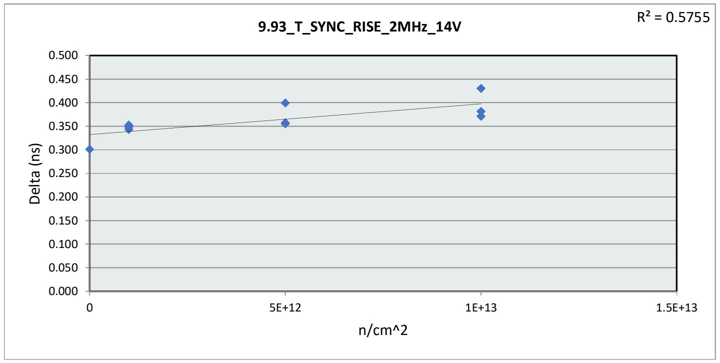


	9.88_FSW_EXT_RT_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1026.728	1032.705	1030.603	1027.869
Average	1026.728	1039.864	1035.347	1033.136
Max	1026.728	1045.531	1038.341	1038.115
UL	1100.000	1100.000	1100.000	1100.000

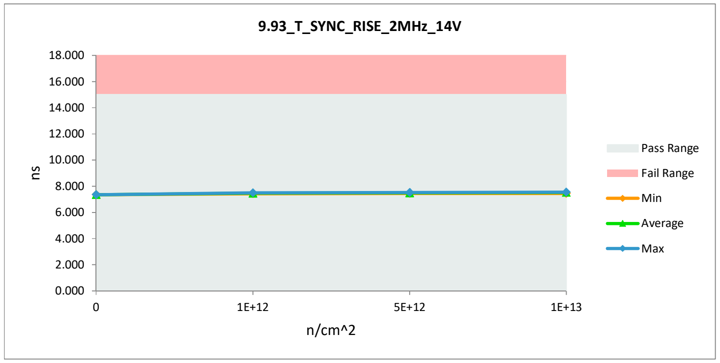


NDD Characterization Report
TPS7H5007-SEP

		9.93_T_SYNC_RISE_2MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.057	7.358	0.301
1E+12	21	7.094	7.437	0.343
1E+12	22	7.114	7.462	0.348
1E+12	23	7.135	7.487	0.352
5E+12	24	7.084	7.483	0.399
5E+12	25	7.101	7.458	0.357
5E+12	26	7.168	7.523	0.355
1E+13	27	7.152	7.523	0.371
1E+13	28	7.077	7.458	0.381
1E+13	29	7.125	7.555	0.430
	Max	7.168	7.555	0.430
	Average	7.111	7.474	0.364
	Min	7.057	7.358	0.301
	Std Dev	0.035	0.055	0.035

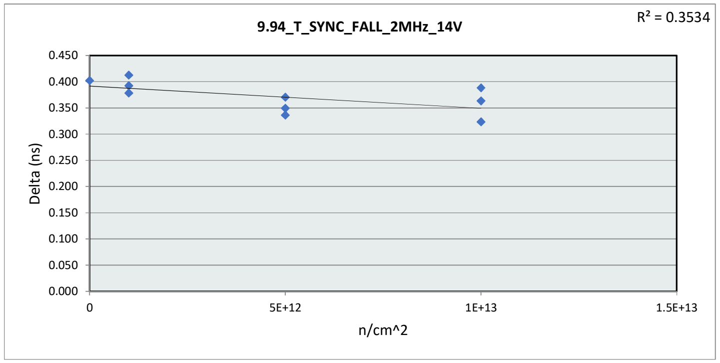


	9.93_T_SYNC_RISE_2MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.358	7.437	7.458	7.458
Average	7.358	7.462	7.488	7.512
Max	7.358	7.487	7.523	7.555
UL	15.000	15.000	15.000	15.000

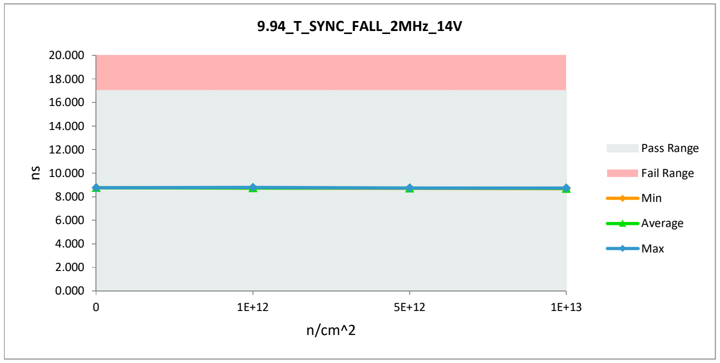


NDD Characterization Report
TPS7H5007-SEP

		9.94_T_SYNC_FALL_2MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.354	8.756	0.402
1E+12	21	8.377	8.789	0.412
1E+12	22	8.349	8.727	0.378
1E+12	23	8.336	8.728	0.392
5E+12	24	8.380	8.716	0.336
5E+12	25	8.396	8.745	0.349
5E+12	26	8.350	8.720	0.370
1E+13	27	8.308	8.671	0.363
1E+13	28	8.340	8.728	0.388
1E+13	29	8.373	8.696	0.323
	Max	8.396	8.789	0.412
	Average	8.356	8.728	0.371
	Min	8.308	8.671	0.323
	Std Dev	0.026	0.032	0.029

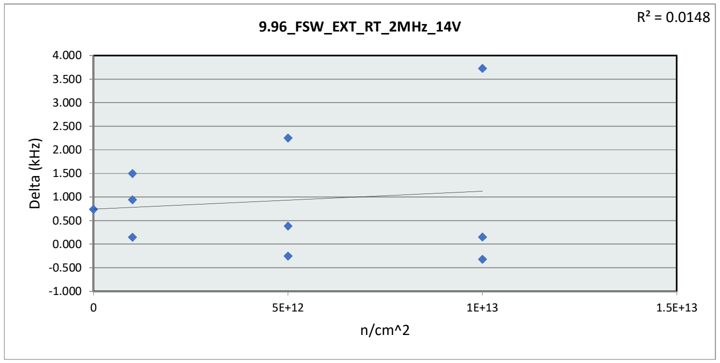


9.94_T_SYNC_FALL_2MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.756	8.727	8.716	8.671
Average	8.756	8.748	8.727	8.698
Max	8.756	8.789	8.745	8.728
UL	17.000	17.000	17.000	17.000

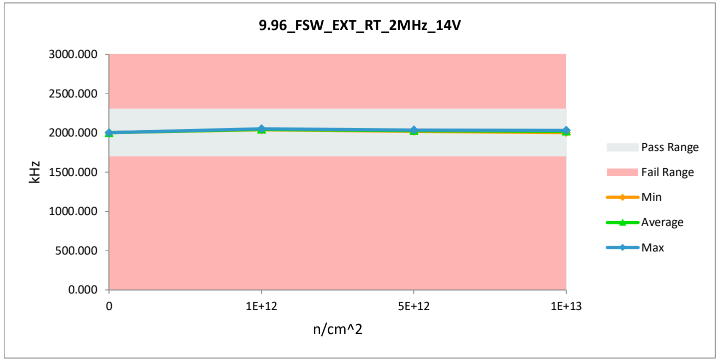


NDD Characterization Report
TPS7H5007-SEP

		9.96_FSW_EXT_RT_2MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2001.568	2002.301	0.733
1E+12	21	2052.750	2052.895	0.145
1E+12	22	2040.858	2041.794	0.936
1E+12	23	2037.126	2038.623	1.497
5E+12	24	2035.908	2035.652	-0.256
5E+12	25	2026.068	2026.448	0.380
5E+12	26	2019.312	2021.561	2.249
1E+13	27	2004.047	2004.196	0.149
1E+13	28	2022.913	2026.635	3.722
1E+13	29	2032.206	2031.882	-0.324
	Max	2052.750	2052.895	3.722
	Average	2027.276	2028.199	0.923
	Min	2001.568	2002.301	-0.324
	Std Dev	16.033	15.878	1.265

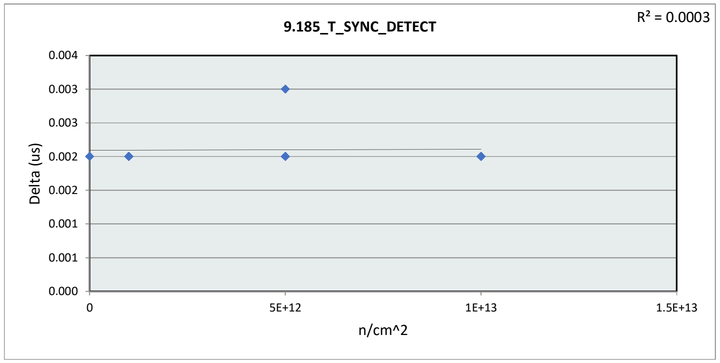


	9.96_FSW_EXT_RT_2MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	2002.301	2038.623	2021.561	2004.196
Average	2002.301	2044.437	2027.887	2020.904
Max	2002.301	2052.895	2035.652	2031.882
UL	2300.000	2300.000	2300.000	2300.000

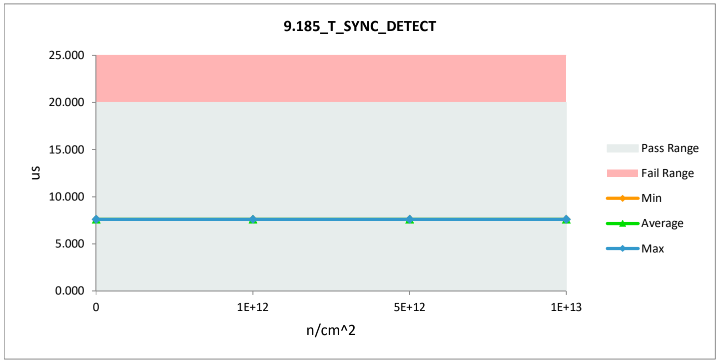


NDD Characterization Report
TPS7H5007-SEP

		9.185_T_SYNC_DETECT		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	12	20	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.587	7.589	0.002
1E+12	21	7.588	7.590	0.002
1E+12	22	7.588	7.590	0.002
1E+12	23	7.588	7.590	0.002
5E+12	24	7.587	7.589	0.002
5E+12	25	7.587	7.590	0.003
5E+12	26	7.588	7.590	0.002
1E+13	27	7.589	7.591	0.002
1E+13	28	7.587	7.589	0.002
1E+13	29	7.587	7.589	0.002
	Max	7.589	7.591	0.003
	Average	7.588	7.590	0.002
	Min	7.587	7.589	0.002
	Std Dev	0.001	0.001	0.000

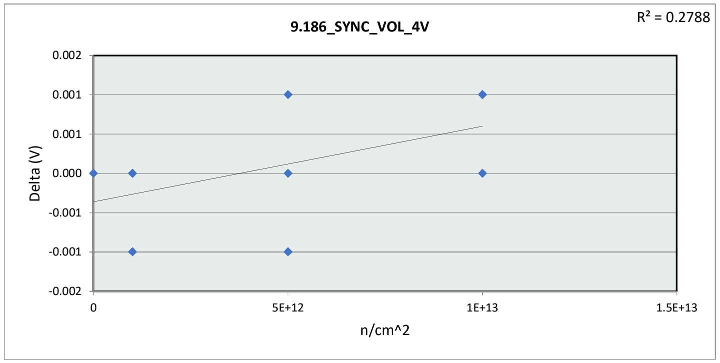


9.185_T_SYNC_DETECT				
Test Site				
Tester				
Test Number				
Max Limit	20	us		
Min Limit	0	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.589	7.590	7.589	7.589
Average	7.589	7.590	7.590	7.590
Max	7.589	7.590	7.590	7.591
UL	20.000	20.000	20.000	20.000

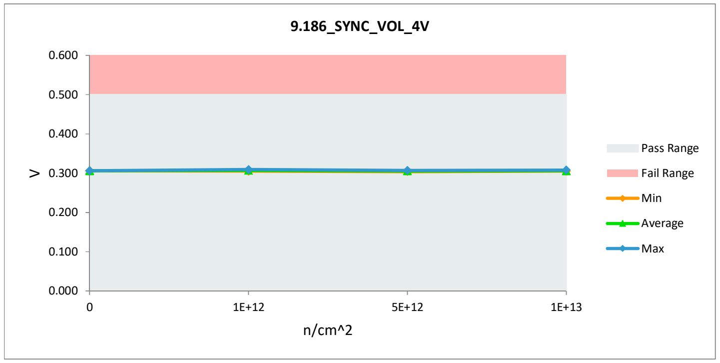


NDD Characterization Report
TPS7H5007-SEP

		9.186_SYNC_VOL_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.306	0.306	0.000
1E+12	21	0.309	0.309	0.000
1E+12	22	0.306	0.306	0.000
1E+12	23	0.306	0.305	-0.001
5E+12	24	0.305	0.304	-0.001
5E+12	25	0.306	0.306	0.000
5E+12	26	0.306	0.307	0.001
1E+13	27	0.305	0.305	0.000
1E+13	28	0.307	0.308	0.001
1E+13	29	0.304	0.305	0.001
	Max	0.309	0.309	0.001
	Average	0.306	0.306	0.000
	Min	0.304	0.304	-0.001
	Std Dev	0.001	0.002	0.001

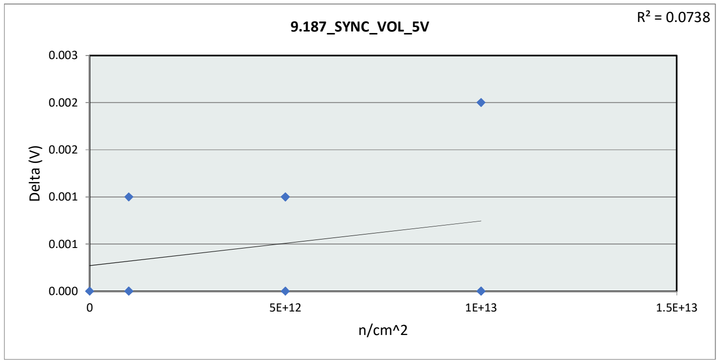


	9.186_SYNC_VOL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit	0	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	0.306	0.305	0.304	0.305
Average	0.306	0.307	0.306	0.306
Max	0.306	0.309	0.307	0.308
UL	0.500	0.500	0.500	0.500

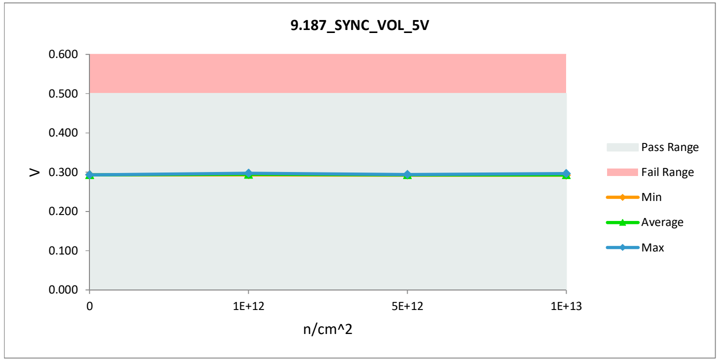


NDD Characterization Report
TPS7H5007-SEP

		9.187_SYNC_VOL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.293	0.293	0.000
1E+12	21	0.296	0.297	0.001
1E+12	22	0.293	0.293	0.000
1E+12	23	0.293	0.293	0.000
5E+12	24	0.292	0.292	0.000
5E+12	25	0.292	0.293	0.001
5E+12	26	0.293	0.294	0.001
1E+13	27	0.292	0.292	0.000
1E+13	28	0.294	0.296	0.002
1E+13	29	0.292	0.292	0.000
	Max	0.296	0.297	0.002
	Average	0.293	0.294	0.000
	Min	0.292	0.292	0.000
	Std Dev	0.001	0.002	0.001

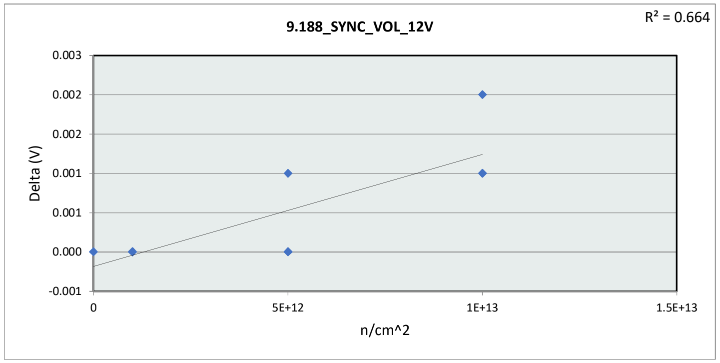


9.187_SYNC_VOL_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit	0	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	0.293	0.293	0.292	0.292
Average	0.293	0.294	0.293	0.293
Max	0.293	0.297	0.294	0.296
UL	0.500	0.500	0.500	0.500

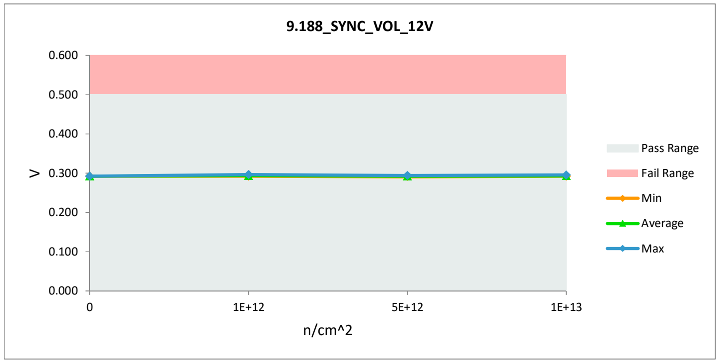


NDD Characterization Report
TPS7H5007-SEP

		9.188_SYNC_VOL_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.292	0.292	0.000
1E+12	21	0.296	0.296	0.000
1E+12	22	0.293	0.293	0.000
1E+12	23	0.292	0.292	0.000
5E+12	24	0.291	0.291	0.000
5E+12	25	0.292	0.292	0.000
5E+12	26	0.293	0.294	0.001
1E+13	27	0.291	0.292	0.001
1E+13	28	0.293	0.295	0.002
1E+13	29	0.291	0.292	0.001
	Max	0.296	0.296	0.002
	Average	0.292	0.293	0.000
	Min	0.291	0.291	0.000
	Std Dev	0.002	0.002	0.001

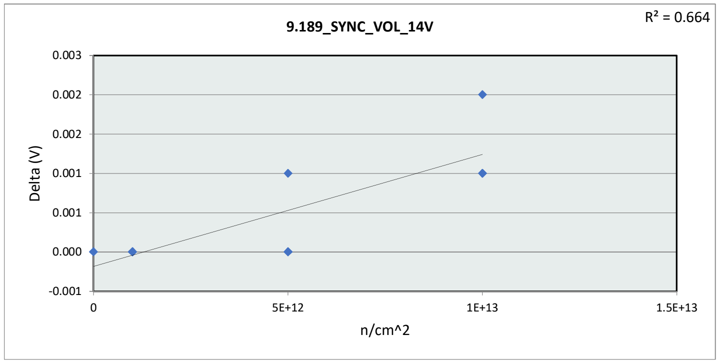


9.188_SYNC_VOL_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit	0	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	0.292	0.292	0.291	0.292
Average	0.292	0.294	0.292	0.293
Max	0.292	0.296	0.294	0.295
UL	0.500	0.500	0.500	0.500

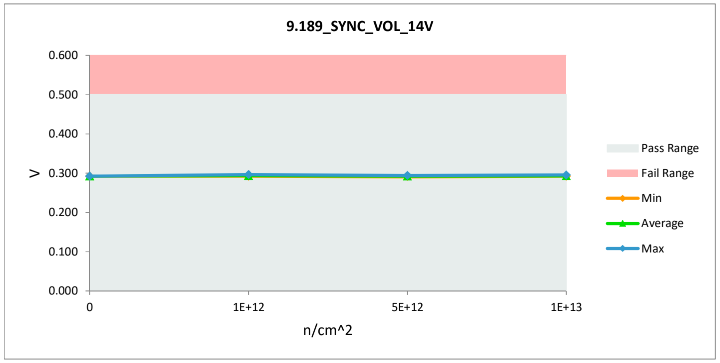


NDD Characterization Report
TPS7H5007-SEP

		9.189_SYNC_VOL_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.5	0.5	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.292	0.292	0.000
1E+12	21	0.296	0.296	0.000
1E+12	22	0.293	0.293	0.000
1E+12	23	0.292	0.292	0.000
5E+12	24	0.291	0.291	0.000
5E+12	25	0.292	0.292	0.000
5E+12	26	0.293	0.294	0.001
1E+13	27	0.291	0.292	0.001
1E+13	28	0.293	0.295	0.002
1E+13	29	0.291	0.292	0.001
	Max	0.296	0.296	0.002
	Average	0.292	0.293	0.000
	Min	0.291	0.291	0.000
	Std Dev	0.002	0.002	0.001

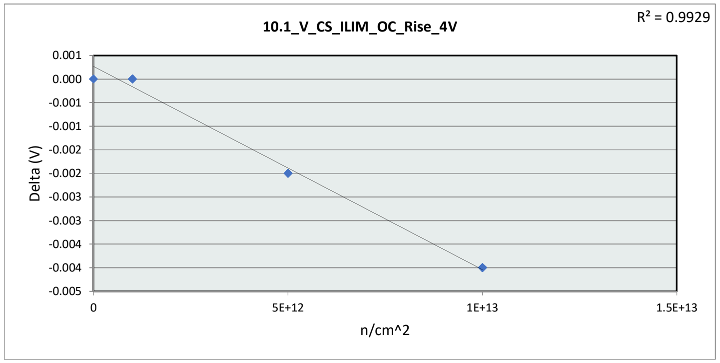


	9.189_SYNC_VOL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit	0	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	0.292	0.292	0.291	0.292
Average	0.292	0.294	0.292	0.293
Max	0.292	0.296	0.294	0.295
UL	0.500	0.500	0.500	0.500

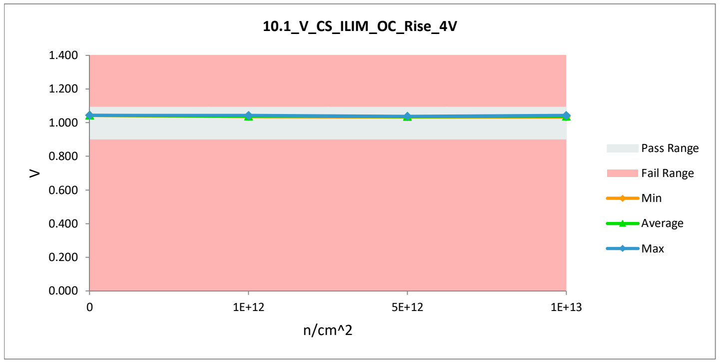


NDD Characterization Report
TPS7H5007-SEP

		10.1_V_CS_ILIM_OC_Rise_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.08	1.09	
	Min Limit	0.95	0.9	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.044	1.044	0.000
1E+12	21	1.042	1.042	0.000
1E+12	22	1.036	1.036	0.000
1E+12	23	1.040	1.040	0.000
5E+12	24	1.040	1.038	-0.002
5E+12	25	1.036	1.034	-0.002
5E+12	26	1.040	1.038	-0.002
1E+13	27	1.042	1.038	-0.004
1E+13	28	1.038	1.034	-0.004
1E+13	29	1.046	1.042	-0.004
	Max	1.046	1.044	0.000
	Average	1.040	1.039	-0.002
	Min	1.036	1.034	-0.004
	Std Dev	0.003	0.003	0.002

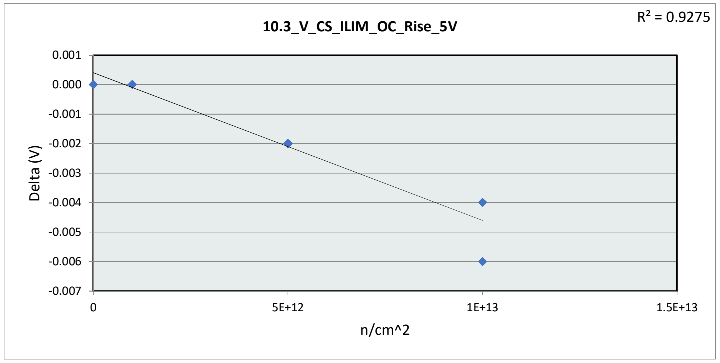


	10.1_V_CS_ILIM_OC_Rise_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit	0.9	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.900	0.900	0.900	0.900
Min	1.044	1.036	1.034	1.034
Average	1.044	1.039	1.037	1.038
Max	1.044	1.042	1.038	1.042
UL	1.090	1.090	1.090	1.090

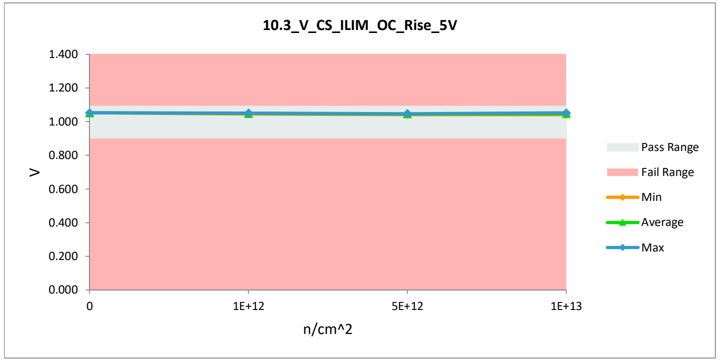


NDD Characterization Report
TPS7H5007-SEP

		10.3_V_CS_ILIM_OC_Rise_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.08	1.09	
	Min Limit	0.95	0.9	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.052	1.052	0.000
1E+12	21	1.050	1.050	0.000
1E+12	22	1.046	1.046	0.000
1E+12	23	1.048	1.048	0.000
5E+12	24	1.050	1.048	-0.002
5E+12	25	1.044	1.042	-0.002
5E+12	26	1.050	1.048	-0.002
1E+13	27	1.052	1.048	-0.004
1E+13	28	1.048	1.042	-0.006
1E+13	29	1.056	1.052	-0.004
	Max	1.056	1.052	0.000
	Average	1.050	1.048	-0.002
	Min	1.044	1.042	-0.006
	Std Dev	0.003	0.004	0.002

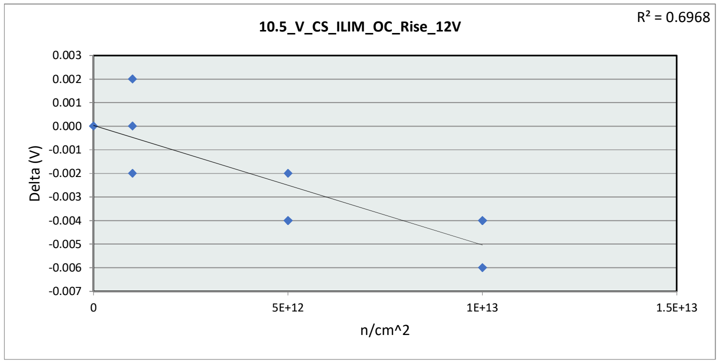


	10.3_V_CS_ILIM_OC_Rise_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit	0.9	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.900	0.900	0.900	0.900
Min	1.052	1.046	1.042	1.042
Average	1.052	1.048	1.046	1.047
Max	1.052	1.050	1.048	1.052
UL	1.090	1.090	1.090	1.090

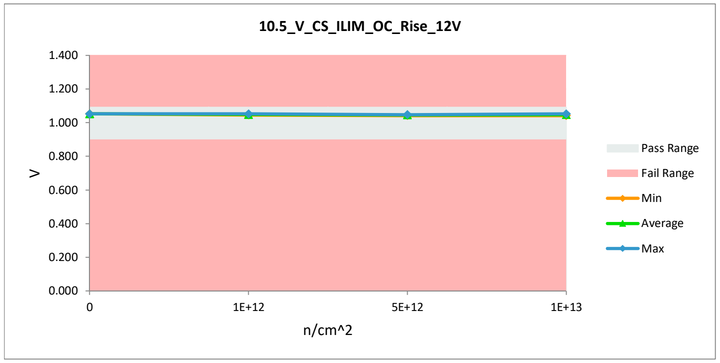


NDD Characterization Report
TPS7H5007-SEP

		10.5_V_CS_ILIM_OC_Rise_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.08	1.09	
	Min Limit	0.95	0.9	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.052	1.052	0.000
1E+12	21	1.050	1.052	0.002
1E+12	22	1.046	1.046	0.000
1E+12	23	1.050	1.048	-0.002
5E+12	24	1.052	1.048	-0.004
5E+12	25	1.046	1.042	-0.004
5E+12	26	1.050	1.048	-0.002
1E+13	27	1.052	1.048	-0.004
1E+13	28	1.048	1.042	-0.006
1E+13	29	1.056	1.052	-0.004
	Max	1.056	1.052	0.002
	Average	1.050	1.048	-0.002
	Min	1.046	1.042	-0.006
	Std Dev	0.003	0.004	0.002

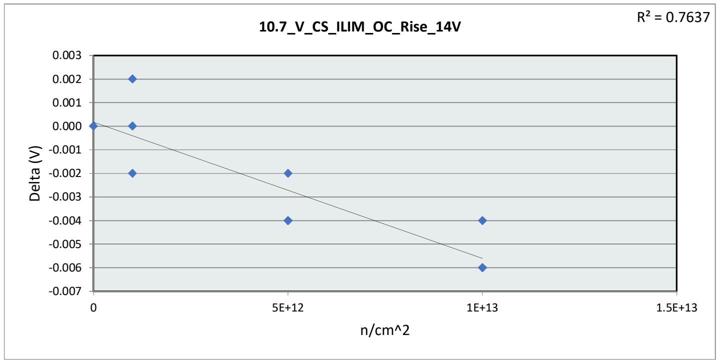


	10.5_V_CS_ILIM_OC_Rise_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit	0.9	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.900	0.900	0.900	0.900
Min	1.052	1.046	1.042	1.042
Average	1.052	1.049	1.046	1.047
Max	1.052	1.052	1.048	1.052
UL	1.090	1.090	1.090	1.090

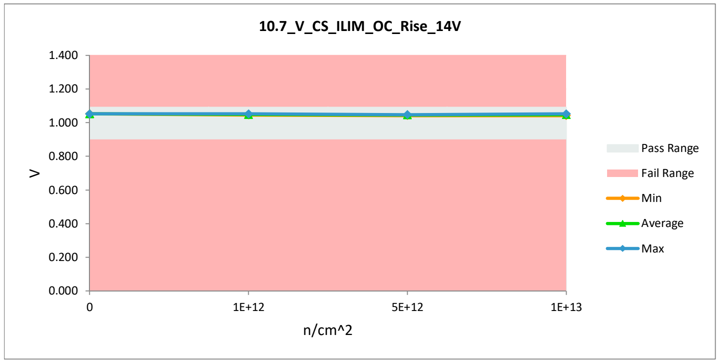


NDD Characterization Report
TPS7H5007-SEP

		10.7_V_CS_ILIM_OC_Rise_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.08	1.09	
	Min Limit	0.95	0.9	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	1.052	1.052	0.000
1E+12	21	1.050	1.052	0.002
1E+12	22	1.046	1.046	0.000
1E+12	23	1.050	1.048	-0.002
5E+12	24	1.052	1.048	-0.004
5E+12	25	1.046	1.042	-0.004
5E+12	26	1.050	1.048	-0.002
1E+13	27	1.052	1.048	-0.004
1E+13	28	1.048	1.042	-0.006
1E+13	29	1.058	1.052	-0.006
	Max	1.058	1.052	0.002
	Average	1.050	1.048	-0.003
	Min	1.046	1.042	-0.006
	Std Dev	0.004	0.004	0.003

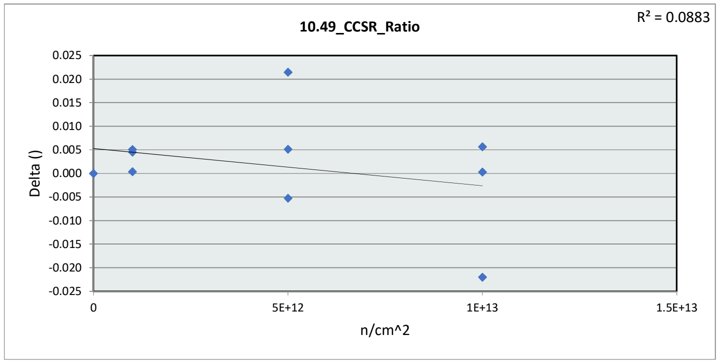


	10.7_V_CS_ILIM_OC_Rise_14			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit	0.9	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.900	0.900	0.900	0.900
Min	1.052	1.046	1.042	1.042
Average	1.052	1.049	1.046	1.047
Max	1.052	1.052	1.048	1.052
UL	1.090	1.090	1.090	1.090

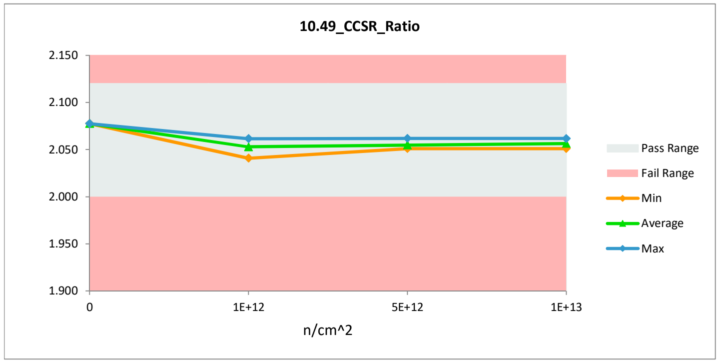


NDD Characterization Report
TPS7H5007-SEP

		10.49_CCSR_Ratio		
	Test Site			
	Tester			
	Test Number			
	Unit			
	Max Limit	2.12	2.12	
	Min Limit	2	2	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	2.078	2.078	0.000
1E+12	21	2.057	2.062	0.005
1E+12	22	2.052	2.056	0.004
1E+12	23	2.041	2.041	0.000
5E+12	24	2.057	2.051	-0.005
5E+12	25	2.041	2.062	0.021
5E+12	26	2.046	2.051	0.005
1E+13	27	2.084	2.062	-0.022
1E+13	28	2.056	2.056	0.000
1E+13	29	2.046	2.051	0.006
	Max	2.084	2.078	0.021
	Average	2.055	2.057	0.001
	Min	2.041	2.041	-0.022
	Std Dev	0.015	0.010	0.011

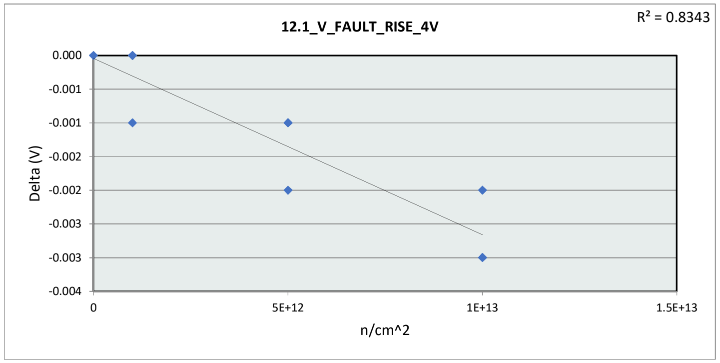


	10.49_CCSR_Ratio			
Test Site				
Tester				
Test Number				
Max Limit	2.12			
Min Limit	2			
n/cm^2	0	1E+12	5E+12	1E+13
LL	2.000	2.000	2.000	2.000
Min	2.078	2.041	2.051	2.051
Average	2.078	2.053	2.055	2.056
Max	2.078	2.062	2.062	2.062
UL	2.120	2.120	2.120	2.120

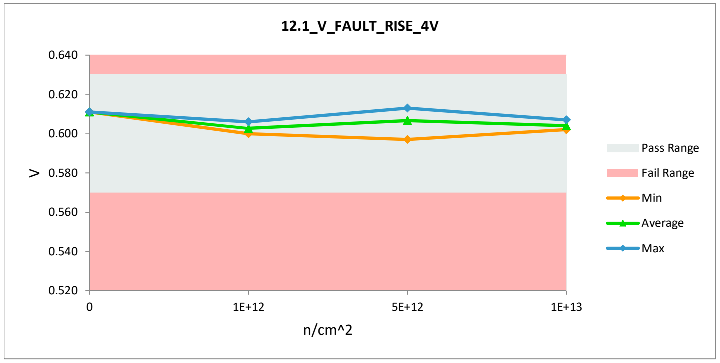


NDD Characterization Report
TPS7H5007-SEP

		12.1_V_FAULT_RISE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.611	0.611	0.000
1E+12	21	0.601	0.600	-0.001
1E+12	22	0.606	0.606	0.000
1E+12	23	0.602	0.602	0.000
5E+12	24	0.599	0.597	-0.002
5E+12	25	0.614	0.613	-0.001
5E+12	26	0.611	0.610	-0.001
1E+13	27	0.606	0.603	-0.003
1E+13	28	0.609	0.607	-0.002
1E+13	29	0.605	0.602	-0.003
	Max	0.614	0.613	0.000
	Average	0.606	0.605	-0.001
	Min	0.599	0.597	-0.003
	Std Dev	0.005	0.005	0.001

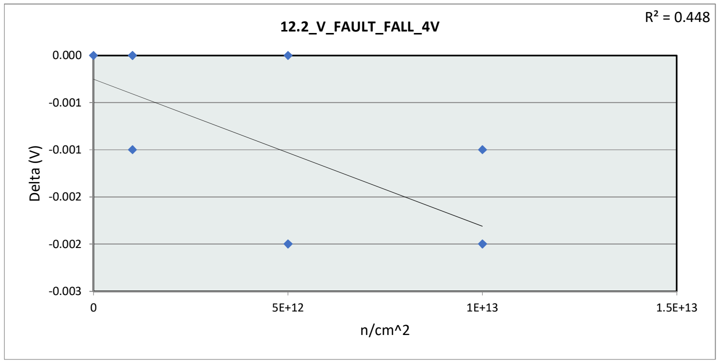


	12.1_V_FAULT_RISE_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.611	0.600	0.597	0.602
Average	0.611	0.603	0.607	0.604
Max	0.611	0.606	0.613	0.607
UL	0.630	0.630	0.630	0.630

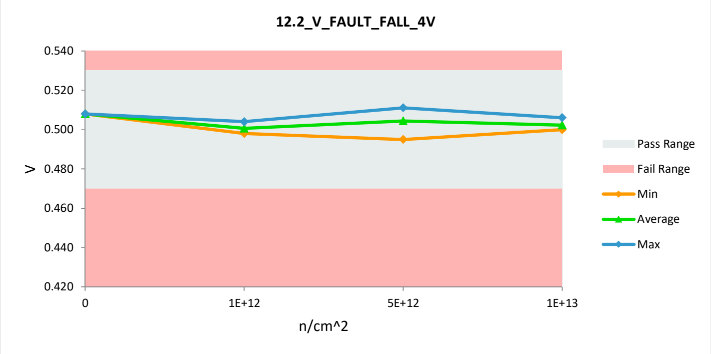


NDD Characterization Report
TPS7H5007-SEP

		12.2_V_FAULT_FALL_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.508	0.508	0.000
1E+12	21	0.499	0.498	-0.001
1E+12	22	0.504	0.504	0.000
1E+12	23	0.500	0.500	0.000
5E+12	24	0.497	0.495	-0.002
5E+12	25	0.511	0.511	0.000
5E+12	26	0.509	0.507	-0.002
1E+13	27	0.503	0.501	-0.002
1E+13	28	0.507	0.506	-0.001
1E+13	29	0.502	0.500	-0.002
	Max	0.511	0.511	0.000
	Average	0.504	0.503	-0.001
	Min	0.497	0.495	-0.002
	Std Dev	0.005	0.005	0.001

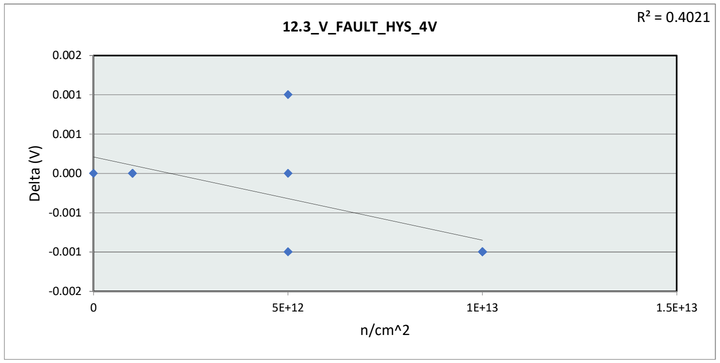


	12.2_V_FAULT_FALL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.498	0.495	0.500
Average	0.508	0.501	0.504	0.502
Max	0.508	0.504	0.511	0.506
UL	0.530	0.530	0.530	0.530

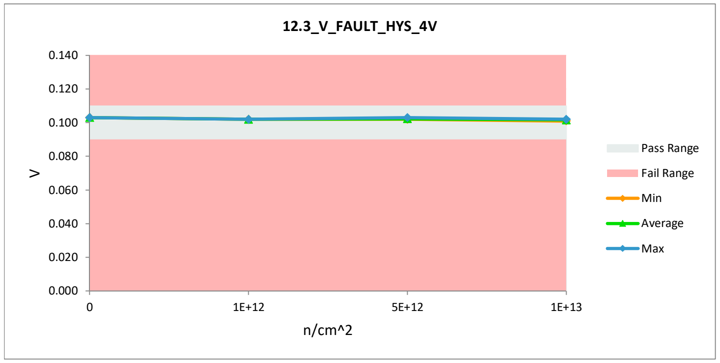


NDD Characterization Report
TPS7H5007-SEP

		12.3_V_FAULT_HYS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.103	0.103	0.000
1E+12	21	0.102	0.102	0.000
1E+12	22	0.102	0.102	0.000
1E+12	23	0.102	0.102	0.000
5E+12	24	0.102	0.102	0.000
5E+12	25	0.103	0.102	-0.001
5E+12	26	0.102	0.103	0.001
1E+13	27	0.103	0.102	-0.001
1E+13	28	0.102	0.101	-0.001
1E+13	29	0.103	0.102	-0.001
	Max	0.103	0.103	0.001
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.001
	Std Dev	0.001	0.001	0.001

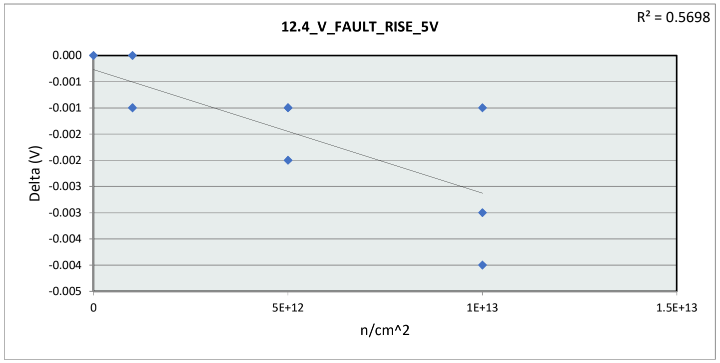


	12.3_V_FAULT_HYS_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.103	0.102	0.102	0.101
Average	0.103	0.102	0.102	0.102
Max	0.103	0.102	0.103	0.102
UL	0.110	0.110	0.110	0.110

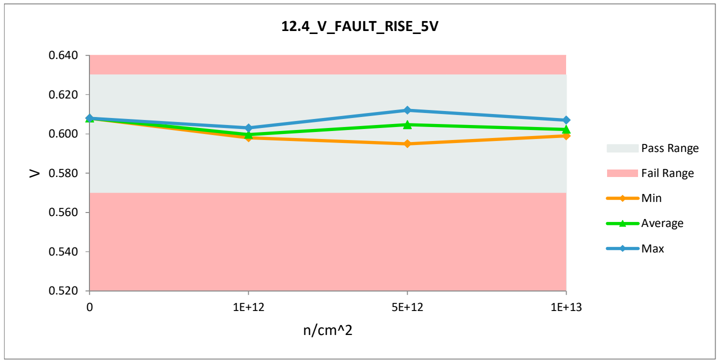


NDD Characterization Report
TPS7H5007-SEP

		12.4_V_FAULT_RISE_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.608	0.608	0.000
1E+12	21	0.598	0.598	0.000
1E+12	22	0.604	0.603	-0.001
1E+12	23	0.599	0.598	-0.001
5E+12	24	0.596	0.595	-0.001
5E+12	25	0.613	0.612	-0.001
5E+12	26	0.609	0.607	-0.002
1E+13	27	0.604	0.601	-0.003
1E+13	28	0.608	0.607	-0.001
1E+13	29	0.603	0.599	-0.004
	Max	0.613	0.612	0.000
	Average	0.604	0.603	-0.001
	Min	0.596	0.595	-0.004
	Std Dev	0.005	0.005	0.001

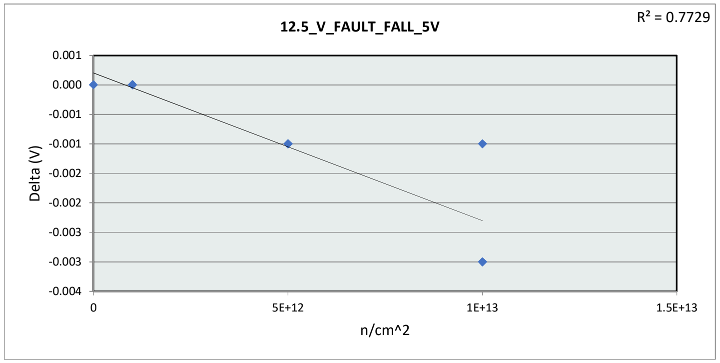


	12.4_V_FAULT_RISE_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.608	0.598	0.595	0.599
Average	0.608	0.600	0.605	0.602
Max	0.608	0.603	0.612	0.607
UL	0.630	0.630	0.630	0.630

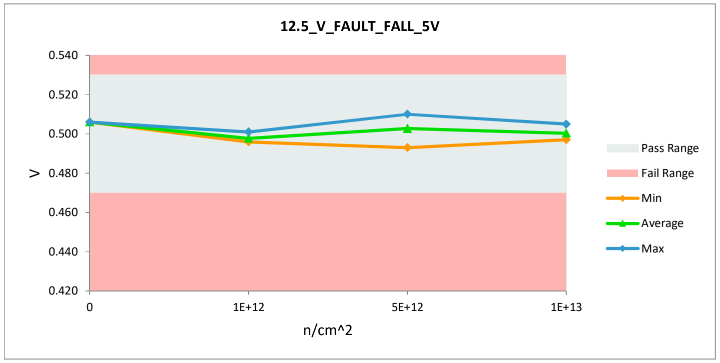


NDD Characterization Report
TPS7H5007-SEP

		12.5_V_FAULT_FALL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.506	0.506	0.000
1E+12	21	0.496	0.496	0.000
1E+12	22	0.501	0.501	0.000
1E+12	23	0.496	0.496	0.000
5E+12	24	0.494	0.493	-0.001
5E+12	25	0.511	0.510	-0.001
5E+12	26	0.506	0.505	-0.001
1E+13	27	0.502	0.499	-0.003
1E+13	28	0.506	0.505	-0.001
1E+13	29	0.500	0.497	-0.003
	Max	0.511	0.510	0.000
	Average	0.502	0.501	-0.001
	Min	0.494	0.493	-0.003
	Std Dev	0.005	0.005	0.001

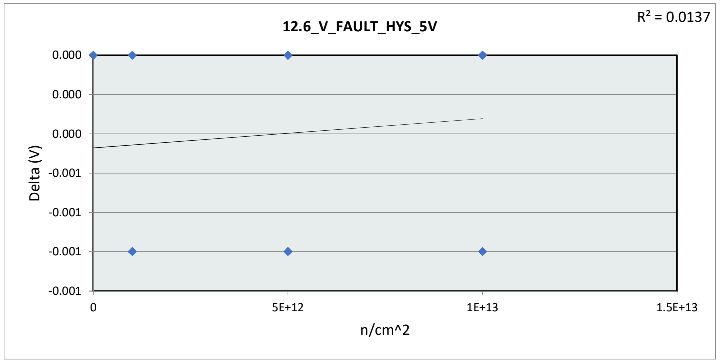


	12.5_V_FAULT_FALL_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.496	0.493	0.497
Average	0.506	0.498	0.503	0.500
Max	0.506	0.501	0.510	0.505
UL	0.530	0.530	0.530	0.530

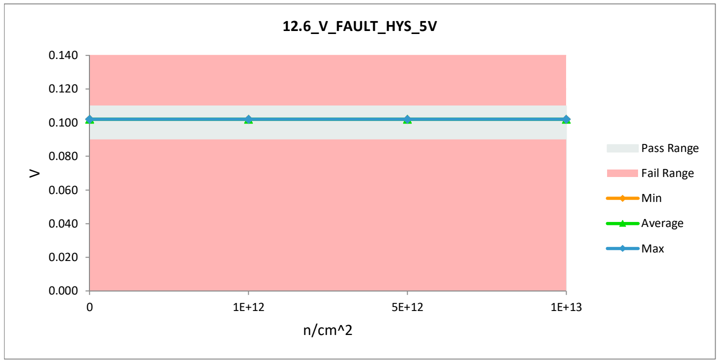


NDD Characterization Report
TPS7H5007-SEP

		12.6_V_FAULT_HYS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.102	0.102	0.000
1E+12	21	0.102	0.102	0.000
1E+12	22	0.103	0.102	-0.001
1E+12	23	0.103	0.102	-0.001
5E+12	24	0.102	0.102	0.000
5E+12	25	0.102	0.102	0.000
5E+12	26	0.103	0.102	-0.001
1E+13	27	0.102	0.102	0.000
1E+13	28	0.102	0.102	0.000
1E+13	29	0.103	0.102	-0.001
	Max	0.103	0.102	0.000
	Average	0.102	0.102	0.000
	Min	0.102	0.102	-0.001
	Std Dev	0.001	0.000	0.001



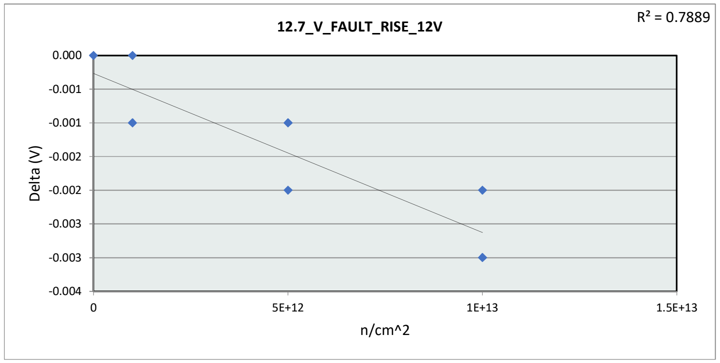
	12.6_V_FAULT_HYS_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.102
Average	0.102	0.102	0.102	0.102
Max	0.102	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110



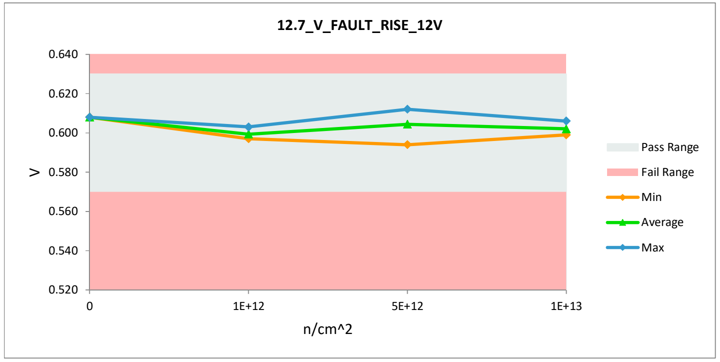
NDD Characterization Report
TPS7H5007-SEP

	12.7_V_FAULT_RISE_12V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.63	0.63
Min Limit	0.58	0.57

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.608	0.608	0.000
1E+12	21	0.598	0.597	-0.001
1E+12	22	0.603	0.603	0.000
1E+12	23	0.599	0.598	-0.001
5E+12	24	0.596	0.594	-0.002
5E+12	25	0.613	0.612	-0.001
5E+12	26	0.608	0.607	-0.001
1E+13	27	0.604	0.601	-0.003
1E+13	28	0.608	0.606	-0.002
1E+13	29	0.602	0.599	-0.003
	Max	0.613	0.612	0.000
	Average	0.604	0.602	-0.001
	Min	0.596	0.594	-0.003
	Std Dev	0.005	0.006	0.001

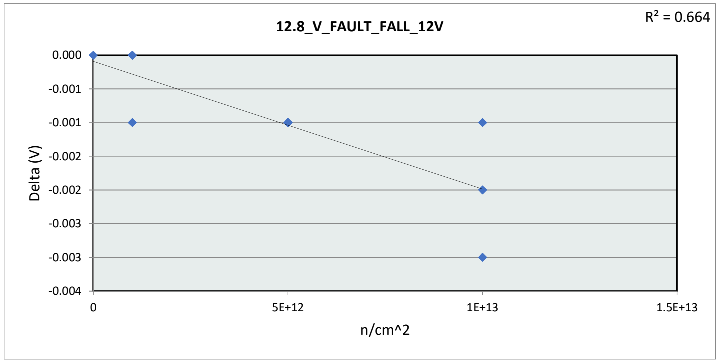


	12.7_V_FAULT_RISE_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.608	0.597	0.594	0.599
Average	0.608	0.599	0.604	0.602
Max	0.608	0.603	0.612	0.606
UL	0.630	0.630	0.630	0.630

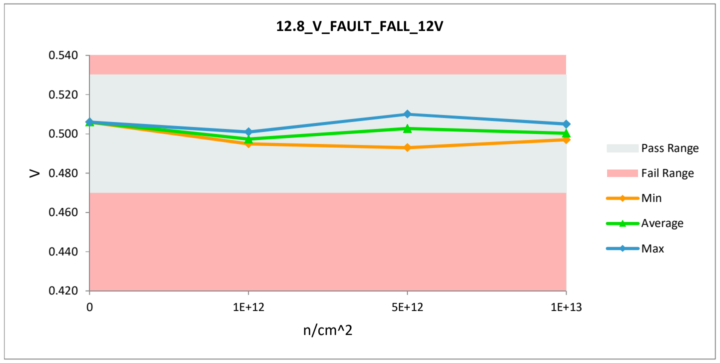


NDD Characterization Report
TPS7H5007-SEP

		12.8_V_FAULT_FALL_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.506	0.506	0.000
1E+12	21	0.496	0.495	-0.001
1E+12	22	0.501	0.501	0.000
1E+12	23	0.496	0.496	0.000
5E+12	24	0.494	0.493	-0.001
5E+12	25	0.511	0.510	-0.001
5E+12	26	0.506	0.505	-0.001
1E+13	27	0.501	0.499	-0.002
1E+13	28	0.506	0.505	-0.001
1E+13	29	0.500	0.497	-0.003
	Max	0.511	0.510	0.000
	Average	0.502	0.501	-0.001
	Min	0.494	0.493	-0.003
	Std Dev	0.005	0.006	0.001

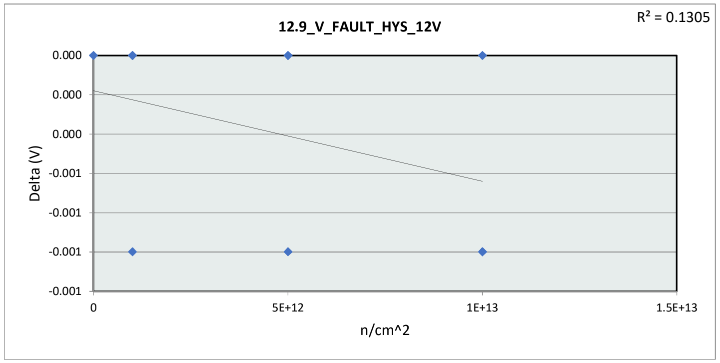


	12.8_V_FAULT_FALL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.495	0.493	0.497
Average	0.506	0.497	0.503	0.500
Max	0.506	0.501	0.510	0.505
UL	0.530	0.530	0.530	0.530

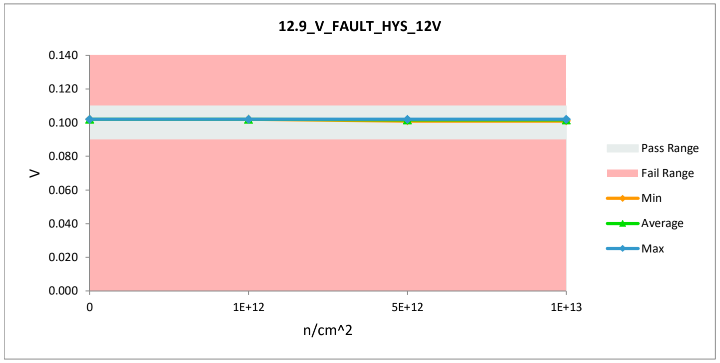


NDD Characterization Report
TPS7H5007-SEP

		12.9_V_FAULT_HYS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.102	0.102	0.000
1E+12	21	0.102	0.102	0.000
1E+12	22	0.102	0.102	0.000
1E+12	23	0.103	0.102	-0.001
5E+12	24	0.102	0.101	-0.001
5E+12	25	0.102	0.102	0.000
5E+12	26	0.102	0.102	0.000
1E+13	27	0.103	0.102	-0.001
1E+13	28	0.102	0.101	-0.001
1E+13	29	0.102	0.102	0.000
	Max	0.103	0.102	0.000
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.001
	Std Dev	0.000	0.000	0.001

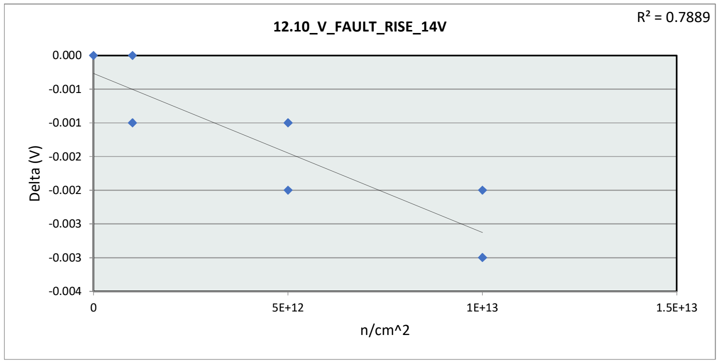


	12.9_V_FAULT_HYS_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.101	0.101
Average	0.102	0.102	0.102	0.102
Max	0.102	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

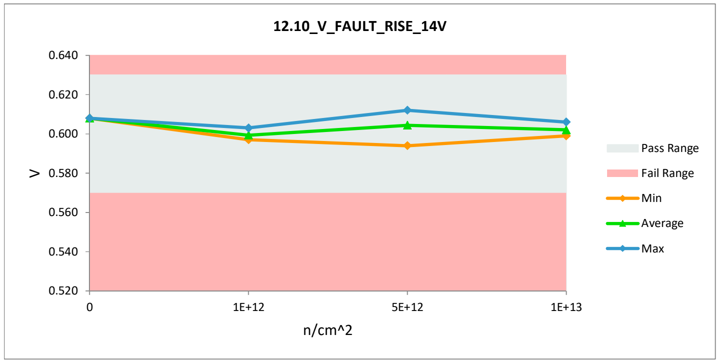


NDD Characterization Report
TPS7H5007-SEP

		12.10_V_FAULT_RISE_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.608	0.608	0.000
1E+12	21	0.598	0.597	-0.001
1E+12	22	0.603	0.603	0.000
1E+12	23	0.599	0.598	-0.001
5E+12	24	0.596	0.594	-0.002
5E+12	25	0.613	0.612	-0.001
5E+12	26	0.608	0.607	-0.001
1E+13	27	0.604	0.601	-0.003
1E+13	28	0.608	0.606	-0.002
1E+13	29	0.602	0.599	-0.003
	Max	0.613	0.612	0.000
	Average	0.604	0.602	-0.001
	Min	0.596	0.594	-0.003
	Std Dev	0.005	0.006	0.001

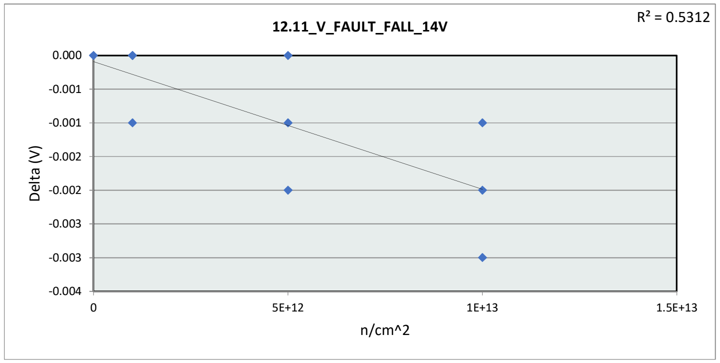


	12.10_V_FAULT_RISE_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.608	0.597	0.594	0.599
Average	0.608	0.599	0.604	0.602
Max	0.608	0.603	0.612	0.606
UL	0.630	0.630	0.630	0.630

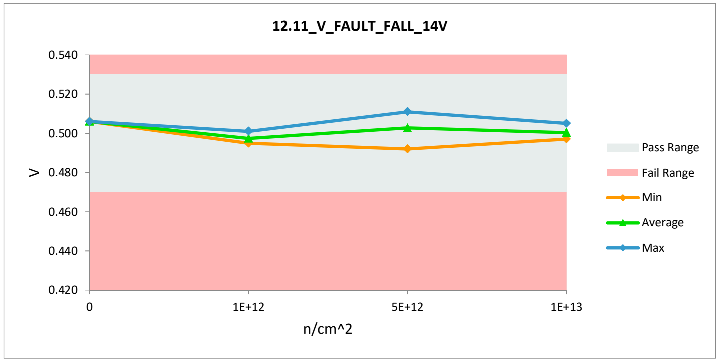


NDD Characterization Report
TPS7H5007-SEP

		12.11_V_FAULT_FALL_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.506	0.506	0.000
1E+12	21	0.496	0.495	-0.001
1E+12	22	0.501	0.501	0.000
1E+12	23	0.496	0.496	0.000
5E+12	24	0.494	0.492	-0.002
5E+12	25	0.511	0.511	0.000
5E+12	26	0.506	0.505	-0.001
1E+13	27	0.501	0.499	-0.002
1E+13	28	0.506	0.505	-0.001
1E+13	29	0.500	0.497	-0.003
	Max	0.511	0.511	0.000
	Average	0.502	0.501	-0.001
	Min	0.494	0.492	-0.003
	Std Dev	0.005	0.006	0.001

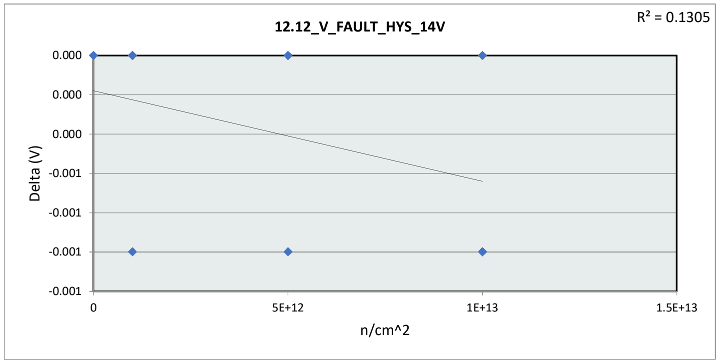


	12.11_V_FAULT_FALL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.495	0.492	0.497
Average	0.506	0.497	0.503	0.500
Max	0.506	0.501	0.511	0.505
UL	0.530	0.530	0.530	0.530

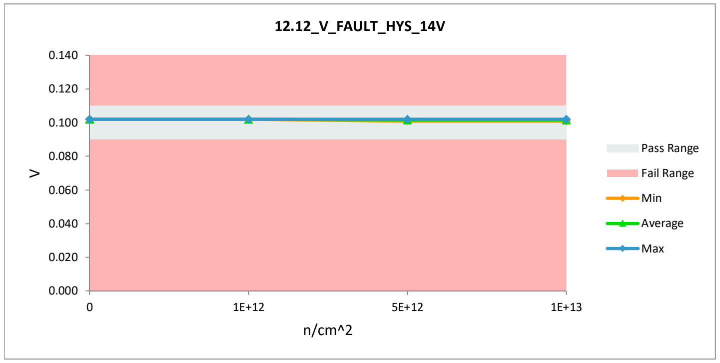


NDD Characterization Report
TPS7H5007-SEP

		12.12_V_FAULT_HYS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.102	0.102	0.000
1E+12	21	0.102	0.102	0.000
1E+12	22	0.102	0.102	0.000
1E+12	23	0.103	0.102	-0.001
5E+12	24	0.102	0.102	0.000
5E+12	25	0.102	0.101	-0.001
5E+12	26	0.102	0.102	0.000
1E+13	27	0.103	0.102	-0.001
1E+13	28	0.102	0.101	-0.001
1E+13	29	0.102	0.102	0.000
	Max	0.103	0.102	0.000
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.001
	Std Dev	0.000	0.000	0.001

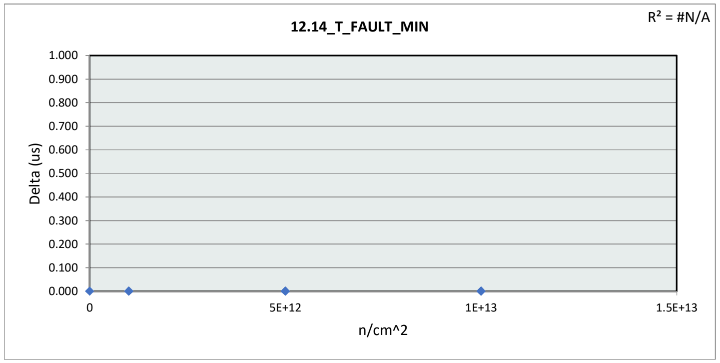


	12.12_V_FAULT_HYS_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.101	0.101
Average	0.102	0.102	0.102	0.102
Max	0.102	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

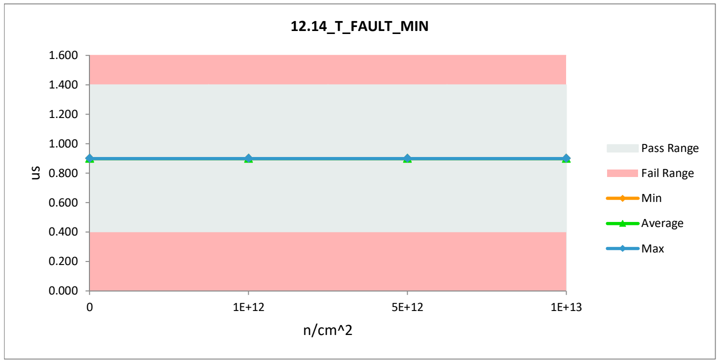


NDD Characterization Report
TPS7H5007-SEP

		12.14_T_FAULT_MIN		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	1.2	1.4	
	Min Limit	0.6	0.4	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	0.900	0.900	0.000
1E+12	21	0.900	0.900	0.000
1E+12	22	0.900	0.900	0.000
1E+12	23	0.900	0.900	0.000
5E+12	24	0.900	0.900	0.000
5E+12	25	0.900	0.900	0.000
5E+12	26	0.900	0.900	0.000
1E+13	27	0.900	0.900	0.000
1E+13	28	0.900	0.900	0.000
1E+13	29	0.900	0.900	0.000
	Max	0.900	0.900	0.000
	Average	0.900	0.900	0.000
	Min	0.900	0.900	0.000
	Std Dev	0.000	0.000	0.000

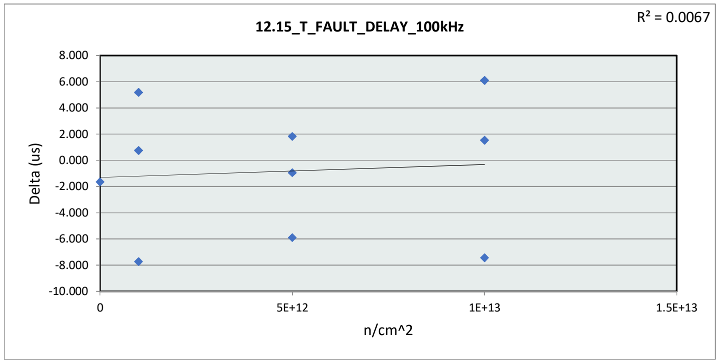


	12.14_T_FAULT_MIN			
Test Site				
Tester				
Test Number				
Max Limit	1.4	us		
Min Limit	0.4	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.400	0.400	0.400	0.400
Min	0.900	0.900	0.900	0.900
Average	0.900	0.900	0.900	0.900
Max	0.900	0.900	0.900	0.900
UL	1.400	1.400	1.400	1.400

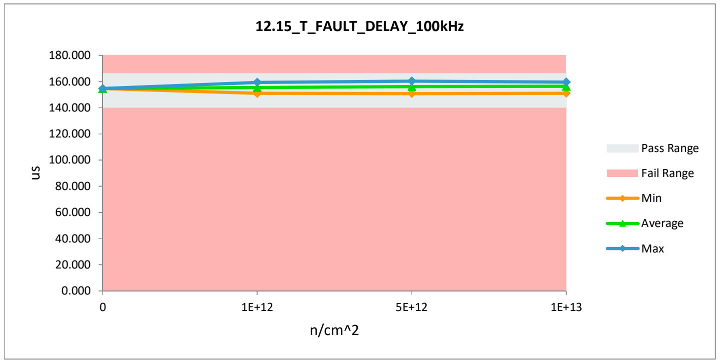


NDD Characterization Report
TPS7H5007-SEP

		12.15_T_FAULT_DELAY_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	166	166	
	Min Limit	140	140	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	156.269	154.611	-1.658
1E+12	21	150.485	155.657	5.172
1E+12	22	158.646	159.388	0.742
1E+12	23	158.713	150.976	-7.737
5E+12	24	157.772	156.818	-0.954
5E+12	25	156.794	150.888	-5.906
5E+12	26	158.572	160.385	1.813
1E+13	27	158.021	159.537	1.516
1E+13	28	152.274	158.362	6.088
1E+13	29	158.434	150.983	-7.451
	Max	158.713	160.385	6.088
	Average	156.598	155.760	-0.838
	Min	150.485	150.888	-7.737
	Std Dev	2.897	3.764	4.909

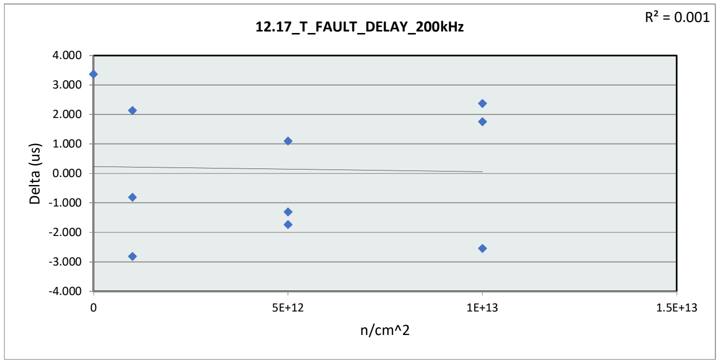


12.15_T_FAULT_DELAY_100kH				
Test Site				
Tester				
Test Number				
Max Limit	166	us		
Min Limit	140	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	140.000	140.000	140.000	140.000
Min	154.611	150.976	150.888	150.983
Average	154.611	155.340	156.030	156.294
Max	154.611	159.388	160.385	159.537
UL	166.000	166.000	166.000	166.000

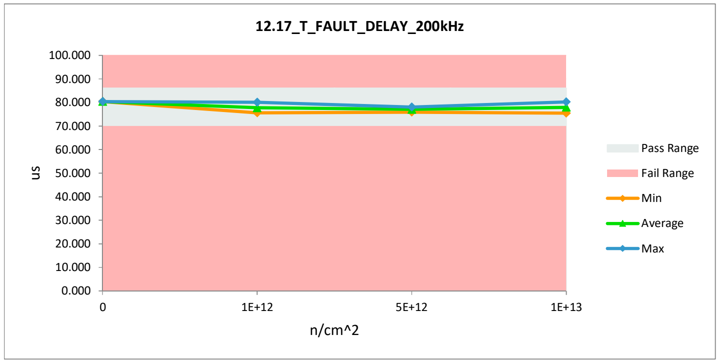


NDD Characterization Report
TPS7H5007-SEP

		12.17_T_FAULT_DELAY_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	86	86	
	Min Limit	70	70	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	77.075	80.432	3.357
1E+12	21	77.998	80.126	2.128
1E+12	22	78.457	75.634	-2.823
1E+12	23	78.268	77.454	-0.814
5E+12	24	79.343	78.035	-1.308
5E+12	25	77.680	75.938	-1.742
5E+12	26	76.204	77.300	1.096
1E+13	27	77.908	80.276	2.368
1E+13	28	78.022	75.476	-2.546
1E+13	29	76.308	78.061	1.753
	Max	79.343	80.432	3.357
	Average	77.726	77.873	0.147
	Min	76.204	75.476	-2.823
	Std Dev	0.966	1.899	2.244

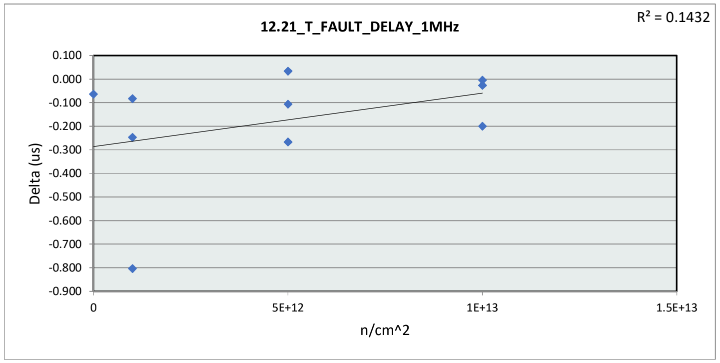


	12.17_T_FAULT_DELAY_200kH			
Test Site				
Tester				
Test Number				
Max Limit	86	us		
Min Limit	70	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	70.000	70.000	70.000	70.000
Min	80.432	75.634	75.938	75.476
Average	80.432	77.738	77.091	77.938
Max	80.432	80.126	78.035	80.276
UL	86.000	86.000	86.000	86.000

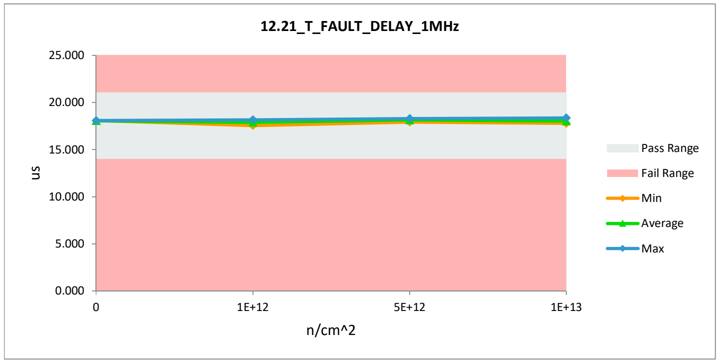


NDD Characterization Report
TPS7H5007-SEP

		12.21_T_FAULT_DELAY_1MHz		
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		21	21	
Min Limit		14	14	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	18.140	18.075	-0.065
1E+12	21	18.247	18.164	-0.083
1E+12	22	18.199	17.951	-0.248
1E+12	23	18.332	17.528	-0.804
5E+12	24	18.392	18.285	-0.107
5E+12	25	18.212	18.245	0.033
5E+12	26	18.186	17.919	-0.267
1E+13	27	18.361	18.356	-0.005
1E+13	28	17.973	17.772	-0.201
1E+13	29	17.952	17.925	-0.027
	Max	18.392	18.356	0.033
	Average	18.199	18.022	-0.177
	Min	17.952	17.528	-0.804
	Std Dev	0.149	0.255	0.243

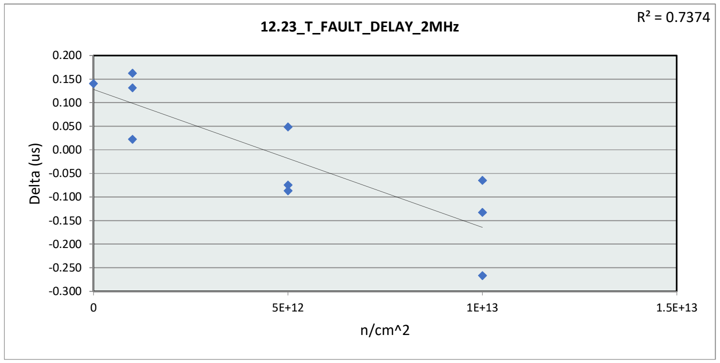


	12.21_T_FAULT_DELAY_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	21	us		
Min Limit	14	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	14.000	14.000	14.000	14.000
Min	18.075	17.528	17.919	17.772
Average	18.075	17.881	18.150	18.018
Max	18.075	18.164	18.285	18.356
UL	21.000	21.000	21.000	21.000

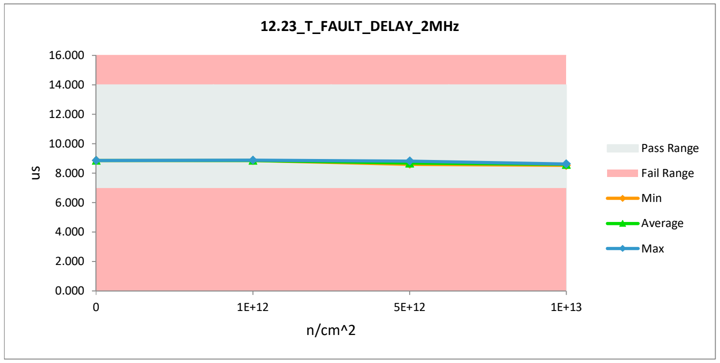


NDD Characterization Report
TPS7H5007-SEP

		12.23_T_FAULT_DELAY_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	14	14	
	Min Limit	7	7	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.716	8.856	0.140
1E+12	21	8.681	8.843	0.162
1E+12	22	8.749	8.880	0.131
1E+12	23	8.856	8.878	0.022
5E+12	24	8.677	8.602	-0.075
5E+12	25	8.560	8.608	0.048
5E+12	26	8.914	8.827	-0.087
1E+13	27	8.592	8.527	-0.065
1E+13	28	8.894	8.627	-0.267
1E+13	29	8.742	8.609	-0.133
	Max	8.914	8.880	0.162
	Average	8.738	8.726	-0.012
	Min	8.560	8.527	-0.267
	Std Dev	0.120	0.141	0.138

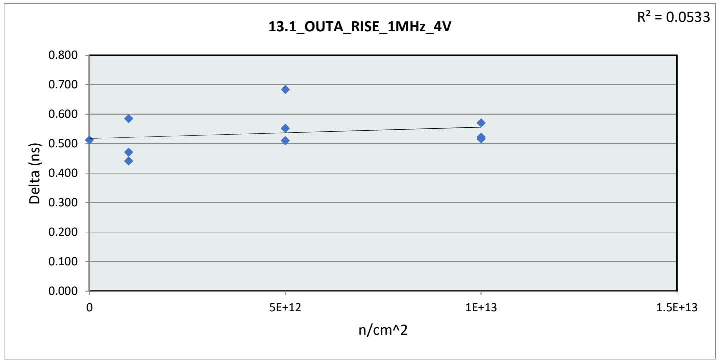


	12.23_T_FAULT_DELAY_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	14	us		
Min Limit	7	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	7.000	7.000	7.000	7.000
Min	8.856	8.843	8.602	8.527
Average	8.856	8.867	8.679	8.588
Max	8.856	8.880	8.827	8.627
UL	14.000	14.000	14.000	14.000

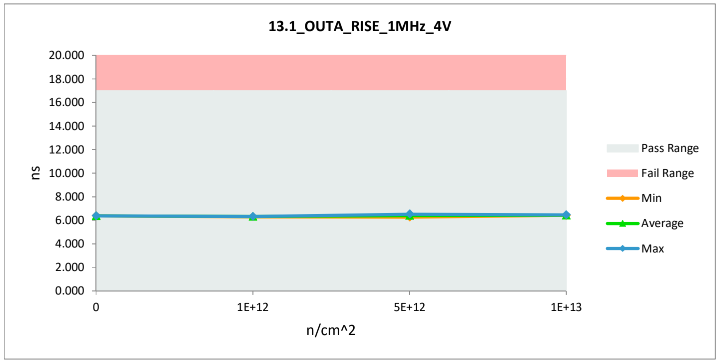


NDD Characterization Report
TPS7H5007-SEP

		13.1_OUTA_RISE_1MHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		16.5	17	
Min Limit		4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	5.878	6.390	0.512
1E+12	21	5.859	6.300	0.441
1E+12	22	5.835	6.306	0.471
1E+12	23	5.741	6.326	0.585
5E+12	24	5.761	6.271	0.510
5E+12	25	5.726	6.409	0.683
5E+12	26	5.970	6.522	0.552
1E+13	27	5.941	6.463	0.522
1E+13	28	5.903	6.419	0.516
1E+13	29	5.857	6.427	0.570
	Max	5.970	6.522	0.683
	Average	5.847	6.383	0.536
	Min	5.726	6.271	0.441
	Std Dev	0.083	0.080	0.067

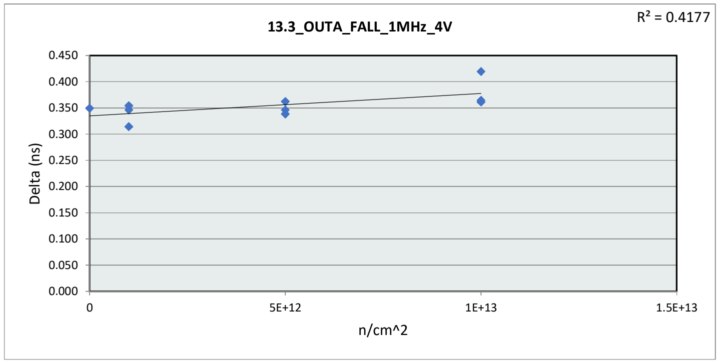


	13.1_OUTA_RISE_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.390	6.300	6.271	6.419
Average	6.390	6.311	6.401	6.436
Max	6.390	6.326	6.522	6.463
UL	17.000	17.000	17.000	17.000

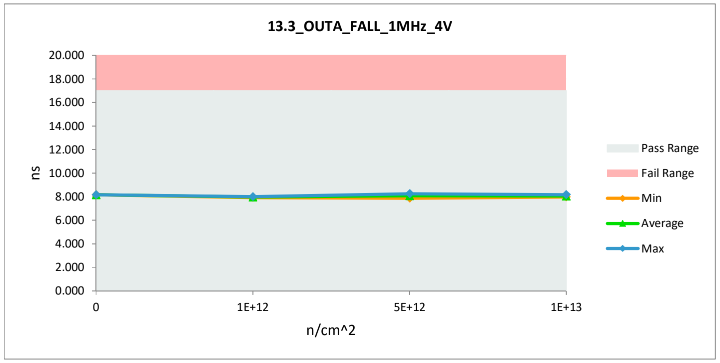


NDD Characterization Report
TPS7H5007-SEP

		13.3_OUTA_FALL_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.815	8.164	0.349
1E+12	21	7.636	7.990	0.354
1E+12	22	7.623	7.937	0.314
1E+12	23	7.636	7.982	0.346
5E+12	24	7.530	7.876	0.346
5E+12	25	7.894	8.256	0.362
5E+12	26	7.782	8.120	0.338
1E+13	27	7.613	7.974	0.361
1E+13	28	7.762	8.181	0.419
1E+13	29	7.622	7.986	0.364
	Max	7.894	8.256	0.419
	Average	7.691	8.047	0.355
	Min	7.530	7.876	0.314
	Std Dev	0.114	0.124	0.027

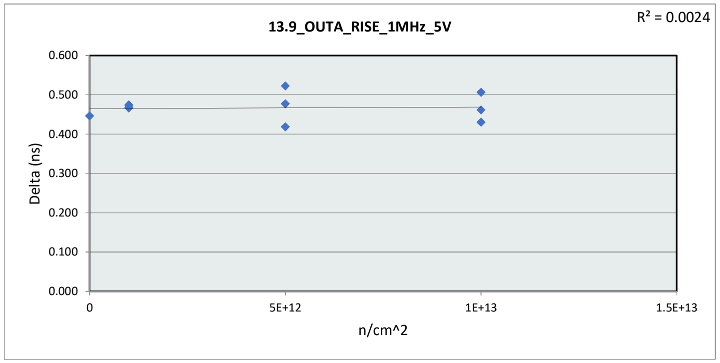


13.3_OUTA_FALL_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.164	7.937	7.876	7.974
Average	8.164	7.970	8.084	8.047
Max	8.164	7.990	8.256	8.181
UL	17.000	17.000	17.000	17.000

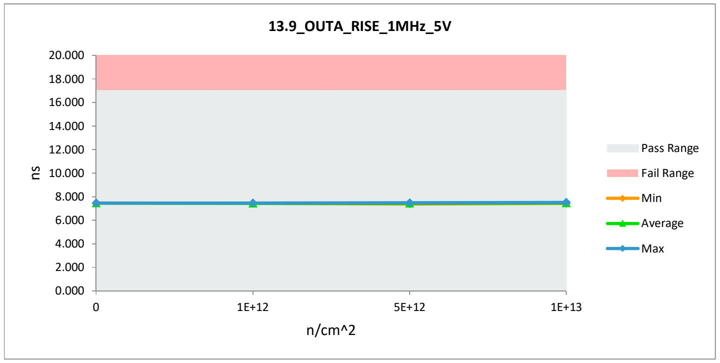


NDD Characterization Report
TPS7H5007-SEP

		13.9_OUTA_RISE_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.004	7.450	0.446
1E+12	21	6.984	7.452	0.468
1E+12	22	6.975	7.449	0.474
1E+12	23	6.967	7.433	0.466
5E+12	24	6.958	7.376	0.418
5E+12	25	6.946	7.468	0.522
5E+12	26	6.999	7.476	0.477
1E+13	27	7.012	7.442	0.430
1E+13	28	6.999	7.460	0.461
1E+13	29	6.997	7.503	0.506
	Max	7.012	7.503	0.522
	Average	6.984	7.451	0.467
	Min	6.946	7.376	0.418
	Std Dev	0.022	0.033	0.032

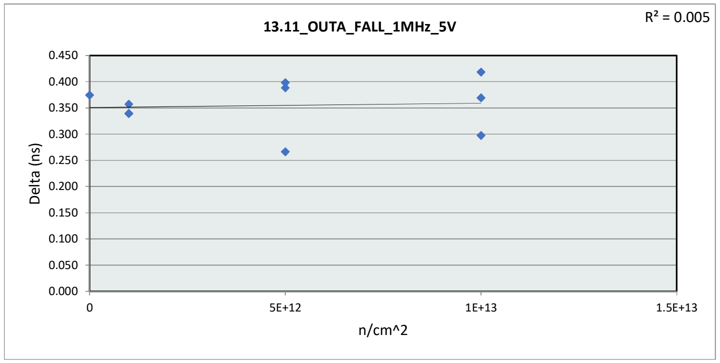


	13.9_OUTA_RISE_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.450	7.433	7.376	7.442
Average	7.450	7.445	7.440	7.468
Max	7.450	7.452	7.476	7.503
UL	17.000	17.000	17.000	17.000

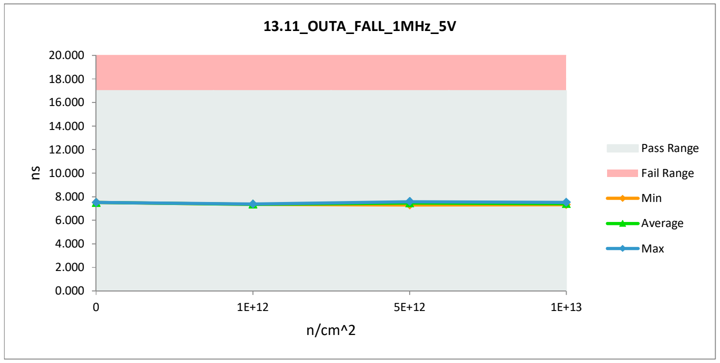


NDD Characterization Report
TPS7H5007-SEP

		13.11_OUTA_FALL_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.139	7.513	0.374
1E+12	21	7.019	7.376	0.357
1E+12	22	7.015	7.354	0.339
1E+12	23	6.997	7.336	0.339
5E+12	24	6.899	7.297	0.398
5E+12	25	7.194	7.582	0.388
5E+12	26	7.212	7.478	0.266
1E+13	27	7.001	7.370	0.369
1E+13	28	7.108	7.526	0.418
1E+13	29	7.030	7.327	0.297
	Max	7.212	7.582	0.418
	Average	7.061	7.416	0.355
	Min	6.899	7.297	0.266
	Std Dev	0.099	0.099	0.046

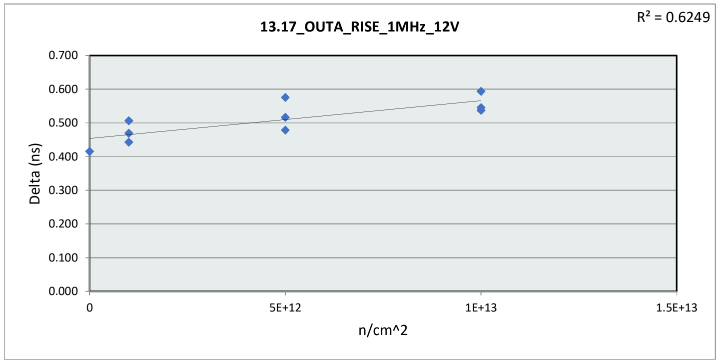


	13.11_OUTA_FALL_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.513	7.336	7.297	7.327
Average	7.513	7.355	7.452	7.408
Max	7.513	7.376	7.582	7.526
UL	17.000	17.000	17.000	17.000

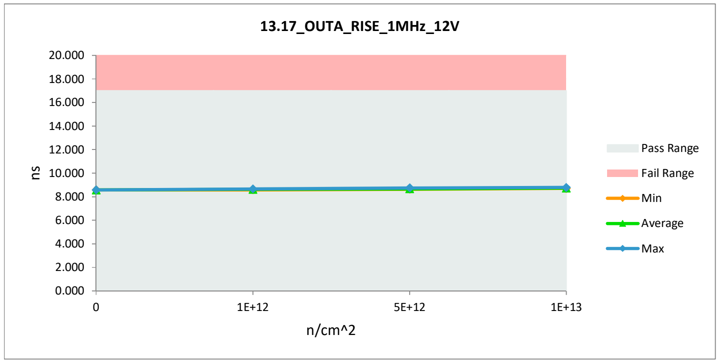


NDD Characterization Report
TPS7H5007-SEP

		13.17_OUTA_RISE_1MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		16.5	17	
Min Limit		4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.150	8.565	0.415
1E+12	21	8.148	8.590	0.442
1E+12	22	8.138	8.607	0.469
1E+12	23	8.141	8.647	0.506
5E+12	24	8.113	8.629	0.516
5E+12	25	8.159	8.637	0.478
5E+12	26	8.163	8.738	0.575
1E+13	27	8.189	8.782	0.593
1E+13	28	8.166	8.703	0.537
1E+13	29	8.183	8.728	0.545
	Max	8.189	8.782	0.593
	Average	8.155	8.663	0.508
	Min	8.113	8.565	0.415
	Std Dev	0.022	0.071	0.057

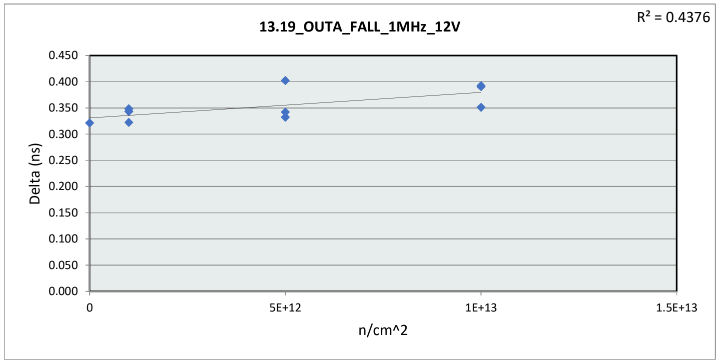


	13.17_OUTA_RISE_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.565	8.590	8.629	8.703
Average	8.565	8.615	8.668	8.738
Max	8.565	8.647	8.738	8.782
UL	17.000	17.000	17.000	17.000

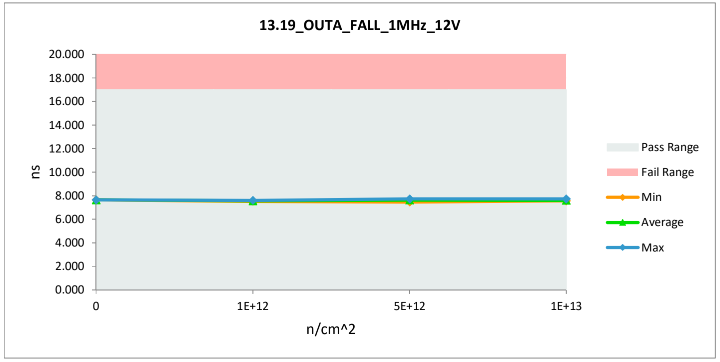


NDD Characterization Report
TPS7H5007-SEP

		13.19_OUTA_FALL_1MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		16.5	17	
Min Limit		4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.324	7.645	0.321
1E+12	21	7.180	7.528	0.348
1E+12	22	7.239	7.561	0.322
1E+12	23	7.243	7.586	0.343
5E+12	24	7.128	7.460	0.332
5E+12	25	7.374	7.716	0.342
5E+12	26	7.280	7.682	0.402
1E+13	27	7.164	7.556	0.392
1E+13	28	7.328	7.718	0.390
1E+13	29	7.212	7.563	0.351
	Max	7.374	7.718	0.402
	Average	7.247	7.602	0.354
	Min	7.128	7.460	0.321
	Std Dev	0.079	0.086	0.030

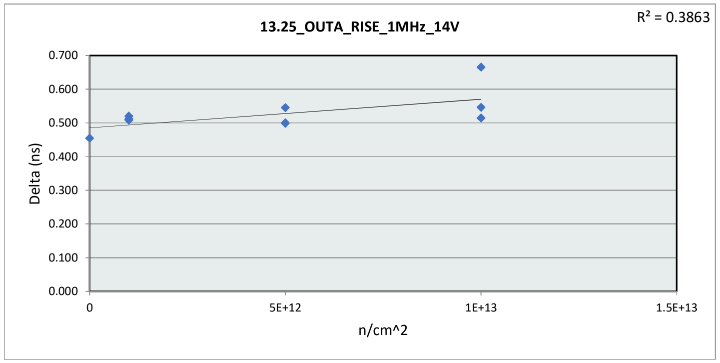


	13.19_OUTA_FALL_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.645	7.528	7.460	7.556
Average	7.645	7.558	7.619	7.612
Max	7.645	7.586	7.716	7.718
UL	17.000	17.000	17.000	17.000

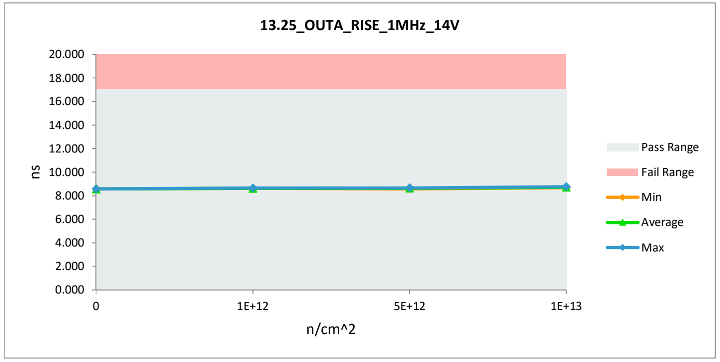


NDD Characterization Report
TPS7H5007-SEP

		13.25_OUTA_RISE_1MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	8.117	8.571	0.454
1E+12	21	8.107	8.615	0.508
1E+12	22	8.090	8.610	0.520
1E+12	23	8.132	8.643	0.511
5E+12	24	8.089	8.587	0.498
5E+12	25	8.114	8.659	0.545
5E+12	26	8.141	8.641	0.500
1E+13	27	8.103	8.768	0.665
1E+13	28	8.127	8.673	0.546
1E+13	29	8.191	8.705	0.514
	Max	8.191	8.768	0.665
	Average	8.121	8.647	0.526
	Min	8.089	8.571	0.454
	Std Dev	0.030	0.058	0.055

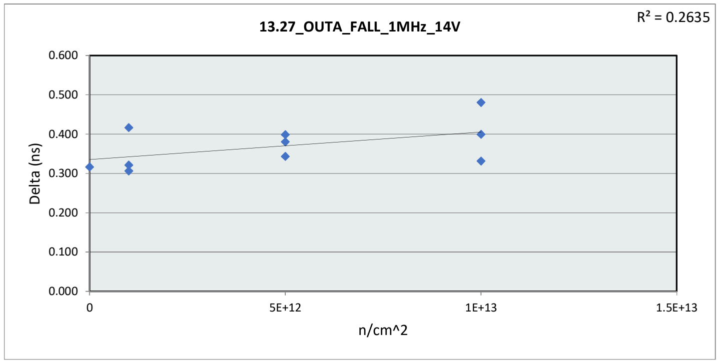


	13.25_OUTA_RISE_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.571	8.610	8.587	8.673
Average	8.571	8.623	8.629	8.715
Max	8.571	8.643	8.659	8.768
UL	17.000	17.000	17.000	17.000

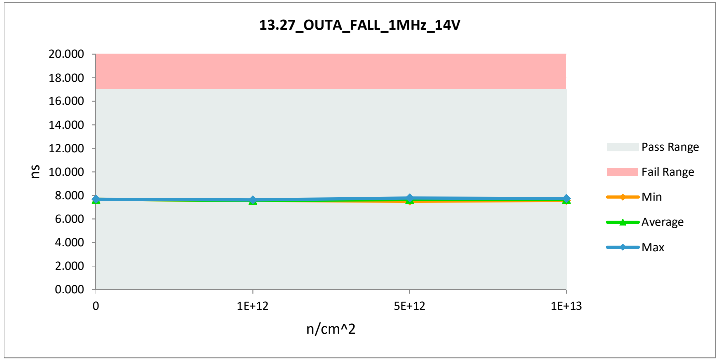


NDD Characterization Report
TPS7H5007-SEP

		13.27_OUTA_FALL_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		16.5	17	
Min Limit		4	0	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	7.352	7.668	0.316
1E+12	21	7.231	7.552	0.321
1E+12	22	7.205	7.621	0.416
1E+12	23	7.259	7.565	0.306
5E+12	24	7.172	7.515	0.343
5E+12	25	7.379	7.777	0.398
5E+12	26	7.292	7.672	0.380
1E+13	27	7.286	7.685	0.399
1E+13	28	7.247	7.727	0.480
1E+13	29	7.249	7.580	0.331
	Max	7.379	7.777	0.480
	Average	7.267	7.636	0.369
	Min	7.172	7.515	0.306
	Std Dev	0.063	0.084	0.055

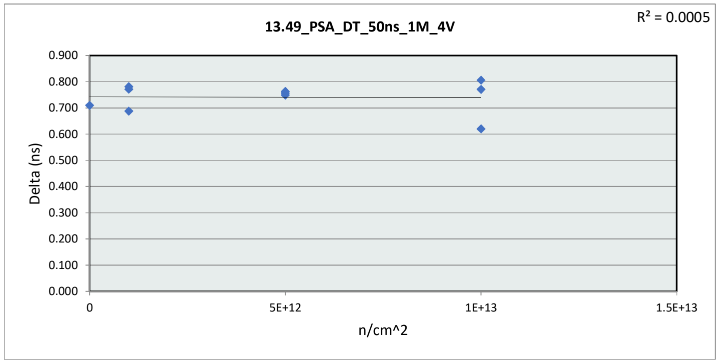


	13.27_OUTA_FALL_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.668	7.552	7.515	7.580
Average	7.668	7.579	7.655	7.664
Max	7.668	7.621	7.777	7.727
UL	17.000	17.000	17.000	17.000

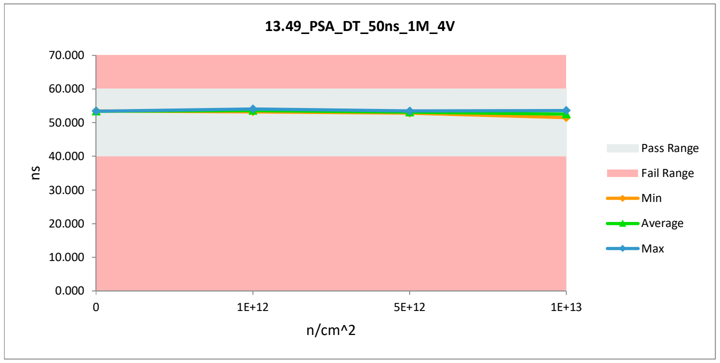


NDD Characterization Report
TPS7H5007-SEP

		13.49_PSA_DT_50ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	60	60	
	Min Limit	40	40	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	52.753	53.462	0.709
1E+12	21	53.311	54.091	0.780
1E+12	22	52.428	53.199	0.771
1E+12	23	52.907	53.594	0.687
5E+12	24	52.053	52.815	0.762
5E+12	25	52.487	53.243	0.756
5E+12	26	52.712	53.460	0.748
1E+13	27	52.794	53.599	0.805
1E+13	28	52.070	52.689	0.619
1E+13	29	50.711	51.481	0.770
	Max	53.311	54.091	0.805
	Average	52.423	53.163	0.741
	Min	50.711	51.481	0.619
	Std Dev	0.711	0.715	0.055



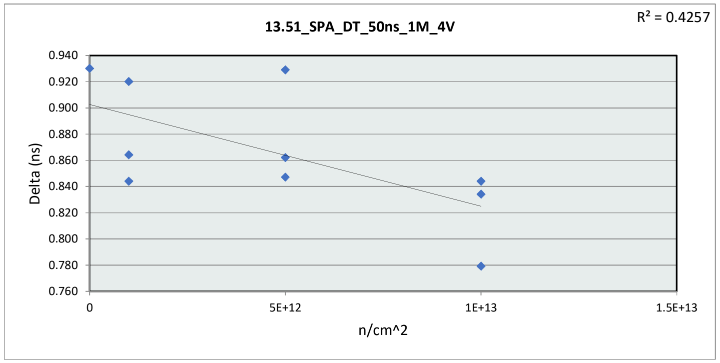
	13.49_PSA_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	60	ns		
Min Limit	40	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	40.000	40.000	40.000	40.000
Min	53.462	53.199	52.815	51.481
Average	53.462	53.628	53.173	52.590
Max	53.462	54.091	53.460	53.599
UL	60.000	60.000	60.000	60.000



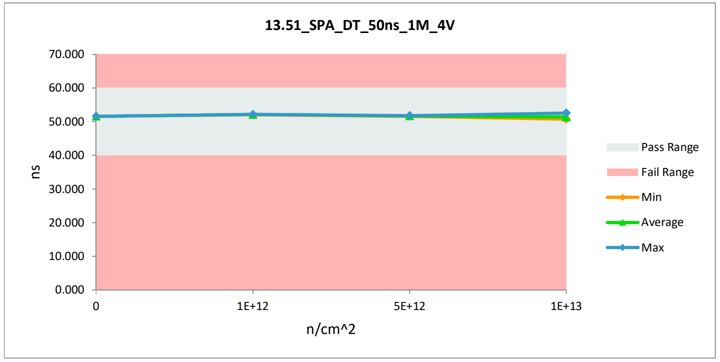
NDD Characterization Report
TPS7H5007-SEP

	13.51_SPA_DT_50ns_1M_4V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	60	60
Min Limit	40	40

n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	50.668	51.598	0.930
1E+12	21	51.185	52.029	0.844
1E+12	22	51.267	52.187	0.920
1E+12	23	51.287	52.151	0.864
5E+12	24	50.935	51.782	0.847
5E+12	25	50.775	51.637	0.862
5E+12	26	50.748	51.677	0.929
1E+13	27	51.733	52.567	0.834
1E+13	28	50.001	50.780	0.779
1E+13	29	49.936	50.780	0.844
	Max	51.733	52.567	0.930
	Average	50.854	51.719	0.865
	Min	49.936	50.780	0.779
	Std Dev	0.565	0.578	0.048

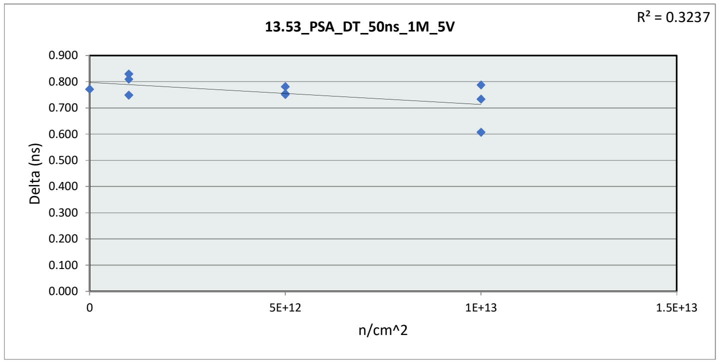


	13.51_SPA_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	60	ns		
Min Limit	40	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	40.000	40.000	40.000	40.000
Min	51.598	52.029	51.637	50.780
Average	51.598	52.122	51.699	51.376
Max	51.598	52.187	51.782	52.567
UL	60.000	60.000	60.000	60.000

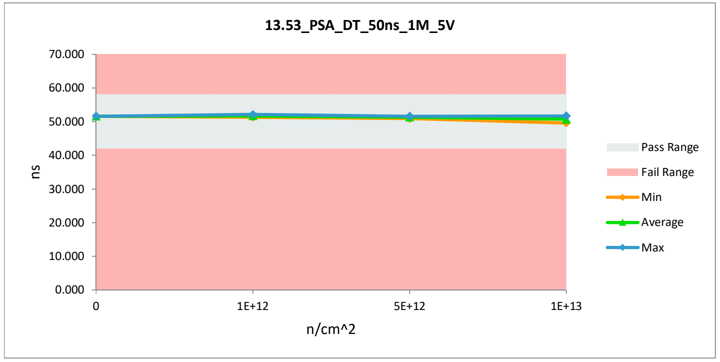


NDD Characterization Report
TPS7H5007-SEP

		13.53_PSA_DT_50ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	58	58	
	Min Limit	42	42	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	50.857	51.628	0.771
1E+12	21	51.316	52.125	0.809
1E+12	22	50.489	51.318	0.829
1E+12	23	51.018	51.766	0.748
5E+12	24	50.194	50.944	0.750
5E+12	25	50.632	51.386	0.754
5E+12	26	50.830	51.610	0.780
1E+13	27	50.882	51.669	0.787
1E+13	28	50.271	50.878	0.607
1E+13	29	48.883	49.616	0.733
	Max	51.316	52.125	0.829
	Average	50.537	51.294	0.757
	Min	48.883	49.616	0.607
	Std Dev	0.673	0.698	0.060

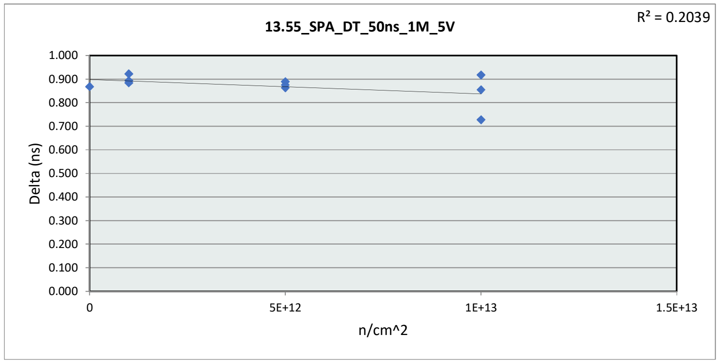


	13.53_PSA_DT_50ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	58	ns		
Min Limit	42	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	42.000	42.000	42.000	42.000
Min	51.628	51.318	50.944	49.616
Average	51.628	51.736	51.313	50.721
Max	51.628	52.125	51.610	51.669
UL	58.000	58.000	58.000	58.000

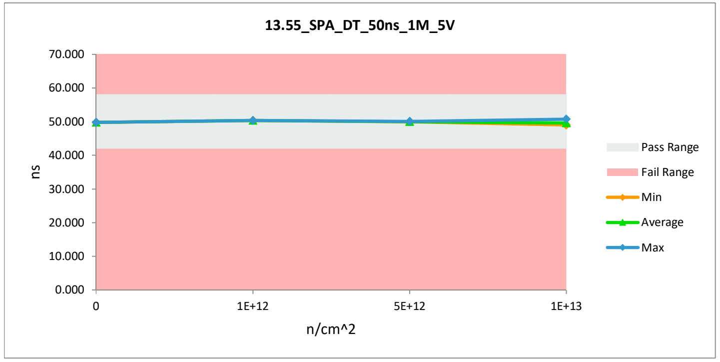


NDD Characterization Report
TPS7H5007-SEP

		13.55_SPA_DT_50ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	58	58	
	Min Limit	42	42	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	48.917	49.784	0.867
1E+12	21	49.417	50.339	0.922
1E+12	22	49.486	50.378	0.892
1E+12	23	49.466	50.349	0.883
5E+12	24	49.187	50.075	0.888
5E+12	25	49.065	49.927	0.862
5E+12	26	49.075	49.949	0.874
1E+13	27	49.859	50.776	0.917
1E+13	28	48.412	49.139	0.727
1E+13	29	48.157	49.011	0.854
	Max	49.859	50.776	0.922
	Average	49.104	49.973	0.869
	Min	48.157	49.011	0.727
	Std Dev	0.513	0.553	0.054

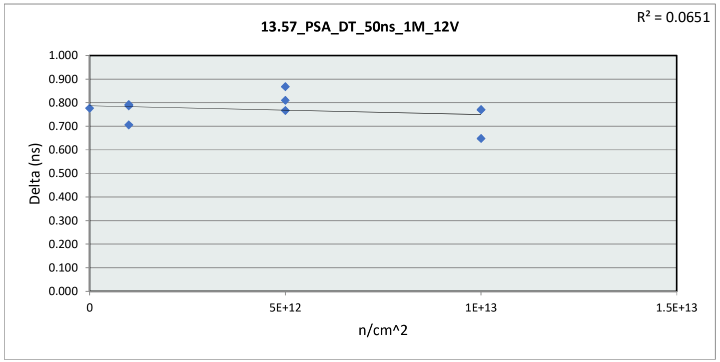


13.55_SPA_DT_50ns_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	58	ns		
Min Limit	42	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	42.000	42.000	42.000	42.000
Min	49.784	50.339	49.927	49.011
Average	49.784	50.355	49.984	49.642
Max	49.784	50.378	50.075	50.776
UL	58.000	58.000	58.000	58.000

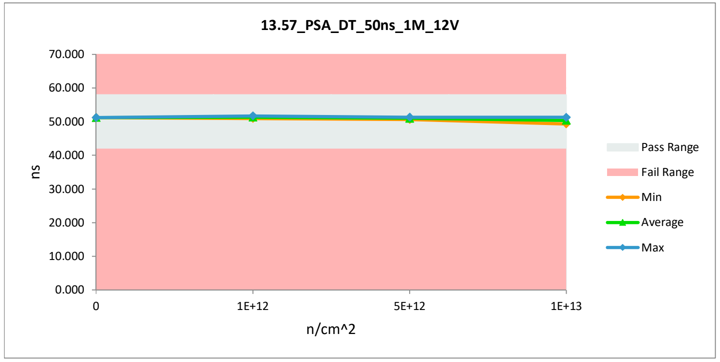


NDD Characterization Report
TPS7H5007-SEP

		13.57_PSA_DT_50ns_1M_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		58	58	
Min Limit		42	42	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	50.444	51.220	0.776
1E+12	21	50.921	51.707	0.786
1E+12	22	50.142	50.933	0.791
1E+12	23	50.688	51.393	0.705
5E+12	24	49.840	50.649	0.809
5E+12	25	50.296	51.062	0.766
5E+12	26	50.437	51.304	0.867
1E+13	27	50.603	51.250	0.647
1E+13	28	49.854	50.623	0.769
1E+13	29	48.559	49.328	0.769
	Max	50.921	51.707	0.867
	Average	50.178	50.947	0.769
	Min	48.559	49.328	0.647
	Std Dev	0.666	0.658	0.059

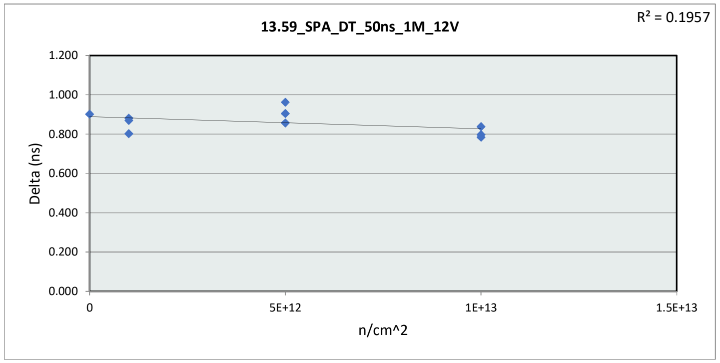


	13.57_PSA_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	58	ns		
Min Limit	42	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	42.000	42.000	42.000	42.000
Min	51.220	50.933	50.649	49.328
Average	51.220	51.344	51.005	50.400
Max	51.220	51.707	51.304	51.250
UL	58.000	58.000	58.000	58.000

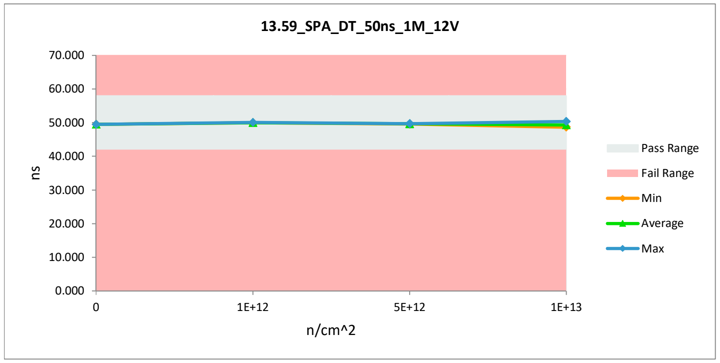


NDD Characterization Report
TPS7H5007-SEP

		13.59_SPA_DT_50ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	58	58	
	Min Limit	42	42	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	48.592	49.493	0.901
1E+12	21	49.097	49.977	0.880
1E+12	22	49.164	49.965	0.801
1E+12	23	49.192	50.061	0.869
5E+12	24	48.807	49.711	0.904
5E+12	25	48.713	49.569	0.856
5E+12	26	48.726	49.687	0.961
1E+13	27	49.587	50.371	0.784
1E+13	28	48.053	48.849	0.796
1E+13	29	47.858	48.695	0.837
	Max	49.587	50.371	0.961
	Average	48.779	49.638	0.859
	Min	47.858	48.695	0.784
	Std Dev	0.526	0.525	0.056

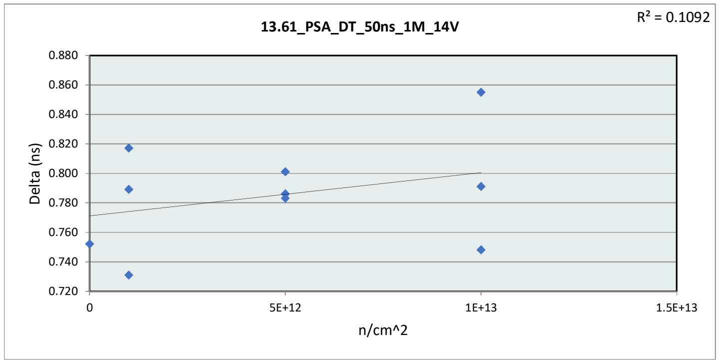


	13.59_SPA_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	58	ns		
Min Limit	42	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	42.000	42.000	42.000	42.000
Min	49.493	49.965	49.569	48.695
Average	49.493	50.001	49.656	49.305
Max	49.493	50.061	49.711	50.371
UL	58.000	58.000	58.000	58.000

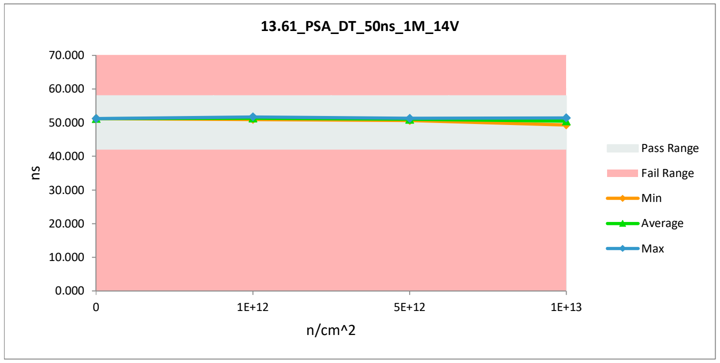


NDD Characterization Report
TPS7H5007-SEP

		13.61_PSA_DT_50ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	58	58	
	Min Limit	42	42	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	50.434	51.186	0.752
1E+12	21	50.936	51.725	0.789
1E+12	22	50.132	50.949	0.817
1E+12	23	50.660	51.391	0.731
5E+12	24	49.828	50.614	0.786
5E+12	25	50.255	51.056	0.801
5E+12	26	50.482	51.265	0.783
1E+13	27	50.545	51.400	0.855
1E+13	28	49.834	50.625	0.791
1E+13	29	48.569	49.317	0.748
	Max	50.936	51.725	0.855
	Average	50.167	50.953	0.785
	Min	48.569	49.317	0.731
	Std Dev	0.661	0.671	0.036

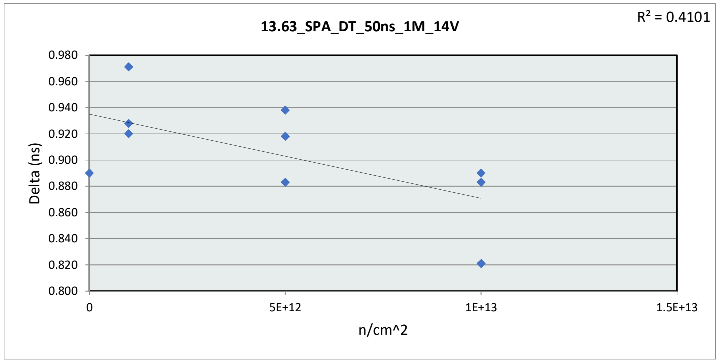


	13.61_PSA_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	58	ns		
Min Limit	42	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	42.000	42.000	42.000	42.000
Min	51.186	50.949	50.614	49.317
Average	51.186	51.355	50.978	50.447
Max	51.186	51.725	51.265	51.400
UL	58.000	58.000	58.000	58.000

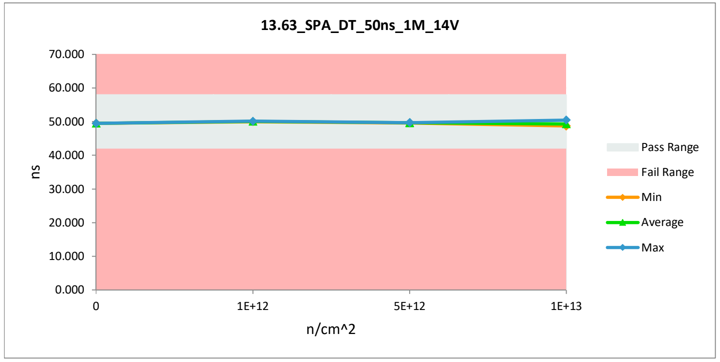


NDD Characterization Report
TPS7H5007-SEP

		13.63_SPA_DT_50ns_1M_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		58	58	
Min Limit		42	42	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	48.614	49.504	0.890
1E+12	21	49.055	49.983	0.928
1E+12	22	49.104	50.024	0.920
1E+12	23	49.149	50.120	0.971
5E+12	24	48.804	49.742	0.938
5E+12	25	48.706	49.589	0.883
5E+12	26	48.727	49.645	0.918
1E+13	27	49.556	50.446	0.890
1E+13	28	48.009	48.830	0.821
1E+13	29	47.821	48.704	0.883
	Max	49.556	50.446	0.971
	Average	48.754	49.659	0.904
	Min	47.821	48.704	0.821
	Std Dev	0.523	0.548	0.041

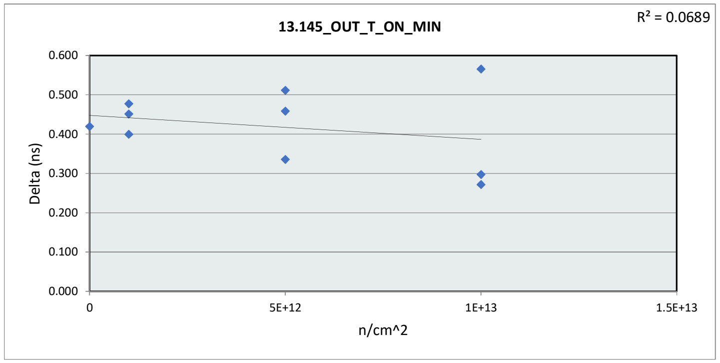


	13.63_SPA_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	58	ns		
Min Limit	42	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	42.000	42.000	42.000	42.000
Min	49.504	49.983	49.589	48.704
Average	49.504	50.042	49.659	49.327
Max	49.504	50.120	49.742	50.446
UL	58.000	58.000	58.000	58.000

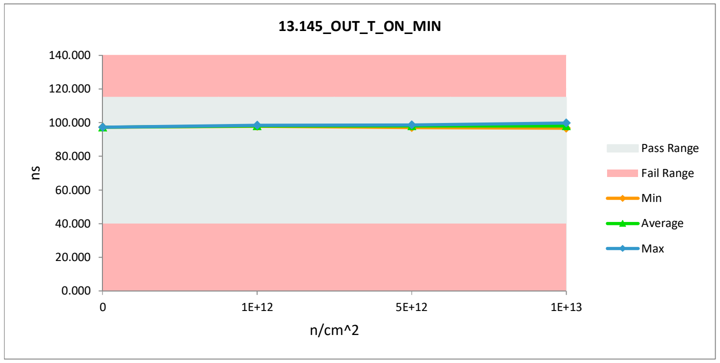


NDD Characterization Report
TPS7H5007-SEP

	13.145_OUT_T_ON_MIN			
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		115	115	
Min Limit		40	40	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	96.811	97.230	0.419
1E+12	21	97.380	97.857	0.477
1E+12	22	98.072	98.471	0.399
1E+12	23	97.417	97.868	0.451
5E+12	24	96.639	97.097	0.458
5E+12	25	98.309	98.644	0.335
5E+12	26	97.914	98.425	0.511
1E+13	27	99.484	99.755	0.271
1E+13	28	96.402	96.699	0.297
1E+13	29	97.339	97.904	0.565
	Max	99.484	99.755	0.565
	Average	97.577	97.995	0.418
	Min	96.402	96.699	0.271
	Std Dev	0.913	0.885	0.094

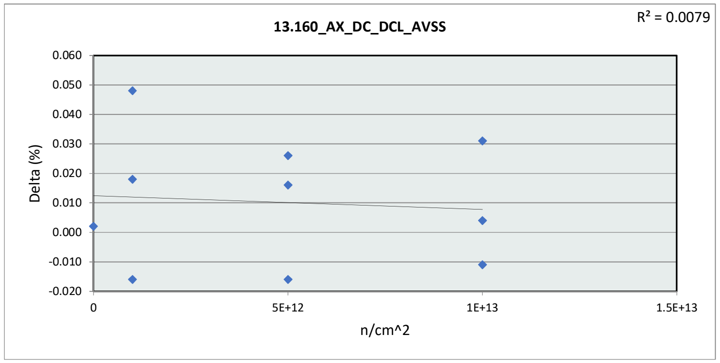


13.145_OUT_T_ON_MIN				
Test Site				
Tester				
Test Number				
Max Limit	115	ns		
Min Limit	40	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	40.000	40.000	40.000	40.000
Min	97.230	97.857	97.097	96.699
Average	97.230	98.065	98.055	98.119
Max	97.230	98.471	98.644	99.755
UL	115.000	115.000	115.000	115.000

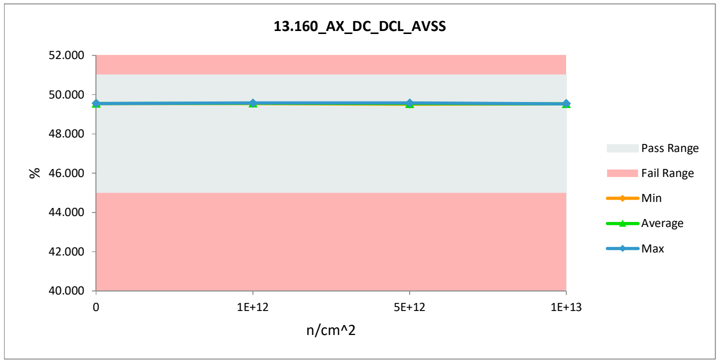


NDD Characterization Report
TPS7H5007-SEP

		13.160_AX_DC_DCL_AVSS		
	Test Site			
	Tester			
	Test Number			
	Unit	%	%	
	Max Limit	51	51	
	Min Limit	45	45	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	49.549	49.551	0.002
1E+12	21	49.561	49.545	-0.016
1E+12	22	49.506	49.554	0.048
1E+12	23	49.558	49.576	0.018
5E+12	24	49.532	49.516	-0.016
5E+12	25	49.514	49.530	0.016
5E+12	26	49.541	49.567	0.026
1E+13	27	49.502	49.533	0.031
1E+13	28	49.544	49.533	-0.011
1E+13	29	49.533	49.537	0.004
	Max	49.561	49.576	0.048
	Average	49.534	49.544	0.010
	Min	49.502	49.516	-0.016
	Std Dev	0.021	0.018	0.021

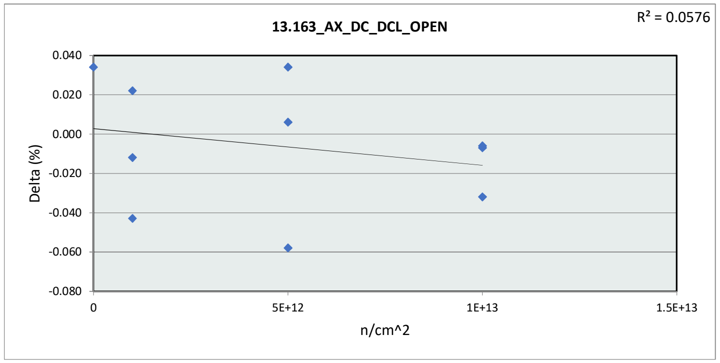


	13.160_AX_DC_DCL_AVSS			
Test Site				
Tester				
Test Number				
Max Limit	51	%		
Min Limit	45	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	45.000	45.000	45.000	45.000
Min	49.551	49.545	49.516	49.533
Average	49.551	49.558	49.538	49.534
Max	49.551	49.576	49.567	49.537
UL	51.000	51.000	51.000	51.000

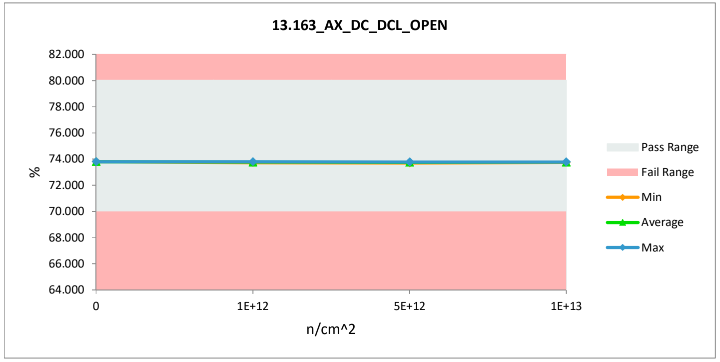


NDD Characterization Report
TPS7H5007-SEP

		13.163_AX_DC_DCL_OPEN		
Test Site				
Tester				
Test Number				
Unit		%	%	
Max Limit		80	80	
Min Limit		70	70	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	73.773	73.807	0.034
1E+12	21	73.769	73.726	-0.043
1E+12	22	73.770	73.792	0.022
1E+12	23	73.795	73.783	-0.012
5E+12	24	73.741	73.775	0.034
5E+12	25	73.766	73.708	-0.058
5E+12	26	73.764	73.770	0.006
1E+13	27	73.785	73.778	-0.007
1E+13	28	73.810	73.778	-0.032
1E+13	29	73.752	73.746	-0.006
	Max	73.810	73.807	0.034
	Average	73.772	73.766	-0.006
	Min	73.741	73.708	-0.058
	Std Dev	0.020	0.031	0.031

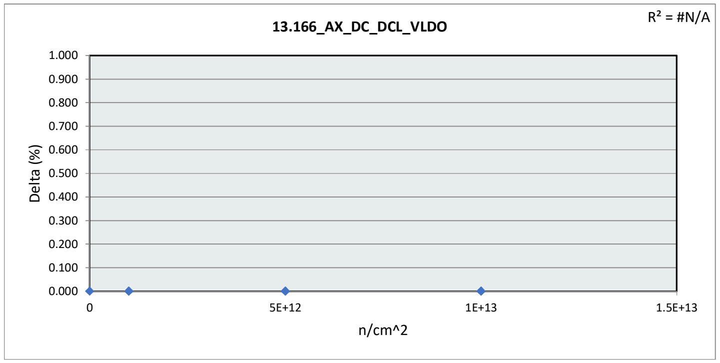


	13.163_AX_DC_DCL_OPEN			
Test Site				
Tester				
Test Number				
Max Limit	80	%		
Min Limit	70	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	70.000	70.000	70.000	70.000
Min	73.807	73.726	73.708	73.746
Average	73.807	73.767	73.751	73.767
Max	73.807	73.792	73.775	73.778
UL	80.000	80.000	80.000	80.000

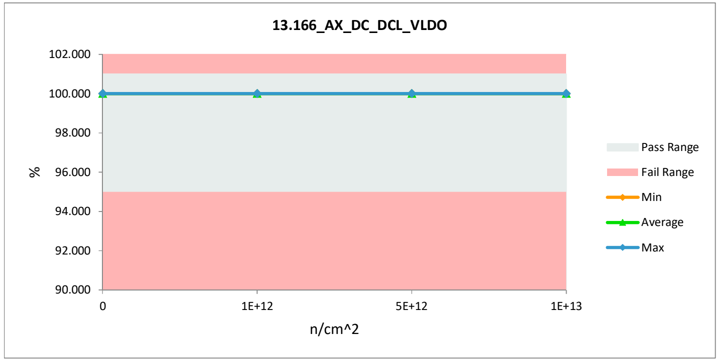


NDD Characterization Report
TPS7H5007-SEP

		13.166_AX_DC_DCL_VLDO		
	Test Site			
	Tester			
	Test Number			
	Unit	%	%	
	Max Limit	101	101	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5007SEP	Post_NDD_5007-SEP	Delta
0	48	100.000	100.000	0.000
1E+12	21	100.000	100.000	0.000
1E+12	22	100.000	100.000	0.000
1E+12	23	100.000	100.000	0.000
5E+12	24	100.000	100.000	0.000
5E+12	25	100.000	100.000	0.000
5E+12	26	100.000	100.000	0.000
1E+13	27	100.000	100.000	0.000
1E+13	28	100.000	100.000	0.000
1E+13	29	100.000	100.000	0.000
	Max	100.000	100.000	0.000
	Average	100.000	100.000	0.000
	Min	100.000	100.000	0.000
	Std Dev	0.000	0.000	0.000



	13.166_AX_DC_DCL_VLDO			
Test Site				
Tester				
Test Number				
Max Limit	101	%		
Min Limit	95	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	100.000	100.000	100.000	100.000
Average	100.000	100.000	100.000	100.000
Max	100.000	100.000	100.000	100.000
UL	101.000	101.000	101.000	101.000



6 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (August 2022) to Revision A (August 2024)	Page
• Updated document title	1
• Updated document to include information for TPS7H5003-SP QMLP	1

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